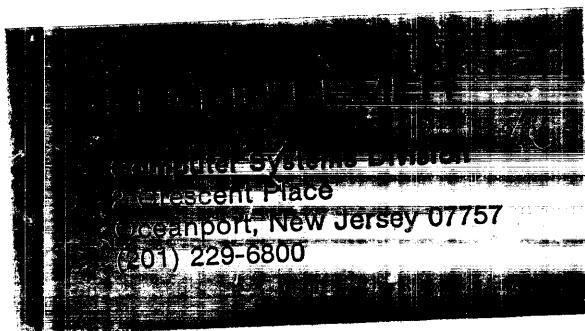


SERIES - 16 19-221
MOS MEMORY TEST
PART 2

Consists of:

Test Program Description	B06-214M95A15
Test Program Listing	06-214F01M96A13
Test Program Listing	06-214F02M96A13
Test Program Paper Tape	06-214F01M17
Test Program Paper Tape	06-214F02M17



B06-214M95R00A15
August 1978

SERIES-16 19-221 MOS
MEMORY TEST, PART 2

1. GENERAL

Title:

Series-16 19-221 MOS Memory Test, Part 2 06-214R00

Related documents:

Program Listings	06-214F01M96R00A13
Program Paper Tapes	06-214F02M96R00A13
	06-214F01M17R00
	06-214F02M17R00

Test programs to be run prior to loading
this test:

8/16E Processor Test, Part 1	06-211
8/16E Processor Test, Part 2	06-212

Other applicable tests:

Common Teletype Basic Confidence Test	06-004
Common CRT Test	06-146
Common Line Printer Test	06-170
Common Carousel 300 Test	06-183
Common Current Loop Interface Test	06-184

2. PURPOSE OF THE TEST

The Series-16 19-221 MOS Memory Test Part 2, Program Number 06-214, verifies the operation of all 8/16E 64kb and larger MOS memories. Part 1 of this program, 06-213, verifies the operation of all 8/16E 32kb MOS memories.

The following test modules are available:

Test 0 (Memory Search Test): This test module lists the limits of memory under test.

Test 1 (Bit Set - Reset Test): This test ensures that all available memory bits can be set and reset at will.

Test 2 (Marching Pattern Test): This test ensures that three patterns can be written throughout memory and complemented.

Test 3 (0 and 1 Walk Test): This test marches a 1 through a field of 0s and a 0 through a field of 1s. It also checks the parity bit.

Test 4 (Double Operation Column Disturb Test): This module ensures that a double column disturb will not cause an error in adjacent columns.

Test 5 (Short Count Relocatable Hammer Disturb Test): This test (short count) relocates a short program throughout memory and executes the program.

Test 6 (Diagonal Galpat Test): This test runs a complete diagonal Galpat on each 32kb of RAM.

Test 7 (Memory Hold Test): This test checks the ability of the MOS memory refresh circuit to operate if a power failure occurs.

Test 8 (Long Count Relocatable Hammer Disturb Test): This overnight (long count) test checks each test location 65,000 times. It also checks background for soft failures.

Test 9 (ECC Disturb Test): This test uses logical data patterns to check the ECC syndrome bits.

Test A (Parity Disturb Test): This test checks the parity bit for set and reset operations under even and odd parity conditions.

3. MINIMUM HARDWARE REQUIRED

Processor:

8/16E with battery backup power supply

Minimum MOS Memory:

64kb or larger

Console Input Device (See Appendix A):

Teletype type device or
CRT on current loop interface or
CRT on PASLA/PALM or
Carousel 15, 30, 35, 300

List Device (See Appendix A):

Teletype type device or
CRT on current loop interface or
CRT on PASLA/PALM or
Line printer or
Carousel 15, 30, 35, 300

Paper Tape Reader:

Teletype type device or
Carousel 35 or
High-speed, paper-tape reader

4. REQUIREMENTS

This program assumes that the applicable test programs have been run without detecting an error.

5. LOADING PROCEDURE

5.1 Test Tape Format

Absolute, non-zoned object tape (M17) with front end bootloader. The test program occupies approximately 7kb memory per section.

5.2 Normal Loading Procedure

1. Manually enter the X'50' sequence shown below into memory:

	LOCATION	CONTENTS
	X'30'	X'0000'
	X'32'	X'0000'
	X'34'	X'0000'
	X'36'	X'0050'
	X'50'	X'D500'
	X'52'	X'00CF'
	X'54'	X'4300'
	X'56'	X'0080'
For TTY or Carousel 35	X'78'	X'0294'
HSPTR	X'78'	X'0399'
HSPTR/P	X'78'	X'1399'

2. Place the program tape in the paper-tape reader.
3. Execute at address X'30'.
4. When the processor halts, observe the CHKSUM byte displayed on the console display register D1. If it is zero, loading is completed. If it is not zero, repeat this loading procedure.

5.3 Loading From Multimedia Diagnostic System

To load this program from the Interdata Multimedia Diagnostic System, refer to Program Description 06-176M95A15 provided in Program Number 06-176.

5.4 Program Execution

Refer to Appendix A and set up the address for the console input device and the list device. Address memory location X'100' for F01 and X'8000' for F02. Start program execution and observe that the following title is output to the list device:

```
S16 19-221 MOS MEMORY TEST PART 2 06-214F01  
or: S16 19-221 MOS MEMORY TEST PART 2 06-214F02
```

6. OPERATING PROCEDURES

6.1 Normal Testing

To execute the default tests (Tests 0 through 4), enter the following options from the console device. (See Appendix C.) Appendix B summarizes the command option input format.

*TEST	CR	Selects the default tests (default 0-4).
*SCOPE	0 CR	Selects the error option (default 0).
*DTAPAT	FFFF CR	Selects the background data pattern (default X'FFFF').
*RUN	CR	Starts the test sequence.

The program executes Test 0 through Test 4 in the default test sequence. Appendix D summarizes expected results. Section 7 summarizes error messages and fault isolation procedures.

6.2 Extended Normal Testing

To execute Test 5, Test 6, Test 9, or Test A, enter the following options from the console device. (See Appendix C.)

*TEST	5 (6,9, or A) CR	Selects Test 5 (6, 9, or A).
*SCOPE	0 CR	Selects the error option.
*RUN	CR	Starts the test sequence.

The program executes Test 0 and Tests 5 or 6 in sequence.

To execute Test 7, enter the following options from the console device. (See Appendix C.) Appendix B summarizes the command option input format.

*TEST	7 CR	Selects Test 7.
*SCOPE	0 CR	Selects the error option.
*RUN	CR	Starts the test sequence.

The program now executes Test 0 and Test 7 in sequence. Appendix D summarizes expected results. Section 7 summarizes error messages and fault isolation procedures.

6.3 Optional Testing

6.3.1 General

The appropriate options should be changed (refer to the option table in Appendix C) for the configuration under test. Over-night testing is allowed by turning the console off-line while the test is running. When the console is returned to the on-line condition, the program prints its statistics (total passes and total errors) when it reaches the end of a test module and after a delay has been provided to let CRT warm up. If the console is not returned to the on-line condition before X'7FFF' passes are executed or X'7FFF' errors are detected, the processor halts and resumes execution only upon depressing RUN.

6.3.2 Test 8

To run the Long Relocatable Hammer Disturb Test, use the following option entry sequence:

*TEST	8	CR
*SCOPE	0	CR
*DTAPAT	FFFF	CR
*RUN	CR	

Test 0 prints out the addresses under test. Test 8 increments the display for each location tested. Errors are printed on the list device and the specified SCOPE option dictates further processor action.

7. ERROR PROCEDURES

Error Recovery - If the program detects an error in any test, it executes the SCOPE option entered before the start of program execution.

Error Message and Fault Isolation - Appendix E summarizes error messages. It is designed to guide the user through a systematic fault isolation procedure. Looping can be accomplished by entering the appropriate option. See Appendix C.

8. PROGRAMMING NOTES

To abort a test in progress or exit the testing sequence when CONTIN equals 1, depress and hold the BREAK key on the console device for five seconds. The test terminates when the console device is interrogated.

If present, the display panel (D3 and D4) indicates the PSW Bits 8-11 (Physical Memory Segment) under test. D1 and D2 indicate the location under test.

Tests 9 and A cannot be run in conjunction with each other. An "ILLEGAL TEST SEQUENCE" message will result.

APPENDIX A
USER DEVICE DEFINITION

The halfword labeled 'IO' (see the Program Listing) has the default value for Teletype, CRT, or Carousel 15/30/35 (all on Current Loop Interface) as the input/output console device. If the setup is different, 'IO' must be changed as follows:



CONSOLE DEVICE IDENTIFIER	MEANING
X'01'	GDT/CRT on PASLA/PALM interface, strapped for FDX operation and highest baud rate.
X'02'	TTY/GDT/CRT/Carousel 15/30/35 on current loop interface.
X'03'	Reserved; interpreted as X'02'.
X'04'	Carousel 300 on PASLA/PALM interface, strapped for FDX operation and highest baud rate.
X'05'	Micro I/O bus (or adapter).
X'00', X'06' - X'FF'	Reserved; interpreted at X'02'.

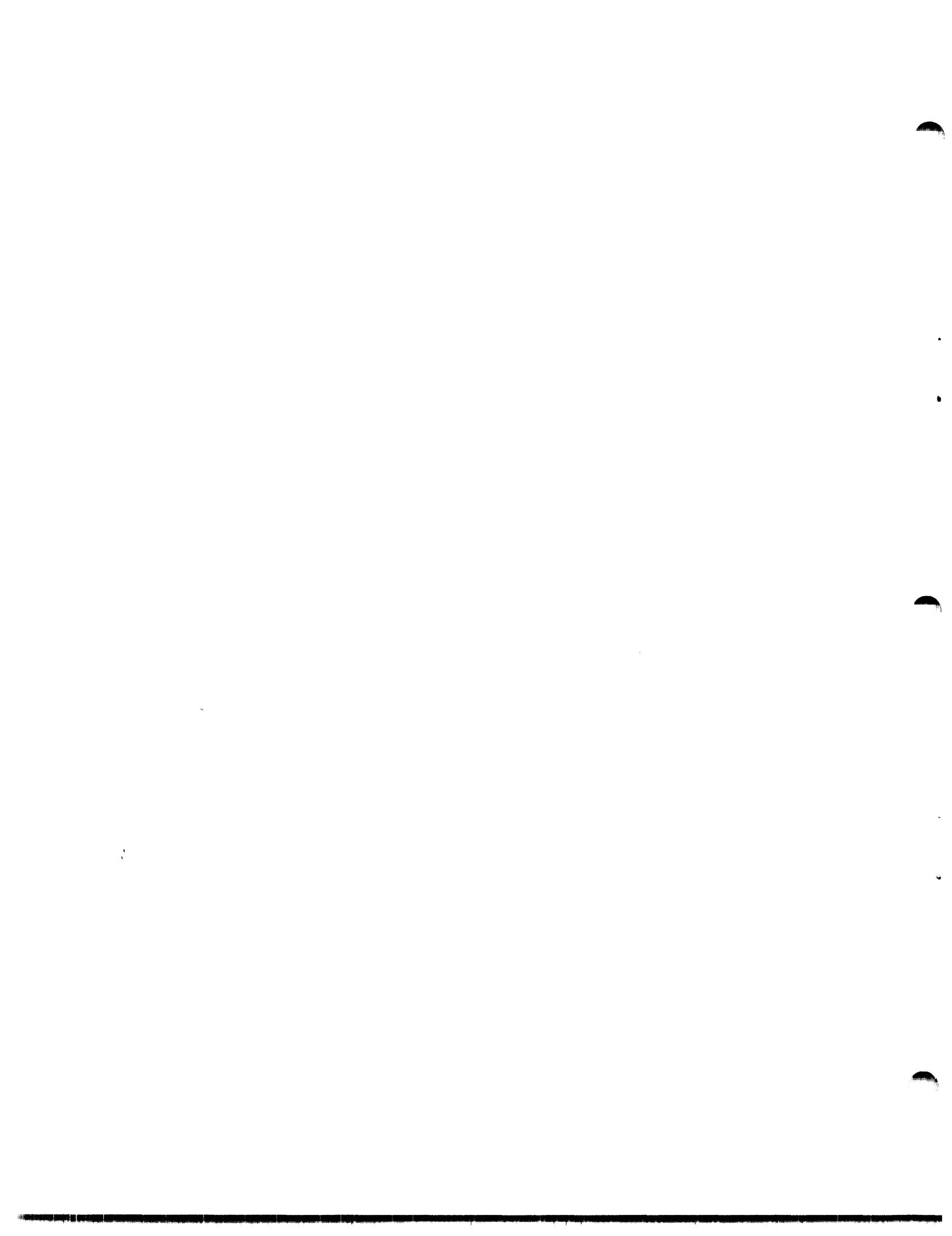
APPENDIX A (Continued)
USER DEVICE DEFINITION

LIST DEVICE IDENTIFIER	MEANING
X'01'	GDT/CRT on PASLA/PALM interface, strapped for FDX operation and highest baud rate.
X'02'	TTY/GDT/CRT/Carousel 15/30/35 on current loop interface.
X'03'	Line printer (Data Printer or Centronics) on line printer interface.
X'04'	Carousel 300 on PASLA/PALM interface, strapped for FDX operation and highest baud rate.
X'05'	Micro I/O bus (or adapter).
X'00', X'06' - X'FF'	Reserved; interpreted as X'02'.

1. If the Graphic Display Terminal (GDT) is used on PASLA/PALM interface, it should be strapped for device addresses X'10' and X'11' for receive and transmit sides, respectively. If the addresses are different, then the halfword labeled 'PASLADR' (see the Program Listing) must be changed accordingly.
2. If the Teletype typewriter or current loop interface is used, it should be strapped for device address X'02'. If the address is different, the halfword labeled 'CLIFADR' (see the Program Listing) must be changed accordingly.
3. If the line printer interface is used, it should be strapped for device address X'62'. If the address is different, the halfword labeled 'LPADR' (see the Program Listing) must be changed accordingly.
4. If the Carousel 300 is used, it should be strapped for device addresses X'10' and X'11', for receive and transmit sides, respectively. If the addresses are different, the halfword labeled 'C300ADR' (see the Program Listing) must be changed accordingly.

APPENDIX B COMMAND/OPTION INPUT METHOD

An asterisk (*) output to the console device indicates that the program is waiting user input. All option names must be typed in from the console followed by a space and the desired argument or arguments separated by commas. A carriage return (CR) must be typed to end every command-option input. An invalid command-option name or option value causes a question mark (?) followed by a carriage return (CR), line feed (LF), and an asterisk (*) to be output. If an error is made during command/option entry, it can be handled in two ways: the hash mark (#) can be typed to delete the entire line, causing a carriage return (CR), line feed (LF), and an asterisk (*) to be output; or either the left arrow (\leftarrow) or backspace (Control-H) can be typed to delete the previous character; or a string of characters can be deleted by typing a left arrow (\leftarrow) or backspace (Control-H) for each character to be deleted.

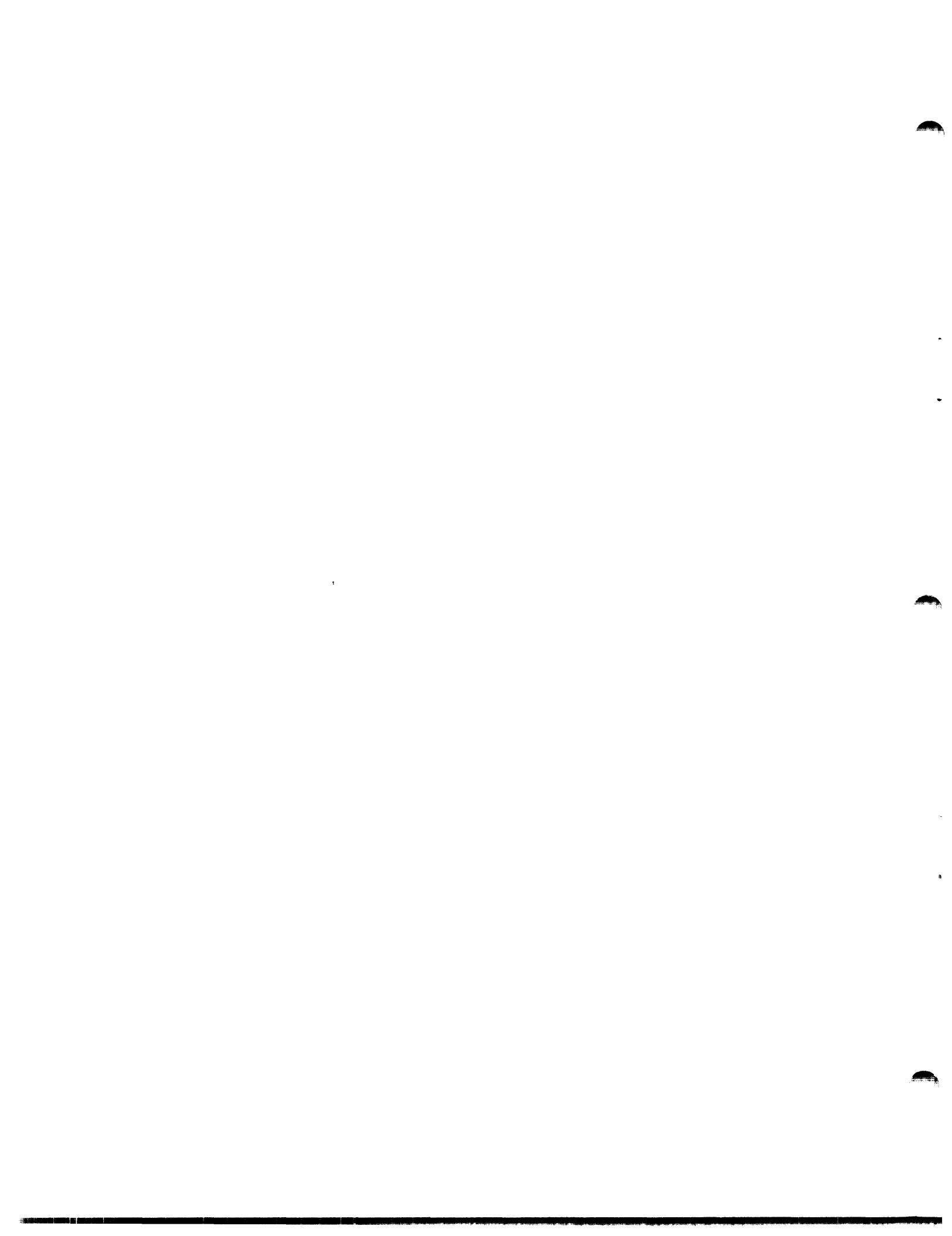


APPENDIX C
OPTION TABLE

OPTION	DEFAULT	TESTS	DESCRIPTION
LOPHYS	0	ALL	Low physical sector (address PSW) 0-6
HIPHYS	6	ALL	High physical sector (address PSW) 0-6
DATA	FFFF	5	Data pattern used as background in relocatable hammer disturb tests (four hexadecimal characters)
SCOPE	0	ALL	Error handling procedure 0 = Print error data and skip to next test 1 = Print chip number(s) and skip to next test 2 = Print error data and continue test 3 = Print error data and halt 4 = Ignore error and continue test 5 = Print chip number(s) and error data and continue test
TEST	0,1,2,3,4	ALL	Test number (0 - A) Note: Tests 9 and A cannot be run together
NOMSG	0	ALL	Message handling option 0 = Print all messages 1 = Print only error messages
CONTIN	0	ALL	Testing sequence option 0 = No effect on testing sequence 1 = Run all selected tests con- tinuously (e.g., 0 → 4, 0 → 4, 0 → 4, etc.)
LOOP	0	ALL	Number of loops through each test (0-7FFF)
POUND	A	5	Number of times each location is checked in Test 5
CON	0		Return to console (use with X'8800' code support only)

NOTE

The limits of memory under test are fixed and
cannot be changed except with LOPHYS and HIPHYS.
LOPHYS and HIPHYS correspond to MSD of OS address.



APPENDIX D
EXPECTED RESULT TABLE

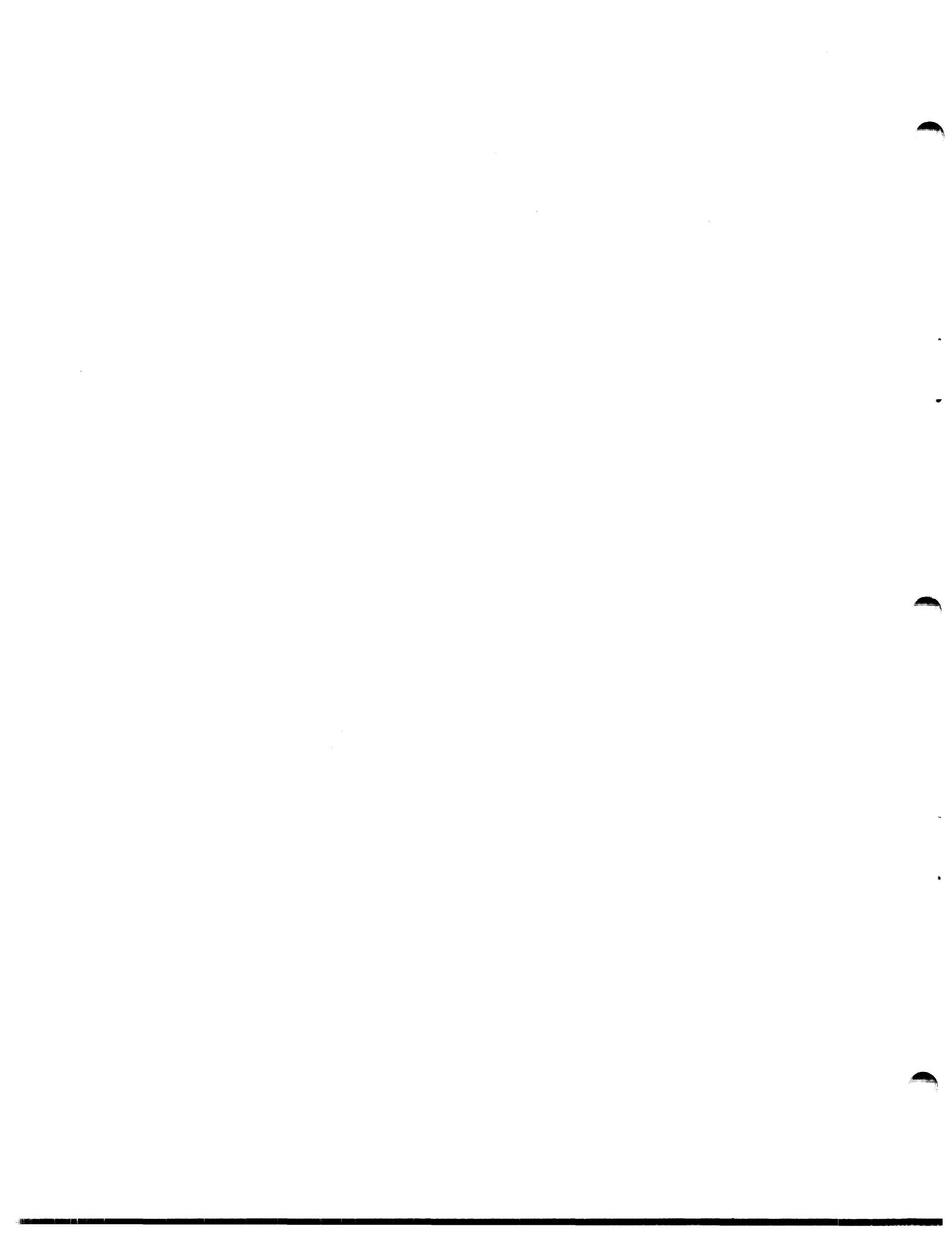
S16 19-221 MOS MEMORY TEST PART 2 06-214F01 (or F02)

*TEST
*RUN

TEST 00
MEMORY UNDER TEST
08000-6FFFF (or 00000-07FFF)
NO ERROR
TEST 01
NO ERROR
TEST 02
NO ERROR
TEST 03
NO ERROR
TEST 04
NO ERROR
END OF TEST
*

*TEST 5,6,7,8,9 (or 5,6,7,8,A)
*RUN

TEST 00
MEMORY UNDER TEST
08000-6FFFF (or 00000-07FFF)
NO ERROR
TEST 05
NO ERROR
TEST 06
MEMORY UNDER GALPAT TEST
08000-6FFFF (or 00000-07FFF)
NO ERROR
TEST 07
POWER DOWN PROCESSOR FOR 30 SECONDS
NO ERROR
TEST 08
NO ERROR
TEST 09 (or TEST 0A)
NO ERROR
END OF TEST
*



APPENDIX E ERROR MESSAGES

EXPECTED ERROR PRINTOUT

If SCOPE = 0, 2, or 3

ERROR TTNN
LOC PXXXX DATA EXP YYYY DATA READ ZZZZ PSW = QQQQ

If SCOPE = 4, no error printout until end of test and then
only the number of passes and the number of
errors are printed.

If SCOPE = 1 or 5

ERROR TTNN
SUSPECTED BAD CHIP DEEE
LOC PXXXX DATA ESP YYYY DATA READ ZZZZ PSW = QQQQ

Where: TT = Test number
 NN = Error number

D = Drive letter (A or B)
EEE = Chip number within drive area
P = Physical segment of failure (0 - 6)
XXXX = Location of memory failure(as seen by processor)
YYYY = Data written to location XXXX
ZZZZ = Data read from location XXXX
QQQQ = PSW at the time of error

i.e. LOC 38002 = physical segment 3 and location
0002 in that segment.

If equipped, the display panel register D3 shows the most
significant digit of the address under test (as per OS16/MT).
Registers D2 and D1 show the address under test (when dis-
played).

APPENDIX E (Continued)
ERROR MESSAGES

ERROR NUMBER	ERROR CONDITION	POSSIBLE EXPLANATION	SUGGESTED ACTION
TT01	Bit did not set in halfword when X'FFFF' was stored at LOC.	1. Hard reset bit in memory chip 2. "Soft" reset bit in memory chip 3. Timing problem	1. Manually write X'FFFF' to LOC and read LOC. 2. Check timing. 3. Replace memory chip.
TT02	Bit did not reset in half-word when 0 was stored at LOC.	1. Hard set bit in memory chip 2. Hard to reset bit in memory chip 3. Timing problem	1. Manually write X'FFFF' to LOC and read LOC. 2. Check timing. 3. Replace memory chip.
TT03	Bit pattern was not written/read correctly.	1. Hard bit failure (set or reset) 2. Hard to set or reset bit in memory chip (soft failure) 3. Timing problem 4. Double addressing	1. Manually write X'FFFF' to LOC and read LOC. 2. Check timing. 3. Replace memory chip.
TT04	Bit pattern did not complement.	1. Hard bit failure (set or reset) 2. Hard to set or reset bit in memory chip 3. Timing problem	1. Manually write X'FFFF' to LOC and read LOC. 2. Check timing. 3. Replace memory chip.
TT05	Complement bit pattern was disturbed while writing to another location.	1. Double addressing 2. Timing problem 3. Hard to set or reset bit in memory chip (soft failure)	1. Check refresh circuitry. 2. Check memory chip address lines. 3. Replace memory chip.

APPENDIX E (Continued)
ERROR MESSAGES

ERROR NUMBER	ERROR CONDITION	POSSIBLE EXPLANATION	SUGGESTED ACTION
TT06	Original data pattern did not restore properly.	1. Double addressing 2. Timing problem 3. Hard to set or reset bit in memory chip (soft failure)	1. Check refresh circuitry 2. Check memory chip address lines. 3. Replace memory chip.
TT07	Test bit did not reset in halfword when a 0 was walked through a field of all 1s.	1. Hard to reset bit in memory chip 2. Timing problem	1. Manually write X'FFFF' to LOC and read LOC. 2. Check timing. 3. Replace memory chip.
TT08	Test bit did not set in halfword when a 1 was walked through a field of all 0s.	1. Hard to set bit in memory chip 2. Timing problem	1. Manually write X'FFFF' to LOC and read LOC. 2. Check timing. 3. Replace memory chip.
TT09	Original background pattern did not set after single disturb.	1. Refresh problem 2. Double addressing 3. Bad memory chip	1. Check refresh circuitry. 2. Check memory chip address lines. 3. Replace memory chip.
TT0A	Complement background pattern did not set while doing a double disturb.	1. Refresh problem 2. Double addressing 3. Bad memory chip	1. Check refresh circuitry. 2. Check memory chip address lines. 3. Replace memory chip.
TT0B	Complement background pattern did not set after a single disturb.	1. Refresh problem 2. Double addressing 3. Bad memory chip	1. Check refresh circuitry. 2. Check memory chip address lines. 3. Replace memory chip.

APPENDIX E (Continued)
ERROR MESSAGES

ERROR NUMBER	ERROR CONDITION	POSSIBLE EXPLANATION	SUGGESTED ACTION
TT0C	Original background pattern did not reset while doing a double disturb.	1. Refresh problem 2. Double addressing 3. Bad memory chip	1. Check refresh circuitry. 2. Check memory chip address lines. 3. Replace memory chip.
TT0D	Bit(s) failed to set or reset while doing a location pound.	1. Hard bit failure (set or reset) 2. Hard to set or reset bit in memory chip 3. Timing problem	1. Manually write X'FFFF' to LOC and read LOC. 2. Check timing. 3. Replace memory chip.
TT0E	Background cell was disturbed when a test location was written.	1. Double addressing 2. Timing problem 3. Hard to set or reset bit in memory chip (soft failure)	1. Check refresh circuitry. 2. Check memory chip. address lines. 3. Replace memory chip.
TT10	Test cell failed to complement on a diagonal Galpat.	1. Timing problem 2. "Soft" memory chip failure	1. Check timing circuitry. 2. Replace memory chip.
TT11	Running cell changed when test cell was written to on diagonal Galpat.	1. Refresh problem 2. Timing problem 3. "Soft" memory chip failure	1. Check refresh circuitry. 2. Check timing circuitry. 3. Replace memory chip.
TT12	Parity bit error.	1. Parity check failure 2. Refresh problem 3. Timing problem 4. "Soft" memory chip failure	1. Check parity circuitry. 2. Check refresh circuitry. 3. Check timing circuitry. 4. Replace memory chip.

APPENDIX E (Continued)
ERROR MESSAGES

ERROR NUMBER	ERROR CONDITION	POSSIBLE EXPLANATION	SUGGESTED ACTION
TT2N	Upon powering down processor, memory changed at LOC indicated and was detected on read pass "N".	1. P12 or P5S problem 2. Refresh problem 3. Memory chip fails to refresh in standby (burst mode)	1. Check P12 and P5S (W/WO AC power). 2. Check refresh circuitry. 3. Replace memory chip.
TTF1	16-bit, fixed-point arithmetic fault interrupt.	1. Fixed-point division by zero 2. Fixed-point quotient overflow	1. Depress INIT. 2. Restart program from beginning.
TTF2	Illegal instruction interrupt.	1. Program did not load properly 2. Program destroyed	1. Reload program. 2. Start from beginning.
TTF3	Machine malfunction interrupt. Condition code in PSW printout indicates nature of machine malfunction interrupt.	1. Power fail/restore 2. Initialize 3. Memory malfunction	1. Machine will be halted. 2. Depress RUN.
TTF4	Unexpected device spurious interrupt	1. Device interrupt queued 2. RACK0/TACK0 problem	1. Depress INIT. 2. Restart program from beginning. 3. Check backpanel.
TTF5	16-bit, floating-point fault interrupt.	1. Floating-point division by zero 2. Floating-point exponent overflow or underflow	1. Depress INIT. 2. Restart program from beginning.



PROG= MOSQ21 ASSEMBLED BY CAL 03-066R05-01 (32-BIT)

1	CROSS	MOS 30010	
2	TARGT 16	MOS 30020	
3	WIDTH 120	MOS 30030	
4	MOSQ21 PROG S16 19-221 MOS MEMORY TEST PART 2 06-214F01M96R00A13	MOS 30040	
5	SQCHK	MOS 30050	
6	* *****	MOS 30060	
7	SERIES-16 19-221 MOS MEMORY TEST PART 2 - SECTION 1 (F01)	MOS 30070	
8	COPYRIGHT PERKIN-ELMER CORP. OCTOBER, 1978	MOS 30080	
9	*	MCS 30090	
10	THIS PROGRAM TESTS THE UPPER PORTION OF A 64KB OR LARGER	MOS 30100	
11	MOS MEMORY IN AN INTERDATA SERIES 16 EXTENDED MEMORY	MOS 30110	
12	PROCESSOR WITH AN OPTIONAL BATTERY BACK-UP POWER SUPPLY.	MOS 30120	
13	*	MOS 30130	
14	TEST 0 MEMORY SEARCH TEST	MOS 30140	
15	*	MOS 30150	
16	TEST 1 BIT SET-RESET TEST	MOS 30160	
17	*	MOS 30170	
18	TEST 2 MARCHING PATTERN TEST	MOS 30180	
19	*	MOS 30190	
20	TEST 3 0 AND 1 WALK TEST	MOS 30200	
21	*	MOS 30210	
22	TEST 4 DOUBLE OPERATION COLUMN DISTURB TEST	MOS 30220	
23	*	MCS 30230	
24	TEST 5 (OPTIONAL) SHORT COUNT RELOCATABLE	MOS 30240	
25	*	HAMMER DISTURB TEST	MOS 30250
26	*	MOS 30260	
27	TEST 6 (OPTIONAL) DIAGONAL GALPAT TEST	MOS 30270	
28	*	MOS 30280	
29	TEST 7 (OPTIONAL) MEMORY HOLD TEST	MOS 30290	
30	*	(REQUIRES MANUAL INTERVENTION & BATTERY BACK-UP POWER SUPPLY)	MCS 30300
31	*	MOS 30310	
32	TEST 8 (OPTIONAL) LONG COUNT RELOCATABLE	MOS 30320	
33	*	HAMMER DISTURB TEST	MOS 30330
34	*	MOS 30340	
35	TEST 9 (OPTIONAL) ECC DISTURB TEST (IN 2 PARTS)	MOS 30350	
36	*	MOS 30360	
37	TEST A (OPTIONAL) PARITY DISTURB TEST (IN 2 PARTS)	MOS 30370	
38	*	MOS 30380	
39	THE DEFAULT TESTS ARE 0, 1, 2, 3, & 4.	MOS 30390	
40	*	MOS 30400	
41	TEST 0 IS EXECUTED WHENEVER "RUN" IS ENTERED.	MOS 30410	
42	*	TEST 0 FORCES "LOLIM" AND "HILIM" TO THE BOUDRIES PRINTED	MOS 30420
43	*	ON THE LIST DEVICE.	MOS 30430
44	*	MOS 30440	
45	TEST 7 REQUIRES MANUAL INTERVENTION AND CANNOT BE LOOPED ON	MOS 30450	
46	*	WHILE THE PROCESSOR IS UNATTENDED.	MOS 30460
47	*	MOS 30470	
48	TEST 8 IS AN OPTIONAL, LONG TERM (I.E., OVERNIGHT) TEST.	MOS 30480	
49	*	MOS 30490	
50	TEST 9 IS AN OPTIONAL TEST TO BE USED WITH ECC TURNED ON.	MOS 30500	
51	*	MOS 30510	
52	TEST A IS AN OPTIONAL TEST TO BE USED W/PARITY MEMORIES ONLY.	MOS 30520	
53	* *****	MOS 30530	

0000 0000	56	R0	EQU	0	MOS 30560
0000 0001	57	R1	EQU	1	MOS 30570
0000 0002	58	R2	EQU	2	MOS 30580
0000 0003	59	R3	EQU	3	MOS 30590
0000 0004	60	R4	EQU	4	MOS 30600
0000 0005	61	R5	EQU	5	MOS 30610
0000 0006	62	R6	EQU	6	MOS 30620
0000 0007	63	R7	EQU	7	MOS 30630
0000 0008	64	R8	EQU	8	MOS 30640
0000 0009	65	R9	EQU	9	MOS 30650
0000 000A	66	R10	EQU	10	MOS 30660
0000 000B	67	R11	EQU	11	MOS 30670
0000 000C	68	R12	EQU	12	MOS 30680
0000 000D	69	R13	EQU	13	MOS 30690
0000 000E	70	R14	EQU	14	MOS 30700
0000 000E	71	RET	EQU	14	MOS 30710
0000 000F	72	R15	EQU	15	MOS 30720
0000 000F	73	LINK	EQU	15	MOS 30730

75 * LISTING NOTES:

76 *

77 * 1) TRIPLE ASTERISKS IN COLUMNS 69-71 INDICATE A
78 * DELETION OR MINOR MODIFICATION TO THE EXECUTIVES.

79 *

80 * 2) QUAD ASTERISKS IN COLUMNS 68-71 INDICATE MAJOR
81 * CHANGES TO THE EXEC WHICH MUST BE NOTED. THESE
82 * CHANGES MAY YIELD INCOMPATIBILITIES BETWEEN THIS
83 * (MODIFIED) AND OTHER (UNMODIFIED) EXTENDED TEST
84 * PROGRAM EXECUTIVES.

MOS 30750

MOS 30760

MOS 30770

MOS 30780

MOS 30790

MOS 30800

MOS 30810

MOS 30820

MOS 30830

MOS 30840

BOOTSTRAP LOADER

	86 *			MOS 30860
	87 *	BOOTLOADER WITH CHKSUM		MOS 30870
	88 *			MOS 30880
0000P	89	ORG X'80'		MOS 30890
0080 2421	90	LIS R2,1		MOS 30900
0082 2303	91	BS BOOT		MOS 30910
0084 1EB8	92	DC Z(PWSAVE)	CURRENT PSW SAVE POINTER(32-BIT M/C)	MOS 30920
0086 1F40	93	DC Z(RSAVE)	REGISTER SAVE POINTER(32-BIT M/C)	MOS 30930
0088 C810 0100	94	BOOT LHI R1,ORIGIN1	R1 = ADR(FIRST BYTE OF TEST PROG)	MCS 30940
008C C830 1EAE	95	LHI R3,LNZB+1	R3 = ADR(LAST NON-ZERO BYTE)	MOS 30950
0090 4030 0022	96	STH R3,X'22'	REGISTER SAVE POINTER (16-BIT M/C)	MOS 30960
0094 2731	97	SIS R3,1		MOS 30970
0096 C860 0000	98	MN LHI R6,0	R6 = CHKSUM BYTE = X'MN'	MOS 30980
009A D340 0078	99	LB R4,X'78'	INPUT DEV ADR	MOS 30990
009E DE40 0079	100	OC R4,X'79'		MOS 31000
00A2 9D45	101	LEADER SSR R4,R5		MOS 31010
00A4 2091	102	BTBS 9,1	DU,BSY	MOS 31020
00A6 9B45	103	RDR R4,R5		MOS 31030
00A8 0855	104	LDAR R5,R5		MOS 31040
00AA 2234	105	BZS LEADER	IGNORE LEADER	MOS 31050
00AC D251 0000	106	LOAD STB R5,0(R1)	STORE 1ST NON-ZERO & SUBSEQUENT BYTE	MOS 31060
00B0 D351 0000	107	LB R5,0(R1)	RELOAD DATA BYTE TO	MOS 31070
00B4 0765	108	XAR R6,R5	GENERATE CHKSUM	MOS 31080
00B6 9481	109	EXBR R8,R1		MOS 31090
00B8 9828	110	WHR R2,R8	DISPLAY MEMORY ADDRESS	MOS 31100
00BA 9D45	111	SSR R4,R5		MCS 31110
00BC 2091	112	BTBS 9,1	DU,BSY	MOS 31120
00BE 9245	113	RDR R4,R5		MOS 31130
00C0 C110 00AC	114	BXLE R1,LOAD	LOAD TILL LAST BYTE	MOS 31140
00C4 9486	115	EXBR R8,R6		MOS 31150
00C6 9828	116	WHR R2,R8	FINAL CHKSUM	MOS 31160
00C8 2478	117	LIS R7,8		MOS 31170
00CA 917C	118	SLLS R7,12	R7 = X'8000'	MOS 31180
00CC 9557	119	EPSR R5,R7	HALT PROCESSOR.	MOS 31190
00CE 2203	120	BS LDWT		MOS 31200

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00D0		122	ORG	X'100'	*	***	MOS 31220
0100	4300 011E	123	ORIGIN1	B START2	START HERE FOR 16-BIT PROCESSOR	***	MOS 31230
		124	*				MOS 31240
		125	-----				MOS 31250
		126	*	TEST CONSTANTS	*	***	MOS 31260
		127	*				MOS 31270
0104	00C0	128	FIRST	DCX 0	*	***	MOS 31280
0106	30C0	129	PSW	DCX 3000			MOS 31290
0108	30C0	130	PSW2	DCX 3000			MOS 31300
010A	00C0	131	IOSAVE	DCX 0			MOS 31310
010C	"00C0	132	TEMP	DCX 0			MOS 31320
010E	80	133	NORM	DB X'80'			MOS 31330
010F	40	134	INCR	DB X'40'			MOS 31340
		135	*				MOS 31350
		136	*				MOS 31360
0110	05C5	137	IO	DC X'0505'	I/O DEVICE(S) IDENTIFIER	***	MOS 31370
0112	1011	138	PASLADR	DC X'1011'	PASLA/PALM READ/WRITE ADDRESSES	***	MOS 31380
0114	0202	139	CLIFADR	DC X'0202'	CURRENT LOOP INTERFACE R/W ADDRESSES	***	MOS 31390
0116	6262	140	LPADR	DC X'6262'	LINE PRINTER ADDRESS	***	MOS 31400
0118	1011	141	C300ADR	DC X'1011'	CAROUSEL 300/PASLA ADDRESSES	***	MOS 31410
011A	COC0	142	MICROBUS	DC X'COC0'	MICROBUS ADDRESS	***	MOS 31420
011C	00C0	143		DCX 0	PROVISION FOR SPECIAL DEVICE	***	MOS 31430
		144	*				MOS 31440
		145	*	IO = 0101 FOR CBT ON PASLA			MOS 31450
		146	*	0202 FOR TELETYPE, CAROUSEL 15/30			MOS 31460
		147	*	XX03 FOR LINE PRINTER			MOS 31470
		148	*	0404 FOR CAROUSEL 300			MOS 31480
		149	*	0505 FOR MICROBUS			MOS 31490
		150	*				MOS 31500
		151	*				MOS 31510
		152	-----				MOS 31520
		153	*				MOS 31530
011E	4810 0108	154	START2	LH R1,PSW2	*	***	MOS 31540
0122	C820 0132	155	ST	LDAI R2,START	*	***	MOS 31550
0126	4010 0034	156	STH	R1,X'34'			MOS 31560
012A	4020 0036	157	STH	R2,X'36'	II INT NEW PSW LOC	***	MOS 31570
012E	0000	158	DCX	0	TAKE AN ILLEGAL INSTRUCTION INT	***	MOS 31580
0130	2200	159	BS	*	HALT IF II INTERRUPT NOT TAKEN	***	MOS 31590
		160	*				MOS 31600
0132	D310 0110	161	START	LB R1,IO	GET I/O IDENTIFIERS	***	MOS 31610
0136	D320 0111	162		LB R2,IO+1			MOS 31620
013A	2436	163	LIS	R3,6	IDENTIFIER CAN BE 1,2,3,4,5	***	MOS 31630
013C	0513	164	CLAR	R1,R3			MOS 31640
013E	2182	165	BLS	IO.OK1	BRANCH IF KB IDENTIFIER OK	***	MOS 31650
0140	2412	166	LIS	R1,2	OTHERWISE FORCE IT TO BE TTY	***	MOS 31660
0142	0523	167	IO.OK1	CLAR R2,R3			MOS 31670
0144	2182	168	BLS	IO.OK2	SAME TEST FOR LIST DEVICE	***	MOS 31680
0146	2422	169	LIS	R2,2			MOS 31690
0148	D210 0110	170	IO.OK2	STB R1,IO	REESTABLISH VALUES	***	MOS 31700
014C	D220 0111	171		STB R2,IO+1			MOS 31710
0150	D362 0B04	172	LB	R6,CONRQ2S(R2)			MOS 31720
0154	4060 0AE8	173	STH	R6,PASFLG2	SET PASLA FLAG (LIST DEVICE)	***	MOS 31730
0158	0866	174	LDAR	R6,R6			MOS 31740

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015A	2336	175	BZS	IO.0K3	SKIP IF NOT PASLA (SLHLS R2,1)	****	MOS31750	
015C	0A22	176	AAR	R2,R2			MOS31760	
015E	D302 0111	177	LB	RO,IO+1(R2)			MOS31770	
0162	DEC2 0AF8	178	OC	RO,CON2ND(R2)	ISSUE 2ND COMMAND (LIST DEVICE)	***	MOS31780	
		179 *					MOS31790	
0166	41F0 098E	180	IC.0K3	BAL	LINK,SETKB		MOS31800	
016A	9310	181	IBR	R1,RO	ESTABLISH KEYBOARD DEVICE (R1) = 1,2,4,5	****	MOS31810	
016C	0A11	182	AAB	R1,R1	(R1) = 2,4,6,A (SLHLS R1,1)	****	MOS31820	
016E	4831 0110	183	LH	R3,IO(R1)			MOS31830	
0172	4030 0AEC	184	STH	R3,CONADP	SET UP CONSOLE DEVICE ADDRESS		MOS31840	
0176	4821 0AEC	185	LH	R2,CONRD(R1)			MOS31850	
017A	4020 0AEC	186	STH	R2,CONRD	SET UP R/W COMMANDS		MOS31860	
017E	4821 0AF8	187	LH	R2,CON2ND(R1)			MOS31870	
0182	4020 0AF8	188	STH	R2,CON2ND	2ND CMD; ENABLE READ CMD		MOS31880	
0186	9011	189	SRHLS	R1,1			MOS31890	
0188	D341 0B04	190	LB	R4,CONRQ2S(R1)			MOS31900	
018C	D240 0B04	191	STB	R4,CONRQ2S	CONSOLE REQUEST TO SEND		MOS31910	
0190	4040 0AE6	192	STH	R4,PASFLG	SET PASLA FLAG (CONSOLE)		MOS31920	
0194	9333	193	LBR	R3,R3	MASK CONSOLE DEVICE TC 3 BITS	***	MOS31930	
0196	0844	194	LDAP	R4,R4			MOS31940	
0198	2333	195	BZS	IO.0K4	SKIP 2ND OC IF NOT PASLA		MOS31950	
019A	9422	196	EXBR	R2,R2			MOS31960	
019C	9E32	197	CCR	R3,R2	ISSUE 2ND COMMAND (CONSOLE)		MOS31970	
019E	DE30 0AEC	198	IO.0K4	OC	PUT CONSOLE IN READ MODE		MOS31980	
01A2	9B3F	199	RDB	R3,R15	READ A DUMMY CHARACTER (SET BUSY)		MOS31990	
		200 *					MOS32000	
01A4	41F0 09D0	201	BAL	LINK,LCORE	SET UP LOW CORE		MOS32010	
01A8	24C0	202	LIS	RO,0			MOS32020	
01AA	4000 0B12	203	STH	RO,WASDU	RESET 'DEVICE UNAVAILABLE' FLAGS		MOS32030	
01AE	4000 0B14	204	STH	RO,WASDU1			MOS32040	
01B2	41F0 07DE	205	BAL	LINK,CRLF			MOS32050	
01B6	C850 0D6E	206	LDAI	R5,TITLE			MOS32060	
01BA	41F0 0756	207	BAL	R15,PRINT	PRINT TEST PROGRAM TITLE		MOS32070	
		208 *-----*					MOS32080	
		209 * KEYBOARD INPUT ROUTINE					MOS32090	
		210 *					MOS32100	
01BE	C8E0 0A5A	211	OPTIN	LDAI	LINK,MM	*	***	MOS32110
01C2	40F0 003E	212	STH	LINK,X'3E'	RESTORE ETPE MM POINTER	***		MOS32120
01C6	41F0 07DE	213	BAL	LINK,CRLF	CR,LF TO LIST DEVICE			MOS32130
01CA	4820 0108	214	OPTIN1	LH	R2,PSW2			MOS32140
01CE	9512	215	EPSR	R1,R2	NO INT. REG SET 15			MOS32150
01D0	41F0 098E	216	BAL	LINK,SETKB	ESTABLISH CONSOLE			MOS32160
01D4	D340 0B98	217	LB	R4,AMSG	OUTPUT AN * TO INDICATE			MOS32170
01D8	41F0 07EC	218	BAL	LINK,OUTCHR	COMMAND MODE ESTABLISHED			MOS32180
01DC	2541	219	LCS	R4,1	X'FF'			MOS32190
01DE	41F0 07EC	220	BAL	LINK,OUTCHR				MOS32200
01E2	C8C0 08A8	221	LDAI	R12,QUESTN	SET UP R12 FOR ERR ROUTINE			MOS32210
01E6	C8C0 2020	222	LDAI	RO,X'2020'	BLANK OUT COMMAND BUFFER			MOS32220
01EA	40C0 1EAE	223	STH	RO,OPTBUF	WHICH WILL CONTAIN OPTION			MOS32230
01EE	4000 1EB0	224	STH	RO,OPTBUF+2	NAME			MOS32240
01F2	4000 1EB2	225	STH	RO,OPTBUF+4				MOS32250
01F6	2410	226	LIS	R1,0	CLEAR OPTBUF INDEX			MOS32260
01F8	4010 0B0C	227	STH	R1,ISITERR	RESET FORCED PRINTING FLAG	****		MOS32270

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01FC	41E0 087A	228	RDCHR	BAL R15,GETCHR	GET A CHAR IN R4	MOS 32280
0200	C540 0060	229	CLAI	R4,X'60'	UPPER CASE ALPHA ?	MOS 32290
0204	2183	230	BLS	RDCHAR0	BRANCH IF NO.	MOS 32300
0206	CB40 0020	231	SAI	R4,X'20'	CONVERT TO LOWER CASE	MOS 32310
020A	C540 0023	232	RDCHAR0	CLAI R4,X'23'	IS IT A HASH MARK ?	MOS 32320
020E	4330 C1BE	233	SE	OPTIN		MOS 32330
0212	C540 005F	234	CLAI	R4,X'5F'	LEFT ARROW, UNDERLINE CR DELETE ?	MOS 32340
0216	2334	235	BES	RDCHAR1	YES, BRANCH	MOS 32350
0218	C540 0008	236	CLAI	R4,X'08'	BACK SPACE ?	MOS 32360
021C	2139	237	ENES	RDCHR1	NO, BRANCH	MOS 32370
021E	2711	238	RDCHAR1	SIS R1,1	YES, DECREMENT INDEX	MOS 32380
0220	021C	239	BMR	R12	BUFFER UNDERFLOW; PRINT ??	MOS 32390
0222	C8C0 0020	240	LDAI	R0,X'20'		MOS 32400
0226	D201 1EAE	241	STB	R0,OPTBUF(B1)		MOS 32410
022A	43300 01FC	242	B	RDCHR		MOS 32420
022E	C540 000D	243	RDCHR1	CLAI R4,X'0D'	IS IT CR ?	MOS 32430
0232	233C	244	BES	LOOKUP	YES, TRY MATCH	MOS 32440
0234	C540 0020	245	CLAI	R4,X'20'	IS IT A BLANK?	MOS 32450
0238	2339	246	BES	LOOKUP	YES, TRY MATCH	MOS 32460
023A	C510 0006	247	CLAI	R1,6	7 CHARACTERS INPUT ?	MOS 32470
023E	038C	248	BNLR	R12	IF YES, ERROR	MOS 32480
0240	D241 1EAE	249	STB	R4,OPTBUF(B1)	STORE CURRENT BYTE	MOS 32490
0244	2611	250	AIS	R1,1	BUMP BUFFER INDEX	MOS 32500
0246	43300 01FC	251	B	RDCHR	READ NEXT CHARACTER	MOS 32510
252	*					MOS 32520
253	*					MOS 32530
254	*					MOS 32540
024A	C810 03B4	255	LOOKUP	LDAI R1,OPT	LOAD ADDRESS OF OPTION TABLE	MOS 32550
024E	2430	256	LOOK1	LIS R3,0	CLEAR BUFFER INDEX	MOS 32560
0250	0861	257	LDAR	R6,R1	SET OPTION WORD INDEX	MOS 32570
0252	4856 0000	258	LOOK2	LH R5,0(R6)		MOS 32580
0256	021C	259	BMR	R12	IF MINUS, THEN NO MATCH = ERROR	MOS 32590
0258	4553 1EAE	260	CLH	R5,OPTBUF(B3)	COMPARE TO OPTBUF HW	MOS 32600
025C	2333	261	BES	LOOK3		MOS 32610
025E	261C	262	AIS	R1,12		MOS 32620
0260	2209	263	BS	LOOK1		MOS 32630
0262	2632	264	LOOK3	AIS R3,2	TRY NEXT HW	MOS 32640
0264	2662	265	AIS	R6,2		MOS 32650
0266	C530 0006	266	CLAI	R3,6	3 MATCHING HW FOUND ?	MOS 32660
026A	208C	267	BLS	LOOK2		MOS 32670
026C	C510 0C50	268	*			MOS 32680
0270	4330 03EA	269	CLAI	R1,RUN	RUN COMMAND ?	MOS 32690
0274	C510 0C44	270	BE	RUNIT		MOS 32700
0278	4230 038A	271	CLAI	R1,OPTION	OPTION CMD ?	MOS 32710
272		272	BNE	LOOK4	NO, LOOK FURTHER	MOS 32720
273	*					MOS 32730
274	*					MOS 32740
275	*					MOS 32750
027C	C540 000D	276	CLAI	R4,X'0D'	YES, CR ?	MOS 32760
0280	233C	277	BES	OPTEXX	YES, BRANCH	MOS 32770
0282	41E0 0682	278	BAL	R14,OPTVAL	NO, GET OPTION DEV PRINTOUT NO.	MOS 32780
0286	C560 0006	279	CLAI	R6,6	IS DEVICE NO. VALID ?	MOS 32790
028A	2387	280	BNLS	OPTEXX	NO, BRANCH	MOS 32800

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028C	C840 000A	281	LDAI	R4,X'0A'		MOS32810
0290	41F0 07EC	282	BAL	LINK,OUTCHR	YES, LOAD A LF CHARACTER	MOS32820
0294	D260 010B	283	STB	R6,IOSAVE+1	WRITE IT TO THE CONSOLE	MOS32830
0298	4820 0C4C	284	OPTEXX	LH R2,OPTION+8	CHANGE THE LIST DEVICE NO.	MOS32840
029C	0232	285	BNZR	R2	CHECK FOR SPECIAL ROUTINE	MOS32850
		286 *			LINK TO ROUTINE	MOS32860
029E	C830 0BB4	287	OPTRTN	LDAI R3,TEST	RETURN HERE	MOS32870
02A2	C8EC 0328	288	LDAI	R14,OPTCMD8		MOS32880
02A6	41F0 07DE	289	BAL	LINK,CRLF		MOS32890
02AA	2420	290	OPTCMD	LIS R2,0	RESET COUNTER	MOS32900
02AC	D342 0BB4	291	OPTCMD1	LB R4,OPT(R2)	TO PRINT TEST	MOS32910
02B0	41F0 07EC	292	BAL	LINK,OUTCHR		MOS32920
02B4	2621	293	AIS	R2,1		MOS32930
02B6	C520 0006	294	CLAI	R2,5		MOS32940
02BA	2087	295	BLS	OPTCMD1		MOS32950
02BC	C840 0020	296	LDAI	R4,C'		MOS32960
02C0	41F0 07EC	297	BAL	LINK,OUTCHR	OUTPUT 1 SPACE	MOS32970
02C4	2450	298	LIS	R5,0	TO PRINT SELECTED TEST NUMBERS	MOS32980
02C6	4050 0104	299	STH	R5,FIRST		MOS32990
02CA	4823 0006	300	LH	R2,6(R3)	FIRST TEST WORD	MOS33000
02CE	2440	301	OPTCMD2	LIS R4,0	START WITH TEST 0	MOS33010
02D0	4040 010C	302	STH	R4,TEMP		MOS33020
02D4	0A22	303	OPTCMD3	AAR R2,R2	(SLHLS R2,1) ****	MOS33030
02D6	4380 0308	304	BNC	OPTCMD7		MOS33040
02DA	4040 010C	305	OPTCMD4	STH R4,TEMP	OPTION VALUE FOUND.	MOS33050
02DE	48C0 0104	306	LH	R0,FIRST	IS IT FIRST ?	MOS33060
02E2	2335	307	BZS	OPTCMD5		MOS33070
02E4	C840 002C	308	LDAI	R4,C','	NO, OUTPUT COMMA	MOS33080
02E8	41F0 07EC	309	BAL	LINK,OUTCHR		MOS33090
02EC	40F0 0104	310	OPTCMD5	STH LINK,FIRST		MOS33100
02F0	0855	311	LDAR	R5,R5	TEST VALUE FROM SECOND HW	MOS33110
02F2	2335	312	BZS	OPTCMD6	NO	MOS33120
02F4	C840 0031	313	LDAI	R4,C'1'	YES,OUTPUT '1'	MOS33130
02F8	41F0 07EC	314	BAL	LINK,OUTCHR		MOS33140
02FC	4840 010C	315	OPTCMD6	LH R4,TEMP	RESTORE R4	MOS33150
0300	D344 0B34	316	LB	R4,HEXTAB(R4)	CONVERT	MOS33160
0304	41F0 07EC	317	BAL	LINK,OUTCHR	OUTPUT 0-F	MOS33170
0308	4840 010C	318	OPTCMD7	LH R4,TEMP	RESTORE	MOS33180
030C	2641	319	AIS	R4,1	INCREMENT TEST NUMBER	MOS33190
030E	4040 010C	320	STH	R4,TEMP		MOS33200
0312	C540 0010	321	CLAI	R4,16		MOS33210
0316	4280 02D4	322	BL	OPTCMD3		MOS33220
031A	0855	323	OPTCMD71	LDAR R5,R5	DONE ?	MOS33230
031C	023E	324	BNZR	R14		MOS33240
031E	4823 0008	325	LH	R2,8(R3)	SECOND TEST WORD	MOS33250
0322	24E1	326	LIS	R5,1	R5 = 1 FOR SECOND TEST HW	MOS33260
0324	4360 02CE	327	B	OPTCMD2		MOS33270
		328 *				MOS33280
		329 *			TO OUTPUT OTHER OPTION NAMES & VALUES	MOS33290
		330 *				MOS33300
0328	41F0 07DE	331	OPTCMD8	BAL LINK,CRLF		MOS33310
032C	2461	332	LIS	R6,1	SET LINE COUNTER	MOS33320
032E	C820 0BC0	333	LDAI	R2,OPT+12	R2 POINTS TO THE NAME	MOS33330

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0332	2436	334	OPTCMD9	LIS	R3,5		MOS 33340
0334	D342 0000	335	OPTCMD10	LB	R4,0(R2)		MOS 33350
0338	41F0 07EC	336	BAL	LINK,OUTCHR		OUTPUT OPTION NAME CHAR	MOS 33360
033C	2621	337	AIS	R2,1			MOS 33370
033E	2731	338	SIS	R3,1		6 CHARACTERS OUTPUT ?	MOS 33380
0340	2026	339	BPS	OPTCMD10		NO,LOOP	MOS 33390
0342	C840 0020	340	LDAI	R4,C'			MOS 33400
0346	41F0 07EC	341	BAL	LINK,OUTCHR		OUTPUT ONE SPACE	MOS 33410
034A	48E2 0000	342	LH	R5,0(R2)		R5 = OPTION VALUE	MOS 33420
034E	2404	343	LIS	R0,4			MOS 33430
0350	41F0 05CC	344	BAL	LINK,R5HEX		WRITE OPTION VALUE IN HEX (4 DIGITS)	MOS 33440
0354	D300 0110	345	LB	R0,IO			MOS 33450
0358	2701	346	SIS	R0,1		CONSOLE = CRT ?	MOS 33460
035A	213D	347	BNZS	OPTCMD12		BRANCH: NO.	MOS 33470
035C	2661	348	AIS	R6,1		INCREMENT LINE COUNTER.	MOS 33480
035E	C560 0014	349	CLAI	R6,20		PAGE FULL ?	MOS 33490
0362	2189	350	BLS	OPTCMD12		NO, BRANCH	MOS 33500
0364	2460	351	LIS	R6,0		YES, INITIALIZE LINE COUNT	MOS 33510
0366	41F0 087A	352	OPTCMD11	BAL	LINK,GETCHR		MOS 33520
036A	274D	353	SIS	R4,13		CR ?	MOS 33530
036C	4330 01BE	354	BZ	OPTIN		NO, ACCEPT NEXT COMMAND	MOS 33540
0370	2643	355	AIS	R4,3		LF ?	MOS 33550
0372	2036	356	BNZS	OPTCMD11		YES, GO PRINT NEXT PAGE	MOS 33560
0374	41F0 07DE	357	OPTCMD12	BAL	LINK,CRLF		MOS 33570
0378	41F0 08D4	358	BAL	LINK,TSTBRK		NO, CRLF	MOS 33580
037C	2626	359	AIS	R2,6		EXIT IF 'BREAK' PRESSED.	MOS 33590
037E	C520 0C2C	360	CLAI	R2,OPTEND2		ALL PRINTING OPTIONS DONE ?	MOS 33600
0382	4280 0332	361	BL	OPTCMD9		NO,LOOP FOR NEXT ONE	MOS 33610
0386	4300 01CA	362	B	OPTIN1		TO ACCEPT NEXT COMMAND	MOS 33620
		363	*				MOS 33630
038A	C510 0BB4	364	LOOK4	CLAI	R1,TEST	'TEST' OPTION ?	MOS 33640
038E	4330 03B6	365		BE	TESTOP		MOS 33650
		366	*				MOS 33660
		367	*			TO PROCESS COMMANDS OTHER THAN 'TEST', 'OPTION'.	MOS 33670
		368	*				MOS 33680
0392	274D	369	SIS	R4,13		OPT FOLLOWED BY CR ?	MOS 33690
0394	033C	370	BZR	R12		YES, ERROR	MOS 33700
0396	41F0 0682	371	BAL	R14,OPTVAL		GET OPTION VALUE IN R6	MOS 33710
039A	274D	372	SIS	R4,13		TERMINATED BY CR ?	MOS 33720
039C	023C	373	BNZR	R12		IF NO, BRANCH	MOS 33730
039E	48E1 0008	374	LH	R14,8(R1)		GET OPTION CHECK ROUTINE ADDRESS	MOS 33740
03A2	2332	375	BZS	LOOK5			MOS 33750
03A4	01FE	376	BALR	R15,R14		LINK TO OPTION CHECK ROUTINE	MOS 33760
		377	*			* RETURN HERE IF OK *	MOS 33770
03A6	40E1 0006	378	LOOK5	STH	R6,6(R1)	STORE OPTION VALUE	MOS 33780
03AA	4300 01BE	379		B	OPTIN	ACCEPT NEXT COMMAND	MOS 33790
		380	*				MOS 33800
		381	*				*** MOS 33810
		382	*				MOS 33820
03AE	45E1 000A	383	LEVELIN	CLH	R6,10(R1)	IS R6 > MAX VALUE ?	*** MOS 33830
03B2	022C	384		BPR	R12	YES, ERROR RETURN	*** MOS 33840
03B4	030F	385		BR	R15	NO, RETURN TO LOOK5	*** MOS 33850
		386	*				MOS 33860

EXEC - ETPE R03-05 (16 BIT/STRIPPED AND MODIFIED)

		387	*	-----	MOS33870
		388	*	TEST OPTION PROCESS ROUTINE	MOS33880
		389	*		MOS33890
03B6	274D	390	TESTOP	SIS R4,13 BNZS TSTOP1	'TEST' FOLLOWED BY (CR) ? MOS33900
03B8	2137	391		LH R0,DEFTESTS	MOS33910
03BA	4800 0D9E	392		STH R0,TEST+6	MOS33920
03BE	4000 0BBA	393		B OPTIN	MOS33930
03C2	4300 01BE	394			MOS33940
		395	*		MOS33950
03C6	4850 0DA0	396	TSTOP1	LH R5,MAXTST	MOS33960
03CA	2470	397		LIS R7,0	MOS33970
03CC	2480	398		LIS R8,0	MOS33980
03CE	41E0 0682	399	TSTOP2	BAL R14,OPTVAL	MOS33990
03D2	0556	400		CLAR R5,R6	MOS34000
03D4	028C	401		BLR R12	MOS34010
03D6	41E0 06BE	402		BAL R14,UNARY	MOS34020
03DA	0673	403		OAR R7,R3	MOS34030
03DC	274D	404	TSTOP4	SIS R4,13	MOS34040
03DE	4230 03CE	405		BNZ TSTOP2	MOS34050
03E2	4070 0BBA	406		STH R7,TEST+6	MOS34060
03E6	4300 01BE	407		B OPTIN	MOS34070
		408	*		MOS34080
		409	*		MOS34090
03EA	41F0 07DE	410	RUNIT	BAL LINK,CRLF	MOS34100
03EE	24F0	411		LIS R15,0	MOS34110
03F0	40F0 0B12	412		STH R15,WASDU	MOS34120
03F4	40F0 0B14	413		STH R15,WASDU1	MOS34130
03F8	24CF	414		LIS R0,15	MOS34140
03FA	4810 0BBA	415		LH R1,TEST+6	MOS34150
03FE	9011	416	KEEP2	SRLS R1,1	MOS34160
0400	2184	417		BCS FOUND2	MOS34170
0402	2701	418		SIS R0,1	MOS34180
0404	2213	419		BNMS KEEP2	MOS34190
0406	030C	420		BR R12	MOS34200
0408	4000 0B10	421	FOUND2	STH R0,SELTST	HIGHEST SELECTED TEST NUMBER *** MOS34210
		422	*		MOS34220
		423	*	RESET TEST PARAMETERS	MOS34230
		424	*		MOS34240
040C	4800 0110	425		LH R0,IC	MOS34250
0410	4000 010A	426		STH R0,IOSAVE	MOS34260
0414	41F0 07DE	427		BAL LINK,CRLF	MOS34270
0418	41F0 0C64	428		BAL LINK,INIT	MOS34280
		429	*		MOS34290
041C	2400	430	INITRET	LIS R0,0	RETURN HERE FROM INIT MOS34300
041E	4000 0B0C	431		STH R0,ISITERR	RESET ERROR FLAG MOS34310
0422	4000 0B16	432		STH R0,TOTAL	RESET TOTAL MOS34320
0426	4000 0B18	433		STH R0,TOTERR	RESET TOTERR MOS34330
042A	4000 0B12	434		STH R0,WASDU	RESET WASDU MOS34340
042E	C810 3030	435		LDAI R1,C'00'	MOS34350
0432	4010 0B4A	436		STH R1,MTESTNO	MOS34360
0436	4010 0B54	437		STH R1,ETESTNO	MOS34370
043A	4010 0B56	438		STH R1,ERRNO	MOS34380
043E	41F0 09D0	439		BAL LINK,LCORE	SET UP LOW CORE MOS34390

EXEC - ETPE R03-05 (16 BIT/STRIPPED AND MODIFIED)

		440	*		MOS34400
		441	*	START SELECTION FROM TEST 0	MOS34410
		442	*		MOS34420
0442	2400	443	KEEP3	LIS R0,0	MOS34430
0444	4000 0B1A	444		STH R0,BTESTNO	MOS34440
0448	4000 0B1E	445		STH R0,NEXTST	MOS34450
		446	*		MOS34460
		447	*	TO FIND THE NEXT SELECTED TEST.	MOS34470
		448	*		MOS34480
044C	4820 0B1E	449	KEEP4	LH R2,NEXTST	MOS34490
0450	2408	450	KEEP41	LIS R0,8	MOS34500
0452	91CC	451		SLHLS R0,12	MOS34510
0454	CC02 0000	452		SRHL R0,0(R2)	MOS34520
0458	4400 0BBA	453	KEEP42	NH R0,TEST+6	MOS34530
045C	2133	454		BWZS KEEP5	MOS34540
045E	2621	455	KEEP43	AIS R2,1	MOS34550
0460	2208	456		BS KEEP41	MOS34560
0462	4020 0B1A	457	KEEP5	STH R2,BTESTNO	MOS34570
0466	0812	458		LDAR R1,R2	MOS34580
0468	2621	459		AIS R2,1	MOS34590
046A	4020 0B1E	460		STH R2,NEXTST	MOS34600
046E	2402	461		LIS R0,2	MOS34610
0470	C820 0B4A	462		LDAI R2,MTESTNO	MOS34620
0474	41F0 06F6	463		BAL LINK,HEXASC	MOS34630
0478	4820 0B4A	464		LH R2,MTESTNO	MOS34640
047C	4020 0B54	465		STH R2,ETESTNO	MOS34650
0480	41F0 08D4	466		BAL LINK,TSTBRK	MOS34660
0484	C850 0B44	467		LDAI R5,TSTMMSG	MOS34670
0488	41F0 0756	468		BAL LINK,PRINT	MOS34680
048C	2400	469		LIS R0,0	MOS34690
048E	4000 0B0E	470		STH R0,NOERR	MOS34700
0492	4000 0B1C	471		STH R0,COUNT	MOS34710
0496	4810 0106	472	KEEP6	LH R1,PSW	MOS34720
049A	9501	473		EPSR R0,R1	MOS34730
049C	4820 0B1A	474		LH R2,BTESTNO	MOS34740
04A0	9121	475		SLLS R2,LADC	MOS34750
04A2	4812 0DA4	476		LDA R1,TESTS(R2)	MOS34760
04A6	0301	477		BR B1	MOS34770
		478	*	-----	MOS34780
		479	*		MOS34790
		480	*	TEST MODULE END ROUTINE	MOS34800
		481	*		MOS34810
04A8	C8F0 0A5A	482	TSTEND	LDAI LINK,MM	***
04AC	40F0 003E	483		STH LINK,X'3E'	***
04B0	4810 0108	484		LH R1,PSW2	MOS34830
04B4	95C1	485		EPSR R0,R1	MOS34840
04B6	4800 0B1C	486		LH R0,COUNT	MOS34850
04BA	26C1	487		AIS R0,1	MOS34860
04BC	4000 0B1C	488		STH R0,COUNT	MOS34870
04C0	41F0 08D4	489		BAL LINK,TSTBRK	MOS34880
04C4	4500 0BC6	490		CLH R0,LOOP+6	MOS34890
04C8	2383	491		BNLS KEEP7	MOS34900
04CA	4300 0496	492		B KEEP6	MOS34910
				OTHERWISE, REPEAT SAME TEST	MOS34920

EXEC - ETPE R03-05 (16 BIT/STRIPPED AND MODIFIED)

04CE	4800 0B0E	493	KEEP7	LH	R0,NOERR	LOOK @ ERROR FLAG	MOS34930
04D2	2135	494		BNZS	KEEP71		MOS34940
04D4	C850 0B6A	495		LDAI	R5,NOERMSG	PRINT "NO ERROR"	MOS34950
04D8	41F0 0756	496		BAL	LINK,PRINT	GET TEST NUMBER	MOS34960
04DC	4810 0B1A	497	KEEP71	LH	R1,BTESTNO	IS THE LAST SELECTED TEST DONE ?	MOS34970
04E0	4510 0B10	498		CLH	R1,SELTST	NO, GO SELECT NEXT TEST	MOS34980
04E4	4280 044C	499		BL	KEEP4		MOS34990
		500	*				MOS35000
		501	*	ALL THE SELECTED TESTS ARE NOW RUN			MOS35010
		502	*				MOS35020
04E8	C8F0 0A5A	503	ABORT	LDAI	LINK,MM	COME HERE TO ABORT TEST SEQUENCE ***	MOS35030
04EC	40F0 003E	504		STH	LINK,X'3E'	RESTORE ETPE MM POINTER ***	MOS35040
04F0	4810 0108	505		LH	R1,PSW2		MOS35050
04F4	9501	506		EPSR	RO,R1	PSW = 30F0	MOS35060
04F6	41F0 05DC	507		BAL	LINK,DISPLAY	DISPLAY TOTAL & TOTERR	MOS35070
04FA	0B16	508		DC	Z(TOTAL),Z(TOTERR)		MOS3508C
04FC	0B18						
04FE	41F0 0958	509		BAL	LINK,TSTDU	RETURN WITH R1 = DU BIT	MOS35090
0502	4230 0564	510		BNZ	KEEP9	IF DU, DISPLAY TOTAL	MOS35100
0506	4810 0B14	511		LH	R1,WASDU1	WAS IT EVER ?	MOS35110
050A	4230 059A	512		BNZ	KEEP92	YES, PRINT TOTAL, TOTERR	MOS35120
050E	41F0 08D4	513		BAL	LINK,TSTBRK		MOS35130
0512	4810 0BD2	514		LH	R1,CONTIN+6	IF CONTIN = 0,	MOS35140
0516	233E	515		BZS	ABORT3	GO ABORT TEST ***	MOS35150
0518	6110 0B16	516		AHM	R1,TOTAL	IF TOTAL < MAX ***	MOS35160
051C	4230 0442	517		BNZ	KEEP3	GO TO TEST 0 ***	MOS35170
0520	2511	518		LCS	R1,1	OTHERWISE ***	MOS35180
0522	6110 0B16	519		AHM	R1,TOTAL	SET TOTAL TO MAX &	MOS35190
0526	4300 0594	520		B	HALT9	HALT PROCESSOR ***	MOS35200
		521	*				MOS35210
052A	C8F0 0A5A	522	ABORT1	LDAI	LINK,MM	*	*** MOS35220
052E	40F0 003E	523		STH	LINK,X'3E'	RESTORE ETPE MM POINTER ***	MOS35230
		524	*				*** MOS35240
0532	4810 0108	525	ABORT3	LH	R1,PSW2	*	*** MOS35250
0536	9501	525		EPSR	RO,R1	SET PSW = X'30F0' ***	MOS35260
0538	41F0 098E	527		BAL	LINK,SETKB	KB DEVICE = LIST DEVICE	MOS35270
053C	C850 0B88	528		LDAI	R5,EOTMSG		MOS35280
0540	4050 0B0C	529		STH	R5,ISITERR	*	*** MOS35290
0544	41F0 0756	530		BAL	LINK,PRINT	*END OF TEST*	MOS35300
0548	24F0	531		LIS	R15,0	*	*** MOS35310
054A	40F0 0B0C	532		STH	R15,ISITERR	*	*** MOS35320
		533	*				MOS35330
054E	48F0 0BDE	534		LH	LINK,NOMSG+6	IF "NOMSG" IS SET TO A 1,	MOS35340
0552	4230 059A	535		BNZ	KEEP92	PRINT "TOTAL" & "TOTERR"	MOS35350
0556	48F0 0BEA	536		LH	LINK,SCOPE+6	*	*** MOS35360
055A	27F4	537		SIS	LINK,4	IF "SCOPE" = 4,	*** MOS35370
055C	4330 059A	538		BZ	KEEP92	PRINT "TOTAL" & "TOTERR"	*** MOS35380
0560	4300 01BE	539		B	OPTIN		MOS35390
		540	*				MOS35400
		541	*	ROUTINE INCREMENTS, DISPLAYS & CHECKS 'TOTAL'			MOS35410
		542	*				MOS35420
		543	KEEP9	STH	R1,WASDU	SET 'WASDU' FLAG	MOS35430
		544	*				MOS35440

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0568	4810	OB16	545	ABORT2	LH	R1,TOTAL	INCREMENT TOTAL	MOS 35450
056C	2611		546		AIS	R1,1		MOS 35460
056E	4010	OB16	547		STH	R1,TOTAL		MOS 35470
0572	41F0	05DC	548	KEEP91	BAL	LINK,DISPLAY	DISPLAY "TOTAL" & "TOTERR"	MOS 35480
0576	OB16		549		DC	2(TOTAL),Z(TOTERR)		MOS 35490
0578	OB18							
057A	4810	OB16	550		LH	R1,TOTAL		MOS 35500
057E	C510	7FFF	551		CLAI	R1,X'7FFF'	TOTAL < MAX RETAINABLE ?	MOS 35510
0582	2389		552		BNLS	HALT9	NO, HALT	MOS 35520
0584	4800	OB1A	553		LH	RO,BTESTNO	RO = CURRENT TEST NUMBER	MOS 35530
0588	4500	OB10	554		CLH	RO,SELTST	IS IT LAST TEST ?	MOS 35540
058C	4280	044C	555		BL	KEEP4	NO, GO TO NEXT TEST	MOS 35550
0590	4300	0442	556		B	KEEP3	YES, GO TO TEST 0	MOS 35560
			557	*				MOS 35570
0594	C810	80F0	558		HALT9	LDAI R1,X'80F0'	(R1) = X'80F0'	MOS 35580
0598	9521		559		EPSR	R2,R1	HALT PROCESSOR	MOS 35590
			560	*				MOS 35600
			561	*	WHEN EXE/RUN IS PRESSED, PRINT TOTAL & TOTERR			MOS 35610
			562	*				MOS 35620
059A	41F0	0958	563	KEEP92	BAL	LINK,TSTDU	SEE IF LIST DEV IS ON	MOS 35630
059E	2035		564		BNZS	HALT9	NO, HALT	MOS 35640
05A0	2400		565	KEEP10	LIS	RO,0		MOS 35650
05A2	4000	OB12	566		STH	RO,WASDU	RESET FLAG	MOS 35660
05A6	41F0	07DE	567		BAL	LINK,CRLF		MOS 35670
05AA	C850	0B5A	568		LDAI	R5,TOTMSG		MOS 35680
05AE	4050	OB0C	569		STH	R5,ISITERR		MOS 35690
05B2	41F0	0756	570		BAL	LINK,PRINT	PRINT 'TOTAL TOTERR'	MOS 35700
05B6	24C4		571		LIS	RO,4	TO PRINT 4 HEX DIGITS	MOS 35710
05B8	4850	OB16	572		LH	R5,TOTAL		MOS 35720
05BC	41F0	06CC	573		BAL	LINK,R5HEX	PRINT TOTAL IN HEX	MOS 35730
05C0	2434		574		LIS	R3,4		MOS 35740
05C2	C840	0020	575		LDAI	R4,C'	SPACE	MOS 35750
05C6	41F0	07EC	576	KEEP101	BAL	LINK,OUTCHR	OUTPUT IT	MOS 35760
05CA	2731		577		SIS	R3,1		MOS 35770
05CC	2023		578		BPS	KEEP101	4 TIMES	MOS 35780
05CE	2404		579		LIS	RO,4	TO PRINT 4 HEX DIGITS	MOS 35790
05D0	4850	OB18	580		LH	R5,TOTERR		MOS 35800
05D4	41F0	06CC	581		BAL	LINK,R5HEX	PRINT TOTERR IN HEX	MOS 35810
05D8	4300	01BE	582		B	OPTIN	GO TO BEGINNING	MOS 35820
			583	-----				MOS 35830
			584	*	DISPLAY DATA ROUTINE			MOS 35840
05DC	24C1		585	DISPLAY	LIS	RO,1	GET DISPLAY PANEL ADDRESS	MOS 35850
05DE	DE00	010F	586		OC	RO,INCR	PUT PANEL IN INCREMENTAL MODE	MOS 35860
05E2	481F	0002	587		LH	R1,2(LINK)	GET 2ND PARAMETER ADDRESS	MOS 35870
05E6	4811	0000	588		LH	R1,0(R1)	GET DATA	MOS 35880
05EA	9411		589		EXBR	R1,R1		MOS 35890
05EC	9801		590		WHR	RO,R1	WRITE DATA	MOS 35900
05EE	481F	0000	591		LH	R1,0(LINK)	GET 1ST PARAMETER ADDRESS	MOS 35910
05F2	4811	0000	592		LH	R1,0(R1)	GET DATA	MOS 35920
05F6	9411		593		EXBR	R1,R1		MOS 35930
05F8	9801		594		WHR	RO,R1	WRITE DATA	MOS 35940
05FA	DE00	010E	595		OC	RO,NORM	PUT PANEL IN NORMAL MODE	MOS 35950
05FE	43CF	0004	596		B	4(LINK)	RETURN	MOS 35960

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		597	*				MOS 35970
		598	*	ERROR ROUTINES	(OVERRIDE NOMSG OPTION)		MOS 35980
		599	*				MOS 35990
0602	D000 1F00	600	ERR	STM R0,ERRSAVE	STORE REGISTERS		MOS 36000
0606	4120 0620	601	BAL	R2,ERRCOM	RETURN IF LIST DEVICE IS ON		MOS 36010
060A	41E0 0654	602	BAL	RET,ERR1	PRINT 'ERROR TTNN'		MOS 36020
060E	2400	603	ERRCCM2	LIS R0,0	*	***	MOS 36030
0610	4000 0B0C	604	STH	R0,ISITER	RESET ERROR FLAG		MOS 36040
0614	4820 0106	605	LH	R2,PSW			MOS 36050
0618	9502	606	EPSR	R0,R2			MOS 36060
061A	D100 1F00	607	LM	R0,ERRSAVE	RESTORE REGISTERS		MOS 36070
061E	030F	608	BR	LINK	RETURN TO TEST		MOS 36080
		609	*				MOS 36090
		610	*	ETPE COMMON ERROR ROUTINE		***	MOS 36100
		611	*				MOS 36110
0620	4020 0B22	612	ERRCOM	STH R2,COMRET			MOS 36120
0624	4810 0108	613	LH	R1,PSW2			MOS 36130
0628	9501	614	EPSR	R0,R1	DISABLE INT. @ PROCESSOR LEVEL		MOS 36140
062A	41E0 0958	615	BAL	LINK,TSTDU	GET LIST DEVICE DU BIT IN R1		MOS 36150
062E	2138	616	BNZS	ERRCOM1	BRANCH IF OFF-LINE		MOS 36160
0630	4020 0B0C	617	STH	R2,ISITER	SET ERROR FLAG		MOS 36170
0634	4020 0B0E	618	STH	R2,NOERR			MOS 36180
0638	4820 0B22	619	LH	R2,COMRET			MOS 36190
063C	0302	620	BR	R2	GO, PRINT ERROR MESSAGE		MOS 36200
		621	*				MOS 36210
063E	4810 0B18	622	ERRCOM1	LH R1,TOTERR	LIST DEVICE IS OFF		MOS 36220
0642	2611	623	AIS	R1,1			MOS 36230
0644	4010 0B18	624	STH	R1,TOTERR	INCREMENT TOTERR		MOS 36240
0648	C510 7FFF	625	CLAI	R1,X'7FFF'	TOTERR < MAX RETAINABLE ?		MOS 36250
064C	4280 0572	626	BL	KEEP91	NO, ABORT CURRENT TEST & GOTO NEXT		MOS 36260
0650	4300 0594	627	B	HALT9	YES, HALT PROCESSOR		MOS 36270
		628	*				MOS 36280
		629	*	MESSAGE PRINT ROUTINES	(DO NOT OVERRIDE NOMSG OPTION)		MOS 36290
		630	*				MOS 36300
		631	*	TC PRINT 'ERROR TTNN'			MOS 36310
		632	*				MOS 36320
0654	C850 0B4E	633	ERR1	LDAI R5,ERRMSG			MOS 36330
0658	41F0 0756	634	BAL	LINK,PRINT	PRINT 'ERROR TTNN'		MOS 36340
		635	*		TT = TEST NO., NN = ERROR NO.		MOS 36350
065C	03CE	636	BR	RET	RETURN		MOS 36360
		637	*			***	MOS 36370
		638	*	TO PRINT 'PSW PPPP LOC LLLL'			MOS 36380
		639	*				MOS 36390
065E	24C4	640	ERRPL1	LIS R0,4	SET UP DIGITS = 4		MOS 36400
0660	4810 0AE0	641	LH	R1,OPSW	R1 = OLD PSW		MOS 36410
0664	C820 0B78	642	LDAI	R2,ASCIIPSW			MOS 36420
0668	41F0 06F6	643	BAL	LINK,HEXASC	CONVERT IT TO ASCII		MOS 36430
066C	4810 0AE2	644	LH	R1,OLOC	R1= OLD LOC		MOS 36440
0670	C820 0B82	645	LDAI	R2,ASCILOC			MOS 36450
0674	41F0 06F6	646	BAL	LINK,HEXASC	CONVERT IT TO ASCII		MOS 36460
0678	C850 0374	647	LDAI	R5,PSWMSG			MOS 36470
067C	41F0 0756	648	BAL	LINK,PRINT	PRINT 'PSW PPPP LOC LLLL'		MOS 36480
0680	030E	649	BR	RET	RETURN		MOS 36490

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		650	*	*****	MOS 36500
		651	*	TO OBTAIN OPTION VALUE IN R6 (16 BITS, TARGT 16)	MOS 36510
		652	*		MOS 36520
0682	2460	653	OPTVAL	LIS R6,0 BAL R15,GETCHR	MOS 36530
0684	41F0 087A	654		INITIALIZE ACCUMULATOR GET A CHAR IN R4	MOS 36540
0688	24FF	655	OPTVAL0	LIS R15,15	MOS 36550
068A	D44F 0B34	656	OPTVAL1	CLB R4,HEXTAB(R15)	MOS 36560
068E	2334	657	BES	OPTVAL2	MOS 36570
0690	27F1	658	SIS	R15,1	MOS 36580
0692	2214	659	BNMS	OPTVAL1	MOS 36590
0694	03CC	660	BR	R12	MOS 36600
0696	9164	661	CPTVAL2	SLLS R6,4	MOS 36610
0698	066F	662	OAR	R6,R15	MOS 36620
069A	41F0 087A	663	OPTVAL3	BAL R15,GETCHR	MOS 36630
069E	C540 005F	664	CLAI	R4,X'5F'	MOS 36640
06A2	2334	665	BES	OPTVAL5	MOS 36650
06A4	C540 0008	666	CLAI	R4,X'08'	MOS 36660
06A8	2133	667	BWES	OPTVAL4	MOS 36670
06AA	9064	668	OPTVAL5	SRLS R6,4	MOS 36680
06AC	2209	669	BS	OPTVAL3	MOS 36690
06AE	C540 000D	670	OPTVAL4	CLAI R4,13	MOS 36700
06B2	033E	671	BER	R14	MOS 36710
06B4	C540 002C	672	CLAI	R4,X'2C'	MOS 36720
06B8	4230 0688	673	BNE	OPTVAL0	MOS 36730
06BC	030E	674	BR	R14	MOS 36740
		675	*		MOS 36750
		676	*	TO CONVERT (R6) FROM BINARY TO UNARY PATTERN, IN R3	MOS 36760
		677	*		MOS 36770
068E	2431	678	UNARY	LIS R3,1	MOS 36780
06C0	C560 000F	679	UNARY1	CLAI R6,15	MOS 36790
06C4	033E	680	BER	R14	MOS 36800
06C6	0A33	681	AAR	R3,R3	MOS 36810
06C8	2661	682	AIS	R6,1	MOS 36820
06CA	2205	683	BS	UNARY1	MOS 36830
		684	*		MOS 36840
		685	*	R5HEX PRINTS CONTENTS OF R5 IN HEX	MOS 36850
		686	*	PRINTS UPTO 4 DIGITS (8 DIGITS, TARGT 32)	MOS 36860
		687	*		MOS 36870
06CC	D000 1F40	688	R5HEX	STM R0,RSAVE	MOS 36880
06D0	0820	689		LDAR R2,R0	MOS 36890
06D2	2721	690		SIS R2,1	MOS 36900
06D4	4210 06F0	691		BM R5XB	MOS 36910
06D8	9122	692		SLLS R2,2	MOS 36920
06DA	0845	693	R5X	LDAR R4,R5	MOS 36930
06DC	CC42 0000	694		SRAL R4,0(R2)	MOS 36940
06E0	C440 000F	695		NAI R4,15	MOS 36950
06E4	D344 0B34	696		LB R4,HEXTAB(R4)	MOS 36960
06E8	41F0 07EC	697	R5XA	BAL R15,OUTCHR	MOS 36970
06EC	2724	698		SIS R2,4	MOS 36980
06EE	221A	699		BNMS R5X	MOS 36990
06F0	D100 1F40	700	R5XB	LM R0,RSAVE	MOS 37000
06F4	030F	701		BR LINK	MOS 37010
		702	*		MOS 37020

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			703	* TO CONVERT HEXADECIMAL DATA IN R1 TO ASCII CHAR & STORE @ 0(R2)	MOS37030
			704	* STORE REGISTERS R3 = DIGITS	MOS37040
06F6	D000 1F40		705	HEXASC STM R0,RSAVE LDAR R3,R0	MOS37050
06FA	0830		706	SLLS R3,2	MOS37060
06FC	9132		707	SIS R3,4	MOS37070
06FE	2734		708	R3 = 4(DIGITS)-4	MOS37080
0700	0841		709	HEXASC1 LDAR R4,R1	MOS37090
0702	CC43 0000		710	SRAL R4,0(R3)	MOS37100
0706	C440 000F		711	NAI R4,15	MOS37110
070A	D344 0B34		712	LB R4,HEXTAB(R4)	MOS37120
070E	D242 0000		713	STB R4,0(R2)	MOS37130
0712	2621		714	AIS R2,1	MOS37140
0714	2734		715	SIS R3,4	MCS37150
0716	221B		716	BNMS HEXASC1	MOS37160
0718	D100 1F40		717	LM R0,RSAVE	MOS37170
071C	030F		718	BR LINK	MOS37180
			719	----- *----- * TO CONVERT BINARY DATA IN R1 INTO DECIMAL DIGITS * AND STORE THEM IN ASCII @ 0(R2)	MOS37190
			720		MOS37200
			721	*	MOS37210
			722	*	MOS37220
071E	D000 1F40		723	DECASC STM R0,RSAVE	MOS37230
0722	0830		724	LDAR R3,R0	MOS37240
0724	9131		725	SLLS R3,LADC	MOS37250
0726	2732		726	SIS R3,ADC	MOS37260
0728	2440		727	SDEC1 LIS R4,0	MOS37270
072A	4853 0B2A		728	LDA R5,DECTAB(R3)	MOS37280
072E	0515		729	SDEC2 CLAR R1,R5	MOS37290
0730	2188		730	BLS \$DEC3	MOS37300
0732	0B15		731	SAR R1,R5	MOS37310
0734	2641		732	AIS R4,1	MOS37320
0736	C540 000A		733	CLAI R4,10	MOS37330
073A	2086		734	BLS \$DEC2	MOS37340
073C	274A		735	SIS R4,10	MOS37350
073E	2208		736	BS \$DEC2	MOS37360
0740	D344 0B34		737	SDEC3 LB R4,HEXTAB(R4)	MOS37370
0744	D242 0000		738	STB R4,0(R2)	MOS37380
0748	2621		739	AIS R2,1	MOS37390
074A	2732		740	SIS R3,ADC	MOS37400
074C	4310 0728		741	BNM SDEC1	MOS37410
0750	D100 1F40		742	LM R0,RSAVE	MOS37420
0754	030F		743	BR LINK	MOS37430
			744	----- *----- * TO PRINT THE ASCII MESSAGE	MOS37440
			745	*	MOS37450
			746	*	MOS37460
0756	D000 1F40		747	PRINT STM R0,RSAVE	MOS37470
075A	41F0 0958		748	BAL LINK,TSTDU	MOS37480
075E	2337		749	BZS P1	MOS37490
0760	4010 0B12		750	STH R1,WASDU	MOS37500
0764	4010 0B14		751	STH R1,WASDU1	MOS37510
0768	4300 07D4		752	B PRINT5	MOS37520
076C	4820 0B12		753	P1 LH R2,WASDU	MOS37530
0770	4330 079E		754	BZ P3	MOS37540
0774	C810 0140		755	LDAI R1,X'140'	MOS37550

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0778	C800 1000	756	P4	LDAI	R0,X'1000'	MOS 37560
077C	2701	757	P5	SIS	R0,1	MOS 37570
077E	2031	758		BNZS	P5	MOS 37580
0780	2711	759		SIS	R1,1	MOS 37590
0782	2035	760		BNZS	P4	MOS 37600
		761	*			LOOP TILL TIMEOUT (20 SEC FOR CRT WARM-UP)
0784	2440	762		LIS	R4,0	
0786	4040 0B12	763		STH	R4,WASDU	MOS 37620
078A	2541	764		LCS	R4,1	MOS 37630
078C	4040 0B14	765		STH	R4,WASDU1	MOS 37640
0790	2434	766		LIS	R3,4	MOS 37650
0792	41F0 07EC	767	P2	BAL	LINK,OUTCHR	MOS 37660
0796	2731	768		SIS	R3,1	MOS 37670
0798	2023	769		BPS	P2	MOS 37680
079A	4300 05A0	770		B	KEEP10	MOS 37690
079E	4800 0BDE	771	P3	LH	RO,NOMSG+6	MOS 37700
07A2	2335	772		BZS	PRINT2	MOS 37710
07A4	4800 0B0C	773		LH	RO,ISITERR	MOS 37720
07A8	4330 07D4	774		BZ	PRINT5	MOS 37730
		775	*			NOT AN ERROR MSG. EXIT
07AC	D345 0000	776	PRINT2	LB	R4,0(R5)	MOS 37740
07B0	41F0 07EC	777		BAL	LINK,OUTCHR	MOS 37750
07B4	274D	778		SIS	R4,13	MOS 37760
07B6	2333	779		BZS	PRINT3	MOS 37770
07B8	2651	780		AIS	R5,1	MOS 37780
07BA	2207	781		BS	PRINT2	MOS 37790
07BC	244A	782	PRINT3	LIS	R4,10	MOS 37800
07BE	D310 010B	783		LB	R1,IOSAVE+1	MOS 37810
07C2	2713	784		SIS	R1,3	MOS 37820
07C4	2335	785		BZS	PRINT3A	MOS 37830
07C6	41F0 07EC	786		BAL	LINK,OUTCHR	MOS 37840
07CA	2541	787		LCS	R4,1	MOS 37850
07CC	2302	788		BS	PRINT3B	MOS 37860
07CE	2441	789	PRINT3A	LIS	R4,1	MOS 37870
07D0	41F0 07EC	790	PRINT3B	BAL	LINK,OUTCHR	MOS 37880
07D4	41F0 08D4	791	PRINT5	BAL	LINK,TSTBRK	MOS 37890
07D8	D100 1F40	792		LM	RO,RSAVE	MOS 37900
07DC	03CF	793		BR	LINK	MOS 37910
		794	*			RESTORE REGISTERS
		795	*			RETURN
		796	*			
		797	*			
		798	*			
07DE	D000 1F40	799	CRLF	STM	RO,RSAVE	STORE REGISTERS
07E2	244D	800		LIS	R4,13	MOS 37990
07E4	41F0 07EC	801		BAL	LINK,OUTCHR	MOS 38000
07E8	4300 07BC	802		B	PRINT3	MOS 38010
		803	*			LINE FEED, RESTORE, RETURN
		804	*			
07EC	40F0 0B24	805	OUTCHR	STH	R15,OUT.SAV	SAVE RETURN ADDRESS
07F0	D300 010B	806		LB	RO,IOSAVE+1	MOS 38020
07F4	2704	807		SIS	RO,4	MOS 38030
07F6	4230 0834	808		BNZ	OUTCHR2	MOS 38040
						BRANCH IF NOT CAROUSEL
						MOS 38050
						MOS 38060
						MOS 38070
						MOS 38080

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07FA	4000 0B20	809	STH	R0,PAUSE	*	***	MOS38090
07FE	41F0 0958	810	OTC.0	BAL	LINK,TSTDU		MOS38100
0802	4230 0870	811	BNZ	OUTO	ON LINE ?		MOS38110
0806	9D01	812	SSR	R0,R1	NO, BRANCH		MOS38120
0808	2386	813	BNCS	OTC.1	GET CAROUSEL STATUS		MOS38130
080A	4810 0B20	814	LH	R1,PAUSE	BRANCH IF CHAR. IS TO BE READ	***	MOS38140
080E	2038	815	BNZS	OTC.0	PAUSED NOW ?		MOS38150
0810	4300 0834	816	B	OUTCHR2	YES, LOOP		MOS38160
0814	9BC1	817	OTC.1	RDR	NO, GO OUTPUT CHARACTER		MOS38170
0816	C410 007F	818		HAI	GET CAROUSEL CHARACTER		MOS38180
081A	CB10 0012	819		SAI	R1,X'7F'		MOS38190
081E	2134	820		BNZS	R1,X'12'		MOS38200
0820	4010 0B20	821	STH	R1,PAUSE	DC2 ?		MOS38210
0824	2308	822		BS	NO, BRANCH		MOS38220
0826	2712	823	OTC.3	SIS	YES, SET PAUSE FLAG		MOS38230
0828	4230 07FE	824		BNZ	DC4 ?		MOS38240
082C	40F0 0B20	825	STH	OTC.0	NO, GO WAIT FOR DC2		MOS38250
0830	4300 07FE	826		LINK,PAUSE	RESET PAUSE FLAG		MOS38260
		827	*	B	GO WAIT FOR DC2		MOS38270
0834	4010 0B20	828	OUTCHR2	STH	RESET FLAG		MOS38280
0838	41F0 0958	829		BAL	OFF-LINE ?		MOS38290
083C	4230 0870	830		BNZ	BRANCH IF OFF-LINE		MOS38300
0840	4110 09B8	831		BAL	SET UP FOR OUTPUT		MOS38310
0844	9D01	832	OTC.4	SSR	R0,R1		MOS38320
0846	4230 0870	833		BTC	WAIT FOR NOT BUSY		MOS38330
084A	C510 000C	834		CLAI	BRANCH IF OFF-LINE		MOS38340
084E	4330 0870	835		BE	PASLA OFFLINE ?		MOS38350
0852	C310 0008	836		TAI	BRANCH: YES.		MOS38360
0856	2039	837		BNZS	BUSY ?		MOS38370
0858	9A04	838		WDR	WAIT FOR NOT BUSY.		MOS38380
085A	41F0 0958	839	OTC.5	BAL	OUTPUT DATA BYTE		MOS38390
085E	2139	840		LINK,TSTDU	DEVICE DU ?		MOS38400
0860	D310 010B	841		BNZS	YES, BRANCH		MOS38410
0864	0A11	842		LB	(SLHLS R1,1)	****	MOS38420
0866	D301 0111	843		AAR	GET CONSOLE WRITE ADDRESS		MOS38430
086A	9DC1	844		LB	R0,IO+1(R1)		MOS38440
086C	2089	845		SSR	IF BUSY, LOOP (POSSIBLE HANG)	***	MOS38450
086E	2303	846		BTBS	R0,R1		MOS38460
0870	4010 0B12	847	OUTO	8,OTC.5	READ A CHAR IN R4		MOS38470
0874	48F0 0B24	848	OUT1	STH	SET WASDU FLAG		MOS38480
0878	03CF	849		LH	LINK,OUT.SAY		MOS38490
		850	*	BR	RETURN AS SET UP ABOVE		MOS38500
		851	*	TO GET A CHAR FROM KEYBOARD (IN REG R4)			MOS38510
		852	*				MOS38520
087A	4140 099C	853	GETCHR	BAL	R4,KBREAD		MOS38530
087E	0890	854		IDAR	R9,R0		MOS38540
0880	9D04	855		SSR	R0,R4		MOS38550
0882	2081	856		BTBS	8,1		MOS38560
0884	9B04	857		RDR	R0,R4		MOS38570
		858	*	TO ECHO RECEIVED CHARACTERS TO CONSOLE DEVICE IN FDX MODE			MOS38580
0886	D400 011A	859	ECHO	CLB	RO,MICROBUS		MOS38590
088A	233B	860		BES	ECHO1		MOS38600
088C	D390 0AEC	861		LB	IF MICROBUS, BRANCH		MOS38610

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0890	C590 00A9	862	CLAI	R9,X'A9'	CAROUSEL ?	MOS38620
0894	2137	863	BNES	ECHRTN	YES, DO NOT ECHO	MOS38630
0896	D390 0AEB	864	LB	R9,CONADR+1		MOS38640
089A	DD90 0AE4	865	SS	R9,SINK		MOS38650
089E	2082	866	BTBS	8,2		MOS38660
08A0	9A94	867	ECHO1	WDR R9,R4	ECHO RECEIVED BYTE	MOS38670
08A2	C440 007F	868	ECHRTN	NAI R4,X'7F'	REMOVE PARITY BIT	MOS38680
08A6	030F	869	BR	LINK	RETURN	MOS38690
		870	-----			
		871	* TO OUTPUT '?' TO CONSOLE			
		872	*			
08A8	41F0 07DE	873	QUESTN	BAL LINK,CRLF		MOS38730
08AC	40F0 0B0C	874	STH	LINK,ISITERR	SET FLAG	MOS38740
08B0	C850 0B96	875	LDAI	R5,QMSG		MOS38750
08B4	41F0 0756	876	BAL	LINK,PRINT	PRINT '?'	MOS38760
08B8	2400	877	LIS	R0,O		MOS38770
08BA	4000 0B0C	878	STH	R0,ISITERR		MOS38780
08BE	4300 01CA	879	B	OPTIN1	TO ACCEPT COMMAND INPUT	MOS38790
		880	-----			
		881	* IF BREAK KEY DEPRESSED, GO TO 'OPTIN' OR (BRKVECT); ELSE RETURN.			
		882	* BUT IF "BREAK" & CONTIN = 1, GO TO ABORT1.			
		883	*			
08C2	D000 1F60	884	TSTBRKX	STM R0,16*ADC+RSAVE	STORE REGISTERS	****
08C6	40F0 0B26	885	STH	LINK,BRK.SAV	SAVE RETURN ADDRESS	****
08CA	C8F0 04A8	886	LDAI	LINK,TSTEND	GET TSTEND ADDRESS	****
08CE	40F0 0B0A	887	STH	LINK,BRKVECT	PUT TSTEND IN VECTOR LOCATION	****
08D2	2305	888	BS	TSTBRK6	BRANCH	****
		889	*			
		890	*			
08D4	D000 1F60	891	TSTBRK	STM R0,16*ADC+RSAVE	STORE REGISTERS	MOS38890
08D8	40F0 0B26	892	STH	LINK,BRK.SAV	SAVE RETURN ADDRESS	MOS38920
08DC	D300 0AEA	893	TSTBRK6	LB R0,CONADR	GET KEYBOARD DEVICE ADR	MOS38930
08E0	9D01	894	SSR	R0,R1		MOS38940
08E2	4210 0948	895	BTC	1,TSTBRK3	IF CLI OR MICROBUS DU, BRANCH	MOS38950
08E6	C510 000C	896	CLAI	R1,X'0C'		MOS38960
08EA	4330 0948	897	BE	TSTBRK3		MOS38970
08EE	C310 0020	898	TAI	R1,X'20'	'BREAK' KEY PRESSED ?	MOS38980
08F2	4330 0948	899	BZ	TSTBRK3	NO, EXIT	MOS38990
08F6	D320 0110	900	LB	R2,I0		MOS39000
08FA	C520 0005	901	CLAI	R2,S	IS IT MICROBUS ?	MOS39010
08FE	2139	902	BNES	TSTBRK4	NO, BRANCH	MOS39020
0900	9B02	903	TSTBRK5	RDR R0,R2		MOS39030
0902	9D01	904	SSR	R0,R1		MOS39040
0904	C310 0020	905	TAI	R1,X'20'		MOS39050
0908	4230 0900	906	BNZ	TSTBRK5		MOS39060
090C	4300 0934	907	B	TSTBRK2		MOS39070
0910	4820 0AE6	908	TSTBRK4	LH R2,PASFLG	PASLA ?	MOS39080
0914	233C	909	BZS	TSTBRK1	NO, BRANCH	MOS39090
0916	C310 0008	910	TAI	R1,8	ALREADY ACKNOWLEDGED ?	MOS39100
091A	4230 0948	911	BNZ	TSTBRK3	BRANCH IF YES	MOS39110
091E	9BC2	912	RDR	R0,R2		MOS39120
0920	9D01	913	SSR	R0,R1		MOS39130
0922	2281	914	BFBS	8,1		MOS39140

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0924	0822	915	LDAR	R2,R2	ZERO CHARACTER ?	MOS39150
0926	4230 0948	916	BNZ	TSTBRK3	BRANCH: JUST FRAMING ERROR	MOS39160
092A	2305	917	BS	TSTBRK2		MOS39170
092C	9D01	918	TSTBRK1	SSR	R0,R1	MOS39180
092E	C310 0020	919	TAI	R1,X'20'		MOS39190
0932	2033	920	BNZS	TSTBRK1	WAIT FOR BREAK KEY RELEASE	MOS39200
0934	48F0 0BD2	921	TSTBRK2	LH	LINK,CONTIN+6 IF "CONTIN" = 1,	*** MOS39210
0938	4230 0D08	922	BNZ	OPTIN2	BRANCH & ABORT TESTING	**** MOS39220
093C	48F0 0BOA	923	LH	R15,BRKVECT	CHECK FOR SPECIAL ROUTINE	MOS39230
0940	4330 0D08	924	BZ	OPTIN2	BRK W/NO VECTOR: TO EXEC.	**** MOS39240
0944	40F0 0B26	925	STH	R15,BRK.SAV	SET UP FOR EXIT	MOS39250
0948	24C0	926	TSTBRK3	LIS	R0,0	MOS39260
094A	40C0 0BOA	927	STH	R0,BRKVECT	DELETE VECTOR AFTER ONE SHOT.	MOS39270
094E	D1C0 1F60	928	LM	R0,16*ADC+RSAVE	RESTORE REGISTERS	MOS39280
0952	48F0 0B26	929	LH	LINK,BRK.SAV	RESTORE RETURN ADDRESS	MOS39290
0956	030F	930	BR	LINK	RETURN TO PROGRAM	MOS39300
		931	*			MOS39310
		932	*	SEE IF CURRENT LIST DEVICE OFF-LINE (R1, CC NON-ZERO IF OFF)		MOS39320
		933	*			MOS39330
		934	TSTDU	LIS	R0,1	MOS39340
		935		LH	R1,PASFLG2	MOS39350
		936		BNZS	STSTDUO	MOS39360
		937		LDAI	R0,X'FC'	MOS39370
		938	STSTDUO	LB	R1,IOSAVE+1	GET LIST DEVICE IDENTIFIER
		939		AAR	R1,R1	(R1) = 2,4,6,8,A... (SLHLS R1,1)****
		940		LB	R1,IO(R1)	MOS39390
		941		STB	R1,SINK	GET LIST DEVICE ADDRESS
		942		SSR	R1,R1	SAVE LIST DEVICE ADDRESS
		943		NAR	R1,RO	MOS39410
		944		TAI	R1,1	GRAB STATUS
		945		BNZS	STSTDU2	MOS39420
		946		CLAI	R1,X'0C'	MOS39430
		947		BES	STSTDU2	MOS39440
		948	STSTDU1	LCS	R1,1	MOS39450
		949	STSTDU2	LB	R0,SINK	MOS39460
		950		XAI	R1,-1	FORCE R1 FOR RETURN CC = 0
		951		BR	LINK	MOS39470
		952	*			MOS39480
		953	*	TO DIRECT INPUT AND OUTPUT TO CONSOLE DEVICE		MOS39490
		954	*			MOS39500
		955	SETKB	LB	R0,IO	GET KEYBOARD DEVICE
		956		EXBR	R1,RO	MOS39550
		957		OAR	R1,RO	MOS39560
		958		STH	R1,IOSAVE	MOS39570
		959		BR	LINK	MOS39580
		960	*			MOS39590
		961	*	TO PUT KEYBOARD DEVICE IN READ MODE		MOS39600
		962	*			MOS39610
		963	KBREAD	LB	R0,CONADR	MOS39620
		964		OC	R0,CONRD	MOS39630
		965		RD	R0,SINK	MOS39640
		966		LH	R9,PASFLG	MOS39650
		967		NOP	*	MOS39660
					PASIA ?	MOS39670
					FOR SPECIAL KB DEVICE	

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09B0	2333	968	TTYGET	BZS	KBXIT	NO, RETURN	MOS39680
09B2	DE00 0B04	969		OC	R0,CONRQ2S		MOS39690
09B6	03C4	970	KBXIT	BR	R4	RETURN	MOS39700
		971	*				***
		972	*	LIST DEVICE SET UP ROUTINE			MOS39710
		973	*				MOS39720
		974	SETUP	STH	R1,SET.RTN		MOS39730
		975		LB	R1,IOSAVE+1	GET LIST DEVICE IDENTIFIER	MOS39740
		976		AAR	R1,R1	HW INDEX (SLHLS B1,1)	****
		977		LB	R0,IO+1(R1)	GET LIST DEVICE ADDRESS	MOS39750
		978		CC	RO,CONWR(T(R1))		MOS39760
		979		LH	R1,SET.RTN		MOS39770
		980		BR	R1	RETURN	MOS39780
		981	*	*****			MOS39790
		982	*	LOW CORE SET UP ROUTINE			MOS39800
		983	*				MOS39810
		984	LCORE	LIS	R1,0		MOS39820
		985		LIS	R2,2		MOS39830
		986		LDAI	R3,X'4E'		MOS39840
		987		LIS	R0,0		MOS39850
		988		LH	R4,X'20'	SAVE CONSOLE STATUS	MOS39860
		989	ZERO1	STH	R0,0(R1)		MOS39870
		990		BXLE	R1,ZERO1	ZERO CORE FROM 0 THRU X'4F'	MOS39880
		991		STH	R4,X'20'	RESTORE CONSOLE STATUS	MOS39890
		992		LDAI	R3,II		MOS39900
		993		STH	R3,X'36'	ILL INST INT NEW PSW LOC	MOS39910
		994		LDAI	R4,MM		MOS39920
		995		STH	R4,X'3E'	ILL. INT NEW PSW LOC	MOS39930
		996		LDAI	R4,RSAVE		MOS39940
		997	*				MOS39950
		998	*	SET UP LOW CORE FOR 16 BIT MACHINE			MOS39960
		999	*				MOS39970
		1000		STH	R4,X'22'	BEG SAVE POINTER	MOS39980
		1001		BR	LINK	RETURN	MOS39990
		1002	*				***
		1003	*	SPURIOUS INTERRUPT HANDLERS			MOS40000
		1004	*				MOS40010
		1005	COMM	STH	R14,OPSW		MOS40020
		1006		STH	R15,OLOC		MOS40030
		1007	COMM1	LH	R0,PSW2		MOS40040
		1008		EPSR	R2,RO	NO INT., BEG SET 15	MOS40050
		1009		BAL	LINK,ERR	PRINT 'ERROR XXFN'	MOS40060
		1010		STH	LINK,ISITERR	FORCE PRINT	MOS40070
		1011		BAL	RET,ERRPL1	PRINT 'PSW PPPP LOC LLLL'	MOS40080
		1012		B	OPTIN1	ENTER COMMAND MODE	MOS40090
		1013	*				MOS40100
		1014	*	ILLEGAL INSTRUCTION INTERRUPT TRAP			MOS40110
		1015	*				MOS40120
		1016	II	LDAI	R2,MM	*	MOS40130
		1017		STH	R2,X'3E'	RESTORE ETPE MM POINTER	MOS40140
		1018		LDAI	R2,C'F2'		***
		1019		STH	R2,ERRNO	SET ERROR NUMBER = F2	MOS40150
		1020		LH	R14,X'30'	OLD PSW	MOS40160

EXEC - ETPE R03-05 (16 BIT/STRIPPED AND MODIFIED)

0A36	48F0 0032	1021	LH	R15,X'32'	OLD LOC		MOS40210
0A3A	4300 0A04	1022	II32	B COMM	*	***	MOS40220
		1023	*				MOS40230
		1024	*	MACHINE MALFUNCTION INTERRUPT TRAP			MOS40240
		1025	*				MOS40250
		1026	MM0	EPSR R14,R14	CAPTURE MMINT PSW	***	MOS40260
		1027		LDAI R2,MM	*	***	MOS40270
		1028		STH R2,X'3E'	RESTORE ETPE MM POINTER	***	MOS40280
		1029		LDAR R10,R14	*	***	MOS40290
		1030		NAI R10,X'000F'	HASK OFF CC ONLY	***	MOS40300
		1031		TAI R10,6	CC = MEMORY ERROR ?	***	MOS40310
		1032		BZS MM1	NO, BRANCH	***	MOS40320
		1033		BAL LINK,PABERR	YES, PRINT ERROR (PARITY)	***	MOS40330
		1034		BS MM1	*	***	MOS40340
		1035	*				MOS40350
		1036	MM	EPSR R10,R10	CAPTURE MMINT PSW	***	MOS40360
		1037		NAI R10,X'000F'	HASK OFF CC ONLY	***	MOS40370
		1038	MM1	LDAI R2,C'F3'			MOS40380
		1039		STH B2,ERRNO	SET ERROR NUMBER F3		MOS40390
		1040		LH R14,X'38'	OLD PSW (16 BIT PROCESSOR)		MOS40400
		1041		LH R15,X'3A'	OLD LOC		MOS40410
		1042	MM32	NAI R14,X'FFFO'			MOS40420
		1043		OAR R14,R10	R14 = COMPOSITE PSW		MOS40430
		1044		STH R14,OPSW			MOS40440
		1045		STH R15,OLOC			MOS40450
		1046		LDAI R1,X'7FFF'			MOS40460
		1047	MM16	SIS R1,1	TIMEOUT		MOS40470
		1048		BPS MM16			MOS40480
		1049		LDAI R0,X'80F0'	BO = X'80F0'	***	MOS40490
		1050		EPSR R2,BO	HALT PROCESSOR		MOS40500
		1051	*				MOS40510
		1052	*	WHEN EXE/RUN IS DEPRESSED, ERROR MSG IS PRINTED.			MOS40520
		1053	*				MOS40530
		1054	MMCOM	LB R2,IO	GET CONSOLE IO POINTER		MOS40540
		1055		SIS R2,5	IS CONSOLE ON MICRO-IO BUS ?		MOS40550
		1056		BZS MMCOMA	YES, BRANCH		MOS40560
		1057		LH R2,PASFLG	IS CONSOLE ON PASLA ?	****	MOS40570
		1058		BZS MMCOM1	NO, BRANCH	****	MOS40580
		1059	MMCOMA	LB R1,IO	YES, GET CONSOLE DEVICE IDENT	****	MOS40590
		1060		AAR R1,R1	SET INDEX (SLHLS R1,1)	****	MOS40600
		1061		LB R2,IO(R1)	GET CONSOLE DEVICE ADDRESS	****	MOS40610
		1062		OC R2,CON2ND(R1)	ISSUE CONSOLE SPEED COMMAND	****	MOS40620
		1063		OC R2,CONBD	ISSUE CONSOLE READ COMMAND	****	MOS40630
		1064		RD R2,SINK	DUMMY READ TO SET BUSY	****	MOS40640
		1065	*				MOS40650
		1066	MMCOM1	LB R1,IO+1	GET LIST DEVICE POINTER		MOS40660
		1067		SIS R1,5	IS LIST DEVICE ON MICRC-IO BUS ?		MOS40670
		1068		BZS MMCOM1A	YES, BRANCH		MOS40680
		1069		LH R1,PASFLG2	IS LIST DEVICE ON PASLA ?	****	MOS40690
		1070		BZS MMCOM2	NO, BRANCH	****	MOS40700
		1071	MMCOM1A	LB R1,IO+1	YES, GET LIST DEVICE POINTER	****	MOS40710
		1072		LB R2,IO	GET CONSOLE POINTER	****	MOS40720
		1073		CLAR R1,R2	CONSOLE = LIST DEVICE ?	****	MOS40730

EXEC - ETPE R03-05 (16 BIT/STRIPPED AND MODIFIED)

OAC8	2338	1074	BES	MMCOM2	YES, BRANCH	****	MOS40740
OACA	0A11	1075	AAR	R1,R1	NO, SET INDEX (SLHLS R1,1)	****	MOS40750
OACC	D321 0111	1076	LB	R2,IO+1(R1)	GET LIST DEVICE ADDRESS	****	MOS40760
OADO	DE21 0AF8	1077	CC	R2,LST2ND(R1)	ISSUE LIST SPEED COMMAND	****	MOS40770
OAD4	DE21 0AED	1078	OC	R2,LSTWRT(R1)	ISSUE LIST WRITE COMMAND	****	MOS40780
		1079	*			****	MOS40790
OAD8	4300 0A0C	1080	MMCOM2	B COMM1	*	****	MOS40800
		1081	*	*****			MOS40810
		1082	*	ETPE CONSTANTS & TABLES			MOS40820
		1083	*				MOS40830
OAE0		1084		ALIGN 8			MOS40840
		1085	*	-----			MOS40850
OAE0	0000	1086	OPSW	DCX 0			MOS40860
OAE2	0000	1087	CLOC	DCX 0			MOS40870
		1088	*	-----			MOS40880
OAE4	00	1089	SINK	DB 0	BIT BUCKET		MOS40890
OAE5	00	1090		DB *			MOS40900
OAE6	0000	1091	PASFLG	DCX 0	SET WHEN CONSOLE ON PASLA/PALM		MOS40910
OAE8	0000	1092	PASFIG2	DCX 0	SET WHEN LIST DEVICE ON PASLA		MOS40920
		1093	*	-----			MOS40930
		1094	*	ETPE IO COMMANDS			MOS40940
		1095	*				MOS40950
OAEA	0000	1096	CONADR	DCX 0	CONSOLE DEVICE ADDRESS		MOS40960
OAEc	0000	1097	CONED	DCX 0	CONSOLE READ/WRITE COMMANDS		MOS40970
	0000 OAE0	1098	CONWRt	EQU CONRD+1			MOS40980
	0000 OAE0	1099	LSTWRT	EQU CONWRt	LIST DEVICE WRITE COMMAND		MOS40990
OAEe	B1A3	1100	CTRBD	DCX B1A3	FOR CRT		MOS41000
OAF0	A4D8	1101	CLIFRD	DCX A4D8	* CURRENT LOOP INTERFACE		MOS41010
OAF2	0080	1102	LPWRT	DCX 0080	* LINE PRINTER		MOS41020
OAF4	A1A3	1103	CARRD	DCX A1A3	* CAROUSEL 300		MOS41030
OAF6	8202	1104	HREADC	DCX 8202	* MICROBUS		MOS41040
		1105	*				MOS41050
OAF8	0000	1106	CON2ND	DCX 0	2ND COMMAND; ENABLE READ COMMAND		MOS41060
	0000 OAF8	1107	LST2ND	EQU CON2ND	LIST DEVICE SPEED COMMAND		MOS41070
	0000 OAF9	1108	CONENRD	EQU CON2ND+1			MOS41080
OAFa	F871	1109	CRT2ND	DCX F871	FOR CRT		MOS41090
Oafc	0064	1110	CLIF2ND	DCX 0064	* CURRENT LOOP INTERFACE		MOS41100
Oafe	0000	1111		DCX 0	* DUMMY HW FOR LP		MOS41110
OB00	F061	1112	CAR2ND	DCX F061	* CAROUSEL 300		MOS41120
OB02	03C0	1113		DCX 0300	* DUMMY HW FOR MICROBUS		MOS41130
		1114	*				MOS41140
OB04	00	1115	CONBQ2S	DB 0	CONSOLE REQUEST TO SEND CMD		MOS41150
OB05	33	1116	CTRQ2S	DB X'33'	FOR CRT		MOS41160
OB06	00	1117		DB 0	* DUMMY BYTE FOR CLI		MOS41170
OB07	00	1118		DB 0	* DUMMY BYTE FOR LP		MOS41180
OB08	23	1119	CARRQ2S	DB X'23'	* CAROUSEL 300		MOS41190
CB09	00	1120		DB 0	* DUMMY BYTE FOR MICROBUS		MOS41200
OBOA		1121		DB *			MOS41210
		1122	*	-----			MOS41220
OBOA	0000	1123	BRKVECT	DC Z(0)	BREAK KEY VECTOR		MOS41230
OBOC	0000	1124	ISITERR	DCX 0			MOS41240
OBOE	0000	1125	NOERR	DCX 0			MOS41250
OB10	0000	1126	SELTST	DCX 0	HIGHEST SELECTED TEST NUMBER		MOS41260

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0B12 0000	1127	WASDU	DCX	0	1 IF KEYBOARD DEVICE WAS OFF	MOS41270
0B14 0000	1128	WASDU1	DCX	0	NON-ZERO IF TOTAL,TOTERR TO PRINT	MOS41280
0B16 0000	1129	TOTAL	DCX	0	NO. OF TIMES THE SELECTED TESTS RUN	MOS41290
0B18 0000	1130	TOTERR	DCX	0	TOTAL ERRORS DETECTED WHILE DU	MOS41300
0B1A 0000	1131	BTESTNO	DCX	0	CURRENT TEST NO. IN BINARY	MOS41310
0B1C 0000	1132	COUNT	DCX	0		MOS41320
0B1E 0000	1133	NEXTST	DCX	0	NEXT TEST NUMBER	MOS41330
0B20 0000	1134	PAUSE	DCX	0		MOS41340
	1135	*				***
0B22 0000	1136	COMRET	DCX	0	COMMON ERROR RETURN ADDRESS	MOS41360
0B24 0000	1137	OUT.SAV	DCX	0	OUTCHR RETURN ADDRESS	MOS41370
0B25 0000	1138	BRK.SAV	DCX	0	TSTBRK RETURN ADDRESS	MOS41380
0B28 0000	1139	SET.RTN	DCX	0	SETUP RETURN ADDRESS	MOS41390
	1140	*				MOS41400
0B2A 0001	1141	DECTAB	DC	1,10,100,1000,10000		MOS41410
0B2C 00CA						
0B2E 0064						
0B30 03F8						
0B32 2710						
0B34 3031 3233 3435 3637	1142	HEXTAB	DB	C'0123456789ABCDEF'		MOS41420
0B3C 3839 4142 4344 4546	1143		DB	*		MCS41430
0B44	1145	*				
	1146	*	ETPE MESSAGES			
	1147	*				
0B44 5445 5354 2020 2A2A	1148	TSTMSG	DC	C'TEST ***,X'0D00'		MOS41450
0B4C 0D00						MOS41460
0000 0B4A	1149	HTESTNO	EQU	TSTMSG+6		MOS41470
0B4E 4552 524F 5220 2A2A	1150	ERRMSG	DC	C'ERROR *****,X'0D00'		MOS41480
0B56 2A2A						MOS41490
0B58 0D00						MOS41500
0000 0B54	1151	ETESTNO	EQU	ERRMSG+6	STORED BY ETPE	MOS41510
0000 0B56	1152	ERRNC	EQU	ERRMSG+8	STORE ERRCODE AS CHARACTER CONSTANT	MOS41520
0B5A 544F 5441 4C20 2020	1153	TOTMSG	DC	C'TOTAL TOTERR',X'0D00'		MOS41530
0B62 544F 5445 5252						
0B68 0C00						
0B6A 4E4F 2045 5252 4F52	1154	NCERMSG	DC	C'NO ERROR',X'0D00'		MOS41540
0B72 0C00						
0B74 50E3 5720 2A2A 2A2A	1155	PSWMSG	DC	C'PSW ***** LOC *****,X'0D00'		MOS41550
0B7C 2020 4C4F 4320 2A2A						
0B84 2A2A						
0B86 0D00						
0000 0B78	1156	ASCIIPSW	EQU	PSWMSG+4		MOS41560
0000 0B7E	1157	LOCMMSG	EQU	PSWMSG+10		MOS41570
0000 0B82	1158	ASCILOC	EQU	PSWMSG+14		MOS41580
0B88 454E 4420 4F46 2054	1159	EOTMSG	DC	C'END OF TEST',X'0D00'		MOS41590
0B90 45E3 5420						
0B94 0D00						
0B96 3FCD	1160	QMSG	DC	X'3F0D'		MOS41600
0B98 2ACD	1161	AMSG	DC	X'2A0D'		MOS41610

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OB9A	FFFF	1162	BRKMSG	DC	X'FFFF', X'FFFF', C'BREAK TERMINATION ', X'FFFF', X'0D0A'	MOS41620
OB9C	FFFF					
OB9E	4252	4541	4B20	5445		
OBA6	524D	494E	4154	494F		
OBAE	4E20					
OB80	FFFF					
OB82	0DCA					

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		1165	*	*****	*****	MOS41650
		1166	*			MOS41660
		1167	*	OPTION/COMMAND TABLE		MOS41670
		1168	*			MOS41680
	0000 0BB4	1169	OPT	EQU *		MOS41690
0BB4	5445 5354 2020	1170	TEST	DC C' TEST ',X'F800',X'0',X'0' *	0 TO A	MOS41700
0BBA	F800					
0BBC	0000					
0BBD	0000					
0BC0	4C4F 4F50 2020	1171	LOOP	DC C' LOOP ',X'0',Z(LEVELIN),X'7FFF' *	MAX=X'7FFF'	MOS41710
0BC6	0000					
0BC8	03AE					
0BCA	7FFF					
0BCB	434F 4E54 494E	1172	CONTIN	DC C' CONTIN ',X'0',Z(LEVELIN),X'1' *	0 OR 1	MOS41720
0BD2	0000					
0BD4	03AE					
0BD6	00C1					
0BD8	4E4F 4D53 4720	1173	NOMSG	DC C' NOMSG ',X'0',Z(LEVELIN),X'1' *	0 OR 1	MOS41730
0BDE	0000					
0BE0	03AE					
0BE2	0001					
0BE4	5343 4F50 4520	1174	SCOPE	DC C' SCOPE ',X'0',Z(LEVELIN),X'5' *	MAX = 5	MOS41740
0BEA	0000					
0BEC	03AE					
0BEE	00C5					
0BF0	4441 5441 2020	1175	DATA	DC C' DATA ',X'FFFF',X'0',X'0' *	0 TO FFFF	MOS41750
0BF6	FFFF					
0BF8	0000					
0BFA	0000					
0BFC	504F 554E 4420	1176	POUND	DC C' POUND ',X'A',X'0',X'0' *	1 TO FFFF	MOS41760
0C02	00CA					
0C04	0000					
0C06	00C0					
0C08	4C4F 5048 5953	1177	LOPHYS	DC C' LOPHYS ',X'0',Z(LEVELIN),X'6' *	0 TO 6	MOS41770
0C0E	0000					
0C10	03AE					
0C12	0006					
0C14	4849 5048 5953	1178	HIPHYS	DC C' HIPHYS ',X'6',Z(LEVELIN),X'6' *	0 TO 6	MOS41780
0C1A	0006					
0C1C	03AE					
0C1E	0006					
0C20	434F 4E20 2020	1179	CONSOLE	DC C' CON ',X'0',Z(CON),X'0' *	****	MOS41790
0C26	0000					
0C28	0C5E					
0C2A	0000					
	0000 0C2C	1180	OPTEND2	EQU *		MOS41800
	0000 0C2C	1181	OPTEND	EQU OPTEND2		MOS41810
		1182	*			MOS41820
		1183	*	*****		MOS41830
		1184	*			MOS41840
0C2C	4C4F 4C49 4D20	1185	LOLIM	DC C' LOLIM ',X'8000',X'0',X'FFFC' *	8000	MOS41850
0C32	8000					
0C34	0000					

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OCB0	4300 0C8E	1229	B	INIT3	BRANCH TO CONTINUE	MOS42290
		1230	*			MOS42300
OCB4	48E0 0C3E	1231	INIT4	LH R14,HILIM+6	IS HILIM = 0 ?	MOS42310
OCB8	233D	1232	BZS	INIT1	YES, SKIP LIMIT CHECK	MOS42320
OCBA	48E0 0C32	1233	LH	R14,LOLIM+6	IS LOLIM = 0 ?	MOS42330
OCBE	233A	1234	BZS	INIT1	YES, SKIP LIMIT CHECK	MOS42340
OCC0	C5E0 8000	1235	CLAI	R14,X'8000'	IS LOLIM > OR = X'8000' ?	MOS42350
OCC4	4280 0CF2	1236	BL	HIOPRT	NO, BRANCH TO ERROR PRINTOUT	MOS42360
OCC8	45E0 0C3E	1237	CLH	R14,HILIM+6	IS LOLIM < OR = HILIM ?	MOS42370
OCCC	2333	1238	BES	INIT1	YES, BRANCH	MOS42380
OCCE	4380 0CF2	1239	BNL	HIOPRT	NO, BRANCH TO ERROR PRINTOUT	MOS42390
		1240	*			MOS42400
OCD2	48E0 0BBA	1241	INIT1	LH R14,TEST+6	FORCE TEST 0	MOS42410
OCD6	C6E0 8000	1242	OAI	R14,X'8000'	WHEN "RUN" IS ENTERED	MOS42420
OCDA	40E0 0BBA	1243	STH	R14,TEST+6	IS TEST 9 SELECTED ?	MOS42430
OCDE	C3E0 0040	1244	TAI	R14,X'40'	NO, BRANCH	MOS42440
OCE2	2334	1245	BZS	INIT2	YES, IS TEST A ALSO SELECTED ?	MOS42450
OCE4	C3E0 0020	1246	TAI	R14,X'20'	YES, BRANCH	MOS42460
OCE8	213D	1247	BNZS	ILTSTPRT		MOS42470
		1248	*			MOS42480
OCEA	24E1	1249	INIT2	LIS R14,1	NO	MOS42490
OCEC	DEE0 010E	1250	OC	R14,NORM	PUT DISPLAY IN NORMAL MODE	MOS42500
OCFO	030F	1251	BR	LINK	RETURN TO CALLER	MOS42510
		1252	*			MOS42520
		1253	*			MOS42530
OCF2	C850 1DBA	1254	HIOPRT	LDAI R5,HILOMSG	PRINT: "LOLIM > HILIM IS ILLEGAL"	MOS42540
		1255	*			MOS42550
OCF6	40E0 0B0C	1256	HIOPRT1	STH R5,ISITERR	FORCE PRINTING	MOS42560
OCFA	41F0 0756	1257	BAL	LINK,PRINT	UNCONDITIONALLY PRINT:	MOS42570
OCFE	4300 01BE	1258	B	OPTIN	ABORT TESTING SEQUENCE	MOS42580
		1259	*			MOS42590
OD02	C850 1DD4	1260	ILTSTPRT	LDAI R5,TSTREJ	PRINT: "ILLEGAL TEST SEQUENCE"	MOS42600
OD06	22C8	1261	BS	HIOPRT1	BRANCH	MOS42610
		1262	*			MOS42620
		1263	*			MOS42630
		1264	*			MOS42640
OD08	C850 0B9A	1265	OPTIN2	LDAI R5,BRKMSG	PRINT: "BREAK TERMINATION"	****
ODOC	22CB	1266	BS	HIOPRT1	BRANCH	****
		1267	*			****
		1268	*			MOS42680
ODEE	4810 0COE	1269	LOSET	LH R1,LOPHYS+6	GET LOWEST SEGMENT NUMBER	MOS42690
OD12	C410 0007	1270	NAT	R1,X'0007'	MASK IT	MOS42700
OD16	2441	1271	LIS	R4,1	LOAD DISPLAY ADDRESS	MOS42710
OD18	DE40 010F	1272	OC	R4,INCR	PUT DISPLAY IN INCREMENTAL MODE	MOS42720
OD1C	9451	1273	EXBR	R5,R1		MOS42730
OD1E	2430	1274	LIS	R3,0		MOS42740
OD20	9843	1275	WHR	R4,R3	DUMMY WRITE	MOS42750
OD22	9845	1276	WHR	R4,R5	DISPLAY SEGMENT UNDER TEST	MOS42760
OD24	DE40 010E	1277	OC	R4,NORM	PUT DISPLAY IN NORMAL MODE	MOS42770
OD28	9114	1278	SLHLS	R1,4	SHIFT INTO PSW POSITION	MOS42780
OD2A	9522	1279	EPSR	R2,R2	GRAB CURRENT PSW	MOS42790
OD2C	C420 FFOF	1280	NAT	R2,X'FFOF'	MASK IT	MOS42800
OD30	0621	1281	OAR	R2,R1	FORCE LOWEST PHYSICAL SEGMENT NUMBER	MOS42810

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OD32	9532	1282	EPSR	R3,R2	ESTABLISH LOWEST SEGMENT	MOS42820
OD34	03CF	1283	BR	LINK	RETURN	MOS42830
		1284	*			MOS42840
OD36	9511	1285	ENDCHK	EPSR R1,R1	GRAB CURRENT PSW	MOS42850
OD38	4820 0C1A	1286	LH	R2,HIPHYS+6	GET HIGHEST PHYSICAL SEGMENT	MOS42860
OD3C	C420 0007	1287	NAI	R2,X'0007'	MASK IT	MOS42870
OD40	0831	1288	LDAR	R3,R1		MOS42880
OD42	9034	1289	SRHLS	R3,4	SHIFT CURRENT SEGMENT TO 3 LSB'S	MOS42890
OD44	C430 0007	1290	NAI	R3,X'0007'	MASK IT	MOS42900
OD48	0532	1291	CLAR	R3,R2	HAS HIGHEST SEGMENT BEEN REACHED ?	MOS42910
OD4A	4320 04A8	1292	BNL	TSTEND	YES, BRANCH (TO EXEC)	MOS42920
OD4E	2631	1293	AIS	R3,1	NO, INCREMENT SEGMENT NUMBER	MOS42930
OD50	2441	1294	LIS	R4,1	LOAD DISPLAY ADDRESS	MOS42940
OD52	DE40 010F	1295	OC	R4,INCR	PUT DISPLAY IN INCREMENTAL MODE	MOS42950
OD56	9453	1296	EXBR	R5,R3		MOS42960
OD58	2460	1297	LIS	R6,0		MOS42970
OD5A	9846	1298	WHR	R4,R6	DUMMY WRITE	MOS42980
OD5C	9845	1299	WHR	R4,R5	DISPLAY ADDRESSED SEGMENT	MOS42990
OD5E	DE40 010E	1300	OC	R4,NORM	PUT DISPLAY IN NORMAL MODE	MOS43000
OD62	9134	1301	SLHLS	R3,4	SHIFT NEW SEGMENT INTO POSITION	MOS43010
OD64	C410 FEOF	1302	NAI	R1,X'FF0F'	MASK OFF PRESENT PSW	MOS43020
OD68	0613	1303	CAR	R1,R3	FORCE NEXT SEGMENT NUMBER	MOS43030
OD6A	9541	1304	EPSR	B4,B1	ESTABLISH NEW PHYSICAL SEGMENT	MOS43040
OD6C	03CF	1305	BR	LINK	RETURN	MOS43050
		1306	*		*****	MOS43060
OD5E	5331 3620 3139 2D32	1307	TITLE	DC C'S16 19-221 MOS MEMORY TEST PART 2 '		MOS43070
OD76	3231 204D 4F53 204D					
OD7E	454D 4F52 5920 5445					
OD86	5354 2050 4152 5420					
OD8E	3220					
OD90	3036 2D32 3134 4630	1308	DC	C'06-214F01R00'	TEST PROGRAM NUMBER	MOS43080
OD98	3152 3030	1309	DC	X'0DOA'		MOS43090
OD9C	0DCA	1310	*			MOS43100
OD9E	F800	1311	DEFTESTS	DCX F800	DEFINES TESTS 0,1,2,3, & 4	MOS43110
		1312	*		AS DEFAULT TESTS	MOS43120
		1313	*			MOS43130
ODAO	000A	1314	MAXTST	DCX A	DEFINES TESTS 0,1,2,3,4,5,6,7,8,9&A	MOS43140
		1315	*		AS LEGAL TEST NUMBERS.	MOS43150
		1317	*			
		1318	*	TESTS TABLE		
		1319	*			
ODA4		1320	ALIGN	4		
ODA4	ODEA	1321	TESTS	DC A(TEST0)	MEMORY SEARCH TEST	MOS43170
ODA6	0E1A	1322	DC	A(TEST1)	BIT SET-RESET TEST	MOS43180
ODA8	0E9E	1323	DC	A(TEST2)	MARCHING PATTERN TEST	MOS43190
ODAA	0FAA	1324	DC	A(TEST3)	0 & 1 WALK TEST	MOS43200
ODAC	105C	1325	DC	A(TEST4)	DOUBLE OPERATION COLUMN DISTURB TEST	MOS43210
ODAE	11E2	1326	DC	A(TEST5)	SHORT COUNT RELOCATABLE	MOS43220
		1327	*		HAMMER DISTURB TEST	MOS43230
						MOS43240
						MOS43250
						MOS43260
						MOS43270

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EXEC - ETPE R03-05 (16 BIT/STRIPPED AND MODIFIED)

0DB0	12E4	1328	DC	A(TEST6)	DIAGONAL GALPAT TEST	MOS43280
0DB2	147A	1329	DC	A(TEST7)	MEMORY HOLD TEST	MOS43290
0DB4	1624	1330	DC	A(TEST8)	LONG COUNT RELOCATABLE	MOS43300
		1331	*		HAMMER DISTURB TEST	MOS43310
CDB6	1766	1332	DC	A(TEST9)	ECC DISTURB TEST	MOS43320
0DB8	19EC	1333	DC	A(TESTA)	PARITY DISTURB TEST	MOS43330
		1334	*			MOS43340
		1335	*	*****		MOS43350
		1336	*	END ETPE R03-05 (MODIFIED)		*** MOS43360

TEST 0

1338 * TEST 0 MEMORY SEARCH TEST MOS4338C
 1339 *
 1340 * PURPOSE:
 1341 * THIS UTILITY ENABLES THE USER TO LIST LIMITS OF
 1342 * MEMORY UNDER TEST.
 1343 *
 1344 * ASSUMPTIONS:
 1345 * MINIMUM MEMORY ALLOWABLE IS 64K BYTES.
 1346 *
 1347 * DESIGN SPECIFICATIONS:
 1348 * MEMORY LIMITS ARE FORCED TO THE SECOND 32KB.
 1349 * LOW PHYSICAL SEGMENT TO HIGH PHYSICAL SEGMENT
 1350 * ADDRESSES ARE PRINTED OUT.
 1351 *
 1352 * OPTIONS:
 1353 * NONE
 1354 *
 1355 * HOW TO RUN THE TEST:
 1356 * ENTER "RUN" AND THE AVAILABLE MEMORY LOCATIONS WILL
 1357 * BE PRINTED ON THE LIST DEVICE.
 1358 *
 1359 * NOTE: THIS TEST RESETS "LOLIM" AND "HILIM" TO CORRESPOND TO
 1360 * THE BLOCK OF MEMORY PRINTED OUT.

ODBA	24F0	1362	TEST0	LIS	LINK,0	MOS43620
ODBC	95FF	1363		EPSR	R14,LINK	MOS43630
ODBE	C8E0 8000	1364		LDAI	R6,X'8000'	MOS43640
ODC2	4060 0C32	1365		STH	R6,LOLIM+6	MOS43650
ODC6	2404	1366		LIS	R0,4	MOS43660
ODC8	0816	1367		LDAR	R1,R6	MOS43670
ODCA	C820 1E5D	1368		LDAI	R2,LOMSG+1	MOS43680
ODCE	41F0 06F6	1369		BAL	LINK,HEXASC	MOS43690
		1370 *			PUT LOLIM IN AVAIL. MEM. MESSAGE	MOS43700
ODD2	C880 FFFF	1371		LDAI	R8,X'FFFF'	MOS43710
ODD6	4090 0C3E	1372		STH	R8,HILIM+6	MOS43720
ODDA	0818	1373		LDAR	R1,R8	MOS43740
ODDC	C820 1E63	1374		LDAI	R2,HIMSG+1	MOS43750
ODE0	41F0 06F6	1375		BAL	LINK,HEXASC	MOS43760
ODE4	2401	1376		LIS	R0,1	MOS43770
ODE6	4810 0C0E	1377		LH	R1,LOPHYS+6	MOS43780
ODEA	C410 0007	1378		NAI	R1,7	MOS43790
ODEE	C820 1E5C	1379		LDAI	R2,LOMSG	MOS43800
ODF2	41F0 06F6	1380		BAL	LINK,HEXASC	MOS43810
		1381 *			PUT LOWEST PHYSICAL SEGMENT INTO MEMORY LIMITS MESSAGE	MOS43820
ODF6	4810 0C1A	1382		LH	R1,HIPHYS+6	MOS43830
ODFA	C410 0007	1383		NAI	R1,7	MOS43840
ODFE	C820 1E62	1384		LDAI	R2,HIMSG	MOS43850
OE02	41F0 06F6	1385		BAL	LINK,HEXASC	MOS43860
		1386 *			PUT HIGHEST PHYSICAL SEGMENT INTO MEMORY LIMITS MESSAGE	MOS43870
OE06	C850 1DA8	1387		LDAI	R5,ASMEMMSG	MOS43880
		1388 *				MOS43890

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TEST 0

OE0A 41F0 0756	1389 PRTLIM	BAL	LINK,PRINT	PRINT ASSIGNED MEMORY MESSAGE	MOS43900
OE0E C850 1E5C	1390	LDAI	R5,LOMSG		MOS43910
OE12 41F0 0756	1391	BAL	LINK,PRINT	PRINT MEMORY LIMITS	MOS43920
OE16 4300 04CE	1392	B	KEEP7		MOS43930
	1393 *	*****			MOS43940
	1394 *	END	TEST 0		MOS43950

TEST 1

1396 * TEST 1 BIT SET - RESET TEST MOS43970
 1397 * PURPOSE: MOS43980
 1398 * THIS TEST INSURES THAT ALL BITS IN THE AREA OF MEMORY MOS43990
 1399 * BEING TESTED CAN BE BOTH SET AND RESET. MOS44000
 1400 * ASSUMPTIONS: MOS44010
 1401 * MINIMUM 64KB MOS MEMORY MOS44020
 1402 * DESIGN SPECIFICATIONS: MOS44030
 1403 * 1. A WRITE AND THEN A READ IS EXECUTED TO ALL MEMORY MOS44040
 1404 * WITHIN THE "LOLIM" AND "HILIM" LIMITS. MOS44050
 1405 * 2. IF AN ERROR IS DETECTED, THE "SCOPE" OPTION MOS44060
 1406 * DICTATES HOW THE PROGRAM WILL REACT. MOS44070
 1407 *
 1408 *
 1409 *
 1410 *
 1411 *
 1412 *
 1413 *
 1414 *
 1415 *
 1416 *
 1417 *
 1418 *
 1419 *
 1420 *
 1421 *
 1422 *
 1423 *
 1424 *
 1425 *
 1426 *

LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST
 HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST
 (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW)
 SCOPE - ERROR OPTION MODE
 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST
 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST
 2 - PRINT ERROR DATA AND CONTINUE TEST
 3 - PRINT ERROR DATA AND HALT
 4 - IGNORE ERROR
 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST

HOW TO RUN THE TEST:
 1 ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA
 THE CONSOLE DEVICE.
 2. ENTER "RUN" AND THE TEST WILL EXECUTE.

OE1A	41F0 0D0E	1428	TEST 1	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS44290
OE1E	4860 0C32	1429	*				MOS44300
OE22	4880 0C3E	1430	TEST 1A	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS44310
OE26	C460 7FFE	1431		LH	R6,HILIM+6		MOS44320
OE2A	C480 7FFF	1432		NAI	R6,X'7FFE'		MOS44330
OE2E	2472	1433		NAI	R8,X'7FFF'		MOS44340
OE30	2411	1434		LIS	R7,2		MOS44350
OE32	2531	1435		LIS	R1,1	LOAD DISPLAY ADDRESS	MOS44360
		1436		LCS	R3,1		MOS44370
		1437	*				MOS44380
OE34	4036 8000	1438	STORE11	STH	R3,X'8000'(R6)	STORE BACKGROUND OF ALL 1'S	MOS44390
OE38	C160 0E34	1439		BXLE	R6,STORE11		MOS44400
OE3C	C840 3031	1440		LDAI	R4,C'01'		MOS44410
OE40	4040 0B56	1441		STH	R4,ERRNO	ERRNO = C'01'	MOS44420
OE44	4860 0C32	1442		LH	R6,LOLIM+6		MOS44430
OE48	C460 7FFE	1443		NAI	R6,X'7FFE'		MOS44435
		1444	*				MOS44440
OE4C	41F0 08C2	1445	READ11	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS44450
OE50	4846 8000	1446		LH	R4,X'8000'(R6)	LOAD DATA FROM LOC	MOS44460

TEST 1

OE54 0543	1447	CLAR	R4,R3	IS DATA AT LOC. OK ?	MOS44470
OE56 2139	1448	BNES	RTN11F	YES, BRANCH	MOS44480
OE58 C160 0E4C	1449 RTN11	BXLE	R6,READ11	CONTINUE UNTIL DONE	MOS44490
OE5C 4860 0C32	1450	LH	R6,LOLIM+6		MOS44500
OE60 C460 7FFE	1451	NAI	R6,X'7FFE'		MOS44510
OE64 2430	1452	IIS	R3,0		MOS44520
OE66 2304	1453	BS	STORE10	BRANCH	MOS44530
	1454 *				MOS44540
OE68 41F0 1C74	1455 RTN11F	BAL	LINK,ERROR	ERROR ROUTINE	MOS44550
OE6C 220A	1456	BS	RTN11	RETURN	MOS44560
	1457 *				MOS44570
OE6E 4036 8000	1458 STORE10	STH	R3,X'8000'(R6)	STORE BACKGROUND OF ALL 0'S	MOS44580
OE72 C160 0E6E	1459 BXLE		R6,STORE10		MOS44590
OE76 6110 0B56	1460 AHM		R1,ERRNO	ERRNO = C'02'	MOS44600
OE7A 4860 0C32	1461 LH		R6,LOLIM+6		MOS44610
OE7E C460 7FFE	1462 NAI		R6,X'7FFE'		MOS44615
	1463 *				MOS44620
OE82 41F0 08C2	1464 READ10	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS44630
OE86 4846 8000	1465 LH		R4,X'8000'(R6)	LOAD DATA FROM LOC	MOS44640
OE8A 2137	1466 BNZS		RTN10F	IF DATA NOT 0, BRANCH (DATA NG)	MOS44650
OE8C C160 0E82	1467 RTN10	BXLE	R6,READ10	CONTINUE UNTIL DONE	MOS44660
	1468 *				MOS44670
OE90 41F0 0D36	1469	BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS44680
OE94 43C0 0E1E	1470	B	TEST1A	ELSE BRANCH TO CONTINUE TEST	MOS44690
	1471 *				MOS44700
OE98 41F0 1C74	1472 RTN10F	BAL	LINK,ERROR	ERROR ROUTINE	MOS44710
OE9C 2208	1473 BS		RTN10	RETURN	MOS44720
	1474 *				MOS44730
	1475 * *****				MOS44740
	1476 * END TEST 1				MOS44750

TEST 2

1478 * TEST 2 MARCHING PATTERN TEST MOS44770
 1479 * PURPOSE: MOS44780
 1480 * THIS TEST CHECKS THAT THREE DIFFERENT BASE PATTERNS MOS44790
 1481 * CAN BE WRITTEN, COMPLEMENTED, AND MARCHED THROUGH THE MOS44800
 1482 * AVAILABLE MEMORY WITHOUT ERROR. MOS44810
 1483 * MOS44820
 1484 * MOS44830
 1485 * ASSUMPTIONS: MOS44840
 1486 * MINIMUM 64KB MOS MEMORY MOS44850
 1487 * DESIGN SPECIFICATIONS: MOS44860
 1488 * 1. (IN ASCENDING ORDER) WRITE AND READ THE BASE PATTERN. MOS44870
 1489 * 2. (IN DESCENDING ORDER) WRITE AND READ THE COMPLEMENT MOS44880
 1490 * PATTERN. MOS44890
 1491 * OPTIONS: MOS44900
 1492 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS44910
 1493 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS44920
 1494 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS44930
 1495 * SCOPE - ERROR OPTION MODE MOS44940
 1496 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS44950
 1497 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS44960
 1498 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS44970
 1499 * 3 - PRINT ERROR DATA AND HALT MOS44980
 1500 * 4 - IGNORE ERROR MOS44990
 1501 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS45000
 1502 * HOW TO RUN THE TEST: MOS45010
 1503 * 1 ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA MOS45020
 1504 * THE CONSOLE DEVICE. MOS45030
 1505 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS45040
 1506 * MOS45050
 1507 * MOS45060
 1508 * MOS45070

OE9E	41E0 0D0E	1510	TEST2	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS45090
		1511	*				MOS45100
0EA2	2411	1512	TEST2A	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS45110
0EA4	C840 0A3E	1513		LDAI	R4,MHO		MOS45120
0EA8	4040 003E	1514		STH	R4,X'3E'	SET NEW MM POINTER	MOS45130
0EAC	24A0	1515		LIS	R10,0		MOS45140
0EAE	25B1	1516		LCS	R11,1		MOS45150
0EB0	24D0	1517		LIS	R13,0	W/BACKGROUND = 0'S	MOS45160
0EB2	41E0 0EE4	1518		BAL	R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS45170
		1519	*				MOS45180
0EB6	25A1	1520		LCS	R10,1		MOS45190
0EB8	24B0	1521		LIS	R11,0	W/BACKGROUND = F'S	MOS45200
0EBA	41E0 0EE4	1522		BAL	R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS45210
		1523	*				MOS45220
0EBE	24D2	1524		LIS	R13,2	W/BACKGROUND = A'S	MOS45230
0EC0	41E0 0EE4	1525		BAL	R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS45240
		1526	*				MOS45250
0EC4	24A0	1527		LIS	R10,0		MOS45260
0EC6	25B1	1528		LCS	R11,1	W/BACKGROUND = 5'S	MOS45270

TEST 2

0EC8	41E0 0EE4	1529	BAL	R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS45280
		1530 *				MOS45290
0ECC	C8D0 0100	1531	LDAI	R13,X'100'	W/BACKGROUND =128-0'S,128-F'S,..	MOS45300
0ED0	41E0 0EE4	1532	BAL	R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS45310
		1533 *				MOS45320
0ED4	25A1	1534	LCS	R10,1		MOS45330
0ED6	24E0	1535	LIS	R11,0	W/BACKGROUND =128-F'S,128-0'S,..	MOS45340
0ED8	41E0 0EE4	1536	BAL	R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS45350
		1537 *				MOS45360
0EDC	41E0 0D36	1538	BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS45370
0EE0	43C0 0EA2	1539	B	TEST2A	ELSE BRANCH TO CONTINUE TEST	MOS45380
		1540 *				MOS45390
		1541 *				MOS45400
		1542 *				MOS45410
0EE4	48E0 0C32	1543	CHKLOC	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS45420
0EE8	48E0 0C3E	1544		LH R8,HILIM+6		MOS45430
0EEC	C460 7FFE	1545		NAI R6,X'7FFE'		MOS45440
0EFO	C480 7FFF	1546		NAI R8,X'7FFF'		MOS45450
0EF4	2472	1547	LIS	R7,2		MOS45460
		1548 *				MOS45470
0EF6	083A	1549	CHKLOC1	LDAR R3,R10	STORE APPROPRIATE BACKGROUND PATTERN	MOS45480
0EF8	C36D 0000	1550		TAI R6,0(R13)		MOS45490
0EFC	2332	1551	BZS	CHKLOC2		MOS45500
0EEF	083B	1552	LDAR	R3,R11		MOS45510
0F00	4036 8000	1553	CHKLOC2	STH R3,X'8000'(R6)	IN MEMORY	MOS45520
0F04	C160 0EF6	1554		BXLE R6,CHKLOC1	FROM LOLIM TO HILIM	MOS45530
0F08	48E0 0C32	1555	LH	R6,LOLIM+6		MOS45540
0FOC	C460 7FFE	1556		NAI R6,X'7FFE'		MOS45550
		1557 *				MOS45560
0F10	C840 3033	1558	CHKLOC3	LDAI R4,C'03'		MOS45570
0F14	4040 0B56	1559		STH R4,ERRNO	ERRNO = C'03'	MOS45580
0F18	41E0 08C2	1560	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS45590
0F1C	083A	1561	LDAR	R3,R10	GET APPROPRIATE BACKGROUND PATTERN	MOS45600
0F1E	C36D 0000	1562	TAI	R6,0(R13)		MOS45610
0F22	2332	1563	BZS	CHKLOC4		MOS45620
0F24	083B	1564	LDAR	R3,R11		MOS45630
0F26	4846 8000	1565	CHKLOC4	LH R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS45640
0F2A	0543	1566	CLAR	R4,R3	EQUAL ?	MOS45650
0F2C	213E	1567	BNES	CHKLOC5F	NO, BRANCH	MOS45660
0F2E	C730 FFFF	1568	XAI	R3,-1	COMPLEMENT DATA PATTERN	MOS45670
0F32	4036 8000	1569	STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS45680
0F36	6110 0B56	1570	AHM	R1,ERRNO	ERRNO = C'04'	MOS45690
0F3A	4846 8000	1571	LH	R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS45700
0F3E	0543	1572	CLAR	R4,R3	DATA = C.D.P. ?	MOS45710
0F40	2131	1573	BNES	CHKLOC6	NO, BRANCH	MOS45720
0F42	C160 0F10	1574	CHKLOC6	BXLE R6,CHKLOC3	CONTINUE UNTIL DONE(INCREMENTING)	MOS45730
0F46	23C7	1575	BS	CHKLOC6A	BRANCH	MOS45740
		1576 *				MOS45750
0F48	41E0 1C74	1577	CHKLOC5F	BAL LINK,ERROR	ERROR ROUTINE	MOS45760
0F4C	22CF	1578		BS CHKLOC5	RETURN	MOS45770
		1579 *				MOS45780
0F4E	41E0 1C74	1580	CHKLOC6F	BAL LINK,ERROR	ERROR ROUTINE	MOS45790
0F52	22C8	1581	BS	CHKLOC6	RETURN	MOS45800

TEST 2

OF54	4860	0C3E	1582	*		MOS45810	
OF58	C460	7FFE	1583	CHKLOC6A	LH R6,HILIM+6	MOS45820	
OF5C	4880	0C32	1584	NAI	R6,X'7FFE'	MOS45830	
OF60	C480	7FFE	1585	LH	R8,LCCLIM+6	MOS45840	
OF64	2572		1586	NAI	R8,X'7FFE'	MOS45850	
			1587	LCS	R7,2	MOS45860	
			1588	*		MOS45870	
OF66	083B		1589	CHKLOC7	LDAR R3,R11	GET C.D.P. FOR LOC UNDER TEST	MOS45880
OF68	C36D	0000	1590	TAI	R6,0(R13)		MOS45890
OF6C	2332		1591	BZS	CHKLOC8		MOS45900
OF6E	083A		1592	LDAR	R3,R10		MOS45910
OF70	C840	3035	1593	CHKLOC8	LDAI R4,C'05'		MOS45920
OF74	4040	0B56	1594	STH	R4,ERRNO	ERRNO = C'05'	MOS45930
OF78	41F0	08C2	1595	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS45940
OF7C	4846	8000	1596	LH	R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS45950
OF80	0543		1597	CLAR	R4,R3	DATA = C.D.P. ?	MOS45960
OF82	213E		1598	BNES	CHKLOC9F	NO, BRANCH	MOS45970
OF84	C730	FFFF	1599	CHKLOC9	XAI R3,-1	COMPLEMENT C.D.P. (O.D.P.)	MOS45980
OF88	4036	8000	1600	STH	R3,X'8000'(R6)	STORE PATTERN AT LOC	MOS45990
OF8C	6110	0B56	1601	AHM	R1,ERRNO	ERRNO = C'06'	MOS46000
OF90	4846	8000	1602	LH	R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS46010
OF94	0543		1603	CLAR	R4,R3	DATA = O.D.P. ?	MOS46020
OF96	2137		1604	BNES	CHKLOC1F	NO, BRANCH	MOS46030
OF98	C060	0F66	1605	CHKLOC10	BXH R6,CHKLOC7	CONTINUE UNTIL DONE(DECREMENTING)	MOS46040
OF9C	030E		1606	BR	R14	RETURN	MOS46050
			1607	*			MOS46060
OF9E	41F0	1C74	1608	CHKLOC9F	BAL LINK,ERROR	ERROR ROUTINE	MOS46070
OFA2	220F		1609	BS	CHKLOC9	RETURN	MOS46080
			1610	*			MOS46090
OFA4	41F0	1C74	1611	CHKLOC1F	BAL LINK,ERROR	ERROR ROUTINE	MOS46100
OFA8	2208		1612	BS	CHKLOC10	RETURN	MOS46110
			1613	*			MOS46120
			1614	*	*****		MOS46130
			1615	*	END TEST 2		MOS46140

TEST 3

1617 * TEST 3 O & 1 WALK TEST MOS46160
 1618 * MOS46170
 1619 * MOS46180
 1620 * THIS TEST WALKS A 0 THROUGH A FIELD OF 1'S AND A 1 MOS46190
 1621 * THROUGH A FIELD OF 0'S. MOS46200
 1622 * MOS46210
 1623 * ASSUMPTIONS: MOS46220
 1624 * MINIMUM 64KB MOS MEMORY MOS46230
 1625 * MOS46240
 1626 * DESIGN SPECIFICATIONS: MOS46250
 1627 * 1. WITH A BACKGROUND OF ALL 1'S, A 0 IS WALKED THROUGH MOS46260
 1628 * EACH HALFWORD OF MEMORY. A READ AND COMPARE IS DONE MOS46270
 1629 * ON EACH LOCATION. MCS46280
 1630 * 2. WITH A BACKGROUND OF ALL 0'S, A 1 IS WALKED THROUGH MOS46290
 1631 * EACH HALFWORD OF MEMORY. A COMPARE IS DONE ON EACH MOS46300
 1632 * LOCATION. MOS46310
 1633 * MOS46320
 1634 * OPTIONS: MOS46330
 1635 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS46340
 1636 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS46350
 1637 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS46360
 1638 * SCOPE - ERROR OPTION MODE MOS46370
 1639 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS46380
 1540 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS46390
 1641 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS46400
 1642 * 3 - PRINT ERROR DATA AND HALT MOS46410
 1643 * 4 - IGNORE ERROR MOS46420
 1644 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS46430
 1645 * MOS46440
 1646 * HOW TO RUN THE TEST:
 1647 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA MOS46450
 1648 * THE CONSOLE DEVICE. MOS46460
 1649 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS46470
 1649 * MOS46480

OFAA	41F0 0D0E	1651	TEST3	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS46500
		1652	*				MOS46510
OFAE	2411	1653	TEST3A	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS46520
OFB0	4860 0C32	1654		LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS46530
OFB4	4880 0C3E	1655		LH	R8,HILIM+6		MOS46540
OFB8	C460 7FFE	1656		NAI	R6,X'7FFE'		MOS46550
OFBC	C480 7FFF	1657		NAI	R8,X'7FFF'		MOS46560
OFC0	2472	1658		LIS	R7,2		MOS46570
OFC2	C840 0A3E	1659		LDAI	R4,MM0		MOS46580
OFC6	4040 003E	1660		STH	R4,X'3E'	SET NEW MM POINTER	MOS46590
OFC8	2531	1661		LCS	R3,1		MOS46600
		1662	*				MOS46610
OFCC	4036 8000	1663	STORE31	STH	R3,X'8000'(R6)	STORE BACKGROUND OF ALL 1'S	MOS46620
OFD0	C160 OFCC	1664		BXLE	R6,STORE31		MOS46630
OFD4	4860 0C32	1665		LH	R6,LOLIM+6		MOS46640
OFD8	C840 3037	1666		LDAI	R4,C'07'		MOS46650
OFDC	4040 0B56	1667		STH	R4,ERRNO	ERRNO = C'07'	MOS46660

TEST 3

1668	*			MOS46670	
OFE0	C8D0 0010	1669	T3S1	LDAI R13,16	MOS46680
OFE4	41F0 08C2	1670		BAL LINK,TSTBRKX	MOS46690
OFE8	C8C0 8000	1671		LDAI R12,X'8000'	MOS46700
OFEC	2531	1672	T3S2	LCS R3,1	MOS46710
OFFE	073C	1673		XAR R3,R12	MOS46720
OFF0	4036 8000	1674		STH R3,X'8000'(R6)	MOS46730
OFF4	4846 8000	1675		LH R4,X'8000'(R6)	MOS46740
OFF8	0543	1676		CLAR R4,R3	MOS46750
OFFA	213C	1677		BNES T3S3F	MOS46760
OFFC	90C1	1678	T3S3	SRHLS R12,1	MOS46770
OFFE	27D1	1679		SIS R13,1	MOS46780
1000	203A	1680		BNZS T3S2	MOS46790
1002	C160 OFE0	1681		BXLE R6,T3S1	MOS46800
1006	4860 0C32	1682		LH R6,LCLIM+6	MOS46810
100A	C460 7FFE	1683		MAI R6,X'7FFE'	MOS46820
100E	2430	1684		LIS R3,0	MOS46830
1010	2304	1685		BS STORE30	MOS46840
		1686	*	BRANCH	MOS46850
1012	41F0 1C74	1687	T3S3F	BAL LINK,ERROR	MOS46860
1016	220D	1688		BS T3S3	MOS46870
		1689	*		MOS46880
1018	4036 8000	1690	STORE30	STH R3,X'8000'(R6)	MOS46890
101C	C160 1018	1691		BXLE R6,STORE30	MOS46900
1020	4860 0C32	1692		LH R6,LCLIM+6	MOS46910
1024	C460 7FFE	1693		MAI R6,X'7FFE'	MOS46920
1028	6110 0B56	1694		AHS R1,ERRNO	MOS46930
		1695	*	ERRNO = C'08'	MOS46940
102C	C8D0 0010	1696	T3S4	LDAI R13,16	MOS46950
1030	41F0 08C2	1697		BAL LINK,TSTBRKX	MOS46960
1034	C830 8000	1698		LDAI R3,X'8000'	MOS46970
		1699	*		MOS46980
1038	4036 8000	1700	T3S5	STH R3,X'8000'(R6)	MOS46990
103C	4846 8000	1701		LH R4,X'8000'(R6)	MOS47000
1040	0543	1702		CLAR R4,R3	MOS47010
1042	213A	1703		BNES T3S6F	MOS47020
1044	9031	1704	T3S6	SRHLS R3,1	MOS47030
1046	27D1	1705		SIS R13,1	MOS47040
1048	2038	1706		BNZS T3S5	MOS47050
104A	C160 102C	1707		BXLE R6,T3S4	MOS47060
		1708	*		MOS47070
104E	41F0 0D36	1709		BAL LINK,EMDCCHK	MOS47080
1052	4300 0FAE	1710		B TEST3A	MOS47090
		1711	*		MOS47100
1056	41F0 1C74	1712	T3S6F	BAL LINK,ERROR	MOS47110
105A	220B	1713		BS T3S6	MOS47120
		1714	*		MOS47130
		1715	*****		MOS47140
		1716	*	END TEST 3	MOS47150

TEST 4

1718 * TEST 4 DOUBLE OPERATION COLUMN DISTURB TEST MOS47170
 1719 * MOS47180
 1720 * PURPOSE: MOS47190
 1721 * THIS TEST CHECKS THAT A DOUBLE OPERATION ON AN ADJACENT MOS47200
 1722 * COLUMN DOES NOT DISTURB THE TEST COLUMN. MOS47210
 1723 * MOS47220
 1724 * ASSUMPTIONS: MOS47230
 1725 * MINIMUM 64KB MOS MEMORY MOS47240
 1726 * MOS47250
 1727 * DESIGN SPECIFICATIONS: MOS47260
 1728 * 1. WITH 6 DIFFERENT BACKGROUND PATTERNS, A W-R-WC- MOS47270
 1729 * RC-W-B-WC-RC SERIES IS EXECUTED AT EACH LOCATION. MOS47280
 1730 * 2. A COMPARE IS DONE UPON EACH READ OPERATION. MOS47290
 1731 * 3. A TEST (COMPARISON) OF THE REST OF MEMORY IS DONE MOS47300
 1732 * AFTER EACH SERIES OF OPERATIONS. MOS47310
 1733 * MOS47320
 1734 * OPTIONS: MOS47330
 1735 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS47340
 1736 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS47350
 1737 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS47360
 1738 * SCOPE - ERROR OPTION MODE MOS47370
 1739 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS47380
 1740 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS47390
 1741 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS47400
 1742 * 3 - PRINT ERROR DATA AND HALT MOS47410
 1743 * 4 - IGNORE ERROR MOS47420
 1744 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS47430
 1745 * MOS47440
 1746 * HOW TO RUN THE TEST MOS47450
 1747 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA MOS47460
 1748 * THE CONSOLE DEVICE. MOS47470
 1749 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS47480

105C 41F0 0D0E	1751 TEST4	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS47500
1060 2411	1752 TEST4A	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS47510
1062 24A0	1753	LIS	R10,0		MOS47520
1064 25B1	1754	LCS	R11,1		MOS47530
1066 24D0	1755	LIS	R13,0		MOS47540
1068 41E0 1082	1756	BAL	R14,CHKCOL	W/BACKGROUND = 0'S	MOS47550
	1757 *			DO A DOUBLE OPERATION COLUMN	MOS47560
				DISTURB AND COMPLEMENT TEST	MOS47570
106C 24E2	1758	LIS	R13,2	W/BACKGROUND = 5'S	MOS47580
106E 41E0 1082	1759	BAL	R14,CHKCOL	DO A DOUBLE OPERATION COLUMN	MOS47590
	1760 *			DISTURB AND COMPLEMENT TEST	MOS47600
1072 C8D0 0100	1761	LDAI	R13,X'100'	W/BACKGROUND = 128-0'S,128-F'S,..	MOS47610
1076 41E0 1082	1762	BAL	R14,CHKCOL	DO A DOUBLE OPERATION COLUMN	MOS47620
	1763 *			DISTURB AND COMPLEMENT TEST	MOS47630
107A 41F0 0D36	1764	BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS47640
107E 43C0 1060	1765	B	TEST4A	ELSE BRANCH TO CONTINUE TEST	MOS47650
	1766 *			*****	MOS47660
1082 48E0 0C32	1767	CHKCOL	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS47670
1086 4880 0C3E	1768	LH	R8,HILIM+6		

TEST 4

108A	C460 7FFE	1769	NAI	R6,X'7FFE'	MOS47680
108E	C480 7FFF	1770	NAI	R8,X'7FFF'	MOS47690
1092	2472	1771	LIS	R7,2	MOS47700
1094	083A	1772	CHKCOL1	LDAR R3,R10	MOS47710
1095	C36D 0000	1773	TAI	R6,0(R13)	MOS47720
109A	2332	1774	BZS	CHKCOL2	MOS47730
109C	083B	1775	LDAR	R3,R11	MOS47740
109E	4036 8000	1776	CHKCOL2	STH R3,X'8000'(R6)	MOS47750
10A2	C160 1094	1777	BXLE	R6,CHKCOL1	MOS47760
10A6	4860 0C32	1778	LH	R6,LOLIM+6	MOS47770
10AA	C460 7FFE	1779	NAI	R6,X'7FFE'	MOS47780
10AE	C840 3033	1780	*		MOS47790
10B2	4040 0B56	1781	CHKCOL3	LDAI R4,C'03'	MOS47800
10B6	41F0 08C2	1782	STH	R4,ERRNO	MOS47810
10BA	083A	1783	BAL	LINK,TSTBRKX	MOS47820
10BC	C36D 0000	1784	LDAR	R3,R10	MOS47830
10C0	2332	1785	TAI	R6,0(R13)	MOS47840
10C2	083B	1786	BZS	CHKCOL4	MOS47850
10C4	4846 8000	1787	LDAR	R3,R11	MOS47860
10C8	0543	1788	CHKCOL4	LH R4,X'8000'(R6)	MOS47870
10CA	4230 11A2	1789	CLAR	R4,R3	MOS47880
10CE	C730 FFFF	1790	BNE	CHKCOL5F	MOS47890
10D2	4036 8000	1791	XAI	R3,-1	MOS47900
10D6	6110 0B56	1792	STH	R3,X'8000'(R6)	MOS47910
10DA	4846 8000	1793	AHM	R1,ERRNO	MOS47920
10DE	0543	1794	LH	R4,X'8000'(R6)	MOS47930
10EO	4230 11AA	1795	CLAR	R4,R3	MOS47940
10E4	C730 FFFF	1796	BNE	CHKCOL6F	MOS47950
10E8	4036 8000	1797	CHKCOL6	XAI R3,-1	MOS47960
10EC	C840 3039	1798	STH	R3,X'8000'(R6)	MOS47970
10F0	4040 0B56	1799	LDAI	R4,C'09'	MOS47980
10F4	4846 8000	1800	STH	R4,ERRNO	MOS47990
10F8	0543	1801	LH	R4,X'8000'(R6)	MOS48000
10FA	4230 11B2	1802	CLAR	R4,R3	MOS48010
10FE	C730 FFFF	1803	BNE	CHKCOL7F	MOS48020
1102	4036 8000	1804	XAI	R3,-1	MOS48030
1106	C840 3041	1805	STH	R3,X'8000'(R6)	MOS48040
110A	4040 0B56	1806	LDAI	R4,C'0A'	MOS48050
110E	4846 8000	1807	STH	R4,ERRNO	MOS48060
1112	0543	1808	LH	R4,X'8000'(R6)	MOS48070
1114	4230 11BA	1809	CLAR	R4,R3	MOS48080
1118	C160 10AE	1810	BNE	CHKCOL8F	MOS48090
111C	4860 0C3E	1811	BXLE	R6,CHKCOL3	MOS48100
1120	C460 7FFE	1812	LH	R6,HILIM+6	MOS48110
1124	4880 0C32	1813	NAI	R6,X'7FFE'	MOS48120
1128	C480 7FFE	1814	LH	R8,LCLIM+6	MOS48130
112C	2572	1815	NAI	R8,X'7FFE'	MOS48140
112E	083B	1816	LCS	R7,2	MOS48150
1130	C36D 0000	1817	*		MOS48160
1134	2332	1818	CHKCOL9	LDAR R3,R11	MOS48170
1136	083A	1819	TAI	R6,0(R13)	MOS48180
		1820	BZS	CHKCOLA	MOS48190
		1821	LDAR	R3,R10	MOS48200

GET PROPER BACKGROUND PATTERN
STORE BACKGROUND PATTERN
TO ALL OF MEMORY UNDER TEST
GET ORIGINAL DATA PATTERN (O.D.P.)
ERRNO = C'03'
IF "BREAK" GO TO TSTEND ELSE RETURN
GET DATA FROM LOC
DATA EQUAL ?
YES, BRANCH
COMPLEMENT DATA PATTERN (C.D.P.)
STORE C.D.P. AT LOC
ERRNO = C'04'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT C.D.P. (O.D.P.)
STORE O.D.P. AT LOC
ERRNO = C'09'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT O.D.P.(C.D.P.)
STORE C.D.P. AT LOC
ERRNO = C'0A'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
CONTINUE UNTIL DONE(INCREMENTING
INITIALIZE MEMORY LIMITS
(HILIM MUST BE EVEN)
GET COMPLEMENT DATA PATTERN(C.D.P.)

TEST 4

1138	C840 3035		1822	CHKCOLA	LDAI	R4,C'05'		MOS48210
113C	4040 0B56		1823		STH	R4,ERRNO		MOS48220
1140	41F0 08C2		1824		BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS48230
1144	4846 8000		1825		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS48240
1148	0543		1826		CLAR	R4,R3	DATA EQUAL ?	MOS48250
114A	4230 11C2		1827		BNE	CHKCOLBF	NO, BRANCH	MOS48260
114E	C730 FFFF		1828	CHKCOLB	XAI	R3,-1	COMPLEMENT C.D.P.(O.D.P.)	MOS48270
1152	4036 8000		1829		STH	R3,X'8000'(R6)	STORE O.D.P. AT LOC	MOS48280
1156	6110 0B56		1830		AHM	R1,ERRNO	ERRNO = C'06'	MOS48290
115A	4846 8000		1831		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS48300
115E	0543		1832		CLAR	R4,R3	DATA EQUAL ?	MOS48310
1160	4230 11CA		1833		BNE	CHKCOLCF	NO, BRANCH	MOS48320
1164	C730 FFFF		1834	CHKCCLC	XAI	R3,-1	COMPLEMENT O.D.P. (C.D.P.)	MOS48330
1168	4036 8000		1835		STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS48340
116C	C840 3042		1836		LDAI	R4,C'0B'		MOS48350
1170	4040 0B56		1837		STH	R4,ERRNO	ERRNO = C'0C'	MOS48360
1174	4846 8000		1838		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS48370
1178	0543		1839		CLAR	R4,R3	DATA EQUAL ?	MOS48380
117A	213E		1840		BNES	CHKCOLDF	NO, BRANCH	MOS48390
117C	C730 FFFF		1841	CHKCCLD	XAI	R3,-1	COMPLEMENT C.D.P.(O.D.P.)	MOS48400
1180	4036 8000		1842		STH	R3,X'8000'(R6)	STORE O.D.P. AT LOC	MOS48410
1184	6110 0B56		1843		AHM	R1,ERRNO	ERRNO = C'0C'	MOS48420
1188	4846 8000		1844		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS48430
118C	0543		1845		CLAR	R4,R3	DATA EQUAL ?	MOS48440
118E	2137		1846		BNES	CHKCOLEF	NO, BRANCH	MOS48450
1190	C060 112E		1847	CHKCOLE	BXH	R6,CHKCOL9	CONTINUE UNTIL DONE(DECREMENTING)	MOS48460
1194	030E		1848		BR	R14	RETURN	MOS48470
			1849	*				MOS48480
1196	41F0 1C74		1850	CHKCOLDF	BAL	LINK,ERROR	ERROR ROUTINE	MOS48490
119A	220F		1851		BS	CHKCOLD	RETURN	MOS48500
			1852	*				MOS48510
119C	41F0 1C74		1853	CHKCOLEF	BAL	LINK,ERROR	ERROR ROUTINE	MOS48520
11A0	2208		1854		BS	CHKCOLE	RETURN	MOS48530
			1855	*				MOS48540
11A2	41F0 1C74		1856	CHKCOL5F	BAL	LINK,ERROR	ERROR ROUTINE	MOS48550
11A6	4300 10CE		1857		B	CHKCOL5	RETURN	MOS48560
			1858	*				MOS48570
11AA	41F0 1C74		1859	CHKCOL5F	BAL	LINK,ERROR	ERROR ROUTINE	MOS48580
11AE	4300 10E4		1860		B	CHKCOL6	RETURN	MOS48590
			1861	*				MOS48600
11B2	41F0 1C74		1862	CHKCOL7F	BAL	LINK,ERROR	ERROR ROUTINE	MOS48610
11B6	4300 10FE		1863		B	CHKCOL7	RETURN	MOS48620
			1864	*				MOS48630
11BA	41F0 1C74		1865	CHKCCL8F	BAL	LINK,ERROR	ERROR ROUTINE	MOS48640
11BE	4300 1118		1866		B	CHKCOL8	RETURN	MOS48650
			1867	*				MOS48660
11C2	41F0 1C74		1868	CHKCOLBF	BAL	LINK,ERROR	ERROR ROUTINE	MOS48670
11C6	4300 114E		1869		B	CHKCOLB	RETURN	MOS48680
			1870	*				MOS48690
11CA	41F0 1C74		1871	CHKCOLCF	BAL	LINK,ERROR	ERROR ROUTINE	MOS48700
11CE	4300 1164		1872		B	CHKCOLC	RETURN	MOS48710
			1873	*				MOS48720
			1874	*	END	TEST 4		MOS48730

TEST 5

1876 * TEST 5 SHORT COUNT RELOCATABLE MOS48750
 1877 * HAMMER DISTURB TEST MOS48760
 1878 * MOS48770
 1879 * PURPOSE: MOS48780
 1880 * THIS TEST EXECUTES A SMALL, RELOCATABLE PROGRAM MOS48790
 1881 * (16 HALFWORDS) THROUGHOUT MEMORY, LOOKING FOR "SOFT" MOS48800
 1882 * FAILURES. MOS48810
 1883 * MOS48820
 1884 * ASSUMPTIONS: MOS48830
 1885 * MINIMUM 64KB MOS MEMORY MOS48840
 1886 * MOS48850
 1887 * DESIGN SPECIFICATIONS: MOS48860
 1888 * 1. THE TEST PROGRAM MUST USE 16 HALFWORDS HEAVILY, MOS48870
 1889 * DUE TO THE INTERNAL CHIP ADDRESSING SCHEME.
 1890 * 2. THE TEST RUNS WITH A BACKGROUND PATTERN EQUAL TO MOS48880
 1891 * THE CONTENTS OF "DATA".
 1892 * 3. THE TEST LOOPS 10 TIMES(INTERNAL TO THE MODULE).
 1893 * 4. THE ROUTINE (ROUTIN) IS EXECUTED 10 TIMES. THE ENTIRE MOS48890
 1894 * ROUTINE IS THEN RELOCATED IN MEMORY AND EXECUTED 10 MOS48900
 1895 * TIMES. "ROUTIN" IS MOVED UP IN MEMORY UNTIL THE LAST MOS48910
 1896 * TEST HALFWORD IS IN THE LAST MEMORY HALFWORD.
 1897 * MOS48920
 1898 * OPTIONS: MOS48930
 1899 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS48940
 1900 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS48950
 1901 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW)
 1902 * DATA - 16-BIT DATA PATTERN USED AS BACKGROUND MOS48960
 1903 * POUND - NUMBER OF TIMES A'S & 5'S ARE POUNDED IN MEMORY MOS48970
 1904 * SCOPE - ERROR OPTION MODE
 1905 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS48980
 1906 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS48990
 1907 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS49000
 1908 * 3 - PRINT ERROR DATA AND HALT MOS49010
 1909 * 4 - IGNORE ERROR MOS49020
 1910 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS49030
 1911 * MOS49040
 1912 * HOW TO RUN THE TEST:
 1913 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA MOS49050
 1914 * THE CONSOLE DEVICE.
 1915 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS49060

11D2	41F0 0D0E	1917	TEST5	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS49160
11D6	4860 0C32	1918	*				MOS49170
11DA	4880 0C3E	1919	TEST5A	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS49180
11DE	C460 7FFE	1920		LH	R8,HILIM+6		MOS49190
11E2	C480 7FFF	1921		NAI	R6,X'7FFE'		MOS49200
11E6	08E6	1922		NAI	R8,X'7FFF'		MOS49210
11E8	0898	1923		LDAR	R5,R6		MOS49220
11EA	2472	1924		LDAR	R9,R8		MOS49230
11EC	2411	1925		LIS	R7,2		MOS49240
		1926		LIS	R1,1	LOAD DISPLAY ADDRESS	MOS49250

TEST 5

11EE	C8A0 5555	1927	LDAI	R10,X'5555'	MOS49260	
11F2	C8B0 AAAA	1928	LDAI	R11,X'AAAA'	MOS49270	
11F6	2521	1929	LCS	F2,1	MOS49280	
		1930 *			MOS49290	
11F8	4026 8000	1931 TSS1	STH	P2,X'8000'(R6)	STORE BACKGROUND OF ALL 1'S	MOS49300
11FC	C160 11F8	1932	BXLE	R6,TSS1		MOS49310
1200	08E5	1933	LDAR	R6,R5		MOS49320
1202	41E0 1220	1934	BAL	R14,SFTSET	DO SHORT HAMMER DISTURB TEST	MOS49330
		1935 *			MOS49340	
1206	08E5	1936	LDAR	R6,R5	INITIALIZE MEMORY LIMITS	MOS49350
1208	2420	1937	LIS	R2,0		MOS49360
		1938 *			MOS49370	
120A	4026 8000	1939 TSS2	STH	R2,X'8000'(R6)	STORE BACKGROUND OF ALL 0'S	MOS49380
120E	C160 120A	1940	BXLE	R6,TSS2		MOS49390
1212	08E5	1941	LDAR	R6,R5		MOS49400
1214	41E0 1220	1942	BAL	R14,SFTSET	DO SHORT HAMMER DISTURB TEST	MOS49410
		1943 *			MOS49420	
1218	41E0 0D36	1944	BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS49430
121C	4300 11D6	1945	B	TEST5A	ELSE BRANCH TO CONTINUE TEST	MOS49440
		1946 *			MOS49450	
		1947 *			MOS49460	
		1948 *			MOS49470	
1220	48C0 0C02	1949 SFTSET	LH	R12,POUND+6	LOAD EXECUTION COUNTER	MOS49480
1224	41F0 08C2	1950	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS49490
1228	D000 1EE0	1951	STM	R0,MOSSAVE+32	SAVE REGISTERS 0-F	MOS49500
122C	0816	1952	LDAR	R1,R6		MOS49510
122E	D120 12AC	1953	LM	R2,STLOOP	RELOCATE PROGRAM IN MEMORY	MOS49520
1232	D021 7FE2	1954	STM	R2,X'8000'+STLOOP-ENDMOV5(R1)		MOS49530
1236	48F0 12C8	1955	LH	R15,STLOOP+28		MOS49540
123A	40F1 7FFF	1956	STH	R15,X'8000'+STLOOP-ENDMOV5+28(R1)		MOS49550
123E	2441	1957	LIS	R4,1		MOS49560
1240	9461	1958	EX3R	R6,R1		MOS49570
1242	C660 0080	1959	OAI	R6,X'0080'	RECTIFY ADDRESS FOR DISPLAY	MOS49580
1246	9846	1960	WHR	R4,R6	WRITE PRESENT ADDRESS TO DISPLAY	MOS49590
1248	D100 1EE0	1961	LM	R0,MOSSAVE+32	RESTORE REGISTERS 0-F	MOS49600
124C	41D6 7FE2	1962	BAL	R13,STLOOP-ENDMOV5+X'8000'(R6) *	BRANCH TO "STLOOP"	MOS49610
		1963 *			MOS49620	
		1964 *	TEST	BACKGROUND PATTERN		MOS49630
		1965 *			MOS49640	
1250	D000 1EE0	1966 BGTST	STM	R0,MOSSAVE+32		MOS49650
1254	C840 3045	1967	LDAI	R4,C'OE'		MOS49660
1258	4040 0B56	1968	STH	R4,ERRNO	ERRNO = C'OE'	MOS49670
125C	0832	1969	LDAR	R3,R2	LOAD BACKGROUND PATTERN	MOS49680
125E	08C6	1970	LDAR	R12,R6	SAVE LOC UNDER TEST	MOS49690
1260	0886	1971	LDAR	R8,R6		MOS49700
1262	C380 0020	1972	SAI	R8,ENDMOV5-STLOOP+2	ESTABLISH START OF SUB-2	MOS49710
1266	0865	1973	LDAR	R6,R5	GET START OF BACKGROUND TEST AREA	MOS49720
1268	0568	1974	CLAR	R6,R8	IS LOLIM NOT < START OF SUB-2 ?	MOS49730
126A	238B	1975	BNLS	BGTST3	NO, BRANCH TO TEST HIGH MEMORY	MOS49740
126C	4846 8000	1976 BGTST1	LH	R4,X'8000'(R6)	GET DATA FROM BACKGROUND LOC	MOS49750
1270	0543	1977	CLAR	R4,R3	DATA EQUAL ?	MOS49760
1272	2134	1978	BNES	BGTST2.5		MOS49770
1274	C160 126C	1979 BGTST2	BXLE	R6,BGTST1	CONTINUE LOW BACKGROUND TESTING	MOS49780

TEST 5

1278	23C4	1980		BS	BGTST3	MOS49790	
127A	41F0 1C74	1981	*			MOS49800	
127E	22C5	1982	BGTST2.5	BAL	LINK,ERROR	MOS49810	
		1983		BS	BGTST2	MOS49820	
		1984	*			MOS49830	
1280	086C	1985	BGTST3	LDAR	R6,R12	MOS49840	
1282	2662	1986		AIS	R6,2	MOS49850	
1284	0889	1987		LDAR	R6,R9	MOS49860	
1286	0568	1988		CLAR	R6,R8	MOS49870	
1288	2388	1989		BNLS	BGTST6	MOS49880	
128A	4846 8000	1990	BGTST4	LH	R4,X'8000'(P6)	MOS49890	
128E	0543	1991		CLAR	R4,R3	MOS49900	
1290	2134	1992		BNES	BGTST5.5	MOS49910	
1292	C160 128A	1993	BGTST5	BXLE	R6,BGTST4	MOS49920	
1295	23C4	1994		BS	BGTST6	MOS49930	
		1995	*			MOS49940	
1298	41F0 1C74	1996	BGTST5.5	BAL	LINK,ERROR	MOS49950	
129C	22C5	1997		BS	BGTST5	MOS49960	
		1998	*			MOS49970	
129E	D1C0 1EE0	1999	BGTST6	LM	R0,MOSSAVE+32	RESTORE REGISTERS	MOS49980
12A2	4026 7FE2	2000	BGTST7	STH	R2,X'8000'+STLOOP-ENDMOV5(R6)	* RESTORE BKGD PAT AT LOC.	MOS49990
12A6	C160 1220	2001		BXLE	R6,SFTSET	CONTINUE UNTIL DONE (INCREMENTING)	MOS50000
12AA	030E	2002		BR	R14		MOS50010
		2003	*				MOS50020
		2004	*				MOS50030
12AC	40A6 8000	2005	STLOOP	STH	R10,X'8000'(R6)	STORE FIRST DATA PATTERN	MOS50040
12B0	45A6 8000	2006		CLH	R10,X'8000'(R6)	DATA EQUAL ?	MOS50050
12B4	4230 12CA	2007		BNE	FITERR1	NO, BRANCH TO ERROR	MOS50060
12B8	40B6 8000	2008	LOPRTN1	STH	R11,X'8000'(R6)	YES, STORE SECOND DATA PATTERN	MOS50070
12BC	45B6 8000	2009		CLH	R11,X'8000'(R6)	DATA EQUAL?	MOS50080
12C0	4230 12CE	2010		BNE	FITERR2	NO, BRANCH TO ERROR	MOS50090
12C4	27C1	2011	LOPRTN2	SIS	R12,1	YES, DECREMENT POUND COUNTER	MOS50100
12C6	203D	2012		BNZS	STLOOP	BRANCH IF NOT DONE	MOS50110
12C8	03CD	2013		BR	R13	RETURN	MOS50120
	00C0 12CA	2014	ENDMOV5	EQU	*	(R6)	MOS50130
		2015	*				MOS50140
		2016	*				MOS50150
12CA	083A	2017	*				MOS50160
12CC	23C2	2018	FITERR1	LDAR	R3,R10	LOAD EXPECTED DATA	MOS50170
		2019		BS	FITERR3		MOS50180
		2020	*				MOS50190
12CE	083B	2021	FITERR2	LDAR	R3,R11		MOS50200
		2022	*				MOS50210
12D0	C840 3044	2023	FITERR3	LDAI	R4,C'0D'		MOS50220
12D4	4040 0B56	2024		STH	R4,ERRNO	ERRNO = C'0D'	MOS50230
12D8	4846 8000	2025		LH	R4,X'8000'(R6)		MOS50240
12DC	41F0 1C74	2026		BAL	LINK,ERROR		MOS50250
12E0	4300 12A2	2027		B	BGTST7	RETURN	MOS50260
		2028	*				MOS50270
		2029	*	END	TEST 5		MOS50280

TEST 6

2031 * TEST 6 DIAGONAL GALPAT TEST MOS50300
 2032 * PURPOSE: MOS50310
 2033 * THE TEST RUNS A GALLOPING PATTERN ON ALL DIAGONALS OF MOS50320
 2034 * EACH 16K RAM AND CHECKS THAT NO BACKGROUND LOCATIONS MOS50330
 2035 * HAVE CHANGED DURING THE DIAGONAL TEST. MOS50340
 2036 * MOS50350
 2037 * MOS50360
 2038 * ASSUMPTIONS: MOS50370
 2039 * MINIMUM 64KB MOS MEMORY MOS50380
 2040 *
 2041 * DESIGN SPECIFICATIONS: MOS50390
 2042 * 1. THE TEST IS EXECUTED FOR EACH OF THE SIX BACKGROUND MOS50400
 2043 * PATTERNS. MOS50410
 2044 * 2. AN ALTERNATE R-W-R-W-R-W-R(ETC) IS DONE TO A TEST MOS50420
 2045 * CELL AND FOLLOWING CELLS ON THE DIAGONAL SUCESSIVELY. MOS50430
 2046 * 3. THE TEST CELL IS MOVED ONE CELL UP THE DIAGONAL AND MOS50440
 2047 * THE PROCEDURE IS REPEATED. MOS50450
 2048 * 4. AFTER THE DIAGONAL IS COMPLETED, THE BACKGROUND MOS50460
 2049 * PATTERN IN THE REST OF EACH 16K CHIP AS TESTED. MOS50470
 2050 * 5. THE DIAGONAL IS THEN MOVED AND 2-4 IS REPEATED MOS50480
 2051 * UNTIL ALL DIAGONALS HAVE BEEN TRaversed. MOS50490
 2052 *
 2053 * OPTIONS: MOS50500
 2054 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS50510
 2055 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS50520
 2056 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS50530
 2057 * SCOPE - ERROR OPTION MODE MOS50540
 2058 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS50550
 2059 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS50560
 2060 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS50570
 2061 * 3 - PRINT ERROR DATA AND HALT MOS50580
 2062 * 4 - IGNORE ERROR MOS50590
 2063 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS50600
 2064 *
 2065 * HOW TO RUN THE TEST: MOS50610
 2066 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA MOS50620
 2067 * THE CONSOLE DEVICE. MOS50630
 2068 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS50640
 MOS50650
 MOS50660
 MOS50670

12E4	41F0 0D0E	2070	TEST6	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS50690
		2071	*				MOS50700
12E8	2410	2072	TEST6A	LIS	R1,0	FORCE TO LOLIM OF X'8000'	MOS50710
12EA	4010 1EB4	2073		STH	R1,VLOLIM	ESTABLISH VIRTUAL LOLIM	MOS50720
12EE	C810 7FFF	2074		LDAI	R1,X'7FFF'		MOS50730
12F2	4010 1EB6	2075	T6SX	STH	R1,VHILIM	ESTABLISH VIRTUAL HILIM OF X'FFFF'	MOS50740
12F6	C850 1E42	2076		LDAI	R5,T6MSG		MOS50750
12FA	41F0 0756	2077		BAL	LINK,PRINT	PRINT LIMITS UNDER DIAG. GALPAT TEST	MOS50760
12FE	C850 1E5C	2078		LDAI	R5,LOMSG		MOS50770
1302	41F0 0756	2079		BAL	LINK,PRINT		MOS50780
1306	2411	2080		LIS	R1,1	LOAD DISPLAY ADDRESS	MOS50790
1308	C820 0102	2081		LDAI	R2,X'102'	LOAD CELL INCREMENT VALUE	MOS50800

TEST 6

130C	C890 00FE	2082	LDAI	R9,X'FE'	LOAD TOP OF COLUMN MASK VALUE	MOS50810
1310	C8C0 7FFE	2083	LDAI	R12,X'7FFE'	LOAD CHIP LIMIT MASK	MOS50820
1314	24A0	2084	LIS	R10,0		MOS50830
1316	25B1	2085	LCS	R11,1		MOS50840
1318	24D0	2086	LIS	R13,0		MOS50850
131A	41E0 134C	2087	BAL	R14,TEST6ALL	W/BACKGROUND = 0'S DO DIAGONAL GALPAT TEST	MOS50860
		2088 *				MOS50870
131E	25A1	2089	LCS	R10,1		MOS50880
1320	24E0	2090	LIS	R11,0		MOS50890
1322	41E0 134C	2091	BAL	R14,TEST6ALL	W/BACKGROUND = F'S DO DIAGONAL GALPAT TEST	MOS50900
		2092 *				MOS50910
1326	24D2	2093	LIS	R13,2		MOS50920
1328	41E0 134C	2094	BAL	R14,TEST6ALL	DO DIAGONAL GALPAT TEST	MOS50930
		2095 *				MOS50940
132C	24A0	2096	LIS	R10,0		MOS50950
132E	25B1	2097	LCS	R11,1		MOS50960
1330	41E0 134C	2098	BAL	R14,TEST6ALL	W/BACKGROUND = 5'S/CHIP DO DIAGONAL GALPAT TEST	MOS50970
		2099 *				MOS50980
1334	C8D0 0100	2100	LDAI	R13,X'100'		MOS50990
1338	41E0 134C	2101	BAL	R14,TEST6ALL	W/BACKGROUND = 128-0'S, 128-F'S,.. DO DIAGONAL GALPAT TEST	MOS51000
		2102 *				MOS51010
133C	25A1	2103	LCS	R10,1		MOS51020
133E	24E0	2104	LIS	R11,0		MOS51030
1340	41E0 134C	2105	BAL	R14,TEST6ALL	W/BACKGROUND = 128-F'S, 128-0'S,.. DO DIAGONAL GALPAT TEST	MOS51040
		2106 *				MOS51050
1344	41F0 0D36	2107	BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS51060
1348	43C0 12E8	2108	B	TEST6A	ELSE BRANCH TO CONTINUE TEST	MOS51070
		2109 *				MOS51080
		2110 *	*****	*****	*****	MOS51090
		2111 *				MOS51100
134C	4860 1EB4	2112	TEST6ALL	LH R6,VLOLIM	LOAD AVAILABLE MEMORY LIMITS	MOS51110
1350	4880 1EB6	2113		LH R8,VHILIM		MOS51120
1354	2472	2114	LIS	R7,2		MOS51130
		2115 *				MOS51140
1356	083A	2116	T6S1	LDAR R3,R10	GET APPROPRIATE BACKGROUND PATTERN	MOS51150
1358	C36D 0000	2117		TAI R6,0(R13)		MOS51160
135C	2332	2118	BZS	T6S2		MOS51170
135E	083B	2119	LDAR	R3,R11		MOS51180
1360	4036 8000	2120	T6S2	STH R3,X'8000'(R6)	STORE BACKGROUND PATTERN	MOS51190
1364	C160 1356	2121	BXLE	R6,T6S1	TO ALL AVAILABLE MEMORY	MOS51200
1368	083A	2122	LDAR	R3,R10		MOS51210
136A	C36D 0000	2123	TAI	R6,0(R13)		MOS51220
136E	2332	2124	BZS	T6S2.5		MOS51230
1370	083B	2125	LDAR	R3,R11		MOS51240
1372	4036 8000	2126	T6S2.5	STH R3,X'8000'(R6)	STORE BG AT LAST LOC	MOS51250
1376	4850 1EB4	2127	LH	R5,VLOLIM	INITIALIZE BIAS	MOS51260
		2128 *				MOS51270
137A	2400	2129	T6S3	LIS R0,0	R0 = X0	MOS51280
137C	0880	2130	T6S4	LDAR R8,R0	R8 = TEST CELL	MOS51290
137E	0870	2131	T6S5	LDAR R7,R0	R7 = RUNNING CELL	MOS51300
1380	0578	2132	T6S6	CLAR R7,R8	RUNNING CELL = TEST CELL ?	MOS51310
1382	4330 13CE	2133	BE	INCRRC	YES, INCREMENT THE RUNNING CELL	MOS51320
1386	0865	2134	LDAR	R6,R5	R5 = BIAS	MOS51330

TEST 6

1388	0A68	2135	AAR	R6,R8	R6 = TEST CELL	MOS51340	
138A	083B	2136	LDAR	R3,R11	LOAD COMPLEMENT DATA PATTERN(C.D.P.)	MOS51350	
138C	C36D 0000	2137	TAI	R6,0(R13)		MOS51360	
1390	2332	2138	BZS	T6S7		MOS51370	
1392	083A	2139	LDAR	R3,R10		MOS51380	
1394	4036 8000	2140	T6S7	STH R3,X'8000'(R6)	STORE C.D.P. AT TEST CELL LOC	MOS51390	
1398	C840 3130	2141	LDAI	R4,C'10'		MOS51400	
139C	4040 0B56	2142	STH	R4,ERRNO	ERRNO = C'10'	MOS51410	
13A0	4846 8000	2143	LH	R4,X'8000'(R6)	GET TEST CELL DATA	MOS51420	
13A4	0543	2144	CLAR	R4,R3	DATA EQUAL TO C.D.P. ?	MOS51430	
13A6	4230 13E0	2145	BNE	T6ER10	NO, BRANCH - OTHERWISE	MOS51440	
13AA	4036 8000	2146	T6S8	STH R3,X'8000'(R6)	STORE C.D.P. AT TC LOC	MOS51450	
13AE	0865	2147	LDAR	R6,R5	R5 = BIAS	MOS51460	
13B0	0A67	2148	AAR	R6,R7	R6 = RUNNING CELL	MOS51470	
13B2	6110 0B56	2149	AHM	R1,ERRNO	ERRNO = C'11'	MOS51480	
13B6	083A	2150	LDAR	R3,R10	LOAD O.D.P. AT RUNNING CELL LOC	MOS51490	
13B8	C36D 0000	2151	TAI	R6,0(R13)		MOS51500	
13BC	2332	2152	BZS	T6S9		MOS51510	
13BE	083B	2153	LDAR	R3,R11		MOS51520	
13C0	4846 8000	2154	T6S9	LH R4,X'8000'(R6)	GET RUNNING CELL DATA	MOS51530	
13C4	0543	2155	CLAR	R4,R3	RC DATA = BACKGROUND DATA ?	MOS51540	
13C6	4230 13F0	2156	BNE	T6ER11	NO, BRANCH - OTHERWISE	MOS51550	
13CA	4036 8000	2157	T6S10	STH R3,X'8000'(R6)	STORE O.D.P. AT RUNNING CELL LOC	MOS51560	
		2158 *				MOS51570	
13CE	0867	2159	INCRRIC	LDAR	R6,R7	R6 = RUNNING CELL	MOS51580
13D0	0469	2160	NAR	R6,R9		MOS51590	
13D2	0569	2161	CLAR	R6,R9	RUNNING CELL = TOP OF COLUMN ?	MOS51600	
13D4	4330 1400	2162	BE	INCRTC	YES, INCREMENT THE TEST CELL	MOS51610	
13D8	0A72	2163	AAR	R7,R2	NO, INCREMENT RUNNING CELL (+X'102')	MOS51620	
13DA	047C	2164	NAR	R7,R12	STAY WITHIN CHIP (SECOND 16KB)	MOS51630	
13DC	4300 1380	2165	B	T6S6	CONTINUE TESTING	MOS51640	
		2166 *				MOS51650	
13E0	CA60 8000	2167	T6ER10	AAI	R6,X'8000'	MOS51660	
13E4	41F0 1C74	2168	BAL	LINK,ERROR	PRINT ERROR TT10	MOS51670	
13E8	CB60 8000	2169	SAI	R6,X'8000'		MOS51680	
13EC	4300 13AA	2170	B	T6S8	RETURN	MOS51690	
		2171 *				MOS51700	
13F0	CA60 8000	2172	T6ER11	AAI	R6,X'8000'	MOS51710	
13F4	41F0 1C74	2173	BAL	LINK,ERROR	PRINT ERROR TT11	MOS51720	
13F8	CB60 8000	2174	SAI	R6,X'8000'		MOS51730	
13FC	4300 13CA	2175	B	T6S10	RETURN	MOS51740	
		2176 *				MOS51750	
1400	0865	2177	INCRTC	LDAR	R6,R5	R5 = BIAS	MOS51760
1402	0668	2178	OAR	R6,R8	R6 = TEST CELL	MOS51770	
1404	083A	2179	LDAR	R3,R10	GET APPROPRIATE BACKGROUND PATTERN	MOS51780	
1406	C36D 0000	2180	TAI	R6,0(R13)		MOS51790	
140A	2332	2181	BZS	INCRTC1		MOS51800	
140C	083B	2182	LDAR	R3,R11		MOS51810	
140E	4036 8000	2183	INCRTC1	STH R3,X'8000'(R6)	RESTORE TEST CELL TO BACKGROUND PATRN	MOS51820	
1412	0469	2184	NAR	R6,R9		MOS51830	
1414	0569	2185	CLAR	R6,R9	TEST CELL = TOP OF COLUMN ?	MOS51840	
1416	2335	2186	BES	INCRXO	YES, INCREMENT X0	MOS51850	
1418	0A82	2187	AAR	R8,R2	NO, INCREMENT TEST, CELL (+X'102')	MOS51860	

TEST 6

141A 048C	2188	BAR	R8,R12	STAY WITHIN CHIP (SECOND 16KB)	MOS51870	
141C 43C0 137E	2189	B	T6S5	CONTINUE TEST	MOS51880	
	2190 *				MOS51890	
1420 41F0 08C2	2191	INCRXO	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS51900
	2192 *				MOS51910	
1424 D000 1EE0	2193	CKBG60	STM	R0,MOSSAVE+32	SAVE REGISTERS	MOS51920
1428 08E5	2194	LDAR	R6,R5	ESTABLISH LO OF 16K CHIP	MOS51930	
142A C880 7FFF	2195	LDAI	R6,X'7FFF'	ESTABLISH HI OF 16K CHIP	MOS51940	
142E 2472	2196	CKBG66	LIS	R7,2	LOAD INCREMENT VALUE	MOS51950
1430 C840 3045	2197	LDAI	R4,C'OE'		MOS51960	
1434 4040 0356	2198	STH	R4,ERRNO	ERRNO = C'OE'	MOS51970	
	2199 *				MOS51980	
1438 083A	2200	CKBG61	LDAR	R3,R10	GET APPROPRIATE BACKGRCUND PATTERN	MOS51990
143A C36D 0000	2201	TAI	R6,0(R13)		MOS52000	
143E 2332	2202	BZS	CKBG62		MOS52010	
1440 083B	2203	LDAR	R3,R11		MOS52020	
1442 4846 8000	2204	CKBG62	LH	R4,X'8000'(R6)	LOAD BACKGROUND PATTERN	MOS52030
1446 0543	2205	CLAR	R4,R3	DATA EQUAL ?	MOS52040	
1448 2134	2206	BNES	CKBG64	NO, BRANCH	MOS52050	
144A C160 1438	2207	CKBG63	BXLE	R6,CKBG61	CONTINUE UNTIL DONE	MOS52060
144E 2308	2208	BS	CKBG65		MOS52070	
	2209 *				MOS52080	
1450 CA60 8000	2210	CKBG64	AAI	R6,X'8000'		MOS52090
1454 41F0 1C74	2211	BAL	LINK,ERROR		MOS52100	
1458 CB60 8000	2212	SAI	R6,X'8000'		MOS52110	
145C 2209	2213	BS	CKBG63		MOS52120	
	2214 *				MOS52130	
145E D100 1EE0	2215	CKBG65	LM	R0,MOSSAVE+32	RESTORE REGISTERS	MOS52140
1462 CA00 0100	2216	AAI	R0,X'100'	INCREMENT XO	MOS52150	
1466 9480	2217	EXBR	R8,R0		MOS52160	
1468 C680 0080	2218	CAI	R8,X'0080'	FORCE CORRECT ADDRESS	MOS52170	
146C 2471	2219	LIS	R7,1		MOS52180	
146E 9878	2220	WHR	R7,R8	DISPLAY ADDRESS UNDER TEST	MOS52190	
1470 C500 8000	2221	CLAI	R0,X'8000'	IS THIS THE LAST DIAGONAL ?	MOS52200	
1474 4280 137C	2222	BL	T6S4	NO, BRANCH	MOS52210	
	2223 *				MOS52220	
1478 030E	2224	INCRBIAS	BR	R14	YES, RETURN	MOS52230
	2225 *				MOS52240	
	2226 * *****				MOS52250	
	2227 * END TEST 6				MOS52260	

TEST 7

2229 * TEST 7 MEMORY HOLD TEST MOS52280
 2230 * MOS52290
 2231 * PURPOSE MOS52300
 2232 * THIS TEST CHECKS THE ABILITY OF THE MOS MEMORY REFRESH MOS52310
 2233 * CIRCUIT TO OPERATE IN THE EVENT OF A POWER FAILURE. MOS52320
 2234 * MOS52330
 2235 * ASSUMPTIONS: MOS52340
 2236 * MINIMUM 64KB MOS MEMORY & BATTERY BACK-UP POWER SUPPLY.* MOS52350
 2237 * MOS52360
 2238 * DESIGN SPECIFICATIONS: MOS52370
 2239 * 1. A BACKGROUND PATTERN IS WRITTEN TO ALL MEMORY. MOS52380
 2240 * 2. POWER IS REMOVED FOR 30 SECONDS(MINIMUM). MOS52390
 2241 * 3. UPON RESTART, THE PROGRAM READS MEMORY 8 TIMES MOS52400
 2242 * CHECKING FOR ERRORS. MOS52410
 2243 * MOS52420
 2244 * OPTIONS MOS52430
 2245 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS52440
 2246 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS52450
 2247 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS52460
 2248 * SCOPE - ERROR OPTION MODE MOS52470
 2249 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS52480
 2250 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS52490
 2251 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS52500
 2252 * 3 - PRINT ERROR DATA AND HALT MOS52510
 2253 * 4 - IGNORE ERROR MOS52520
 2254 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS52530
 2255 * MOS52540
 2256 * HOW TO RUN THE TEST: MOS52550
 2257 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA MOS52560
 2258 * THE CONSOLE DEVICE. MOS52570
 2259 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS52580

147A	41F0 0D0E	2261	TEST7	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS52600
		2262	*				MOS52610
147E	4860 0C32	2263	TEST7A	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS52620
1482	4880 0C3E	2264		LH	R8,HILIM+6		MOS52630
1486	C460 7FFF	2265		NAI	R6,X'7FFE'		MOS52640
148A	C480 7FFF	2266		NAI	R8,X'7FFF'		MOS52650
148E	2788	2267		SIS	R8,8		MOS52660
1490	2478	2268		LIS	R7,8		MOS52670
1492	2411	2269		LIS	R1,1	LOAD DISPLAY ADDRESS	MOS52680
1494	24A0	2270		LIS	R10,0	LOAD 4 DATA PATTERNS	MOS52690
1496	25B1	2271		LCS	R11,1		MOS52700
1498	C8C0 AAAA	2272		LDAI	R12,X'AAAA'		MOS52710
149C	C8D0 5555	2273		LDAI	R13,X'5555'		MOS52720
		2274	*				MOS52730
14A0	40A6 8000	2275	T7S1	STH	R10,X'8000'(R6)		MOS52740
14A4	40B6 8002	2276		STH	R11,X'8002'(R6)		MOS52750
14A8	40C6 8004	2277		STH	R12,X'8004'(R6)		MOS52760
14AC	40D6 8006	2278		STH	R13,X'8006'(R6)	STORE DATA PATTERNS	MOS52770
14B0	C160 14A0	2279		BXLE	R6,T7S1	FROM LOLIM TO HILIM	MOS52780

TEST 7

14B4	41E0 15FE	2280	BAL	LINK,ENDCHK1	IF END, BRANCH TO *+4	MOS52790
14B8	43C0 147E	2281	B	TEST7A	ELSE BRANCH TO CONTINUE TEST	MOS52800
14BC	C850 1506	2282	LDAI	R5,T7MM1		MOS52810
14C0	40E0 003E	2283	STH	R5,X'3E'	SET VECTOR FOR MM ON POWER DOWN	MOS52820
14C4	C850 1F20	2284	LDAI	R5,MMSAVE		MOS52830
14C8	40E0 0022	2285	STH	R5,X'22'	SET T7 MM REG. SAVE POINTER	MOS52840
14CC	95E5	2286	EPSR	R5,R5		MOS52850
14CE	C4E0 FFF0	2287	NAI	R5,X'FFF0'	MASK OFF CC TO ZERO	MOS52860
14D2	40E0 003C	2288	STH	R5,X'3C'		MOS52870
		2289 *				MOS52880
		2290 *				MOS52890
14D6	C850 1E6A	2291	T7OUTMSG	LDAI R5,T7MSG	UNCONDITIONALLY PRINT:	MOS52900
14DA	40E0 0B0C	2292	STH	R5,ISITERR		MOS52910
14DE	41E0 0756	2293	BAL	LINK,PRINT	"POWER DOWN PROC. FOR 30 SECONDS"	MOS52920
14E2	2450	2294	LIS	R5,0		MOS52930
14E4	40E0 0B0C	2295	STH	R5,ISITERR		MOS52940
14E8	25F1	2296	LCS	R14,1	ESTABLISH WAIT COUNTERS	MOS52950
14EA	C820 0080	2297	T7S2	LDAI R2,128		MOS52960
		2298 *				MOS52970
14EE	2721	2299	T7S3	SIS R2,1		MOS52980
14F0	2031	2300	BNZS	T7S3	WAIT 256* SF INSTRUCTION TIMES	MOS52990
14F2	C8F0 15F5	2301	LDAI	LINK,T7END		MOS53000
14F6	40E0 0B0A	2302	STH	LINK,BRKVECT		MOS53010
14FA	41E0 09D4	2303	BAL	LINK,TSTBRK	IF "BREAK" GO TO T7END ELSE RETURN	MOS53020
14FE	27E1	2304	SIS	R14,1		MOS53030
1500	2038	2305	BNZS	T7S2	WAIT 30 SECONDS FOR MM	MOS53040
1502	43C0 14D6	2306	B	T7OUTMSG	ON POWER DOWN	MOS53050
		2307 *				MOS53060
		2308 * *****				MOS53070
		2309 *				MOS53080
1506	C8E0 151C	2310	T7MM1	LDAI R14,T7MM2	SET VECTOR FOR MM	MOS53090
150A	40E0 003E	2311	STH	R14,X'3E'	ON POWER UP	MOS53100
150E	95EE	2312	EPSR	R14,R14		MOS53110
1510	C6E0 8000	2313	OAI	R14,X'8000'	SET THE WAIT BIT	MOS53120
1514	C4E0 FFF0	2314	NAI	R14,X'FFF0'	MASK OFF CC TO ZERO	MOS53130
1518	95FE	2315	EPSR	R15,R14	WAIT FOR MM (PSW = X'80F0')	MOS53140
151A	22CA	2316	BS	T7MM1	BRANCH ON RUN W/O SECOND MM	MOS53150
		2317 *				MOS53160
		2318 * *****				MOS53170
		2319 *				MOS53180
151C	D3E0 0110	2320	T7MM2	LB R14,IO	GET CONSOLE DEVICE POINTER	MOS53190
1520	27E5	2321	SIS	R14,5	IS CONSOLE ON MICRO-IC BUS ?	MOS53200
1522	2334	2322	BZS	T7MM2A	YES, BRANCH	MOS53210
1524	48E0 0A56	2323	LH	R14,PASFLG	NO, IS CONSOLE ON PASIA ?	MOS53220
1528	233C	2324	BZS	T7MM3	NO, BRANCH	MOS53230
152A	48E0 0110	2325	T7MM2A	LH R14,IO	YES, GET CONSOLE DEVICE POINTER	MOS53240
152E	0AEE	2326	AAR	R14,R14	SET INDEX	MOS53250
1530	D34E 0110	2327	LB	R4,IO(R14)	GET CONSOLE ADDRESS	MOS53260
1534	DE4E 0AF8	2328	OC	R4,CON2ND(R14)	ISSUE CONSOLE SPEED COMMAND	MOS53270
1538	DE40 0AEC	2329	OC	R4,CONRD	ISSUE CONSOLE READ COMMAND	MOS53280
153C	DB40 0AE4	2330	RD	R4,SINK	DUMMY READ TO SET BUSY	MOS53290
		2331 *				MOS53300
1540	D3E0 0111	2332	T7MM3	LB R14,IO+1	GET LIST DEVICE POINTER	MOS53310

TEST 7

1544	27E5	2333	SIS	R14,5	IS CONSOLE ON MICRO-IO BUS ?	MOS53320
1546	2334	2334	BZS	T7MM3A	YES, BRANCH	MOS53330
1548	48E0 0AE8	2335	LH	R14,PASFLG2	NO, IS LIST DEVICE ON PASLA ?	MOS53340
154C	233E	2336	BZS	T7MMCOM	NO, BRANCH	MOS53350
154E	D3E0 0111	2337	T7MM3A	LB R14,10+1	GET LIST DEVICE POINTER	MOS53360
1552	D340 0110	2338	LB	R4,1C	GET CONSOLE POINTER	MOS53370
1556	C5E4	2339	CLAR	R14,R4	CONSOLE = LIST DEVICE ?	MOS53380
1558	2339	2340	BES	T7MMCOM	YES, BRANCH	MOS53390
155A	0AEF	2341	AAR	R14,R14	NO, SET INDEX	MOS53400
155C	D34E 0111	2342	LB	R4,IC+1(R14)	GET LIST DEVICE ADDRESS	MOS53410
1560	DE4E 0AF8	2343	OC	R4,LST2ND(R14)	ISSUE LIST SPEED COMMAND	MOS53420
1564	DE4E 0AED	2344	OC	R4,LSTWRT(R14)	ISSUE LIST WRITE COMMAND	MOS53430
		2345 *				MOS53440
1568	48E0 0108	2346	T7MMCOM	LH R14,PSW2	PSW = X'30F0'	MOS53450
156C	950E	2347	EPSR	RO,R14	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS53460
156E	41F0 0D0E	2348	BAL	LINK,LOSET		MOS53470
1572	C840 0A3E	2349	T7MM4	LDAI R4,M30	SET NEW MM POINTER	MOS53480
1576	4040 003E	2350	STH	R4,X'3E'		MOS53490
157A	C840 1F40	2351	LDAI	R4,RSAVE		MOS53500
157E	4040 0022	2352	STH	R4,X'22'	RESTORE ETPE MM POINTER	MOS53510
1582	24F8	2353	LIS	R14,8	LOAD MEMORY CHECK COUNTER	MOS53520
1584	C840 3230	2354	LDAI	R4,C'20'		MOS53530
1588	4040 0B56	2355	STH	R4,ERRNO	ERRNO = C'20'	MOS53540
158C	2472	2356	LIS	R7,2		MOS53550
		2357 *				MOS53560
158E	4860 0C32	2358	T7S4	LH R6,LOLIM+6		MOS53570
1592	C460 7FFE	2359	NAI	R6,X'7FFE'		MOS53580
1596	6110 0B56	2360	AHM	R1,ERRNO	INCREMENT ERRNO (21-28)	MOS53590
		2361 *				MOS53600
159A	083A	2362	T7S5	LDAI R3,R10	GET FIRST DATA PATTERN	MOS53610
159C	4846 8000	2363	LH	R4,X'8000'(R6)	LOAD DATA FROM LOC	MOS53620
15A0	0543	2364	CLAR	R4,R3	DATA EQUAL ?	MOS53630
15A2	2333	2365	BES	T7S6	YES, BRANCH	MOS53640
15A4	41F0 1C74	2366	BAL	LINK,ERROR	NO, ERROR	MOS53650
15A8	083B	2367	T7S6	LDAI R3,R11	GET SECOND DATA PATTERN	MOS53660
15AA	2662	2368	AIS	R6,2	INCREMENT LOC COUNTER	MOS53670
15AC	4846 8000	2369	LH	R4,X'8000'(R6)	LOAD DATA FROM LOC	MOS53680
15B0	0543	2370	CLAR	R4,R3	DATA EQUAL ?	MOS53690
15B2	2333	2371	BES	T7S7	YES, BRANCH	MOS53700
15B4	41F0 1C74	2372	BAL	LINK,ERROR	NO, ERROR	MOS53710
15B8	083C	2373	T7S7	LDAI R3,R12	GET THIRD DATA PATTERN	MOS53720
15BA	2662	2374	AIS	R6,2	INCREMENT LOC COUNTER	MOS53730
15BC	4846 8000	2375	LH	R4,X'8000'(R6)	LOAD DATA FROM LOC	MOS53740
15C0	0543	2376	CLAR	R4,R3	DATA EQUAL ?	MOS53750
15C2	2333	2377	BES	T7S8	YES, BRANCH	MOS53760
15C4	41F0 1C74	2378	BAL	LINK,ERROR	NO, ERROR	MOS53770
15C8	083D	2379	T7S8	LDAI R3,R13	GET FOURTH DATA PATTERN	MOS53780
15CA	2662	2380	AIS	R6,2	INCREMENT LOC COUNTER	MOS53790
15CC	4846 8000	2381	LH	R4,X'8000'(R6)	LOAD DATA FROM LOC	MOS53800
15D0	0543	2382	CLAR	R4,R3	DATA EQUAL ?	MOS53810
15D2	2333	2383	BES	T7S9	YES, BRANCH	MOS53820
15D4	41F0 1C74	2384	BAL	LINK,ERROR	NO, ERROR	MOS53830
15D8	C160 159A	2385	T7S9	BXLE R6,T7S5	CHECK LOLIM TO HILIM	MOS53840

TEST 7

15DC	C8F0	15F6	2386	LDAI	LINK,T7END	MOS53850
15E0	40F0	0B0A	2387	STH	LINK,BRKVECT	MOS53860
15E4	41F0	08D4	2388	BAL	LINK,TSTBRK	MOS53870
15E8	27E1		2389	SIS	R14,1	IF "BREAK" GO TO T7END ELSE RETURN CHECKED MEMORY 8 TIMES ?
15EA	4230	158E	2390	BNZ	T7S4	MOS53880
15EE	41F0	15FE	2391	BAL	LINK,ENDCHK1	MOS53890
15F2	4300	1572	2392	B	T7MM4	MOS53900
15F6	41F0	09D0	2393	T7END	BAL LINK,LCORE	MOS53910
15FA	4300	04A9	2394	B	TSTEND	RE-ESTABLISH LOW CORE END OF TEST(RETURN TO EXEC)
			2395	*		MOS53920
			2396	*	*****	MOS53930
			2397	*	*****	MOS53940
			2398	ENDCHK1	EPSR R1,R1	MOS53950
15FE	9511		2399	LH	R2,HIPHYS+6	MOS53960
1600	4820	0C1A	2400	NAI	R2,7	GRAB PRESENT PSW GET HIGHEST PHYSICAL SEGMENT NUMBER
1604	C420	0007	2401	LDAR	R3,R1	MASK IT
1608	0231		2402	SRHLS	R3,4	MOS53970
160A	9034		2403	NAI	R3,7	MOS53980
160C	C430	0007	2404	CLAR	R3,R2	MOS53990
1610	0532		2405	BNL	4(LINK)	MOS54000
1612	438F	0004	2406	AIS	R3,1	SHIFT SEGMENT NUMBER TC 3 LSB'S
1616	2631		2407	SLHLS	R3,4	MOS54010
1618	9134		2408	NAI	R1,X'FF00'	MOS54020
161A	C410	FF00	2409	OAP	R1,R3	DONE ?
161E	0613		2410	EPSR	R4,R1	YES, BRANCH (*+4)
1620	9541		2411	BR	LINK	NO, INCREMENT SEGMENT NUMBER
1622	030F		2412	*		SHIFT INTO POSITION
			2413	*	*****	MASK OFF CURRENT PSW
			2414	*	END TEST 7	MOS54050
						MOS54060
						MOS54070
						MOS54080
						MOS54090
						MOS54100
						MOS54110
						MOS54120
						MOS54130

TEST 8

2416 * TEST 8 (OPTIONAL TEST) LONG COUNT RELOCATABLE MOS54150
 2417 * HAMMER DISTURB TEST MOS54160
 2418 * MOS54170
 2419 * PURPOSE: MOS54180
 2420 * THE TEST EXERCISES THE MOS MEMORY IN AN ENVIRONMENT MOS54190
 2421 * SIMILAR TO THAT OF AN OPERATING SYSTEM. MOS54200
 2422 * MOS54210
 2423 * ASSUMPTIONS: MOS54220
 2424 * MINIMUM 64KB MOS MEMORY MOS54230
 2425 * MOS54240
 2426 * DESIGN SPECIFICATIONS: MOS54250
 2427 * THIS IS AN "OVERNIGHT" (VERY LONG) TEST DESIGNED TO MOS54260
 2428 * POINT OUT POSSIBLE "SOFT" FAILURE LOCATIONS IN MOS MOS54270
 2429 * MEMORY. (SIMILAR TO TEST 5) MOS54280
 2430 * MOS54290
 2431 * MOS54300
 2432 * OPTIONS: MOS54310
 2433 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS54320
 2434 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS54330
 2435 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS54340
 2436 * DATA - 16-BIT BACKGROUND DATA PATTERN MOS54350
 2437 * SCOPE - ERROR OPTION MODE MOS54360
 2438 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS54370
 2439 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS54380
 2440 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS54390
 2441 * 3 - PRINT ERROR DATA AND HALT MOS54400
 2442 * 4 - IGNORE ERROR MOS54410
 2443 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS54420
 2444 * HOW TO RUN THE TEST: MOS54430
 2445 * 1. ENTER THE "SCOPE", "LOPHYS", "HIPHYS", & "DATA" MOS54440
 2446 * OPTIONS VIA THE CONSOLE DEVICE. MOS54450
 2447 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS54460

1624	41F0 0DOE	2449	TEST 8	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS54480
		2450	*				MOS54490
1628	4860 0C32	2451	TEST8A	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS54500
162C	4880 0C3E	2452		LH	R8,HILIM+6		MOS54510
1630	C460 7FFE	2453		NAI	R6,X'7FFE'		MOS54520
1634	C480 7FFF	2454		NAI	R8,X'7FFF'		MOS54530
1638	08A6	2455		LDAR	R10,R6		MOS54540
163A	08B8	2456		LDAR	R11,R8		MOS54550
163C	0878	2457		LDAR	R7,R8		MOS54560
163E	0B76	2458		SAR	R7,R6		MOS54570
1640	C570 0070	2459		CLAI	R7,ENDMOV8-MOVPRG+4	IS HILIM - LOLIM LARGE ENOUGH ?	MOS54580
1644	4280 1756	2460		BL	T8L0PRT	IF NOT, BRANCH AND PRINT ERROR	MOS54590
1648	2411	2461		LIS	R1,1	LOAD DISPLAY ADDRESS	MOS54600
164A	4850 0BF6	2462		LH	R5,DATA+6	LOAD BACKGROUND DATA PATTERN	MOS54610
164E	2472	2463		LIS	R7,2		MOS54620
		2464	*				MOS54630
1550	4056 8000	2465	T8SW	STH	R5,X'8000'(R6)	STORE BACKGROUND DATA PATTERN	MOS54640
1654	C160 1650	2466		BXLE	R6,T8SW	FROM LOLIM TO HILIM	MOS54650

TEST 8

1658	4860 0C32	2467	LH	R6,LOLIM+6	MOS54660		
165C	C460 7FFE	2468	OAI	R6,X'7FFE'	MOS54670		
		2469 *			MOS54680		
1660	D000 1EE0	2470	STM	R0,MOSSAVE+32	SAVE REGISTERS (0-F)	MOS54690	
1664	0816	2471	LDAR	R1,R6		MOS54700	
1666	D120 16EA	2472	LM	R2,MOVPRG	MOVE SUB INTO TEST AREA	MOS54710	
166A	D021 7F92	2473	STM	B2,X'8000'+MOVPRG-ENDMOV8-2(R1)		MOS54720	
166E	D120 1706	2474	LM	R2,MOVPRG+28		MOS54730	
1672	D021 7FAE	2475	STM	B2,X'8000'+MOVPRG-ENDMOV8+26(R1)		MOS54740	
1676	D120 1722	2476	LM	R2,MOVPRG+56		MOS54750	
167A	D021 7FC1	2477	STM	B2,X'8000'+MOVPRG-ENDMOV8+54(R1)		MOS54760	
167E	D140 173E	2478	LM	R4,MOVPRG+84		MOS54770	
1682	D041 7FE6	2479	STM	R4,X'8000'+MOVPRG-ENDMOV8+82(R1)		MOS54780	
1686	D100 1EE0	2480	LM	R0,MOSSAVE+32	RESTORE REGISTERS (0-F)	MOS54790	
168A	C840 0A3E	2481	LDAI	R4,MMO		MOS54800	
168E	4040 003E	2482	STH	R4,X'3E'	SET NEW MM POINTER	MOS54810	
		2483 *				MOS54820	
1692	41F0 08C2	2484	T8SX	BAL	LINK,TSTBRKX	IF "BREAK" GO TO "OPTIN" ELSE RETURN	MOS54830
1696	C840 3044	2485	LDAI	R4,C'0D'		MOS54840	
169A	4040 0B56	2486	STH	R4,ERRNO	ERRNO = C'0D'	MOS54850	
169E	41E6 7F94	2487	BAL	R14,X'8000'+MOVPRG-ENDMOV8(R6) *	BRANCH TO "MOVPRG"	MOS54860	
		2488 *				MOS54870	
16A2	D000 1EE0	2489	STM	R0,MOSSAVE+32	SAVE REGISTERS (0-F)	MOS54880	
16A6	0816	2490	LDAR	R1,R6		MOS54890	
16A8	D121 7FE2	2491	LM	R2,X'8000'-30(R1)	RELOCATE SUB IN MEMORY	MOS54900	
16AC	D021 7FE4	2492	STM	R2,X'8000'-28(R1)		MOS54910	
16B0	D121 7FC6	2493	LM	R2,X'8000'-58(R1)		MOS54920	
16B4	D021 7FC8	2494	STM	R2,X'8000'-56(R1)		MOS54930	
16B8	D121 7FAA	2495	LM	R2,X'8000'-86(R1)		MOS54940	
16BC	D021 7FAC	2496	STM	R2,X'8000'-84(R1)		MOS54950	
16C0	D141 7F90	2497	LM	R4,X'8000'-112(R1)		MOS54960	
16C4	D041 7F92	2498	STM	R4,X'8000'-110(R1)		MOS54970	
16C8	94E1	2499	EXBR	R6,R1		MOS54980	
16CA	C6E0 0080	2500	OAI	R6,X'0080'		MOS54990	
16CE	2441	2501	LIS	R4,1		MOS55000	
16D0	9846	2502	WHR	R4,R6	DISPLAY ADDRESS UNDER TEST	MOS55010	
16D2	D100 1EE0	2503	LM	R0,MOSSAVE+32	RESTORE REGISTERS (0-F)	MOS55020	
		2504 *				MOS55030	
16D6	4056 7F92	2505	STH	R5,X'8000'+MOVPRG-ENDMOV8-2(R6) *	FIX LAST LOC BKGRD PAT	MOS55040	
16DA	088B	2506	LDAR	R8,R11		MOS55050	
16DC	0568	2507	CLAR	R6,R8	DONE ?	MOS55060	
16DE	4280 1692	2508	BL	T8SX	NO, BRANCH	MOS55070	
16E2	41F0 0D36	2509	BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS55080	
16E6	4300 1628	2510	B	TEST8A	ELSE BRANCH TO CONTINUE TEST	MOS55090	
		2511 *				MOS55100	
		2512 *				MOS55110	
		2513 *				MOS55120	
16EA	2430	2514	MOVPRG	LIS R3,0	INITIALIZE DATA PATTERN	MOS55130	
16EC	9D14	2515	SSR	R1,R4	EXERCISE BIT NO.3 IN INSTR. STREAM	MOS55140	
		2516 *				MOS55150	
16EE	4036 8000	2517	MOVPRG1	STM R3,X'8000'(R6)	STORE PATTERN AT TEST LOC	MOS55160	
16F2	4846 8000	2518	LH	R4,X'8000'(R6)	LOAD FROM LOC	MOS55170	
16F6	0543	2519	CLAR	R4,R3	EQUAL ?	MOS55180	

TEST 8

16F8	2134	2520	BNES	MOVPRG2F	NO, BRANCH	MOS55190	
16FA	2731	2521	MOVPRG2	SIS R3,1	DECREMENT DATA PATTERN	MOS55200	
16FC	2037	2522	BNZS	MOVPRG1	REPEAT TILL DONE	MOS55210	
16FE	2304	2523	BS	MOVPRG26	BRANCH	MOS55220	
		2524	*			MOS55230	
1700	41F0 1C74	2525	MOVPRG2F	BAL	LINK, ERROR	ERROR ROUTINE	MOS55240
1704	2205	2526	BS	MOVPRG2		RETURN	MOS55250
		2527	*				MOS55260
1706	0886	2528	MOVPRG26	LDAR	R8,R6		MOS55270
1708	08C6	2529		LDAR	R12,R6	SAVE TEST LOCATION COUNTER	MOS55280
170A	C880 006E	2530	SAI	R8,ENDMOV8-MOVPRG+2			MOS55290
170E	0835	2531	LDAR	R3,R5	GET BACKGROUND DATA PATTERN	MOS55300	
1710	6110 0B56	2532	AHM	R1,ERRNO	ERRNO = 'OE'	MOS55310	
1714	086A	2533	LDAR	R6,R10		MOS55320	
1716	0568	2534	CLAR	R6,R8	TST BG LOC = TEST LOCATION ?	MOS55330	
1718	238B	2535	BNLS	MOVPRG5	YES, BRANCH	MOS55340	
171A	4846 8000	2536	MOVPRG3	LH R4,X'8000'(R6)			MOS55350
171E	0543	2537	CLAR	R4,R3	IS LOW BACKGROUND PATTERN OK ?	MOS55360	
1720	2134	2538	BNES	MOVPRG4F	NO, BRANCH	MOS55370	
1722	C16C 7FC2	2539	MOVPRG4	BXLE R6,X'8000'+MOVPRG3-ENDMOV8-2(R12)	DO TIL DONE LOW BG TST	MOS55380	
1726	2304	2540	BS	MOVPRG5	CONTINUE	MOS55390	
		2541	*				MOS55400
1728	41F0 1C74	2542	MOVPRG4F	BAL	LINK, ERROR	ERROR ROUTINE	MOS55410
172C	2205	2543	BS	MOVPRG4		RETURN	MOS55420
		2544	*				MOS55430
172E	C86C 0002	2545	MOVPRG5	LDAI R6,2(R12)	INCREMENT LOC COUNTER	MOS55440	
1732	088B	2546		LDAR R8,R11			MOS55450
1734	0568	2547	MOVPRG6	CLAR R6,R8	LOC > HILIM ?	MOS55460	
1736	238A	2548	BNLS	MOVPRG8	YES, DONE	MOS55470	
1738	4846 8000	2549	LH R4,X'8000'(R6)				MOS55480
173C	0543	2550	CLAR	R4,R3	NO, IS HI BACKGROUND PATTERN OK ?	MOS55490	
173E	2133	2551	BNES	MOVPRG7F	NO, BRANCH	MOS55500	
1740	2662	2552	MOVPRG7	AIS R6,2	INCREMENT HI LOC	MOS55510	
1742	2207	2553	BS	MOVPRG6	CONTINUE (BRANCH)	MOS55520	
		2554	*				MOS55530
1744	41F0 1C74	2555	MOVPRG7F	BAL	LINK, ERROR	ERROR ROUTINE	MOS55540
1748	2204	2556	BS	MOVPRG7		RETURN	MOS55550
		2557	*				MOS55560
174A	C86C 0002	2558	MOVPRG8	LDAI R6,2(R12)	INDEX THE TEST LOCATION BY TWO	MOS55570	
174E	0568	2559	CLAR	R6,R8	DONE ?	MOS55580	
1750	028E	2560	BLR	R14		MOS55590	
1752	4300 04A8	2561	B	TSTEND	(RETURN TO EXEC)	MOS55600	
	0000 1756	2562	ENDMOV8	EQU *	(R6)	MOS55610	
		2563	*			MOS55620	
		2564	*			MOS55630	
1756	C850 1E90	2565	T8LOPRT	LDAI R5,T8LOMSG	UNCONDITIONALLY PRINT ERROR MESSAGE	MOS55640	
175A	4050 0B0C	2566	STH	R5,ISITERR		MOS55650	
175E	41F0 0756	2567	BAL	LINK,PRINT	"HILIM - LOLIM IS < REQUIRED"	MOS55660	
1762	4300 01BE	2568	B	OPTIN	ABORT TESTING SEQUENCE	MOS55670	
		2569	*			MOS55680	
		2570	*	END TEST 8		MOS55690	

TEST 9

ECC DISTURB TEST

2572 * TEST 9-1 MARCHING PATTERN TEST MOS55710
2573 * MOS55720
2574 * PURPOSE: MOS55730
2575 * THIS TEST CHECKS THAT THREE DIFFERENT BASE PATTERNS
2576 * CAN BE WRITTEN, COMPLEMENTED, AND MARCHED THROUGH THE
2577 * AVAILABLE MEMORY WITHOUT ERROR. MOS55740
2578 *
2579 * ASSUMPTIONS: MOS55750
2580 * MINIMUM 64KB MOS MEMORY MOS55760
2581 *
2582 * DESIGN SPECIFICATIONS: MOS55770
2583 * 1. (IN ASCENDING ORDER) WRITE AND READ THE BASE PATTERN.
2584 * 2. (IN DESCENDING ORDER) WRITE AND READ THE
2585 * COMPLEMENT PATTERN. MOS55780
2586 *
2587 * OPTIONS: MOS55790
2588 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST
2589 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST
2590 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW)
2591 * SCOPE - ERROR OPTION MODE
2592 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST
2593 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST
2594 * 2 - PRINT ERROR DATA AND CONTINUE TEST
2595 * 3 - PRINT ERROR DATA AND HALT
2596 * 4 - IGNORE ERROR
2597 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST
2598 *
2599 * HOW TO RUN THE TEST:
2600 * 1. ENTER THE "SCOPE", LOPHYS", & "HIPHYS" OPTIONS VIA
2601 * THE CONSOLE DEVICE.
2602 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE.

1766	41FO 0D0E	2604	TEST9	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS56030
		2605	*				MOS56040
176A	2411	2606	TEST9A	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS56050
176C	C840 0A3E	2607		LDAI	R4,MNO		MOS56060
1770	4040 003E	2608		STH	R4,X'3E'	SET NEW MM POINTER	MOS56070
1774	24A0	2609		LIS	R10,0		MOS56080
1776	C8B0 8001	2610		LDAI	R11,X'8001'		MOS56090
177A	24D0	2611		LIS	R13,0	W/BACKGROUND = 0'S	MOS56100
177C	41E0 17B0	2612		BAL	R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS56110
		2513	*				MOS56120
1780	C8A0 8001	2614		LDAI	R10,X'8001'		MOS56130
1784	24B0	2615		LIS	R11,0	W/BACKGROUND = F'S	MOS56140
1786	41E0 17B0	2616		BAL	R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS56150
		2617	*				MOS56160
178A	24D2	2618		LIS	R13,2	W/BACKGROUND = A'S	MOS56170
178C	41E0 17B0	2619		BAL	R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS56180
		2620	*				MOS56190
1790	24A0	2621		LIS	R10,0		MOS56200
1792	C8B0 8001	2622		LDAI	R11,X'8001'	W/BACKGROUND = 5'S	MOS56210

TEST 9 ECC DISTURB TEST

1796	41E0 17B0	2623	BAL	R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS56220
		2624 *				MOS56230
179A	C8D0 0100	2625	LDAI	R13,X'100'	W/BACKGROUND =128-0'S,128-F'S,..	MOS56240
179E	41E0 17B0	2626	BAL	R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS56250
		2627 *				MOS56260
17A2	C8A0 8001	2628	LDAI	R10,X'8001'		MOS56270
17A6	24E0	2629	LIS	R11,0	W/BACKGROUND =128-F'S,128-0'S,..	MOS56280
17A8	41E0 17B0	2630	BAL	R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS56290
		2631 *				MOS56300
17AC	4300 1878	2632	B	TEST9B	END OF TEST (GOTO TEST 9B)	MOS56310
		2633 *				MOS56320
		2634 *				MOS56330
		2635 *				MOS56340
17B0	4860 0C32	2636	KHKLOC	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS56350
17B4	4880 0C3E	2637		LH R8,HILIM+6		MOS56360
17B8	C460 7FFE	2638	NAI	R6,X'7FFE'		MOS56370
17BC	C480 7FFF	2639	NAI	R8,X'7FFF'		MOS56380
17C0	2472	2640	LIS	R7,2		MOS56390
		2641 *				MOS56400
17C2	083A	2642	KHKLCC1	LDAR R3,R10	STORE APPROPRIATE BACKGROUND PATTERN	MOS56410
17C4	C36D 0000	2643		TAI R6,0(R13)		MOS56420
17C8	2332	2644	BZS	KHKLOC2		MOS56430
17CA	083B	2645	LDAR	R3,R11		MOS56440
17CC	4036 8000	2646	KHKLOC2	STH R3,X'8000'(R6)	IN MEMORY	MOS56450
17D0	C160 17C2	2647	BXLE	R6,KHKLOC1	FROM LOLIM TO HILIM	MOS56460
17D4	4860 0C32	2648	LH	R6,LOLIM+6		MOS56470
17D8	C460 7FFE	2649	NAI	R6,X'7FFE'		MOS56480
		2650 *				MOS56490
17DC	C840 3033	2651	KHKLOC3	LDAI R4,C'03'		MOS56500
17E0	4040 0B56	2652		STH R4,ERRNO	ERRNO = C'03'	MOS56510
17E4	41F0 08C2	2653	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS56520
17E8	083A	2654	LDAR	R3,R10	GET APPROPRIATE BACKGROUND PATTERN	MOS56530
17EA	C36D 0000	2655	TAI	R6,0(R13)		MOS56540
17EE	2332	2656	BZS	KHKLOC4		MOS56550
17F0	083B	2657	LDAR	R3,R11		MOS56560
17F2	4846 8000	2658	KHKLOC4	LH R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS56570
17F6	0543	2659	CLAR	R4,R3	EQUAL ?	MOS56580
17F8	213E	2660	BNES	KHKLOC5F	NO, BRANCH	MOS56590
17FA	C730 8001	2661	KHKLOC5	XAI R3,X'8001'	COMPLEMENT DATA PATTERN	MOS56600
17FE	4036 8000	2662	STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS56610
1802	6110 0B56	2663	AHM	R1,ERRNO	ERRNO = C'04'	MOS56620
1806	4846 8000	2664	LH	R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS56630
180A	0543	2665	CLAR	R4,R3	DATA = C.D.P. ?	MOS56640
180C	2131	2666	BNES	KHKLOC6	NO, BRANCH	MOS56650
180E	C160 17DC	2667	KHKLOC6	BXLE R6,KHKLOC3	CONTINUE UNTIL DONE(INCREMENTING)	MOS56660
1812	2307	2668	BS	KHKLOC6A	BRANCH	MOS56670
		2669 *-----				MOS56680
1814	41F0 1C74	2670	KHKLOC5F	BAL LINK,ERROR	ERROR ROUTINE	MOS56690
1818	220F	2671		BS KHKLOC5	RETURN	MOS56700
		2672 *				MOS56710
181A	41F0 1C74	2673	KHKLCC6F	BAL LINK,ERROR	ERROR ROUTINE	MOS56720
181E	2208	2674		BS KHKLOC6	RETURN	MOS56730
		2675 *-----				MOS56740

TEST 9

ECC DISTURB TEST

1820	4860	0C3E	2676	KHKLCC6A	LH	R6,HILIM+6		MOS56750
1824	C460	7FFE	2677		NAI	R6,X'7FFE'		MOS56760
1828	4880	0C32	2678		LH	R8,LOLIM+6	ESTABLISH MEMORY LIMITS	MOS56770
182C	C480	7FFE	2679		NAI	R8,X'7FFE'		MOS56780
1830	2781		2680		SIS	R8,1		MOS56790
1832	2572		2681		LCS	R7,2		MOS56800
			2682	*				MOS56810
1834	083B		2683	KHKLOC7	LDAR	R3,R11	GET C.D.P. FOR LOC UNDER TEST	MOS56820
1836	C36D	0000	2684		TAI	R6,0(R13)		MOS56830
183A	2332		2685		BZS	KHKLOC8		MOS56840
183C	083A		2686		LDAR	R3,R10		MOS56850
183E	C840	3035	2687	KHKLOC8	LDAI	R4,C'05'		MOS56860
1842	4040	0356	2688		STH	R4,ERRNO		MOS56870
1846	41E0	08C2	2689		BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS56880
184A	4846	8000	2690		LH	R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS56890
184E	0543		2691		CLAR	R4,R3	DATA = C.D.P. ?	MOS56900
1850	213E		2692		BNES	KHKLOC9F	NO, BRANCH	MOS56910
1852	C730	8001	2693	KHKLOC9	XAI	R3,X'8001'	COMPLEMENT C.D.P. (O.D.P.)	MOS56920
1856	4036	8000	2694		STH	R3,X'8000'(R6)	STORE PATTERN AT LOC	MOS56930
185A	6110	0E56	2695		AHM	R1,ERRNO	ERRNO = C'06'	MOS56940
185E	4846	8000	2696		LH	R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS56950
1862	0543		2697		CLAR	R4,R3	DATA = O.D.P. ?	MOS56960
1864	2137		2698		BNES	KHKLOC1F	NO, BRANCH	MOS56970
1866	C060	1834	2699	KHKLOC10	BXH	R6,KHKLOC7	CONTINUE UNTIL DONE(DECREMENTING)	MOS56980
			2700	*				MOS56990
186A	030E		2701		BR	R14	RETURN	MOS57000
			2702	*				MOS57010
186C	41F0	1C74	2703	KHKLOC9F	BAL	LINK,ERROR	ERROR ROUTINE	MOS57020
1870	220F		2704		BS	KHKLOC9	RETURN	MOS57030
			2705	*				MOS57040
1872	41F0	1C74	2706	KHKLOC1F	BAL	LINK,ERROR	ERROR ROUTINE	MOS57050
1876	2208		2707		BS	KHKLOC10	RETURN	MOS57060
			2708	*				MOS57070
			2709	*			*****	MOS57080
			2710	*	END	TEST 9-1		MOS57090

TEST 9

ECC DISTURB TEST

2712 * TEST 9-2 DOUBLE OPERATION COLUMN DISTURB TEST MOS57110
 2713 * MOS57120
 2714 * MOS57130
 2715 * PURPOSE: THIS TEST CHECKS THAT A DOUBLE OPERATION ON AN ADJACENT MOS57140
 2716 * COLUMN DOES NOT DISTURB THE TEST COLUMN. MOS57150
 2717 * MOS57160
 2718 * ASSUMPTIONS: MOS57170
 2719 * MINIMUM 64KB MOS MEMORY MOS57180
 2720 * MOS57190
 2721 * DESIGN SPECIFICATIONS: MOS57200
 2722 * 1. WITH 6 DIFFERENT BACKGROUND PATTERNS, A W-R-WC- MOS57210
 2723 * RC-W-R-WC-RC SERIES IS EXECUTED AT EACH LOCATION. MOS57220
 2724 * 2. A COMPARE IS DONE UPON EACH READ OPERATION. MOS57230
 2725 * 3. A TEST (COMPARISON) OF THE REST OF MEMORY IS DONE MOS57240
 2726 * AFTER EACH SERIES OF OPERATIONS. MOS57250
 2727 * MOS57260
 2728 * OPTIONS: MOS57270
 2729 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS57280
 2730 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS57290
 2731 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS57300
 2732 * SCOPE - ERROR OPTION MODE MOS57310
 2733 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS57320
 2734 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS57330
 2735 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS57340
 2736 * 3 - PRINT ERROR DATA AND HALT MOS57350
 2737 * 4 - IGNORE ERROR MOS57360
 2738 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS57370
 2739 * MOS57380
 2740 * HOW TO RUN THE TEST MOS57390
 2741 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA MOS57400
 2742 * THE CONSOLE DEVICE. MOS57410
 2743 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS57420

1878	2411	2745	TEST9B	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS57440
187A	24A0	2746		LIS	R10,0		MOS57450
187C	C8B0 8001	2747		LDAI	R11,X'8001'		MOS57460
1880	24D0	2748		LIS	R13,0	W/BACKGROUND = 0'S	MOS57470
1882	41E0 189C	2749		BAL	R14,KHKCOL	DO A DOUBLE OPERATION COLUMN	MOS57480
		2750	*			DISTURB AND COMPLEMENT TEST	MOS57490
1886	24D2	2751		LIS	R13,2	W/BACKGROUND = 5'S	MOS57500
1888	41E0 189C	2752		BAL	R14,KHKCOL	DO A DOUBLE OPERATION COLUMN	MOS57510
		2753	*			DISTURB AND COMPLEMENT TEST	MOS57520
188C	C8D0 0100	2754		LDAI	R13,X'100'	W/BACKGROUND = 128-0'S, 128-F'S,...	MOS57530
1890	41E0 189C	2755		BAL	R14,KHKCOL	DO A DOUBLE OPERATION COLUMN	MOS57540
		2756	*			DISTURB AND COMPLEMENT TEST	MOS57550
1894	41F0 0D36	2757		BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS57560
1898	43C0 176A	2758		B	TEST9A	ELSE BRANCH TO CONTINUE TEST	MOS57570
		2759	*			*****	MOS57580
189C	4860 0C32	2760	KHKCOL	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS57590
18A0	4880 0C3E	2761		LH	R8,HILIM+6		MOS57600
18A4	C460 7FFE	2762		NAI	R6,X'7FFE'		MOS57610

TEST 9 ECC DISTURB TEST

18A8	C480 7FFF	2763	NAI	R8,X'7FFF'	MOS57620	
18AC	2472	2764	LIS	R7,2	MOS57630	
		2765 *			MOS57640	
18AE	083A	2766	KHKCOL1	LDAR R3,R10	GET PROPER BACKGROUND PATTERN	MOS57650
18B0	C36D 0000	2767		TAI R6,0(R13)		MOS57660
18B4	2332	2768		BZS KHKCOL2		MOS57670
18B6	083B	2769		LDAR R3,R11		MOS57680
18B8	4036 8000	2770	KHKCOL2	STH R3,X'8000'(R6)	STORE BACKGROUND PATTERN	MOS57690
18BC	C160 18AE	2771		BXLE R6,KHKCOL1	TO ALL OF MEMORY UNDER TEST	MOS57700
18C0	4860 0C32	2772		LH R6,LOLIM+6		MOS57710
18C4	C460 7FFE	2773		NAI R6,X'7FFE'		MOS57720
		2774 *				MOS57730
18C8	C840 3033	2775	KHKCOL3	LDAR R4,C'03'		MOS57740
18CC	4040 0B56	2776		STH R4,ERRNO	ERRNO = C'03'	MOS57750
18D0	41F0 08C2	2777		BAL LINK,TSTBRKY	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS57760
18D4	083A	2778		LDAR R3,R10	GET ORIGINAL DATA PATTERN (O.D.P.)	MOS57770
18D6	C36D 0000	2779		TAI R6,0(R13)		MOS57780
18DA	2332	2780		BZS KHKCOL4		MOS57790
18DC	083B	2781		LDAI R3,R11		MOS57800
18DE	4846 8000	2782	KHKCOL4	LH R4,X'8000'(R6)	GET DATA FROM LOC	MOS57810
18E2	0543	2783		CLAR R4,R3	DATA EQUAL ?	MOS57820
18E4	4230 19BC	2784		BNE KHKCOL5F	YES, BRANCH	MOS57830
18E8	C730 8001	2785	KHKCOL5	XAI R3,X'8001'	COMPLEMENT DATA PATTERN (C.D.P.)	MOS57840
18EC	4036 8000	2786		STH R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS57850
18F0	6110 0B56	2787		AHM R1,ERRNO	ERRNO = C'04'	MOS57860
18F4	4846 8000	2788		LH R4,X'8000'(R6)	GET DATA FROM LOC	MOS57870
18F8	0543	2789		CLAR R4,R3	DATA EQUAL ?	MOS57880
18FA	4230 19C4	2790		BNE KHKCOL6F	NO, BRANCH	MOS57890
18FE	C730 8001	2791	KHKCOL6	XAI R3,X'8001'	COMPLEMENT C.D.P. (O.D.P.)	MOS57900
1902	4036 8000	2792		STH R3,X'8000'(R6)	STORE O.D.P. AT LOC	MOS57910
1906	C840 3039	2793		LDAI R4,C'09'		MOS57920
190A	4040 0B56	2794		STH R4,ERRNO	ERRNO = C'09'	MOS57930
190E	4846 8000	2795		LH R4,X'8000'(R6)	GET DATA FROM LOC	MOS57940
1912	0543	2796		CLAR R4,R3	DATA EQUAL ?	MOS57950
1914	4230 19CC	2797		BNE KHKCOL7F	NO, BRANCH	MOS57960
1918	C730 8001	2798	KHKCOL7	XAI R3,X'8001'	COMPLEMENT O.D.P.(C.D.P.)	MOS57970
191C	4036 8000	2799		STH R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS57980
1920	C840 3041	2800		LDAI R4,C'0A'		MOS57990
1924	4040 0B56	2801		STH R4,ERRNO	ERRNO = C'0A'	MOS58000
1928	4846 8000	2802		LH R4,X'8000'(R6)	GET DATA FROM LOC	MOS58010
192C	0543	2803		CLAR R4,R3	DATA EQUAL ?	MOS58020
192E	4230 19D4	2804		BNE KHKCOL8F	NO, BRANCH	MOS58030
1932	C160 18C8	2805	KHKCOL8	BXLE R6,KHKCOL3	CONTINUE UNTIL DONE(INCREMENTING	MOS58040
1936	4860 0C3E	2806		LH R6,HILIM+6	INITIALIZE MEMORY LIMITS	MOS58050
193A	C460 7FFE	2807		NAI R6,X'7FFE'	(HILIM MUST BE EVEN)	MOS58060
193E	4880 0C32	2808		LH R8,LOLIM+6		MOS58070
1942	C480 7FFE	2809		NAI R8,X'7FFE'		MOS58080
1946	2572	2810		LCS R7,2		MOS58090
		2811 *				MOS58100
1948	083B	2812	KHKCOL9	LDAR R3,R11	GET COMPLEMENT DATA PATTERN(C.D.P.)	MOS58110
194A	C36D 0000	2813		TAI R6,0(R13)		MOS58120
194E	2332	2814		BZS KHKCOLA		MOS58130
1950	083A	2815		LDAR R3,R10		MOS58140

TEST 9

ECC DISTURB TEST

1952	C840 3035	2816	KHKCOLA	LDAI	R4,C'05'		MOS58150
1956	4040 0R56	2817		STH	R4,ERRNO	ERRNO = C'05'	MOS58160
195A	41F0 08C2	2818		BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS58170
195E	4846 8000	2819		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS58180
1962	0543	2820		CLAR	R4,R3	DATA EQUAL ?	MOS58190
1964	4230 19DC	2821		BNE	KHKCOLBF	NO, BRANCH	MOS58200
1968	C730 8001	2822	KHKCOLB	XAI	R3,X'8001'	COMPLEMENT C.D.P.(O.D.P.)	MOS58210
196C	4036 8000	2823		STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS58220
1970	6110 0B56	2824		AHM	R1,ERRNO	ERRNO = C'06'	MOS58230
1974	4846 8000	2825		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS58240
1978	0543	2826		CLAR	R4,R3	DATA EQUAL ?	MOS58250
197A	4230 19E4	2827		BNE	KHKCOLCF	NO, BRANCH	MOS58260
197E	C730 8001	2828	KHKCOLC	XAI	R3,X'8001'	COMPLEMENT O.D.P. (C.D.P.)	MOS58270
1982	4036 8000	2829		STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS58280
1986	C840 3042	2830		LDAI	R4,C'0B'		MOS58290
198A	4040 0B56	2831		STH	R4,ERRNO	ERRNO = C'0B'	MOS58300
198E	4846 8000	2832		IH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS58310
1992	0543	2833		CLAR	R4,R3	DATA EQUAL ?	MOS58320
1994	213E	2834		BNES	KHKCOLDF	NO, BRANCH	MOS58330
1996	C730 8001	2835	KHKCOLD	XAI	R3,X'8001'	COMPLEMENT C.D.P.(O.D.P.)	MOS58340
199A	4036 8000	2836		STH	R3,X'8000'(R6)	STORE O.D.P. AT LOC	MOS58350
199E	6110 0B56	2837		AHM	R1,ERRNO	ERRNO = C'0C'	MOS58360
19A2	4846 8000	2838		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS58370
19A6	0543	2839		CLAR	R4,R3	DATA EQUAL ?	MOS58380
19A8	2137	2840		BNES	KHKCOLEF	NO, BRANCH	MOS58390
19AA	C060 1948	2841	KHKCCLE	BXH	R6,KHKCOL9	CONTINUE UNTIL DONE(DECREMENTING)	MOS58400
19AE	030E	2842		BR	R14	RETURN	MOS58410
		2843	*				MOS58420
19B0	41F0 1C74	2844	KHKCOLDF	BAL	LINK,ERROR	ERROR ROUTINE	MOS58430
19B4	220F	2845		BS	KHKCOLD	RETURN	MOS58440
		2846	*				MOS58450
19B6	41F0 1C74	2847	KHKCOLEF	BAL	LINK,ERROR	ERROR ROUTINE	MOS58460
19BA	2208	2848		BS	KHKCOLE	RETURN	MOS58470
		2849	*				MOS58480
19BC	41F0 1C74	2850	KHKCOL5F	BAL	LINK,ERROR	ERROR ROUTINE	MOS58490
19C0	4300 18E8	2851		B	KHKCOL5	RETURN	MOS58500
		2852	*				MOS58510
19C4	41F0 1C74	2853	KHKCOL6F	BAL	LINK,ERROR	ERROR ROUTINE	MOS58520
19C8	4300 18FE	2854		B	KHKCOL6	RETURN	MOS58530
		2855	*				MOS58540
19CC	41F0 1C74	2856	KHKCOL7F	BAL	LINK,ERROR	ERROR ROUTINE	MOS58550
19D0	4300 1918	2857		B	KHKCOL7	RETURN	MOS58560
		2858	*				MOS58570
19D4	41F0 1C74	2859	KHKCOL8F	BAL	LINK,ERROR	ERROR ROUTINE	MOS58580
19D8	4300 1932	2860		B	KHKCOL8	RETURN	MOS58590
		2861	*				MOS58600
19DC	41F0 1C74	2862	KHKCOLBF	BAL	LINK,ERROR	ERROR ROUTINE	MOS58610
19E0	4300 1968	2863		B	KHKCOLB	RETURN	MOS58620
		2864	*				MOS58630
19E4	41F0 1C74	2865	KHKCOLCF	BAL	LINK,ERROR	ERROR ROUTINE	MOS58640
19E8	4300 197E	2866		B	KHKCOLC	RETURN	MOS58650
		2867	*				MOS58660
		2868	*	END	TEST 9-2		MOS58670

TEST A PARITY DISTURB TEST

2870 * TEST A-1 MARCHING PATTERN TEST MOS58690
 2871 * MOS58700
 2872 * MOS58710
 2873 * PURPOSE: MOS58720
 2874 * THIS TEST CHECKS THAT THREE DIFFERENT BASE PATTERNS
 2875 * CAN BE WRITTEN, COMPLEMENTED, AND MARCHED THROUGH THE
 2876 * AVAILABLE MEMORY WITHOUT ERROR. MOS58730
 2877 * ASSUMPTIONS: MOS58740
 2878 * MINIMUM 64KB MOS MEMORY MOS58750
 2879 *
 2880 * DESIGN SPECIFICATIONS: MOS58760
 2881 * 1. (IN ASCENDING ORDER) WRITE AND READ THE BASE PATTERN.
 2882 * 2. (IN DESCENDING ORDER) WRITE AND READ THE COMPLEMENT
 2883 * PATTERN. MOS58770
 2884 *
 2885 * OPTIONS: MOS58780
 2886 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS58790
 2887 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS58800
 2888 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS58810
 2889 * SCOPE - ERROR OPTION MODE MOS58820
 2890 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS58830
 2891 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS58840
 2892 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS58850
 2893 * 3 - PRINT ERROR DATA AND HALT MOS58860
 2894 * 4 - IGNORE ERROR MOS58870
 2895 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS58880
 2896 *
 2897 * HOW TO RUN THE TEST:
 2898 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA
 2899 * THE CONSOLE DEVICE.
 2900 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE.

19EC	41E0 0D0E	2902	TESTA	BAL	LINK,LOSET	ESTABLISH LOWEST PHYSICAL SEGMENT	MOS59010
19F0	2411	2903	*				MOS59020
19F2	C840 0A3E	2904	TESTAA	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS59030
19F6	4040 003E	2905		LDAI	R4,MNO		MOS59040
19FA	24A0	2906		STH	R4,X'3E'	SET NEW MM POINTER	MOS59050
19FC	24B1	2907		LIS	R10,0		MOS59060
19FE	24C0	2908		LIS	R11,1		MOS59070
1A00	41E0 1A2E	2909		LIS	R13,0	W/BACKGROUND = 0'S	MOS59080
1A04	24A1	2910		BAL	R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS59090
1A06	24B0	2911	*				MOS59100
1A08	41E0 1A2E	2912		LIS	R10,1		MOS59110
1A0C	24D2	2913		LIS	R11,0	W/BACKGROUND = F'S	MOS59120
1A0E	41E0 1A2E	2914		BAL	R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS59130
1A12	24A0	2915	*				MOS59140
1A14	24B1	2916		LIS	R13,2	W/BACKGROUND = A'S	MOS59150
		2917		BAL	R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS59160
		2918	*				MOS59170
		2919		LIS	R10,0	W/BACKGROUND = 5'S	MOS59180
		2920		LIS	R11,1		MOS59190

TEST A

PARITY DISTURB TEST

1A16	41F0 1A2E	2921	BAL	R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS59200
		2922	*			MOS59210
1A1A	C8D0 0109	2923	LDAI	R13,X'100'	W/BACKGROUND =128-0'S,128-F'S,..	MOS59220
1A1E	41F0 1A2E	2924	BAL	R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS59230
		2925	*			MOS59240
1A22	24A1	2926	LIS	R10,1		MOS59250
1A24	24B0	2927	LIS	R11,0	W/BACKGROUND =128-F'S,128-0'S,..	MOS59260
1A26	41F0 1A2E	2928	BAL	R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS59270
		2929	*			MOS59280
1A2A	4300 1AF4	2930	B	TESTAB	END OF TEST (GOTO TESTAB)	MOS59290
		2931	*			MOS59300
		2932	*	*****		MOS59310
		2933	*			MOS59320
1A2E	4860 0C32	2934	CLKLOC	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS59330
1A32	4880 0C3E	2935		LH R8,HILIM+6		MOS59340
1A36	C4E0 7FFE	2936	NAI	R6,X'7FFE'		MOS59350
1A3A	C480 7FFF	2937	NAI	R8,X'7FFF'		MOS59360
1A3E	2472	2938	LIS	R7,2		MOS59370
		2939	*			MOS59380
1A40	083A	2940	CLKLOC1	LDAR R3,R10	STORE APPROPRIATE BACKGROUND PATTERN	MOS59390
1A42	C36D 0000	2941		TAI R6,0(R13)		MOS59400
1A46	2332	2942	BZS	CLKLOC2		MOS59410
1A48	083B	2943	LDAR	R3,R11		MOS59420
1A4A	4C36 8000	2944	CLKLOC2	STH R3,X'8000'(R6)	IN MEMORY	MOS59430
1A4E	C160 1A40	2945		BXLE R6,CLKLOC1	FROM LCLIM TO HILIM	MOS59440
1A52	4860 0C32	2946	LH	R6,LOLIM+6		MOS59450
1A56	C460 7FFF	2947	NAI	R6,X'7FFE'		MOS59460
		2948	*			MOS59470
1A5A	C840 3033	2949	CLKLOC3	LDAI R4,C'03'		MOS59480
1A5E	4040 0B56	2950		STH R4,ERRNO	ERRNO = C'03'	MOS59490
1A62	41F0 08C2	2951	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS59500
1A66	083A	2952	LDAR	R3,R10	GET APPROPRIATE BACKGROUND PATTERN	MOS59510
1A68	C36D 0000	2953		TAI R6,0(R13)		MOS59520
1A6C	2332	2954	BZS	CLKLOC4		MOS59530
1A6E	083B	2955	LDAR	R3,R11		MOS59540
1A70	4846 8000	2956	CLKLOC4	LH R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS59550
1A74	0543	2957	CLAR	R4,R3	EQUAL ?	MOS59560
1A76	213E	2958	BNES	CLKLOC5F	NO, BRANCH	MOS59570
1A78	C730 0001	2959	CLKLOC5	XAI R3,1	COMPLEMENT DATA PATTERN	MOS59580
1A7C	4036 8000	2960		STH R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS59590
1A80	6110 0B56	2961	AHM	R1,ERRNO	ERRNO = C'04'	MOS59600
1A84	4846 8000	2962	LH	R4,X'8000'(R6)	GET DATA FROM LOC UNDER TEST	MOS59610
1A88	0543	2963	CLAR	R4,R3	DATA = C.D.P. ?	MOS59620
1A8A	2131	2964	BNES	CLKLOC6	NO, BRANCH	MOS59630
1A8C	C160 1A5A	2965	CLKLOC6	BXLE R6,CLKLOC3	CONTINUE UNTIL DONE(INCREMENTING)	MOS59640
1A90	2307	2966	BS	CLKLOC6A	BRANCH	MOS59650
		2967	-----			MOS59660
1A92	41F0 1C74	2968	CLKLOC5F	BAL LINK,ERROR	ERROR ROUTINE	MOS59670
1A96	220F	2969		BS CLKLOC5	RETURN	MOS59680
		2970	*			MOS59690
1A98	41F0 1C74	2971	CLKLOC6F	BAL LINK,ERROR	ERROR ROUTINE	MOS59700
1A9C	2208	2972		BS CLKLOC6	RETURN	MOS59710
		2973	-----			MOS59720

TEST A

PARITY DISTURB TEST

1A9E	4860 0C3E	2974	CLKLOC6A	LH	R6,HILIM+6	MOS59730
1AA2	C460 7FFE	2975		NAI	R6,X'7FFE'	MOS59740
1AA6	4880 0C32	2976		LH	R8,LCLIM+6	MOS59750
1AAA	C480 7FFE	2977		NAI	R8,X'7FFE'	MOS59760
1AAE	2572	2978		ICS	R7,2	MOS59770
		2979	*			MOS59780
1AB0	083B	2980	CLKLOC7	LDAR	R3,R11	MOS59790
1AB2	C36D 0000	2981		TAI	R6,0(R13)	MOS59800
1AB6	2332	2982		BZS	CLKLOC8	MOS59810
1AB8	083A	2983		LDAR	R3,R10	MOS59820
1ABA	C840 3035	2984	CLKLOC8	LDAI	R4,C'05'	MOS59830
1ABE	4040 0856	2985		STH	R4,ERRNO	MOS59840
1AC2	41E0 08C2	2986		BAL	LINK,TSTBRKX	MOS59850
1AC6	4846 8000	2987		LH	R4,X'8000'(R6)	MOS59860
1ACA	0543	2988		CLAR	R4,R3	MOS59870
1ACC	213E	2989		BNES	CLKLOC9F	MOS59880
1ACE	C730 0001	2990	CLKLOC9	XAI	R3,1	MOS59890
1AD2	4036 8000	2991		STH	R3,X'8000'(R6)	MOS59900
1AD6	6110 0856	2992		AHM	R1,ERRNO	MOS59910
1ADA	4846 8000	2993		LH	R4,X'8000'(R6)	MOS59920
1ADE	0543	2994		CLAR	R4,R3	MOS59930
1AE0	2137	2995		BNES	CLKLOC1F	MOS59940
1AE2	C060 1AB0	2996	CLKLOC10	BXH	R6,CLKLOC7	MOS59950
		2997	*			MOS59960
1AE6	03CE	2998		BR	R14	MOS59970
		2999	*			MOS59980
1AE8	41F0 1C74	3000	CLKLOC9F	BAL	LINK,ERROR	MOS59990
1AEC	22CF	3001		BS	CLKLOC9	MOS60000
		3002	*			MOS60010
1AEE	41F0 1C74	3003	CLKLOC1F	BAL	LINK,ERROR	MOS60020
1AF2	2208	3004		BS	CLKLOC10	MOS60030
		3005	*			MOS60040
		3006	*			MOS60050
		3007	*	END	TEST A-1	MOS60060

TEST A

PARITY DISTURB TEST

3009 * TEST A-2 DOUBLE OPERATION COLUMN DISTURB TEST MOS60080
 3010 * MOS60090
 3011 * MOS60100
 3012 * PURPOSE: MOS60110
 3013 * THIS TEST CHECKS THAT A DOUBLE OPERATION ON AN ADJACENT
 3014 * COLUMN DOES NOT DISTURB THE TEST COLUMN. MOS60120
 3015 * ASSUMPTIONS: MOS60130
 3016 * MINIMUM 64KB MOS MEMORY MOS60140
 3017 * MOS60150
 3018 * DESIGN SPECIFICATIONS: MOS60160
 3019 * 1. WITH 6 DIFFERENT BACKGROUND PATTERNS, A W-R-WC-
 3020 * RC-W-R-WC-RC SERIES IS EXECUTED AT EACH LOCATION. MOS60170
 3021 * 2. A COMPARE IS DONE UPON EACH READ OPERATION.
 3022 * 3. A TEST (COMPARISON) OF THE REST OF MEMORY IS DONE
 3023 * AFTER EACH SERIES OF OPERATIONS. MOS60180
 3024 * MOS60190
 3025 * OPTIONS: MOS60200
 3026 * LOPHYS - LOW PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS60210
 3027 * HIPHYS - HIGH PHYSICAL SEGMENT NO. OF MEMORY UNDER TEST MOS60220
 3028 * (FAILING PHYSICAL SEGMENT = MSB OF TASK PSW) MOS60230
 3029 * SCOPE - ERROR OPTION MODE MOS60240
 3030 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS60250
 3031 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS60260
 3032 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS60270
 3033 * 3 - PRINT ERROR DATA AND HALT MOS60280
 3034 * 4 - IGNORE ERROR MOS60290
 3035 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS60300
 3036 * MOS60310
 3037 * MOS60320
 3038 * HOW TO RUN THE TEST MOS60330
 3039 * 1. ENTER THE "SCOPE", "LOPHYS", & "HIPHYS" OPTIONS VIA
 3040 * THE CONSOLE DEVICE. MOS60340
 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS60350
 MOS60360
 MOS60370
 MOS60380
 MOS60390

1AF4	2411	3042	TESTAB	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS60410
1AF6	24A0	3043		LIS	R10,0		MOS60420
1AF8	24B1	3044		LIS	R11,1		MOS60430
1AFA	24D0	3045		LIS	R13,0		MOS60440
1AFC	41E0 1B16	3046		BAL	R14,CLKCOL	W/BACKGROUND = 0'S DO A DOUBLE OPERATION COLUMN DISTURB AND COMPLEMENT TEST	MOS60450
1B00	24D2	3047	*				MOS60460
1B02	41E0 1B16	3048		LIS	R13,2	W/BACKGROUND = 5'S DO A DOUBLE OPERATION COLUMN DISTURB AND COMPLEMENT TEST	MOS60470
1B04	41E0 1B16	3049		BAL	R14,CLKCOL		MOS60480
1B06	C8E0 0100	3050	*				MOS60490
1B0A	41E0 1B16	3051		LDAI	R13,X'100'	W/BACKGROUND = 128-0'S,128-F'S,..	MOS60500
1B0E	41F0 0D36	3052		BAL	R14,CLKCOL	DO A DOUBLE OPERATION COLUMN DISTURB AND COMPLEMENT TEST	MOS60510
1B12	43C0 19F0	3053	*				MOS60520
1B16	4860 0C32	3054		BAL	LINK,ENDCHK	IF END OF TEST, RETURN TO EXEC	MOS60530
1B1A	4880 0C3E	3055		B	TESTAA	ELSE BRANCH TO CONTINUE TEST	MOS60540
1B1E	C460 7FFE	3056	*			*****	MOS60550
		3057	CLKCOL	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS60560
		3058		LH	R8,HILIM+6		MOS60570
		3059		NAI	R6,X'7FFE'		MOS60580

TEST A

PARITY DISTURB TEST

1B22	C480	7FFF	3060	NAI	R8,X'7FFF'	MOS60590	
1B26	2472		3061	LIS	R7,2	MOS60600	
			3062	*		MOS60610	
1B28	083A		3063	CLKCOL1	LDAR R3,R10	GET PROPER BACKGROUND PATTERN	MOS60620
1B2A	C36D	0000	3064	TAI	R6,0(R13)		MOS60630
1B2E	2332		3065	BZS	CLKCOL2		MOS60640
1B30	083B		3066	LDAR	R3,R11		MOS60650
1B32	4036	8000	3067	CLKCOL2	STH R3,X'8000'(R6)	STORE BACKGROUND PATTERN	MOS60660
1B36	C160	1B28	3068	BXLE	R6,CLKCOL1	TO ALL OF MEMORY UNDER TEST	MOS60670
1B3A	4860	0C32	3069	LH	R6,LCLIM+6		MOS60680
1B3E	C460	7FFE	3070	NAI	R6,X'7FFE'		MOS60690
			3071	*			MOS60700
1B42	C840	3033	3072	CLKCOL3	LDAI R4,C'03'		MOS60710
1B46	4040	0856	3073	STH	R4,ERRNO	ERRNO = C'03'	MOS60720
1B4A	41F0	08C2	3074	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS60730
1B4E	083A		3075	LDAR	R3,R10	GET ORIGINAL DATA PATTERN (O.D.P.)	MOS60740
1B50	C36D	0000	3076	TAI	R6,0(R13)		MOS60750
1B54	2332		3077	BZS	CLKCOL4		MOS60760
1B56	083B		3078	LDAR	R3,R11		MOS60770
1B58	4846	8000	3079	CLKCOL4	LH R4,X'8000'(R6)	GET DATA FROM LOC	MOS60780
1B5C	0543		3080	CLAR	R4,R3	DATA EQUAL ?	MOS60790
1B5E	4230	1C36	3081	BNE	CLKCOL5F	YES, BRANCH	MOS60800
1B62	C730	0001	3082	CLKCOL5	XAI R3,1	COMPLEMENT DATA PATTERN (C.D.P.)	MOS60810
1B66	4036	8000	3083	STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS60820
1B6A	6110	0B56	3084	AHM	R1,ERRNO	ERRNO = C'04'	MOS60830
1B6E	4846	8000	3085	LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS60840
1B72	0543		3086	CLAR	R4,R3	DATA EQUAL ?	MOS60850
1B74	4230	1C3E	3087	BNE	CLKCOL6F	NO, BRANCH	MOS60860
1B78	C730	0001	3088	CLKCOL6	XAI R3,1	COMPLEMENT C.D.P. (O.D.P.)	MOS60870
1B7C	4036	8000	3089	STH	R3,X'8000'(R6)	STORE O.D.P. AT LOC	MOS60880
1B80	C840	3039	3090	LDAI	R4,C'09'		MOS60890
1B84	4040	0856	3091	STH	R4,ERRNO	ERRNO = C'09'	MOS60900
1B88	4846	8000	3092	LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS60910
1B8C	0543		3093	CLAR	R4,R3	DATA EQUAL ?	MOS60920
1B8E	4230	1C46	3094	BNE	CLKCOL7F	NO, BRANCH	MOS60930
1B92	C730	0001	3095	CLKCOL7	XAI R3,1	COMPLEMENT O.D.P.(C.D.P.)	MOS60940
1B96	4036	8000	3096	STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MCS60950
1B9A	C840	3041	3097	LDAI	R4,C'0A'		MOS60960
1B9E	4040	0856	3098	STH	R4,ERRNO	ERRNO = C'0A'	MOS60970
1BA2	4846	8000	3099	LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS60980
1BA6	0543		3100	CLAR	R4,R3	DATA EQUAL ?	MOS60990
1BA8	4230	1C4E	3101	BNE	CLKCOL8F	NO, BRANCH	MOS61000
1BAC	C160	1B42	3102	CLKCOL8	BXLE R6,CLKCOL3	CONTINUE UNTIL DONE(INCREMENTING	MOS61010
1BB0	4860	0C3E	3103	LH	R6,HILLIM+6	INITIALIZE MEMORY LIMITS	MOS61020
1BB4	C460	7FFE	3104	NAI	R6,X'7FFE'	(HILLIM MUST BE EVEN)	MOS61030
1BB8	4880	0C32	3105	LH	R8,LOLIM+6		MOS61040
1BBC	C480	7FFE	3106	NAI	R8,X'7FFE'		MOS61050
1BC0	2572		3107	LCS	R7,2		MOS61060
			3108	*			MOS61070
1BC2	083B		3109	CLKCOL9	LDAR R3,R11	GET COMPLEMENT DATA PATTERN(C.D.P.)	MOS61080
1BC4	C36D	0000	3110	TAI	R6,0(R13)		MCS61090
1BC8	2332		3111	BZS	CLKCOLA		MOS61100
1BCA	083A		3112	LDAR	R3,R10		MOS61110

TEST A

PARITY DISTURB TEST

1BCC	C840	3035	3113	CLKCOLA	LDAI	R4,C'05'		MOS61120
1BD0	4040	0B56	3114		STH	R4,ERRNO	ERRNO = C'05'	MOS61130
1BD4	41F0	08C2	3115		BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS61140
1BD8	4846	8000	3115		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS61150
1BDC	0543		3117		CLAR	R4,R3	DATA EQUAL ?	MOS61160
1BDE	4230	1C56	3118		BNE	CLKCOLBF	NO, BRANCH	MOS61170
1BE2	C730	0001	3119	CLKCOLB	XAI	R3,1	COMPLEMENT C.D.P.(O.D.P.)	MOS61180
1BE6	4036	8000	3120		STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS61190
1BEA	6110	0B56	3121		AHM	R1,ERRNO	ERRNO = C'06'	MOS61200
1BEE	4846	8000	3122		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS61210
1BF2	0543		3123		CLAR	R4,R3	DATA EQUAL ?	MOS61220
1BF4	4230	1C5E	3124		BNE	CLKCOLCF	NO, BRANCH	MOS61230
1BF8	C730	0001	3125	CLKCOLC	XAI	R3,1	COMPLEMENT O.D.P. (C.D.P.)	MOS61240
1BFC	4036	8000	3126		STH	R3,X'8000'(R6)	STORE C.D.P. AT LOC	MOS61250
1C00	C840	3042	3127		LDAI	R4,C'0B'		MOS61260
1C04	4040	0B56	3128		STH	R4,ERRNO	ERRNO = C'03'	MOS61270
1C08	4846	8000	3129		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS61280
1C0C	0543		3130		CLAR	R4,R3	DATA EQUAL ?	MOS61290
1C0E	213E		3131		BNES	CLKCOLDF	NO, BRANCH	MOS61300
1C10	C730	0001	3132	CLKCOLD	XAI	R3,1	COMPLEMENT C.D.P.(O.D.P.)	MOS61310
1C14	4036	8000	3133		STH	R3,X'8000'(R6)	STORE O.D.P. AT LOC	MOS61320
1C18	6110	0B56	3134		AHM	R1,ERRNO	ERRNO = C'0C'	MOS61330
1C1C	4846	8000	3135		LH	R4,X'8000'(R6)	GET DATA FROM LOC	MOS61340
1C20	0543		3136		CLAR	R4,R3	DATA EQUAL ?	MOS61350
1C22	2137		3137		BNES	CLKCOLEF	NO, BRANCH	MOS61360
1C24	C060	1BC2	3138	CLKCOLE	BXH	R6,CLKCOL9	CONTINUE UNTIL DONE(DECREMENTING)	MOS61370
1C28	03CE		3139		BR	R14	RETURN	MOS61380
			3140	*				MOS61390
1C2A	41F0	1C74	3141	CLKCOLDF	BAL	LINK,ERROR	ERROR ROUTINE	MOS61400
1C2E	220F		3142		BS	CLKCOLD	RETURN	MOS61410
			3143	*				MOS61420
1C30	41F0	1C74	3144	CLKCCOLEF	BAL	LINK,ERROR	ERROR ROUTINE	MOS61430
1C34	2208		3145		BS	CLKCOLE	RETURN	MOS61440
			3146	*				MOS61450
1C36	41F0	1C74	3147	CLKCOL5F	BAL	LINK,ERROR	ERROR ROUTINE	MOS61460
1C3A	4300	1B62	3148		B	CLKCOL5	RETURN	MOS61470
			3149	*				MOS61480
1C3E	41F0	1C74	3150	CLKCOL6F	BAL	LINK,ERROR	ERROR ROUTINE	MOS61490
1C42	4300	1B78	3151		B	CLKCOL6	RETURN	MOS61500
			3152	*				MOS61510
1C46	41F0	1C74	3153	CLKCOL7F	BAL	LINK,ERROR	ERROR ROUTINE	MOS61520
1C4A	4300	1B92	3154		B	CLKCOL7	RETURN	MOS61530
			3155	*				MOS61540
1C4E	41F0	1C74	3156	CLKCOL8F	BAL	LINK,ERROR	ERROR ROUTINE	MOS61550
1C52	4300	1BAC	3157		B	CLKCOL8	RETURN	MOS61560
			3158	*				MOS61570
1C56	41F0	1C74	3159	CLKCOLBF	BAL	LINK,ERROR	ERROR ROUTINE	MOS61580
1C5A	4300	1BE2	3160		B	CLKCOLB	RETURN	MOS61590
			3161	*				MOS61600
1C5E	41F0	1C74	3162	CLKCOLCF	BAL	LINK,ERROR	ERROR ROUTINE	MOS61610
1C62	4300	1BF8	3163		B	CLKCOLC	RETURN	MOS61620
			3164	* *****				MOS61630
			3165	*	END	TEST A-2		MOS61640

COMMON ERROR ROUTINE

1C56	D000 1EC0	3167	PARERR	STM	R0,MOSSAVE	SET UP TO PRINT PARITY ERROR	MOS61660
1C6A	C8F0 3132	3168	LDAI	R15,C'12'			MOS61670
1C6E	40F0 0B56	3169	STH	R15,ERRNO	SET ERRNO = C'12'		MOS61680
1C72	2308	3170	BS	ERROR1	BRANCH		MOS61690
		3171	*				MOS61700
		3172	*	COMMON ERROR ROUTINE		CALL: BAL LINK,ERRCR	MOS61710
		3173	*				MOS61720
		3174	*	R6= LOCATION OF ERROR	R3= DATA EXPECTED R4= DATA READ		MOS61730
		3175	*				MOS61740
1C74	D000 1EC0	3176	ERROR	STM	R0,MCOSSAVE	SAVE CALLING REGISTERS	MOS61750
1C78	95EE	3177	EPSR	R14,R14	GET THE CURRENT PSW		MOS61760
1C7A	C4E0 FFF0	3178	NAI	R14,X'FFF0'	MASK OFF ALL BUT CC		MOS61770
1C7E	C6E0 0004	3179	CAI	R14,4	ADD MEMORY FAULT CC		MOS61780
1C82	24F1	3180	*				MOS61790
1C84	DEF0 010E	3181	ERROR1	LIS	LINK,1	LOAD DISPLAY PANEL ADDRESS	MOS61800
1C88	C6E0 8000	3182	OC	LINK,NORM	PUT PANEL IN NORMAL MODE		MOS61810
1C8C	9406	3183	OAI	R6,X'8000'	FORCE HIGH 32 KB RANGE		MOS61820
1C8E	98F0	3184	EXBR	R0,R6	READY DISPLAY OUTPUT		MOS61830
		3185	WHR	LINK,R0	DISPLAY ERROR ADDRESS		MOS61840
		3186	*				MOS61850
1C90	41F0 0602	3187	BAL	LINK,ERR	PRINT THE ERROR NUMBER		MOS61860
1C94	25F1	3188	LCS	LINK,1			MOS61870
1C96	40F0 0B0E	3189	STH	LINK,NOERR	SET ERROR FLAG FOR EXEC.		MOS61880
1C9A	48F0 0BEA	3190	LH	LINK,SCOPE+6			MOS61890
1C9E	27F1	3191	SIS	LINK,1	IS SCOPE = 1 ?		MOS61900
1CA0	4330 1D2E	3192	BZ	PARTNO	YES, PRINT PART NUMBER.		MOS61910
1CA4	27F3	3193	SIS	LINK,3	IS SCOPE = 4 ?		MOS61920
1CA6	4330 1D1A	3194	BZ	ERORIN2	YES, RETURN		MOS61930
1CAA	27F1	3195	SIS	LINK,1	IS SCOPE = 5 ?		MOS61940
1CAC	4330 1D2E	3196	BZ	PARTNO	YES, PRINT PART NO. & CONTINUE		MOS61950
1CB0	24C4	3197	ERROR2	LIS	R0,4		MOS61960
1CB2	0816	3198	LDAR	R1,R6			MOS61970
1CB4	C820 1E11	3199	LDAI	R2,ADRMSG+1			MOS61980
1CB8	41F0 06F6	3200	BAL	LINK,HEXASC	STORE LOCATION UNDER TEST		MOS61990
1CBC	0813	3201	LDAR	R1,R3			MOS62000
1CBE	C820 1E20	3202	LDAI	R2,DTAEXP			MOS62010
1CC2	41F0 06F6	3203	BAL	LINK,HEXASC	STORE DATA EXPECTED		MOS62020
1CC6	0814	3204	LDAR	R1,R4			MOS62030
1CC8	C820 1E30	3205	LDAI	R2,DTARED			MOS62040
1CCC	41F0 06F6	3206	BAL	LINK,HEXASC	STORE DATA READ		MOS62050
1CD0	081E	3207	LDAR	R1,R14			MOS62060
1CD2	C820 1E3C	3208	LDAI	R2,DTAPSW			MOS62070
1CD6	41F0 06F6	3209	BAL	LINK,HEXASC	STORE CONCURRENT PSW		MOS62080
1CDA	9014	3210	SRHLS	R1,4			MOS62090
1CDC	C410 0007	3211	NAI	R1,7			MOS62100
1CE0	C820 1E10	3212	LDAI	R2,ADRMSG			MOS62110
1CE4	24C1	3213	LIS	R0,1			MOS62120
1CE6	41F0 06F6	3214	BAL	LINK,HEXASC			MOS62130
1CEA	9456	3215	EXBR	R5,R6			MOS62140
1CEC	98C5	3216	WHR	R0,R5	WRITE TO DISPLAY THE ERROR LOC		MOS62150
1CEE	C850 1EOC	3217	ERROR3	LDAI	R5,ERRORMSG		MOS62160
1CF2	4050 0B0C	3218	STH	R5,ISITERR	SET ISITERR		MOS62170
1CF6	41F0 0756	3219	BAL	LINK,PRINT	PRINT THE ERROR DATA		MOS62180

COMMON ERROR ROUTINE

1CFA	2450	3220	LIS	R5,0	MOS62190
1CFC	4050 0B0C	3221	STH	R5,ISITERR	MOS62200
		3222 *			MOS62210
1D00	48F0 0BEA	3223 ERORTN	LH	LINK,SCOPE+6	MOS62220
1D04	4330 04A8	3224	BZ	TSTEVD	MOS62230
1D08	27F1	3225	SIS	LINK,1	MOS62240
1D0A	4330 04A8	3226	BZ	TSTEND	MOS62250
1D0E	27F2	3227	SIS	LINK,2	MOS62260
1D10	4330 052A	3228	BZ	ABORT1	MOS62270
1D14	D100 1EC0	3229 ERORTN1	LM	RO,MOSSAVE	MOS62280
1D18	03CE	3230	BR	LINK	MOS62290
		3231 *			MOS62300
1D1A	48F0 0B18	3232 ERORTN2	LH	LINK,TOTERR	MOS62310
1D1E	26F1	3233	AIS	LINK,1	MOS62320
1D20	40F0 0B18	3234	STH	LINK,TOTERR	MOS62330
1D24	C5F0 7FFF	3235	CLAI	LINK,X'7FFF'	MOS62340
1D28	203A	3236	BNES	ERORTN1	MOS62350
1D2A	4300 0594	3237	B	HALT9	MOS62360
		3239 *-----			MOS62380
1D2E	C850 2041	3241 PARTNO	LDAI	R5,C' A'	MOS62400
1D32	081E	3242	LDAR	R1,R14	MOS62410
1D34	9014	3243	SRHLS	R1,4	MOS62420
1D36	C410 0007	3244	NAI	R1,7	MOS62430
1D3A	C510 0003	3245	CLAI	R1,3	MOS62440
1D3E	2183	3246	BLS	C01	MOS62450
1D40	C850 2042	3247	LDAI	R5,C' B'	MOS62460
1D44	D250 1E06	3248 CO1	STB	R5,CHIPNO	MOS62470
1D48	C850 2030	3249	LDAI	R5,C' 0'	MOS62480
1D4C	2611	3250	AIS	R1,1	MOS62490
1D4E	0AE1	3251	AAR	R5,R1	MOS62500
1D50	C510 0004	3252	CLAI	R1,4	MOS62510
1D54	2182	3253	BLS	C02	MOS62520
1D56	2754	3254	SIS	R5,4	MOS62530
1D58	D250 1E07	3255 CO2	STB	R5,CHIPNO+1	MOS62540
1D5C	0734	3256	XAR	R3,R4	MOS62550
1D5E	2410	3257	LIS	R1,0	MOS62560
1D60	C530 FFFF	3258	CLAI	R3,-1	MOS62570
1D64	2137	3259	BNES	C03	MOS62580
1D66	C840 4646	3260	LDAI	R4,C'FF'	MOS62590
1D6A	4040 1E08	3261	STH	R4,CHIPNO+2	MOS62600
1D6E	2430	3262	LIS	R3,0	MOS62610
1D70	230C	3263	BS	C05	MOS62620
1D72	0A11	3264 CO3	AAR	R1,R1	MOS62630
		3265 *			MOS62640
1D74	2185	3266	BCS	C04	MOS62650
1D76	2611	3267	AIS	R1,1	MOS62660
1D78	C510 0010	3268	CLAI	R1,16	MOS62670
1D7C	2085	3269	BLS	C03	MOS62680
1D7E	2402	3270 CO4	LIS	R0,2	MOS62690

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COMMON ERROR ROUTINE

1D80 C820 1E08	3271	LDAI R2,CHIPNO+2	CONVERT TO DECIMAL AND	MOS62700
1D84 41F0 071E	3272	BAL LINK,DECASC	STORE IN ERROR MESSAGE	MOS62710
1D88 C850 1DEC	3273 C05	LDAI R5,CHIPMSG		MOS62720
1D8C 4050 0B0C	3274	STH R5,ISITERR	SET ISITERR	MOS62730
1D90 41F0 0756	3275	BAL LINK,PRINT	PRINT SUSPECTED CHIP NUMBER	MOS62740
1D94 2450	3276	LIS R5,0		MOS62750
1D96 4050 0B0C	3277	STH R5,ISITERR	RESET ISITERR	MOS62760
1D9A 0833	3278	LDAR R3,R3	HAVE ALL SUSPECT CHIPS BEEN PRINTED?	MOS62770
1D9C 4230 1D72	3279	BNZ C03	NO, BRANCH	MOS62780
1DAO D100 1EC0	3280	LM R0,MOSSAVE	YES, RESTORE REGISTERS AND	MOS62790
1DA4 4300 1CB0	3281	B ERROR2	GO PRINT ERROR DATA	MOS62800
	3282 *			MOS62810
	3283 * *****			MOS62820
	3284 * END COMMON ERROR ROUTINE			MOS62830

CHKSUM FILE

		3286 *		MOS62850
		3287 *	TEST MESSAGES	MOS62860
		3288 *		MOS62870
1DA8	4153 5349 474E 4544	3289 ASMEMMSG DC	C'ASSIGNED MEMORY ',X'ODOA'	MOS62880
1DB0	204D 454D 4F52 5920			
1DB8	0DCA			
1DBA	4C4F 4C49 4D20 3E20	3290 HILOMSG DC	C'LJLIM > HILIM IS ILLEGAL',X'ODOA'	MOS62890
1DC2	4849 4C49 4D20 4953			
1DCA	2049 4C4C 4547 414C			
1DD2	0DCA			
1DD4	494C 4C45 4741 4C20	3291 TSTREJ DC	C'ILLEGAL TEST SEQUENCE ',X'ODOA'	MOS62900
1DDC	5445 5354 2053 4551			
1DE4	5545 4E43 4520			
1DEA	0DCA			
1DEC	5355 5350 4543 5445	3292 CHIPMSG DC	C'SUSPECTED BAD CHIP NUMBER '	MOS62910
1DF4	4420 4241 4420 4348			
1DFC	4950 204E 554D 4245			
1E04	5220			
1E06	2A2A 2A2A	3293 CHIPNO DC	C'*****,X'ODOA'	MOS62920
1E0A	0DCA			
1E0C	4C4F 4320	3294 ERRORMSG DC	C'LOC '	MOS62930
		3295 *		MOS62940
1E10	2A2A 2A2A 2A20 2044	3296 ADRMSG DC	C'***** DATA EXP '	MOS62950
1E18	4154 4120 4558 5020			
1E20	2A2A 2A2A 2020 4441	3297 DTAEXP DC	C'***** DATA READ '	MOS62960
1E28	5441 2052 4541 4420			
1E30	2A2A 2A2A 2020 5053	3298 DTARED DC	C'***** PSW = '	MOS62970
1E38	5720 3D20			
1E3C	2A2A 2A2A	3299 DTAPSW DC	C'*****,X'ODOA'	MOS62980
1E40	0DOA			
1E42	4D45 4D4F 5259 2055	3300 T6MSG DC	C'MEMORY UNDER GALPAT TEST',X'ODOA'	MOS62990
1E4A	4E44 4552 2047 414C			
1E52	5041 5420 5445 5354			
1E5A	0DCA			
1E5C	3038 3030 302D 3646	3301 LOMSG DC	C'08000-6FFF ',X'ODOA'	MOS63000
1E64	4646 4620			
1E68	0DOA			
	0000 1E62	3302 HIMSG EQU	LOMSG+6	MOS63010
		3303 *		MOS63020
1E6A	504F 5745 5220 444F	3304 T7MSG DC	C'POWER DOWN PROCESSOR FOR 30 SECONDS ',X'ODOA'	MOS63030
1E72	574E 2050 524F 4345			
1E7A	5353 4F52 2046 4F52			
1E82	2033 3020 5345 434F			
1E8A	4E44 5320			
1E8E	0DOA			
1E90	4849 4C49 4D20 2D20	3305 T8LOMSG DC	C'HILIM - LOLIM IS < REQUIRED ',X'ODOA'	MOS63040
1E98	4C4F 4C49 4D20 4953			
1EA0	203C 2052 4551 5549			
1EA8	5245 4420			
1EAC	0DCA			
		3306 * *****		MOS63050
		3307 * END TEST MESSAGE FILE		MOS63060
	0000 1EAD	3308 LNZB EQU	*-1	MOS63070

MOS63090
MOS63100
MOS63110
MOS63120
MOS63130
MOS63140
MOS63150
MOS63160
MOS63170
MOS63180
MOS63190
MOS63200
MOS63210
MOS63220
MOS63230
MOS63240
MOS63250
MOS63260
MOS63270
MOS63280
MOS63290

NES

CHKSUM FILE

	3286 *		MOS62850
	3287 *	TEST MESSAGES	MOS62860
	3288 *		MOS62870
1DA8	4153 5349 474E 4544	3289 ASMEMMSG DC C'ASSIGNED MEMORY ',X'0DOA'	MOS62880
1DB0	204D 454D 4F52 5920		
1DB8	0DCA		
1DBA	4C4F 4C49 4D20 3E20	3290 HILOMSG DC C'LOLIM > HILIM IS ILLEGAL',X'0DOA'	MOS62890
1DC2	4849 4C49 4D20 4953		
1DCA	2049 4C4C 4547 414C		
1DD2	0DCA		
1DD4	494C 4C45 4741 4C20	3291 TSTREJ DC C'ILLEGAL TEST SEQUENCE ',X'0DOA'	MOS62900
1DDC	5445 5354 2053 4551		
1DE4	5545 4E43 4520		
1DEA	0DCA		
1DEC	5355 5350 4543 5445	3292 CHIPMSG DC C'SUSPECTED BAD CHIP NUMBER '	MOS62910
1DF4	4420 4241 4420 4348		
1DFC	4950 204E 554D 4245		
1EO4	5220		
1EO6	2A2A 2A2A	3293 CHIPNO DC C'*****,X'0DOA'	MOS62920
1EOA	0DCA		
1EOC	4C4F 4320	3294 ERRORMSG DC C'LOC '	MOS62930
		3295 *	MOS62940
1E10	2A2A 2A2A 2A20 2044	3296 ADRMSG DC C'***** DATA EXP '	MOS62950
1E18	4154 4120 4558 5020		
1E20	2A2A 2A2A 2020 4441	3297 DTAEXP DC C'***** DATA READ '	MOS62960
1E28	5441 2052 4541 4420		
1E30	2A2A 2A2A 2020 5053	3298 DTARED DC C'***** PSW = '	MOS62970
1E38	5720 3D20		
1E3C	2A2A 2A2A	3299 DTAPSW DC C'*****,X'0DOA'	MOS62980
1E40	0DCA		
1E42	4D45 4D4F 5259 2055	3300 T6MSG DC C'MEMORY UNDER GALPAT TEST',X'0DOA'	MOS62990
1E44	4E44 4552 2047 414C		
1E52	5041 5420 5445 5354		
1E5A	0DCA		
1E5C	3038 3030 302D 3646	3301 LOMSG DC C'08000-6FFFF ',X'0DOA'	MOS63000
1E64	4646 4620		
1E68	0DCA		
	0000 1E62	3302 HIMSG EQU LOMSG+6	MOS63010
		3303 *	MOS63020
1E6A	504F 5745 5220 444F	3304 T7MSG DC C'POWER DOWN PROCESSOR FOR 30 SECONDS ',X'0DOA'	MOS63030
1E72	574E 2050 524F 4345		
1E7A	5353 4F52 2046 4F52		
1E82	2033 3020 5345 434F		
1E8A	4E44 5320		
1E8E	0DCA		
1E90	4849 4C49 4D20 2D20	3305 T8LOMSG DC C'HILIM - LOLIM IS < REQUIRED ',X'0DOA'	MOS63040
1E98	4C4F 4C49 4D20 4953		
1EA0	203C 2052 4551 5549		
1EA8	5245 4420		
1EAC	0DCA		
		3306 * *****	MOS63050
		3307 * END TEST MESSAGE FILE	MOS63060
	0000 1EAD	3308 LN2B EQU *-1	MOS63070

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CHKSUM FILE

	3310 *		MOS63090
	3311 *	TEST PROGRAM STORAGE AREA	MOS63100
	3312 *		MOS63110
	3313 *	*****	MOS63120
	3314 *		MOS63130
1EAE	3315 OPTBUF DS 6	OPTION INPUT BUFFER	MOS63140
1EB4	3316 VLOLIM DS 2	VIRTUAL LOW LIMIT	MOS63150
1EB6	3317 VHILIM DS 2	VIRTUAL HIGH LIMIT	MOS63160
	3318 *		MOS63170
	3319 *	*****	MOS63180
	3320 *		MOS63190
1EB8	3321 ALIGN 8		MOS63200
	3322 *		MOS63210
1EB8	3323 PSWSAVE DS 8	PPF PSW SAVE AREA	MOS63220
1EC0	3324 MOSSAVE DS 64	S16MMT REGISTER SAVE AREA	MOS63230
1F00	3325 ERRSAVE DS 32	REG STORAGE FOR ERROR ROUTINES	MOS63240
1F20	3326 MMSAVE DS 32	T7 MM REGISTER SAVE AREA	MOS63250
1F40	3327 RSAVE DS 160	REGISTER SAVE AREA	MOS63260
1FE0	3328 DB *		MOS63270
	3329 *	*****	MOS63280
	3330 * END TEST PROGRAM 06-214F01R00 PART 2 SECTION 1 ***		MOS63290

		3383	*	SCHKSUM/M17 PUNCHER (CONTINUED)		
		3384	*			MOS63820
		3385	*			MOS63830
205A	C800 0100	3386	STAPL	LDAI R0,256	TO PUNCH BLANK LEADER	MOS63840
205E	23C3	3387		BS STAPLP		MOS63850
		3388	*			MOS63860
2060	C800 0080	3389	STAPL1	LDAI R0,128	TO PUNCH 1-FOLD GAP	MOS63870
		3390	*			MOS63880
2064	27C1	3391	STAPLP	SIS R0,1		MOS63890
2066	032F	3392		BNPR R15	RETURN	MOS63900
2068	2430	3393		LIS R3,0		MOS63910
206A	9A63	3394		WDR R6,R3	PUNCH BLANK FRAME	MOS63920
206C	9D68	3395		SSR R6,R8		MOS63930
206E	2081	3396		BTBS 8,1		MOS63940
2070	2206	3397		BS STAPLP	CONTINUE	MOS63950
		3398	*			MOS63960
		3399	*	*****		MOS63970
2072		3400		END		MOS63980
						MOS63990

CHKSUM/M17 PUNCHER

1FE0 2400	3332	SCHKSUM	LIS R0,0	PUNCH M17 TAPE WITH CHECKSUM	MOS63310
1FE2 9510	3333		EPSR R1,R0	SELECT REG. SET 0 & CLEAR PSW	MOS63320
	3334	*			MOS63330
1FE4 C810 0100	3335		LDAI R1,ORIGIN1	LOAD START ADDRESS	MOS63340
1FE8 2421	3336		LIS R2,1	LOAD INCREMENT VALUE	MOS63350
1FEA C830 1EAD	3337		LDAI R3,LNZB	LOAD FINAL ADDRESS	MOS63360
1FEE 2440	3338		LIS R4,0	INITIALIZE CHKSUM BYTE	MOS63370
	3339	*			MOS63380
1FF0 D3E1 0000	3340	SGEN	LB R5,0(R1)		MOS63390
1FF4 0745	3341		XAR R4,R5	CALCULATE CHKSUM BYTE	MOS63400
1FF6 C110 1FF0	3342		BXLE R1,SGEN		MOS63410
1FFA D240 0099	3343		STB R4,MN+3	CHECKSUM BYTE TO BOOT LOADER	MOS63420
	3344	*			MOS63430
1FFE C810 0080	3345	STAPE	LDAI R1,X'0080'		MOS63440
2002 9E21	3346		OCR R2,R1	DISPLAY IN NORMAL MODE	MOS63450
2004 9444	3347		EXBR R4,R4		MOS63460
2006 9824	3348		WHR R2,R4	DISPLAY CHKSUM BYTE (TO D1)	MOS63470
2008 9411	3349		EXBR R1,R1		MOS63480
200A 95C1	3350		EPSR R0,R1	HALT PROCESSOR	MOS63490
	3351	*			MOS63500
	3352	*	*****		MOS63510
	3353	*			MOS63520
200C D360 007A	3354	SPUNCH	LB R6,X'7A'	GET BOUTDV (PUNCH) ADDRESS	MOS63530
2010 DE60 007B	3355		OC R6,X'7B'	START TAPE PUNCH	MOS63540
2014 9D60	3356		SSR R6,R0		MOS63550
2016 2081	3357		BTBS 8,1		MOS63560
2018 41F0 205A	3358		BAL R15,STAPL	PUNCH LEADER (256 CHARACTERS)	MOS63570
201C 9411	3359		EXBR R1,R1	(R1) = X'0080'	MOS63580
201E C830 00CF	3360		LDAI R3,X'CF'		MOS63590
	3361	*			MOS63600
2022 DA61 0000	3362	SPNCH1	WD R6,0(R1)	PUNCH BOOT LOADER	MOS63610
2026 9D60	3363		SSR R6,R0		MOS63620
2028 2081	3364		BTBS 8,1		MOS63630
202A C110 2022	3365		BXLE R1,SPNCH1		MOS63640
202E 41F0 2060	3366		BAL R15,STAPL1	PUNCH ONE-FOLD GAP	MOS63650
	3367	*			MOS63660
2032 D340 0099	3368		LB R4,MN+3	GET CHECKSUM BYTE	MOS63670
2036 C810 0100	3369		LDAI R1,ORIGIN1	(NORMALLY X'A00')	MOS63680
203A C830 1EAD	3370		LDAI R3,LNZB		MOS63690
	3371	*			MOS63700
203E D3E1 0000	3372	SPNCH2	LB R5,0(R1)	PUNCH PROGRAM	MOS63710
2042 0745	3373		XAR R4,R5	(ORIGIN1 TO LNZB)	MOS63720
2044 9A65	3374		WDR R6,R5		MOS63730
2046 9401	3375		EXBR R0,R1		MOS63740
2048 9820	3376		WHR R2,R0	DISPLAY ADDRESS PUNCHED	MOS63750
204A 9D60	3377		SSR R6,R0		MOS63760
204C 2081	3378		BTBS 8,1		MOS63770
204E C110 203E	3379		BXLE R1,SPNCH2		MOS63780
2052 41F0 205A	3380		BAL R15,STAPL	PUNCH TRAILER	MOS63790
2056 43C0 1FFE	3381		B STAPE	DISPLAY CHKSUM & HALT PROCESSOR	MOS63800

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ASSEMBLED BY CAL 03-066R05-01 (32-BIT)

START OPTIONS: T=16,CROSS,ERLST,

NO CAL ERRORS
NO CAL WARNINGS
2 PASSES

SCHKSUM	0000 1FE0	3332*				
SDEC1	0000 0728	727*	741			
SDEC2	0000 072E	729*	734	736		
SDEC3	0000 0740	730	737*			
SGEN	0000 1FF0	3340*	3342			
SPNCH1	0000 2022	3362*	3365			
SPNCH2	0000 203E	3372*	3379			
SPUNCH	0000 200C	3354*				
STAPE	0000 1FFE	3345*	3381			
STAPL	0000 205A	3358	3380	3386*		
STAPL1	0000 2060	3366	3389*			
STAPLP	0000 2064	3387	3391*	3397		
STSTDUO	0000 0964	936	938*			
STSTDU1	0000 0982	948*				
STSTDU2	0000 0984	945	947	949*		
ABORT	0000 04E8	503*				
ABORT1	0000 052A	522*	3228			
ABORT2	0000 0568	545*				
ABORT3	0000 0532	515	525*			
ABSTOP	0000 2072					
ADC	0000 0002	726	740	884	891	928
ADRMMSG	0000 1E10	3199	3212	3296*		
AMSG	0000 0B98	217	1161*			
ASCIILCC	0000 0B82	645	1158*			
ASCIPSW	0000 0B78	642	1156*			
ASMEMMSG	0000 1DA8	1387	3289*			
BGTST	0000 1250	1966*				
BGTST1	0000 126C	1976*	1979			
BGTST2	0000 1274	1979*	1983			
BGTST2.5	0000 127A	1978	1982*			
BGTST3	0000 1280	1975	1980	1985*		
BGTST4	0000 128A	1990*	1993			
BGTST5	0000 1292	1993*	1997			
BGTST5.5	0000 1298	1992	1996*			
BGTST6	0000 129E	1989	1994	1999*		
BGTST7	0000 12A2	2000*	2027			
BOOT	0000 0088	91	94*			
BRK.SAV	0000 0B26	885	892	925	929	1138*
BRKMSG	0000 0B9A	1162*	1265			
BRKVECT	0000 0B0A	887	923	927	1123*	2302
BTESTNO	0000 0B1A	444	457	474	497	553
C300ADR	0000 0118	141*				
CAR2ND	0000 0B00	1112*				
CARRD	0000 0AF4	1103*				
CARRQ2S	0000 0B08	1119*				
CHIPMSG	0000 1DEC	3273	3292*			
CHIPNC	0000 1E06	3248	3255	3261	3271	3293*

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CHKCOL	0000 1082	1756	1759	1762	1767*			
CHKCOL1	0000 1094	1772*	1777					
CHKCOL2	0000 109E	1774	1776*					
CHKCOL3	0000 10AE	1781*	1811					
CHKCOL4	0000 10C4	1786	1788*					
CHKCOL5	0000 10CE	1791*	1857					
CHKCOL5F	0000 11A2	1790	1856*					
CHKCOL6	0000 10E4	1797*	1860					
CHKCOL6F	0000 11AA	1796	1859*					
CHKCOL7	0000 10FE	1804*	1863					
CHKCOL7F	0000 11B2	1803	1862*					
CHKCOL8	0000 1118	1811*	1866					
CHKCOL8F	0000 11BA	1810	1865*					
CHKCOL9	0000 112E	1818*	1847					
CHKCOLA	0000 1138	1820	1822*					
CHKCOLB	0000 114E	1828*	1869					
CHKCOLBF	0000 11C2	1827	1868*					
CHKCOLC	0000 1164	1834*	1872					
CHKCOLCF	0000 11CA	1833	1871*					
CHKCOLD	0000 117C	1841*	1851					
CHKCOLDF	0000 1196	1840	1850*					
CHKCOLE	0000 1190	1847*	1854					
CHKCOLEF	0000 119C	1846	1853*					
CHKLOC	0000 0EE4	1518	1522	1525	1529	1532	1536	1543*
CHKLOC1	0000 0EF6	1549*	1554					
CHKLOC10	0000 0F98	1605*	1612					
CHKLOC1F	0000 0FA4	1604	1611*					
CHKLOC2	0000 0F00	1551	1553*					
CHKLOC3	0000 0F10	1558*	1574					
CHKLOC4	0000 0F26	1563	1565*					
CHKLOC5	0000 0F2E	1568*	1578					
CHKLOC5F	0000 0F48	1567	1577*					
CHKLOC6	0000 0F42	1573	1574*	1581				
CHKLOC6A	0000 0F54	1575	1583*					
CHKLOC6F	0000 0F4E	1580*						
CHKLOC7	0000 0F66	1589*	1605					
CHKLOC8	0000 0F70	1591	1593*					
CHKLOC9	0000 0F84	1599*	1609					
CHKLOC9F	0000 0F9E	1598	1608*					
CKBG60	0000 1424	2193*						
CKBG61	0000 1438	2200*	2207					
CKBG62	0000 1442	2202	2204*					
CKBG63	0000 144A	2207*	2213					
CKBG64	0000 1450	2206	2210*					
CKBG65	0000 145E	2208	2215*					
CKBG66	0000 142E	2196*						
CLIF2ND	0000 0AFC	1110*						
CLIFADR	0000 0114	139*						
CLIFRD	0000 0AF0	1101*						
CLKCOL	0000 1B16	3046	3049	3052	3057*			
CLKCOL1	0000 1B28	3063*	3068					
CLKCOL2	0000 1B32	3065	3067*					
CLKCOL3	0000 1B42	3072*	3102					
CLKCOL4	0000 1B58	3077	3079*					
CLKCOL5	0000 1B62	3082*	3148					

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KHKCOL5	0000	18E8	2785*	2851
KHKCOL5F	0000	19BC	2784	2850*
KHKCOL6	0000	18FE	2791*	2854
KHKCOL6F	0000	19C4	2790	2853*
KHKCOL7	0000	1918	2798*	2857
KHKCOL7F	0000	19CC	2797	2856*
KHKCOL8	0000	1932	2805*	2860
KHKCOL8F	0000	19D4	2804	2859*
KHKCOL9	0000	1948	2812*	2841
KHKCOLA	0000	1952	2814	2816*
KHKCOLB	0000	1968	2822*	2863
KHKCOLBF	0000	19DC	2821	2862*
KHKCOLC	0000	197E	2828*	2866
KHKCOLCF	0000	19E4	2827	2865*
KHKCOLD	0000	1996	2835*	2845
KHKCOLDF	0000	19B0	2834	2844*
KHKCOLE	0000	19AA	2841*	2848
KHKCOLEF	0000	19B6	2840	2847*
KHKLOC	0000	17B0	2612	2616 2619 2623 2626 2630 2636*
KHKLOC1	0000	17C2	2642*	2647
KHKLOC10	0000	1866	2699*	2707
KHKLOC1F	0000	1872	2698	2706*
KHKLOC2	0000	17CC	2644	2646*
KHKLOC3	0000	17DC	2651*	2667
KHKLOC4	0000	17F2	2656	2658*
KHKLOC5	0000	17FA	2661*	2671
KHKLOC5F	0000	1814	2660	2670*
KHKLOC6	0000	180E	2666	2667* 2674
KHKLOC6A	0000	1820	2668	2676*
KHKLOC6F	0000	181A	2673*	
KHKLOC7	0000	1834	2683*	2699
KHKLOC8	0000	183E	2685	2687*
KHKLOC9	0000	1852	2693*	2704
KHKLOC9F	0000	186C	2692	2703*
LADC	0000	0001	475	725
LCORE	0000	09D0	201	439 984* 2393
LDWT	0000	00C8	117*	120
LEADER	0000	00A2	101*	105
LEVELIN	0000	03AE	383*	1171 1172 1173 1174 1177 1178
LINK	0000	000F	73*	180 201 205 211 212 213 216 218 220 282 289 292
			297	309 310 314 317 331 336 341 344 352 357 358 410
			427	428 439 463 466 468 482 483 489 496 503 504 507
			509	513 522 523 527 530 534 536 537 548 563 567 570
			573	576 581 587 591 596 608 615 634 643 646 648 701
			718	743 748 767 777 786 790 791 793 801 810 825 829
			839	848 849 869 873 874 876 885 886 887 892 921 929
			930	951 959 1001 1009 1010 1033 1251 1257 1283 1305 1362 1363
			1369	1375 1380 1385 1389 1391 1428 1445 1455 1464 1469 1472 1510
			1538	1560 1577 1580 1595 1608 1611 1651 1670 1687 1697 1709 1712
			1751	1764 1783 1824 1850 1853 1856 1859 1862 1865 1868 1871 1917
			1944	1950 1982 1996 2026 2070 2077 2079 2107 2168 2173 2191 2211
			2261	2280 2293 2301 2302 2303 2348 2366 2372 2378 2384 2386 2387
			2388	2391 2393 2405 2411 2449 2484 2509 2525 2542 2555 2567 2604
			2653	2670 2673 2689 2703 2706 2757 2777 2818 2844 2847 2850 2853
			2856	2859 2862 2865 2902 2951 2968 2971 2986 3000 3003 3054 3074

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		2992	3042	3084	3121	3134	3198	3201	3204	3207	3210	3211	3242	3243	
		3244	3245	3250	3251	3252	3257	3264	3264	3267	3268	3333	3335	3340	
		3342	3345	3346	3349	3349	3350	3359	3359	3362	3365	3369	3372	3375	
		3379													
	R10	0000 000A	66*	1029	1030	1031	1036	1036	1037	1043	1515	1520	1527	1534	1549
			1561	1592	1753	1772	1784	1821	1927	2005	2006	2018	2084	2089	2096
			2103	2116	2122	2139	2150	2179	2200	2270	2275	2362	2455	2533	2609
			2614	2621	2628	2642	2654	2686	2746	2766	2778	2815	2907	2912	2919
	R11	0000 000B	67*	1516	1521	1528	1535	1552	1564	1589	1754	1775	1787	1818	1928
			2003	2009	2021	2085	2090	2097	2104	2119	2125	2136	2153	2182	2203
			2271	2276	2367	2456	2506	2545	2610	2615	2622	2629	2645	2657	2683
			2747	2769	2781	2812	2908	2913	2920	2927	2943	2955	2980	3044	3066
	R12	0000 000C	68*	221	239	248	259	370	373	384	401	420	660	1671	1673
			1678	1949	1970	1985	2011	2083	2164	2188	2272	2277	2373	2529	2539
			2545	2558											
	R13	0000 000D	69*	1517	1524	1531	1550	1562	1590	1669	1679	1695	1705	1755	1758
			1761	1773	1785	1819	1962	2013	2086	2093	2100	2117	2123	2137	2151
			2180	2201	2273	2278	2379	2611	2618	2625	2643	2655	2684	2748	2751
			2754	2767	2779	2813	2909	2916	2923	2941	2953	2981	3045	3048	3051
	R14	0000 000E	70*	278	288	324	371	374	376	399	402	671	674	680	1005
			1020	1026	1026	1029	1040	1042	1043	1044	1200	1201	1202	1204	1205
			1206	1207	1208	1210	1211	1212	1214	1215	1218	1222	1222	1223	1224
			1225	1227	1228	1231	1233	1235	1237	1241	1242	1243	1244	1246	1249
			1250	1363	1518	1522	1525	1529	1532	1536	1606	1756	1759	1762	1848
			1934	1942	2002	2087	2091	2094	2098	2101	2105	2224	2296	2304	2310
			2311	2312	2312	2313	2314	2315	2320	2321	2323	2325	2326	2326	2327
			2328	2332	2333	2335	2337	2339	2341	2341	2342	2343	2344	2346	2347
			2353	2389	2487	2560	2612	2616	2619	2623	2626	2630	2701	2749	2752
			2755	2842	2910	2914	2917	2921	2924	2928	2998	3046	3049	3052	3139
	R15	0000 000F	72*	199	207	228	376	385	411	412	413	531	532	654	655
			656	658	662	663	697	805	923	925	1006	1021	1041	1045	1955
	R2	0000 0002	58*	90	110	116	155	157	162	167	169	171	172	176	176
			177	178	185	186	187	188	196	196	197	214	215	284	285
			290	291	293	294	300	303	303	325	333	335	337	342	359
			360	449	452	455	457	458	459	460	462	464	465	474	475
			476	559	601	605	606	612	617	618	619	620	642	645	689
			690	692	694	698	713	714	738	739	753	900	901	903	908
			912	915	915	985	1008	1016	1017	1018	1019	1027	1028	1038	1039
			1050	1054	1055	1057	1061	1062	1063	1064	1072	1073	1076	1077	1078
			1279	1279	1280	1281	1282	1285	1287	1291	1368	1374	1379	1384	1929
			1931	1937	1939	1953	1954	1969	2000	2081	2163	2187	2297	2299	2399
			2400	2404	2472	2473	2474	2475	2476	2477	2491	2492	2493	2494	2495
	R3	0000 0003	59*	95	96	97	163	164	167	183	184	193	197	198	
			199	256	260	264	266	287	300	325	334	338	403	574	577
			678	681	681	706	707	708	710	715	724	725	726	728	740
			766	768	986	992	993	1274	1275	1282	1288	1289	1290	1291	1293
			1296	1301	1303	1436	1438	1447	1452	1458	1549	1552	1553	1561	1564
			1566	1568	1569	1572	1589	1592	1597	1599	1600	1603	1661	1663	1672
			1673	1674	1676	1684	1690	1698	1700	1702	1704	1772	1775	1776	1784

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		1787	1789	1791	1792	1795	1797	1798	1802	1804	1805	1809	1818	1821
		1826	1828	1829	1832	1834	1835	1839	1841	1842	1845	1969	1977	1991
		2018	2021	2116	2119	2120	2122	2125	2126	2136	2139	2140	2144	2146
		2150	2153	2155	2157	2179	2182	2183	2200	2203	2205	2362	2364	2367
		2370	2373	2376	2379	2382	2401	2402	2403	2404	2406	2407	2409	2514
		2517	2519	2521	2531	2537	2550	2642	2645	2646	2654	2657	2659	2661
		2662	2665	2683	2686	2691	2693	2694	2697	2766	2769	2770	2778	2781
		2783	2785	2786	2789	2791	2792	2796	2798	2799	2803	2812	2815	2820
		2822	2823	2826	2828	2829	2833	2835	2836	2839	2940	2943	2944	2952
		2955	2957	2959	2960	2963	2980	2983	2988	2990	2991	2994	3063	3066
		3067	3075	3078	3080	3082	3083	3086	3088	3089	3093	3095	3096	3100
		3109	3112	3117	3119	3120	3123	3125	3126	3130	3132	3133	3136	3201
		3256	3258	3262	3278	3278	3337	3360	3370	3393	3394			
R4	0000 0004	60*	99	100	101	103	111	113	190	191	192	194	194	217
		219	229	231	232	234	236	243	245	249	276	281	291	296
		301	302	305	308	313	315	316	316	318	319	320	321	335
		340	353	355	369	372	390	404	575	656	664	666	670	672
		693	694	695	696	696	709	710	711	712	712	713	727	732
		733	735	737	737	738	762	763	764	765	776	778	782	787
		789	800	838	853	855	857	867	868	970	988	991	994	995
		996	1000	1271	1272	1275	1276	1277	1294	1295	1298	1299	1300	1304
		1440	1441	1446	1447	1465	1513	1514	1558	1559	1565	1566	1571	1572
		1593	1594	1596	1597	1602	1603	1659	1660	1666	1667	1675	1676	1701
		1702	1781	1782	1788	1789	1794	1795	1799	1800	1801	1802	1806	1807
		1808	1809	1822	1823	1825	1826	1831	1832	1836	1837	1838	1839	1844
		1845	1957	1960	1967	1968	1976	1977	1990	1991	2023	2024	2025	2141
		2142	2143	2144	2154	2155	2197	2198	2204	2205	2327	2328	2329	2330
		2338	2339	2342	2343	2344	2349	2350	2351	2352	2354	2355	2363	2364
		2369	2370	2375	2376	2381	2382	2410	2478	2479	2481	2482	2485	2486
		2497	2498	2501	2502	2515	2518	2519	2536	2537	2549	2550	2607	2608
		2651	2652	2658	2659	2664	2665	2687	2688	2690	2691	2696	2697	2775
		2776	2782	2783	2788	2789	2793	2794	2795	2796	2800	2801	2802	2803
		2816	2817	2819	2820	2825	2826	2826	2830	2831	2832	2833	2838	2839
		2906	2949	2950	2956	2957	2962	2963	2984	2985	2987	2988	2993	2994
		3072	3073	3079	3080	3085	3086	3090	3091	3092	3093	3097	3098	3099
		3100	3113	3114	3116	3117	3122	3123	3127	3128	3129	3130	3135	3136
		3204	3256	3260	3261	3338	3341	3343	3347	3347	3348	3368	3373	
R5	0000 0005	61*	101	103	104	104	106	107	108	111	113	119	206	258
		260	298	299	311	311	323	323	326	342	396	400	467	495
		528	529	568	569	572	580	633	647	693	728	729	731	776
		780	875	1254	1256	1260	1265	1273	1276	1296	1299	1387	1390	1923
		1933	1936	1941	1973	2076	2078	2127	2134	2147	2177	2194	2282	2283
		2284	2285	2286	2286	2287	2288	2291	2292	2294	2295	2462	2465	2505
		2531	2565	2566	3215	3216	3217	3218	3220	3221	3241	3247	3248	3249
		3251	3254	3255	3273	3274	3276	3277	3340	3341	3372	3373	3374	
R5H EX	0000 06CC	344	573	581	688*									
R5X	0000 06DA	693*	699											
R5XA	0000 06E8	697*												
R5XB	0000 06F0	691	700*											
R6	0000 0006	62*	98	108	115	172	173	174	174	257	258	265	279	283
		332	348	349	351	378	383	400	653	661	662	668	679	682
		1297	1298	1364	1365	1367	1430	1432	1438	1439	1442	1443	1446	1449
		1450	1451	1458	1459	1461	1462	1465	1467	1543	1545	1550	1553	1554
		1555	1556	1562	1565	1569	1571	1574	1583	1584	1590	1596	1600	1602
		1605	1654	1656	1663	1664	1665	1674	1675	1681	1682	1683	1690	1691

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START2	0000 011E	123	154*								
STLOOP	0000 12AC	1953	1954	1955	1956	1962	1972	2000	2005*	2012	
STORE10	0000 0E6E	1453	1458*	1459							
STORE11	0000 0E34	1438*	1439								
STORE30	0000 1018	1685	1690*	1691							
STORE31	0000 0FCC	1663*	1664								
T3S1	0000 0FE0	1669*	1681								
T3S2	0000 0FEC	1672*	1680								
T3S3	0000 0FFC	1678*	1688								
T3S3F	0000 1012	1677	1687*								
T3S4	0000 102C	1696*	1707								
T3S5	0000 1038	1700*	1705								
T3S6	0000 1044	1704*	1713								
T3S6F	0000 1056	1703	1712*								
T5S1	0000 11F8	1931*	1932								
T5S2	0000 120A	1939*	1940								
T6ER10	0000 13E0	2145	2167*								
T6ER11	0000 13F0	2156	2172*								
T6MSG	0000 1E42	2076	3300*								
T6S1	0000 1356	2116*	2121								
T6S10	0000 13CA	2157*	2175								
T6S2	0000 1360	2118	2120*								
T6S2.5	0000 1372	2124	2126*								
T6S3	0000 137A	2129*									
T6S4	0000 137C	2130*	2222								
T6S5	0000 137E	2131*	2189								
T6S6	0000 1380	2132*	2165								
T6S7	0000 1394	2138	2140*								
T6S8	0000 13AA	2146*	2170								
T6S9	0000 13C0	2152	2154*								
T6SX	0000 12F2	2075*									
T7END	0000 15F6	2301	2386	2393*							
T7MM1	0000 1506	2282	2310*	2316							
T7MM2	0000 151C	2310	2320*								
T7MM2A	0000 152A	2322	2325*								
T7MM3	0000 1540	2324	2332*								
T7MM3A	0000 154E	2334	2337*								
T7MM4	0000 1572	2349*	2392								
T7MMCOM	0000 1568	2336	2340	2346*							
T7MSG	0000 1E6A	2291	3304*								
T7OUTMSG	0000 14D6	2291*	2306								
T7S1	0000 14A0	2275*	2279								
T7S2	0000 14EA	2297*	2305								
T7S3	0000 14EE	2299*	2300								
T7S4	0000 158E	2358*	2390								
T7S5	0000 159A	2362*	2385								
T7S6	0000 15A8	2365	2367*								
T7S7	0000 15B8	2371	2373*								
T7S6	0000 15C8	2377	2379*								
T7S9	0000 15D8	2383	2385*								
T8LOMSG	0000 1E90	2565	3305*								
T8LOPRT	0000 1756	2460	2565*								
T8SW	0000 1650	2465*	2466								
T8SX	0000 1692	2484*	2508								
TEMP	0000 010C	132*	302	305	315	318	320				

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PROG= MOSQ22 ASSEMBLED BY CAL 03-066R05-01 (32-BIT)

1	CROSS	MOS40010	
2	TARGT 16	MOS40020	
3	WIDTH 120	MOS40030	
4	MOSQ22 PROG S16 19-221 MCS MEMORY TEST PART 2 06-214F02M96R00A13	MOS40040	
5	SQCHK	MOS40050	
6	* *****	MOS40060	
7	SERIES-16 19-221 MCS MEMORY TEST PART 2 - SECTION 2 (F02)	MOS40070	
8	COPYRIGHT PERKIN-ELMER CORP.	MOS40080	
9	OCTOBER, 1978	MOS40090	
10	THIS PROGRAM TESTS THE LOWER 32KB OF A 64KB OR LARGER MOS	MOS40100	
11	MEMORY IN AN INTERDATA SERIES 16 EXTENDED MEMORY PROCESSOR	MOS40110	
12	WITH AN OPTIONAL BATTERY BACK-UP POWER SUPPLY.	MOS40120	
13	*	MOS40130	
14	TEST 0	MEMORY SEARCH TEST	MOS40140
15	*		MOS40150
16	TEST 1	BIT SET-RESET TEST	MOS40160
17	*		MOS40170
18	TEST 2	MARCHING PATTERN TEST	MOS40180
19	*		MOS40190
20	TEST 3	0 AND 1 WALK TEST	MOS40200
21	*		MOS40210
22	TEST 4	DOUBLE OPERATION COLUMN DISTURB TEST	MOS40220
23	*		MOS40230
24	TEST 5 (OPTIONAL)	SHORT COUNT RELOCATABLE	MOS40240
25	*	HAMMER DISTURB TEST	MOS40250
26	*		MOS40260
27	TEST 6 (OPTIONAL)	DIAGONAL GALPAT TEST	MOS40270
28	*		MOS40280
29	TEST 7 (OPTIONAL)	MEMORY HOLD TEST	MOS40290
30	*	(REQUIRES MANUAL INTERVENTION & BATTERY BACK-UP POWER SUPPLY)	MOS40300
31	*		MOS40310
32	TEST 8 (OPTIONAL)	LONG COUNT RELOCATABLE	MOS40320
33	*	HAMMER DISTURB TEST	MOS40330
34	*		MOS40340
35	TEST 9 (OPTIONAL)	ECC DISTURB TEST (IN 2 PARTS)	MOS40350
36	*		MOS40360
37	TEST A (OPTIONAL)	PARITY DISTURB TEST (IN 2 PARTS)	MOS40370
38	*		MOS40380
39	*	THE DEFAULT TESTS ARE 0, 1, 2, 3, 4, 5, & 6.	MOS40390
40	*		MOS40400
41	*	TEST 0 IS EXECUTED WHENEVER "RUN" IS ENTERED.	MOS40410
42	*	TEST 0 FORCES "LOIM" AND "HILIM" TO THE BOUNDRIES PRINTED	MOS40420
43	*	ON THE LIST DEVICE.	MOS40430
44	*		MOS40440
45	*	TEST 7 REQUIRES MANUAL INTERVENTION AND CANNOT BE LOOPED ON	MOS40450
46	*	WHILE THE PROCESSOR IS UNATTENDED.	MOS40460
47	*		MOS40470
48	*	TEST 8 IS AN OPTIONAL, LONG TERM (I.E.,OVERNIGHT) TEST.	MOS40480
49	*		MOS40490
50	*	TEST 9 IS AN OPTIONAL TEST TO BE USED WITH ECC TURNED ON.	MOS40500
51	*		MOS40510
52	*	TEST A IS AN OPTIONAL TEST TO BE USED W/PARITY MEMORIES ONLY.	MOS40520
53	*	*****	MOS40530

0000 0000	56	R0	EQU	0	MOS40560
0000 0001	57	R1	EQU	1	MOS40570
0000 0002	58	R2	EQU	2	MOS40580
0000 0003	59	R3	EQU	3	MOS40590
0000 0004	60	R4	EQU	4	MOS40600
0000 0005	61	R5	EQU	5	MOS40610
0000 0006	62	R6	EQU	6	MOS40520
0000 0007	63	R7	EQU	7	MOS40630
0000 0008	64	R8	EQU	8	MOS40640
0000 0009	65	R9	EQU	9	MOS40650
0000 000A	66	R10	EQU	10	MOS40660
0000 000B	67	R11	EQU	11	MOS40670
0000 000C	68	R12	EQU	12	MOS40680
0000 000D	69	R13	EQU	13	MOS40690
0000 000E	70	R14	EQU	14	MOS40700
0000 000F	71	RET	EQU	14	MOS40710
0000 000F	72	R15	EQU	15	MOS40720
0000 000F	73	LINK	EQU	15	MOS40730

LISTING NOTES:

- | | | |
|------|---|----------|
| 75 * | 1) TRIPLE ASTERISKS IN COLUMNS 69-71 INDICATE A
DELETION OR MINOR MODIFICATION TO THE EXECUTIVES. | MOS40750 |
| 76 * | 2) QUAD ASTERISKS IN COLUMNS 68-71 INDICATE MAJOR
CHANGES TO THE EXEC WHICH MUST BE NOTED. THESE
CHANGES MAY YIELD INCOMPATIBILITIES BETWEEN THIS
(MODIFIED) AND OTHER (UNMODIFIED) EXTENDED TEST
PROGRAM EXECUTIVES. | MOS40760 |
| 77 * | | MOS40770 |
| 78 * | | MOS40780 |
| 79 * | | MOS40790 |
| 80 * | | MOS40800 |
| 81 * | | MOS40810 |
| 82 * | | MOS40820 |
| 83 * | | MOS40830 |
| 84 * | | MOS40840 |

BOOTSTRAP LOADER

	86 *			MOS40860
	87 * BOOTLOADER WITH CHKSUM			MOS40870
	88 *			MOS40880
0000R	89 ORG X'80'			MOS40890
0080 2421	90 LIS R2,1			MOS40900
0082 2303	91 BS BOOT			MOS40910
0084 9DC8	92 DC Z(PWSAVE)	CURRENT PSW SAVE POINTER(32-BIT M/C)		MOS40920
0086 9E50	93 DC Z(RSAVE)	REGISTER SAVE POINTER(32-BIT M/C)		MOS40930
0088 C810 8000	94 BOOT LHI R1,ORIGIN1	R1 = ADR(FIRST BYTE OF TEST PROG)		MOS40940
008C C820 9DBC	95 LHI R3,LNZB+1	R3 = ADR(LAST NON-ZERO BYTE)		MOS40950
0090 4020 003E	96 STH R3,X'3E'	REGISTER SAVE POINTER(16-BIT M/C)		MOS40960
0094 2731	97 SIS R3,1			MOS40970
0096 C860 0000	98 MN LHI R6,0	R6 = CHKSUM BYTE = X'MN'		MOS40980
009A D340 0078	99 LB R4,X'78'	INPUT DEV ADR		MOS40990
009E DE40 0079	100 OC R4,X'79'			MOS41000
00A2 9D45	101 LEADER SSR R4,R5			MOS41010
00A4 2091	102 BTBS 9,1	DU,BSY		MOS41020
00A6 9B45	103 BDR R4,R5			MOS41030
00A8 0855	104 LDAR R5,R5			MOS41040
00AA 2234	105 EZS LEADER	IGNORE LEADER		MOS41050
00AC D251 0000	106 LOAD STB R5,0(R1)	STORE 1ST NON-ZERO & SUBSEQUENT BYTE		MOS41060
00B0 D351 0000	107 LB R5,0(R1)	RELOAD DATA BYTE TO		MOS41070
00B4 0765	108 XAR R6,R5	GENERATE CHKSUM		MOS41080
00B6 9481	109 EXBR R8,B1			MOS41090
00B8 9828	110 WHR R2,R8	DISPLAY MEMORY ADDRESS		MOS41100
00BA 9D45	111 SSR R4,R5			MOS41110
00BC 2091	112 BTBS 9,1	DU,BSY		MOS41120
00BE 9B45	113 BDR R4,R5			MOS41130
00C0 C110 00AC	114 BXLE R1,LOAD	LOAD TILL LAST BYTE		MOS41140
00C4 9486	115 EXBR R8,R6			MOS41150
00C6 9828	116 WHR R2,R8	FINAL CHKSUM		MOS41160
00C8 2478	117 LDWT LIS R7,8			MOS41170
00CA 917C	118 SLLS R7,12	R7 = X'8000'		MOS41180
00CC 9557	119 EPSR R5,R7	HALT PROCESSOR.		MOS41190
00CE 22C3	120 BS LDWT			MOS41200

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EXEC - ETPE R03-05 (16 BIT/STRIPPED & MODIFIED)

0000	4300	801E	122	ORG	X'8000'	*	MOS41220	
8000			123	ORIGIN1	B	START2	START HERE FOR 16-BIT PROCESSOR	MOS41230
			124	*				MOS41240
			125	*				MOS41250
8004	0000		126	FIRST	DCX	0	*	MOS41260
8006	3000		127	PSW	DC	X'3000'	PSW USED IN TEST (BASIC)	MOS41270
8008	3000		128	PSW2	DC	X'3000'	PSW USED IN EXEC	MOS41280
800A	0000		129	IOSAVE	DCX	0		MOS41290
800C	0000		130	TEMP	DCX	0		MOS41300
800E	80		131	NORM	DB	X'80'	DISPLAY NORMAL MODE COMMAND	MOS41310
800F	40		132	INCR	DB	Y'40'	DISPLAY INCREMENTAL MODE COMMAND	MOS41320
			133	*				MOS41330
			134	*			*	MOS41340
			135	*	TEST CONSTANTS		*	MOS41350
			136	*				MOS41360
8010	05C5		137	IO	DC	X'0505'	I/O DEVICE(S) IDENTIFIER	MOS41370
8012	1011		138	PASLADR	DC	X'1011'	PASLA/PALM READ/WRITE ADDRESSES	MOS41380
8014	0202		139	CLIFADR	DC	X'0202'	CURRENT LOOP INTERFACE R/W ADDRESSES	MOS41390
8015	62E2		140	LPADR	DC	X'6262'	LINE PRINTER ADDRESS	MOS41400
8018	1011		141	C300ADR	DC	X'1011'	CAROUSEL 300/PASLA ADDRESSES	MOS41410
801A	COCO		142	MICROBUS	DC	X'COCO'	MICROBUS ADDRESS	MOS41420
801C	0000		143		DCX	0	PROVISION FOR SPECIAL DEVICE	MOS41430
			144	*				MOS41440
			145	*	IO = 0101 FOR CRT ON PASLA			MOS41450
			146	*	0202 FOR TELETYPE, CAROUSEL 15/30			MOS41460
			147	*	XX03 FOR LINE PRINTER			MOS41470
			148	*	0404 FOR CAROUSEL 300			MOS41480
			149	*	0505 FOR MICROBUS			MOS41490
			150	*				MOS41500
			151	*			*	MOS41510
			152	*				MOS41520
801E	4810	8008	153	START2	LH	R1,PSW2	*	***
8022	C820	8032	154	ST	LDAI	R2,START	*	***
8026	4010	0034	155		STH	R1,X'34'		MOS41530
802A	4020	0036	156		STH	R2,X'36'	II INT NEW PSW LOC	MOS41540
802E	0000		157		DCX	0	TAKE AN ILLEGAL INSTRUCTION INT	MOS41550
8030	2200		158		BS	*	HALT IF II INTERRUPT NOT TAKEN	MOS41560
			159	*				MOS41570
8032	D310	8010	160	START	LB	R1,IO	GET I/O IDENTIFIERS	MOS41580
8036	D320	8011	161		LB	R2,IO+1		MOS41590
803A	2436		162		LIS	R3,6	IDENTIFIER CAN BE 1,2,3,4,5	MOS41600
803C	0513		163		CLAR	R1,R3		MOS41610
803E	2182		164		BLS	IO.OK1	BRANCH IF KB IDENTIFIER OK	MOS41620
8040	2412		165		LIS	R1,2	OTHERWISE FORCE IT TO BE TTY	MOS41630
8042	0523		166	IO.OK1	CLAR	R2,R3		MOS41640
8044	2182		167		BLS	IO.OK2	SAME TEST FOR LIST DEVICE	MOS41650
8046	2422		168		LIS	R2,2		MOS41660
8048	D210	8010	169	IO.OK2	STB	R1,IO		MOS41670
804C	D220	8011	170		STB	R2,IO+1	REESTABLISH VALUES	MOS41680
8050	D362	8A04	171		LB	R6,CONRQ2S(R2)		MOS41690
8054	4060	89E8	172		STH	R6,PASFLG2	SET PASLA FLAG (LIST DEVICE)	MOS41700
8058	0866		173		LDAR	R6,R6		MOS41710
805A	2336		174		BZS	IO.OK3	SKIP IF NOT PASLA	MOS41720

EXEC - ETPE R03-05 (16 BIT/STRIPPED & MODIFIED)

805C	0A22	175	AAR	R2,R2	(SLHLS R2,1)	****	MOS41750	
805E	D302 8011	176	LB	R0,IO+1(R2)			MOS41760	
8052	DE02 89F8	177	OC	R0,CON2ND(R2)	ISSUE 2ND COMMAND (LIST DEVICE) ***	***	MOS41770	
		178 *					MOS41780	
8056	41F0 888E	179	IO.OK3	BAL	LINK,SETKB		MOS41790	
806A	9310	180	LBR	R1,R0	ESTABLISH KEYBOARD DEVICE		MOS41800	
805C	0A11	181	AAR	R1,R1	(R1) = 1,2,4,5		MOS41810	
805E	4931 8010	182	LH	R3,IO(R1)	(R1) = 2,4,6,A (SLHLS R1,1) ****	****	MOS41820	
8072	4030 89EA	183	STH	R3,CONADR	SET UP CONSOLE DEVICE ADDRESS		MOS41830	
8076	4821 89EC	184	LH	R2,CONRD(R1)			MOS41840	
807A	4020 89EC	185	STH	R2,CONRD	SET UP R/W COMMANDS		MOS41850	
807E	4821 89F3	186	LH	R2,CON2ND(R1)			MOS41860	
8082	4020 89F8	187	STH	R2,CON2ND	2ND CMD; ENABLE READ CMD		MOS41870	
8086	9011	188	SRHLS	R1,1			MOS41880	
8088	D341 8A04	189	LB	R4,CONRQ2S(R1)			MOS41890	
808C	D240 8A04	190	STB	R4,CONRQ2S	CONSOLE REQUEST TO SEND		MOS41900	
8090	4040 89E6	191	STH	R4,PASFLG	SET PASLA FLAG (CONSOLE)		MOS41910	
8094	9333	192	LBR	R3,R3	HOLD CONSOLE DEVICE TO 8 BITS ***	***	MOS41920	
8096	0844	193	LDAE	R4,R4			MOS41930	
8098	2333	194	BZS	IO.OK4	SKIP 2ND OC IF NOT PASLA		MOS41940	
809A	9422	195	EXBR	R2,R2			MOS41950	
809C	9E32	196	OCR	R3,R2	ISSUE 2ND COMMAND (CONSOLE)		MOS41960	
809E	DE30 89EC	197	IO.OK4	OC	PUT CONSOLE IN READ MODE		MOS41970	
80A2	9E3F	198	RDB	R3,R15	READ A DUMMY CHARACTER (SET BUSY)		MOS41980	
		199 *					MOS41990	
80A4	41F0 88D0	200	BAL	LINK,LCORE	SET UP LOW CORE		MOS42000	
80A8	24C0	201	LIS	R0,0			MOS42010	
80AA	4000 8A12	202	STH	R0,WASDU	RESET 'DEVICE UNAVAILABLE' FLAGS		MOS42020	
80AE	4000 8A14	203	STH	R0,WASDU1			MOS42030	
80B2	41F0 86DE	204	BAL	LINK,CRLF			MOS42040	
80B6	C850 8BFC	205	LDAI	R5,TITLE			MOS42050	
80BA	41F0 8656	206	BAL	R15,PRINT	PRINT TEST PROGRAM TITLE		MOS42060	
		207 -----					MOS42070	
		208 * KEYBOARD INPUT ROUTINE					MOS42080	
		209 *					MOS42090	
80BE	C8F0 895A	210	OPTIN	LDAI	LINK,MM	*	***	MOS42100
80C2	40F0 003E	211		STH	LINK,X'3E'	RESTORE ETPE MM POINTER	***	MOS42110
80C6	41F0 86DE	212		BAL	LINK,CRLF	CR,LF TO LIST DEVICE		MOS42120
80CA	4820 8008	213	OPTIN1	LH	R2,PSW2			MOS42130
80CE	9512	214		EPSR	R1,R2	NO INT. REG SET 15		MOS42140
80D0	41F0 888E	215		BAL	LINK,SETKB	ESTABLISH CONSOLE		MOS42150
80D4	D340 8A98	216		LB	R4,AMSG	OUTPUT AN * TO INDICATE		MOS42160
80D8	41F0 86EC	217		BAL	LINK,OUTCHR	COMMAND MODE ESTABLISHED		MOS42170
80DC	2541	218		LCS	R4,1	X'FF'		MOS42180
80DE	41F0 86EC	219		BAL	LINK,OUTCHR			MOS42190
80E2	C8C0 87A8	220		LDAI	R12,QUESTN	SET UP R12 FOR ERR ROUTINE		MOS42200
80E6	C800 2020	221		LDAI	R0,X'2020'	BLANK OUT COMMAND BUFFER		MOS42210
80EA	4000 9DBC	222		STH	R0,OPTBUF	WHICH WILL CONTAIN OPTION		MOS42220
80EE	4000 9DBE	223		STH	R0,OPTBUF+2	NAME		MOS42230
80F2	40C0 9DC0	224		STH	R0,OPTBUF+4			MOS42240
80F6	2410	225		LIS	R1,0	CLEAR OPTBUF INDEX		MOS42250
80F8	4010 8A0C	226		STH	R1,ISITERR	RESET FORCED PRINTING FLAG	****	MOS42260
80FC	41F0 877A	227	RDCHR	BAL	R15,GETCHR	GET A CHAR IN R4		MOS42270

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8100	C540 0060	228	CLAI	R4,X'60'	UPPER CASE ALPHA ?	MOS42280	
8104	2183	229	BLS	RDCHAR0	BRANCH IF NC.	MOS42290	
8106	C840 0020	230	SAI	R4,X'20'	CONVERT TO LOWER CASE	MOS42300	
810A	C540 0023	231	RDCHAR0	CLAI	R4,X'23'	IS IT A HASH MARK ?	MOS42310
810E	4330 80BE	232	BE	OPTIN			MOS42320
8112	C540 005F	233	CLAI	R4,X'5F'	LEFT ARROW, UNDERLINE OR DELETE ?	MOS42330	
8116	2334	234	BES	RDCHAR1	YES, BRANCH	MOS42340	
8118	C540 0008	235	CLAI	R4,X'08'	BACK SPACE ?	MOS42350	
811C	2139	236	BNES	RDCHR1	NO, BRANCH	MOS42360	
811E	2711	237	RDCHAR1	SIS	R1,1	YES, DECREMENT INDEX	MOS42370
8120	021C	238	BMR	R12	BUFFER UNDERFLOW; PRINT '?'	MOS42380	
8122	C800 0020	239	LDAI	R0,X'20'			MOS42390
8126	D201 9DBC	240	STB	R0,OPTBUF(R1)			MOS42400
812A	4300 80FC	241	B	RDCHR			MOS42410
812E	C540 000E	242	RDCHR1	CLAI	R4,X'0D'	IS IT CR ?	MOS42420
8132	233C	243	BES	LOOKUP	YES, TRY MATCH	MOS42430	
8134	C540 0020	244	CLAI	R4,X'20'	IS IT A BLANK?	MOS42440	
8138	2339	245	BES	LOOKUP	YES, TRY MATCH	MOS42450	
813A	C510 0006	246	CLAI	R1,6	7 CHARACTERS INPUT ?	MOS42460	
813E	038C	247	BNLR	R12	IF YES, ERROR	MOS42470	
8140	D241 9DBC	248	STB	R4,OPTBUF(R1)	STORE CURRENT BYTE	MOS42480	
8144	2611	249	AIS	R1,1	BUMP BUFFER INDEX	MOS42490	
8146	4300 80FC	250	B	RDCHR	READ NEXT CHARACTER	MOS42500	
814A	C610 8AB4	251	-----				MOS42510
814E	2430	252	* OPTION MATCH ROUTINE				MOS42520
8150	0861	253	*-----				MOS42530
8152	4856 0000	254	LOOKUP	LDAI	R1,OPT	LOAD ADDRESS OF OPTION TABLE	MOS42540
8156	021C	255	LOOK1	LIS	R3,0	CLEAR BUFFER INDEX	MOS42550
8158	4553 9DBC	256	LDAR	R6,R1		SET OPTION WORD INDEX	MOS42560
815C	2333	257	LOOK2	LH	R5,0(R6)		MOS42570
815E	261C	258	BMR	R12		IF MINUS, THEN NO MATCH = ERROR	MOS42580
8160	2269	259	CLH	R5,OPTBUF(R3)		COMPARE TO OPTBUF HW	MOS42590
8162	2632	260	BES	LOOK3			MOS42600
8164	2662	261	AIS	R1,12			MOS42610
8166	C530 0006	262	BS	LOOK1			MOS42620
816A	208C	263	LOOK3	AIS	R3,2	TRY NEXT HW	MOS42630
816C	C510 8B38	264	AIS	R6,2			MOS42640
8170	4330 82EA	265	CLAI	R3,6	3 MATCHING HW FOUND ?	MOS42650	
8174	C510 8B2C	266	BLS	LOOK2			MOS42660
8178	4230 828A	267	*				MOS42670
817C	C540 000D	268	CLAI	R1,RUN	RUN COMMAND ?	MOS42680	
8180	233C	269	BE	RUNIT			MOS42690
8182	4150 8582	270	CLAI	R1,OPTION	OPTION CMD ?	MOS42700	
8186	C560 0006	271	BNE	LOOK4	NO, LOOK FURTHER	MOS42710	
818A	2387	272	-----				MOS42720
818C	C840 000A	273	* TO PROCESS INPUT COMMAND 'OPTION'				MOS42730
8190	41F0 86EC	274	CLAI	R4,X'0D'	CR ?	MOS42740	
		275	BES	OPTEXX	YES, BRANCH	MOS42750	
		276	BAL	R14,OPTVAL	NO, GET OPTION DEV PRINTOUT NO.	MOS42760	
		277	CLAI	R6,5	IS DEVICE NUMBER VALID ?	MOS42770	
		278	BNLS	OPTEXX	NO, BRANCH	MOS42780	
		279	LDAI	R4,X'0A'	YES, LOAD A LF CHARACTER	MOS42790	
		280	BAL	LINK,OUTCHR	WRITE IT TO THE CONSOLE	MOS42800	

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8194	D260 800B	281	STB	R6,IOSAVE+1	CHANGE THE LIST DEVICE NUMBER	MOS42810
8198	4820 8B34	282	OPTEXX	LH R2,OPTION+8	CHECK FOR SPECIAL ROUTINE	MOS42820
819C	0232	283	BNZR	R2	LINK TO ROUTINE	MOS42830
		284	*			MOS42840
819E	C830 8AB4	285	OPTRTN	LDAI R3,TEST	RETURN HERE	MOS42850
81A2	C8E0 8228	286		LDAI R14,OPTCMD8		MOS42860
81A6	41F0 86DE	287	BAL	LINK,CRLF		MOS42870
81AA	2420	288	OPTCMD	LIS R2,0	RESET COUNTER	MOS42880
81AC	D342 8AB4	289	OPTCMD1	LB R4,OPT(R2)	TO PRINT TEST	MOS42890
81B0	41F0 86EC	290	BAL	LINK,OUTCHR		MOS42900
81B4	2621	291	AIS	R2,1		MOS42910
81B6	C520 0006	292	CLAI	R2,6		MOS42920
81BA	2087	293	BLS	OPTCMD1		MOS42930
81BC	C840 0020	294	LDAI	R4,C*''		MOS42940
81C0	41F0 86EC	295	BAL	LINK,OUTCHR	OUTPUT 1 SPACE	MOS42950
81C4	2450	296	LIS	R5,0	TO PRINT SELECTED TEST NUMBERS	MOS42960
81C6	4050 8004	297	STH	R5,FIRST		MOS42970
81CA	4823 0006	298	LH	R2,6(R3)	FIRST TEST WORD	MOS42980
81CE	2440	299	OPTCMD2	LIS R4,0	START WITH TEST 0	MOS42990
81D0	4040 800C	300	STH	R4,TEMP		MOS43000
81D4	0A22	301	OPTCMD3	AAR R2,R2	(SLHLS R2,1)	**** MOS43010
81D6	43E0 8208	302	BNC	OPTCMD7		MOS43020
81DA	4040 800C	303	OPTCMD4	STH R4,TEMP	OPTION VALUE FOUND.	MOS43030
81DE	4800 8004	304	LH	R0,FIRST	IS IT FIRST ?	MOS43040
81E2	2335	305	BZS	OPTCMD5	NO, OUTPUT COMMA	MOS43050
81E4	C840 002C	306	LDAI	R4,C*''		MOS43060
81E8	41F0 86EC	307	BAL	LINK,OUTCHR		MOS43070
81EC	40F0 8004	308	OPTCMD5	STH LINK,FIRST		MOS43080
81F0	0855	309	LDAR	R5,R5	TEST VALUE FROM SECOND HW	MOS43090
81F2	2335	310	BZS	OPTCMD6	NO	MOS43100
81F4	C840 0031	311	LDAI	R4,C*''	YES,OUTPUT '1'	MOS43110
81F8	41F0 86EC	312	BAL	LINK,OUTCHR		MOS43120
81FC	4840 800C	313	OPTCMD6	LH R4,TEMP	RESTORE R4	MOS43130
8200	D344 8A34	314	LB	R4,HEXTAB(R4)	CONVERT	MOS43140
8204	41F0 86EC	315	BAL	LINK,OUTCHR	OUTPUT 0-F	MOS43150
8208	4840 800C	316	OPTCMD7	LH R4,TEMP	RESTORE	MOS43160
820C	2641	317	AIS	R4,1	INCREMENT TEST NUMBER	MOS43170
820E	4040 800C	318	STH	R4,TEMP		MOS43180
8212	C540 0010	319	CLAI	R4,16		MOS43190
8216	4280 81D4	320	BL	OPTCMD3		MOS43200
821A	0855	321	OPTCMD71	LDAR R5,R5	DONE ?	MOS43210
821C	023E	322	BNZR	R14		MOS43220
821E	4823 0008	323	LH	R2,8(R3)	SECOND TEST WORD	MOS43230
8222	2451	324	LIS	R5,1	R5 = 1 FOR SECOND TEST HW	MOS43240
8224	43C0 81CE	325	B	OPTCMD2		MOS43250
		326	*			MOS43260
		327	*	TO OUTPUT OTHER OPTION NAMES & VALUES		MOS43270
		328	*			MOS43280
8228	41F0 86DE	329	OPTCMD8	BAL LINK,CRLF		MOS43290
822C	2461	330	LIS	R6,1	SET LINE COUNTER	MOS43300
822E	C820 8AC0	331	LDAI	R2,OPT+12	R2 POINTS TO THE NAME	MOS43310
8232	2436	332	OPTCMD9	LIS R3,6		MOS43320
8234	D342 0000	333	OPTCMD10	LB R4,0(R2)		MOS43330

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					OUTPUT OPTION NAME CHAR		
8238	41F0 86EC	334	BAL	LINK,OUTCHR	MOS43340		
823C	2621	335	AIS	R2,1	MOS43350		
823E	2731	336	SIS	R3,1	MOS43360		
8240	2026	337	BPS	OPTCMD10	MOS43370		
8242	C840 0020	338	LDAI	R4,C* *	MOS43380		
8246	41F0 86EC	339	BAL	LINK,OUTCHR	MOS43390		
824A	4852 0000	340	LH	R5,0(R2)	MOS43400		
824E	24C4	341	LIS	R0,4	MOS43410		
8250	41F0 85CC	342	BAL	LINK,R5HEX	MOS43420		
8254	D300 8010	343	LB	R0,IO	MOS43430		
8258	27C1	344	SIS	R0,1	MOS43440		
825A	213D	345	BNZS	OPTCMD12	MOS43450		
825C	2661	346	AIS	R6,1	MOS43460		
825E	C560 0014	347	CLAI	R6,20	MOS43470		
8262	2189	348	BLS	OPTCMD12	MOS43480		
8264	24E0	349	LIS	R6,0	MOS43490		
8266	41F0 877A	350	OPTCMD11	BAL	WRITE OPTION VALUE IN HEX (4 DIGITS)	MOS43500	
826A	274D	351	SIS	R4,13	MOS43510		
826C	4330 80BE	352	BZ	OPTIN	MOS43520		
8270	2643	353	AIS	R4,3	MOS43530		
8272	2036	354	BNZS	OPTCMD11	MOS43540		
8274	41F0 86DE	355	OPTCMD12	BAL	LINK,CRLF	MOS43550	
8278	41F0 87D4	356	BAL	LINK,TSTBRK	MOS43560		
827C	2626	357	AIS	R2,6	MOS43570		
827E	C520 8B14	358	CLAI	R2,OPTEND2	MOS43580		
8282	4280 8232	359	BL	OPTCMD9	MOS43590		
8286	4300 80CA	360	B	OPTIN1	MOS43600		
		361	*			MOS43610	
828A	C510 9AB4	362	LOCK4	CLAI R1,TEST	'TEST' OPTION ?	MOS43620	
828E	4330 8286	363		BE TESTOP		MOS43630	
		364	*			MOS43640	
		365	*	TO PRPROCESS COMMANDS OTHER THAN 'TEST', 'OPTION'.		MOS43650	
		366	*			MOS43660	
8292	274D	367	SIS	R4,13	OPT FOLLOWED BY CR ?	MOS43670	
8294	033C	368	BZR	R12	YES, ERROR	MOS43680	
8296	41E0 8582	369	BAL	R14,OPTVAL	GET OPTION VALUE IN R6	MOS43690	
829A	274D	370	SIS	R4,13	TERMINATED BY CR ?	MOS43700	
829C	023C	371	BNZR	R12	IF NO, BRANCH	MOS43710	
829E	48F1 0008	372	LH	R14,8(R1)	GET OPTION CHECK ROUTINE ADDRESS	MOS43720	
82A2	2332	373	BZS	LOOK5		MOS43730	
82A4	01FE	374	BALR	R15,R14	LINK TO OPTION CHECK ROUTINE	MOS43740	
		375	*		* RETURN HERE IF OK *	MOS43750	
82A6	4061 0006	376	LOOK5	STH R6,6(R1)	STORE OPTION VALUE	MOS43760	
82AA	4300 80BE	377	B	OPTIN	TO ACCEPT NEXT COMMAND	MOS43770	
		378	*			MOS43780	
		379	*			MOS43790	
		380	*			MOS43800	
82AE	4561 000A	381	LEVELIN	CLH R6,10(R1)	IS R6 > MAX VALUE ?	***	MOS43810
82B2	022C	382	BPR	R12	YES, ERROR RETURN	***	MOS43820
82B4	030F	383		BR R15	NO, RETURN TO LOOK5	***	MOS43830
		384	*				MOS43840
		385	*				MOS43850
		386	*	TEST OPTION PROCESS ROUTINE			MOS43860

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82B6	274D	387 *				MOS43870
82B8	2137	388 TESTOP	SIS	R4,13	"TEST" FOLLOWED BY (CR) ?	MOS43880
82BA	4800 8C2C	389 BNZS		TSTOP1		MOS43890
82BE	4000 8ABA	390 LH		R0,DEFTESTS	YES, SET TEST OPTION TO	MOS43900
82C2	4300 80BE	391 STH		B0,TEST+6	FIRST TEST WORD	MOS43910
		392 B		OPTIN	TO ACCEPT NEXT COMMAND	MOS43920
		393 *				MOS43930
82C6	4850 8C2E	394 TSTOP1	LH	R5,MAXTST	RESET TEST BIT ACCUMULATORS	MOS43940
82CA	2470	395 LIS		R7,0		MOS43950
82CC	2480	396 LIS		R8,0		MOS43960
82CE	41E0 8582	397 TSTOP2	BAL	R14,OPTVAL	GET OPTION VALUE IN R6	MOS43970
82D2	0556	398 CLAR		R5,R6		MOS43980
82D4	028C	399 BLR		R12	ERROR: INVALID TEST NUMBER	MOS43990
82D6	41E0 85BE	400 BAL		R14,UNARY	GET UNARY OPERAND IN R3	MOS44000
82DA	0673	401 OAR		R7,R3	SET CURRENT BIT	MOS44010
82DC	274D	402 TSTOP4	SIS	R4,13	TERMINATED BY CR ?	MOS44020
82DE	4230 82CE	403 BNZ	TSTOP2			MOS44030
82E2	4070 8ABA	404 STH		R7,TEST+6	STORE VALID SELECTED TESTS	MOS44040
82E6	4300 80BE	405 B		OPTIN	TO ACCEPT NEXT COMMAND	MOS44050
		406 *				MOS44060
		407 *				MOS44070
82EA	41E0 86DE	408 RUNIT	BAL	LINK,CRLF		MOS44080
82EE	24F0	409 LIS		R15,0		MOS44090
82FO	40F0 8A12	410 STH		R15,WASDU	RESET DU FLAGS	MOS44100
82F4	40F0 8A14	411 STH		R15,WASDU1		MOS44110
82F8	24CF	412 LIS		R0,15	TO FIND HIGHEST SELECTED TEST NO.	MOS44120
82FA	4810 8ABA	413 LH		R1,TEST+6	CHECK FIRST TEST HW	MOS44130
82FE	9011	414 KEEP2	SRLS	R1,1		MOS44140
8300	2184	415 BCS	FOUND2		R0 = F-0 = TEST NUMBER	MOS44150
8302	2701	416 SIS		R0,1		MOS44160
8304	2213	417 BNMS	KEEP2		LOOP	MOS44170
8306	030C	418 BR		R12	TEST NOT SELECTED	MOS44180
8308	4000 8A10	419 FOUND2	STH	B0,SELTST	HIGHEST SELECTED TEST NUMBER ***	MOS44190
		420 *				MOS44200
		421 * RESET TEST PARAMETERS				MOS44210
		422 *				MOS44220
830C	4800 8010	423 LH		R0,IO		MOS44230
8310	4000 800A	424 STH		R0,IOSAVE	RESTORE USER'S I/O CHOICE	MOS44240
8314	41E0 86DE	425 BAL		LINK,CRLF		MOS44250
8318	41E0 8B4C	426 BAL		LINK,INIT	LINK USER INITIALIZATION ROUTINE	MOS44260
		427 *				MOS44270
831C	2400	428 INITRET	LIS	R0,0	RETURN HERE FROM INIT	MOS44280
831E	4000 8A0C	429 STH		R0,ISITERR	RESET ERROR FLAG	MOS44290
8322	4000 8A16	430 STH		R0,TOTAL	RESET TOTAL	MOS44300
8326	4000 8A18	431 STH		R0,TOTERR	RESET TOTERR	MOS44310
832A	4000 8A12	432 STH		R0,WASDU	RESET WASDU FLAG	MOS44320
832E	C810 3030	433 LDAI		R1,C'00'		MOS44330
8332	4010 8A4A	434 STH		R1,MTESTNO	RESET THESE FLAGS TO C'00'	MOS44340
8336	4010 8A54	435 STH		R1,ETESTNO		MOS44350
833A	4010 8A56	436 STH		R1,ERRNO		MOS44360
833E	41E0 88D0	437 BAL		LINK,LCORE	SET UP LOW CORE	MOS44370
		438 *				MOS44380
		439 * START SELECTION FROM TEST 0				MOS44390

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8342	2400	440	*		MOS44400	
8344	4000 8A1A	441	KEEP3	LIS R0,0	MOS44410	
8348	4000 8A1E	442	STH	R0,BTESTNO	MOS44420	
		443	STH	R0,NEXTST	MOS44430	
		444	*	RESET BINARY TEST NUMBER	MOS44440	
		445	*	RESET NEXT TEST NUMBER	MOS44450	
		TO FIND THE NEXT SELECTED TEST.				MOS44460
		446	*		MOS44470	
834C	4820 8A1E	447	KEEP4	LH R2,NEXTST	MOS44480	
9350	2408	448	KEEP41	LIS R0,8	MOS44490	
8352	910C	449	SLHLS	R0,12	MOS44500	
8354	CCC2 0000	450	SRHL	R0,0(R2)	MOS44510	
8358	44C0 8ABA	451	KEEP42	NH R0,TEST+6	MOS44520	
835C	2133	452	BNZS	KEEP5	MOS44530	
835E	2621	453	KEEP43	AIS R2,1	MOS44540	
8360	2208	454	BS	KEEP41	MOS44550	
8362	4020 8A1A	455	KEEP5	STH R2,BTESTNO	MOS44560	
8366	0812	456	LDAR	R1,B2	MOS44570	
8368	2621	457	AIS	R2,1	MOS44580	
836A	4020 8A1E	458	STH	R2,NEXTST	MOS44590	
836E	24C2	459	LIS	R0,2	MOS44600	
8370	C820 8A4A	460	LDAI	R2,MTESTNO	MOS44610	
8374	41F0 85F6	461	BAL	LINK,HEXASC	MOS44620	
8378	4820 8A4A	462	LH	R2,MTESTNO	MOS44630	
837C	4020 8A54	463	STH	R2,ETESTNO	MOS44640	
8380	41F0 87D4	464	BAL	LINK,TSTBRK	MOS44650	
8384	C850 8A44	465	LDAI	R5,TSTMMSG	MOS44660	
8388	41F0 8656	466	BAL	LINK,PRINT	MOS44670	
838C	24C0	467	LIS	R0,0	MOS44680	
838E	4000 8A0E	468	STH	R0,NCERR	MOS44690	
8392	4000 8A1C	469	STH	R0,COUNT	MOS44700	
8396	4810 8006	470	KEEP6	LH R1,PSW	MOS44710	
839A	9501	471	EPSR	R0,R1	MOS44720	
839C	4820 8A1A	472	LH	R2,BTESTNO	MOS44730	
83A0	9121	473	SLLS	R2,LADC	MOS44740	
83A2	4812 8C30	474	LDA	R1,TESTS(R2)	MOS44750	
83A6	0301	475	BR	R1	MOS44760	
		476	*	GO TO TEST MODULE	MOS44770	
		477	*		MOS44780	
		478	*	TEST MODULE END ROUTINE	MOS44790	
		479	*			
83A8	C8F0 895A	480	TSTEND	LDAI LINK,MM	*** MOS44800	
83AC	40F0 003E	481	STH	LINK,X'3E'	*** MOS44810	
83B0	4810 8008	482	LH	R1,PSW2	MOS44820	
83B4	95C1	483	EPSR	R0,R1	MOS44830	
83B6	48C0 8A1C	484	LH	R0,COUNT	MOS44840	
83BA	26C1	485	AIS	R0,1	MOS44850	
83BC	40C0 8A1C	486	STH	R0,COUNT	MOS44860	
83C0	41F0 87D4	487	BAL	LINK,TSTBRK	IF BREAK GO TO OPTIN *** MOS44870	
83C4	4500 8AC6	488	CLH	R0,LOOP+6	IF COUNT > LOOP, MOS44880	
83C8	2383	489	BNLS	KEEP7	GO TO NEXT TEST MODULE MOS44890	
83CA	4300 8396	490	B	KEEP6	OTHERWISE, REPEAT SAME TEST MOS44900	
83CE	4800 8A0E	491	KEEP7	LH R0,NOERR	LOOK @ ERROR FLAG MOS44910	
83D2	2135	492	BNZS	KEEP71	MOS44920	

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83D4	C850 8A6A	493	LDAI	R5,NOERMSG		MOS44930
83D8	41F0 8656	494	BAL	LINK,PRINT	PRINT "NO ERROR"	MOS44940
83DC	4810 8A1A	495	KEEP71	LH R1,BTESTNO	GET TEST NUMBER	MOS44950
83E0	4510 8A10	496	CLH	R1,SELTST	IS THE LAST SELECTED TEST DONE ?	MOS44960
83E4	4280 834C	497	BL	KEEP4	NO, GO SELECT NEXT TEST	MOS44970
		498	*			MOS44980
		499	*	ALL THE SELECTED TESTS ARE NOW RUN		MOS44990
		500	*			MOS45000
83E8	C8F0 895A	501	ABORT	LDAI LINK,MM	COME HERE TO ABORT TEST SEQUENCE ***	MOS45010
83EC	40F0 003E	502	STH	LINK,X'3E'	RESTORE ETPE MM POINTER ***	MOS45020
83F0	4810 8008	503	LH	R1,PSW2		MOS45030
83F4	95C1	504	EPSR	RO,R1	PSW = 30F0	MOS45040
83F6	41F0 84DC	505	BAL	LINK,DISPLAY	DISPLAY TOTAL & TOTERR	MOS45050
83FA	8A16	506	DC	Z(TOTAL),Z(TOTERR)		MOS45060
83FC	8A18					
83FE	41F0 8858	507	BAL	LINK,TSTDU	RETURN WITH R1 = DU BIT	MOS45070
8402	4230 8464	508	BNZ	KEEP9	IF DU, DISPLAY TOTAL	MOS45080
8406	4810 8A14	509	LH	R1,WASDU1	WAS IT EVER ?	MOS45090
840A	4230 849A	510	BNZ	KEEP92	YES, PRINT TOTAL, TOTEPR	MOS45100
840E	41F0 87D4	511	BAL	LINK,TSTBRK		MOS45110
8412	4810 8AD2	512	LH	R1,CONTIN+6	IF CONTIN = 0,	MOS45120
8416	233E	513	BZS	ABORT3	GO TO ABORT TEST	*** MOS45130
8418	6110 8A16	514	AHM	R1,TOTAL	INCREMENT TOTAL COUNTER	*** MOS45140
841C	4230 8342	515	BNZ	KEEP3	IF TOTAL < MAX, BRANCH	*** MOS45150
8420	2511	516	LCS	R1,1	OTHERWISE	*** MOS45160
8422	6110 8A16	517	AHM	R1,TOTAL	SET "TOTAL" TO MAX &	*** MOS45170
8426	4300 8494	518	B	HALT9	HALT PROCESSOR	*** MOS45180
		519	*			MOS45190
842A	C8F0 895A	520	ABORT1	LDAI LINK,MM	*	*** MOS45200
842E	40F0 003E	521	STH	LINK,X'3E'	RESTORE ETPE MM POINTER	*** MOS45210
		522	*			*** MOS45220
8432	4810 8008	523	ABORT3	LH R1,PSW2	*	*** MOS45230
8436	9501	524	EPSR	RO,R1	SET PSW = X'30F0'	*** MOS45240
8438	41F0 888E	525	BAL	LINK,SETKB	KB DEVICE = LIST DEVICE	MOS45250
843C	C850 8A88	526	LDAI	R5,EOTHSG		MOS45260
8440	4050 8A0C	527	STH	R5,ISITERR	*	*** MOS45270
8444	41F0 8656	528	BAL	LINK,PRINT	*END OF TEST*	MOS45280
8448	24F0	529	LIS	R15,0	*	MOS45290
844A	40F0 8A0C	530	STH	R15,ISITERR	*	*** MOS45300
		531	*			MOS45310
844E	48F0 8ADE	532	LH	LINK,NOMSG+6	IF "NOMSG" = 1,	MOS45320
8452	4230 849A	533	BNZ	KEEP92	PRINT "TOTAL" & "TOTERR"	MOS45330
8456	48F0 8AEA	534	LH	LINK,SCOPE+6	*	*** MOS45340
845A	27F4	535	SIS	LINK,4	IF "SCOPE" = 4,	*** MOS45350
845C	4330 849A	536	BZ	KEEP92	PRINT "TOTAL" & "TOTERR"	*** MOS45360
8460	4300 80BE	537	B	OPTIN	*	MOS45370
		538	*			MOS45380
		539	*	ROUTINE INCREMENTS, DISPLAYS & CHECKS "TOTAL"		MOS45390
		540	*			MOS45400
		541	KEEP9	STH R1,WASDU	SET 'WASDU' FLAG	MOS45410
		542	*			MOS45420
		543	ABORT2	LH R1,TOTAL	INCREMENT TOTAL	MOS45430
		544	AIS	R1,1		MOS45440

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846E	4010	8A15	545	STH	R1,TOTAL		MOS45450	
8472	41E0	84DC	546	KEEP91	BAL	LINK,DISPLAY	DISPLAY TOTAL & TOTERR	MOS45460
8476	8A16		547	DC	Z(TOTAL),Z(TOTERR)		MOS45470	
8478	8A18							
847A	4810	8A15	548	LH	R1,TOTAL		MOS45480	
847E	C510	7FFF	549	CLAI	R1,X'7FFF'	TOTAL < MAX RETAINABLE ?	MOS45490	
8482	2389		550	BNLS	HALT9	NO, BRANCH	MOS45500	
8484	48C0	8A1A	551	LH	R0,BTESTNO	R0 = CURRENT TEST NUMBER	MOS45510	
8488	45C0	8A10	552	CLH	R0,SELTST	IS IT LAST TEST ?	MOS45520	
848C	4280	834C	553	BL	KEEP4	NO, GO TO NEXT TEST	MOS45530	
8490	4300	8342	554	B	KEEP3	YES, GC TO TEST 0	MCS45540	
			555	*			MOS45550	
8494	C810	30F0	556	HALT9	LDAI	R1,X'30F0'	***	MOS45560
8498	9521		557		EPSR	R2,31	HALT PROCESSOR	MOS45570
			558	*			MOS45580	
			559	*	WHEN EXE/RUN IS PRESSED, PRINT TOTAL & TOTERR		MOS45590	
			560	*			MOS45600	
849A	41E0	8858	561	KEEP92	BAL	LINK,TSTDU	SEE IF LIST DEV IS ON	MOS45610
849E	2035		562	BNZS	HALT9	NO, HALT	MOS45620	
84A0	24C0		563	KEEP10	LIS	R0,0	MOS45630	
84A2	40C0	8A12	564	STH	R0,WASDU	RESET FLAG	MCS45640	
84A6	41E0	86DE	565	BAL	LINK,CRLF		MOS45650	
84AA	C850	8A5A	566	LDAI	R5,TOTMSG		MOS45660	
84AE	4050	8A0C	567	STH	R5,ISITERR		MOS45670	
84B2	41E0	8656	568	BAL	LINK,PRINT	PRINT 'TOTAL TOTERR'	MOS45680	
84B6	24C4		569	LIS	R0,4	TO PRINT 4 HEX DIGITS	MOS45690	
84B8	4850	8A16	570	LH	R5,TOTAL		MOS45700	
84BC	41E0	85CC	571	BAL	LINK,R5HEX	PRINT TOTAL IN HEX	MOS45710	
84C0	2434		572	LIS	R3,4		MOS45720	
84C2	C840	0020	573	LDAI	R4,C'	SPACE	MOS45730	
84C6	41E0	86EC	574	KEEP101	BAL	LINK,OUTCHR	OUTPUT IT	MOS45740
84CA	2731		575	SIS	R3,1		MOS45750	
84CC	2023		576	BPS	KEEP101	4 TIMES	MOS45760	
84CE	2404		577	LIS	R0,4	TO PRINT 4 HEX DIGITS	MOS45770	
84D0	4850	8A18	578	LH	R5,TOTERR		MOS45780	
84D4	41E0	85CC	579	BAL	LINK,R5HEX	PRINT TOTERR IN HEX	MOS45790	
84D8	43C0	80BE	580	B	OPTIN	GO TO BEGINNING	MOS45800	
			581	*			MOS45810	
			582	*	DISPLAY DATA ROUTINE		MOS45820	
84DC	2401		583	DISPLAY	LIS	R0,1	GET DISPLAY PANEL ADDRESS	MOS45830
84DE	DE00	800F	584	OC	R0,INCR	PUT PANEL IN INCREMENTAL MODE	MOS45840	
84E2	481F	0002	585	LH	B1,2(LINK)	GET 2ND PARAMETER	MOS45850	
84E6	4811	0000	586	LH	R1,0(R1)	GET DATA	MOS45860	
84EA	9411		587	EXBR	R1,R1		MOS45870	
84EC	98C1		588	WHR	R0,R1	WRITE DATA	MOS45880	
84EE	481F	0000	589	LH	R1,0(LINK)	GET 1ST PARAMETER	MOS45890	
84F2	4811	0000	590	LH	R1,0(R1)	GET DATA	MOS45900	
84F6	9411		591	EXBR	R1,R1		MOS45910	
84F8	9801		592	WHR	R0,R1	WRITE DATA	MOS45920	
84FA	DE00	800E	593	OC	R0,NORM	PUT PANEL IN NORMAL MODE	MOS45930	
84FE	43CF	0004	594	B	4(LINK)	RETURN	MOS45940	
			595	*			***	MOS45950
			596	*	ERROR ROUTINES	(OVERRIDE NOMSG OPTION)	MOS45960	

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8502	D000	9E10	597	*		MOS45970
8506	4120	8520	598	ERR	STM R0,ERRSAVE	MOS45980
850A	41E0	8554	599	BAL	R2,ERRCOM	MOS45990
850E	24C0		600	BAL	RET,ERR1	MOS46000
8510	4000	8A0C	601	ERRCOM2	LIS R0,0	*** MOS46010
8514	4820	8006	602	STH	R0,ISITERR	MOS46020
8518	95C2		603	LH	R2,PSW	MOS46030
851A	D100	9E10	604	EPSR	R0,R2	MOS46040
851E	030F		605	LM	R0,ERRSAVE	MOS46050
			606	BR	LINK	MOS46060
			607	*		MOS46070
			608	*	ETPE COMMON ERROR ROUTINE	*** MOS46080
			609	*		MOS46090
8520	4020	8A22	610	ERRCOM	STH R2,COMRET	MOS46100
8524	4810	8008	611	LH	R1,PSW2	MOS46110
8528	95C1		612	EPSR	R0,R1	DISABLE INT. @ PROCESSOR LEVEL MOS46120
852A	41F0	8858	613	BAL	LINK,TSTDU	MOS46130
852E	2138		614	BWZS	ERRCOM1	MOS46140
8530	4020	8A0C	615	STH	R2,ISITERR	MOS46150
8534	4020	8A0E	616	STH	R2,NCERR	MOS46160
8538	4820	8A22	617	LH	R2,COMRET	MOS46170
853C	03C2		618	BR	R2	MOS46180
			619	*		MOS46190
853E	4810	8A18	620	ERRCOM1	LH R1,TOTERR	MOS46200
8542	2611		621	AIS	R1,1	MOS46210
8544	4010	8A18	622	STH	R1,TOTERR	INCREMENT TOTERR MOS46220
8548	C510	7FFF	623	CLAI	R1,X'7FFF'	TOTERR < MAX RETAINABLE ? MOS46230
854C	4280	8472	624	BL	KEEP91	NO, ABORT CURRENT TEST & GOTO NEXT MOS46240
8550	4300	8494	625	B	HALT9	YES, HALT PROCESSOR MOS46250
			626	*		MOS46260
			627	*	MESSAGE PRINT ROUTINES	(DO NOT OVERRIDE NOMSG OPTION) MOS46270
			628	*		MOS46280
			629	*	TO PRINT 'ERROR TTNN'	MOS46290
			630	*		MOS46300
8554	C850	8A4E	631	ERR1	LDAI R5,ERRMSG	MOS46310
8558	41F0	8656	632	BAL	LINK,PRINT	PRINT 'ERROR TTNN' TT = TEST NO., NN = ERROR NO. MOS46320
855C	030E		633	*		MOS46330
			634	BR	RET	MOS46340
			635	*		*** MOS46350
			636	*	TO PRINT 'PSW PPPP LOC LLLL'	MOS46360
			637	*		MOS46370
855E	2404		638	ERRPL1	LIS R0,4	SET UP DIGITS = 4 R1 = OLD PSW MOS46380
8560	4810	89E0	639	LH	R1,OPSW	MOS46390
8564	C820	8A78	640	LDAI	R2,ASCIPSW	MOS46400
8568	41F0	85F6	641	BAL	LINK,HEXASC	CONVERT IT TO ASCII MOS46410
856C	4810	89E2	642	LH	R1,OLOC	R1= OLD LOC MOS46420
8570	C820	8A82	643	LDAI	R2,ASCIOLC	MOS46430
8574	41F0	85F6	644	BAL	LINK,HEXASC	CONVERT IT TO ASCII MOS46440
8578	C850	8A74	645	LDAI	R5,PSWMSG	MOS46450
857C	41F0	8656	646	BAL	LINK,PRINT	PRINT 'PSW PPPP LOC LLLL' MOS46460
8580	030E		647	BR	RET	MOS46470
			648	*	*****	MOS46480
			649	*	TO OBTAIN OPTION VALUE IN R6 (16 BITS, TARGT 16)	MOS46490

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8582	2460	650 *		MOS46500
8584	41E0 877A	651 OPTVAL LIS R6,0	INITIALIZE ACCUMULATOR	MOS46510
8588	24FF	652 BAL R15,GETCHR	GET A CHAR IN R4	MOS46520
858A	D44F 8A34	653 CPTVAL0 LIS R15,15		MOS46530
858E	2334	654 CPTVAL1 CLB R4,HEXTAB(R15)	SCAN TABLE	MOS46540
8590	27E1	655 BES OPTVAL2	MATCH	MOS46550
8592	2214	656 SIS R15,1		MOS46560
8594	03CC	657 BNMS OPTVAL1		MOS46570
8596	91E4	658 BR R12	ERROR; VALUE NOT IN TABLE.	MOS46580
8598	06EF	659 OPTVAL2 SLLS R6,4	SHIFT LEFT 4	MOS46590
859A	41E0 877A	660 CAR R6,R15	OR IN CURRENT DIGIT	MOS46600
859E	C540 005F	661 OPTVAL3 BAL R15,GETCHR	GET NEXT CHAR	MOS46610
85A2	2334	662 CLAI R4,X'5F'	IS IT LEFT ARROW ?	MOS46620
85A4	C540 0008	663 BES OPTVAL5	YES, BRANCH	MOS46630
85A8	2133	664 CLAI R4,X'08'	BACK SPACE ?	MOS46640
85AA	90E4	665 BNES OPTVAL4	NO, BRANCH	MOS46650
85AC	2209	666 OPTVAL5 SBLS R6,4	YES, THROW AWAY LAST HEX ENTRY	MOS46660
85AE	C540 000D	667 BS OPTVAL3		MOS46670
85B2	033E	668 OPTVAL4 CLAI R4,13	EXIT IF CR	MOS46680
85B4	C540 002C	669 BER R14		MOS46690
85B8	4230 8588	670 CLAI R4,X'2C'	OR COMMA	MOS46700
85BC	03CE	671 BNE OPTVAL0	LOOP TO PROCESS	MOS46710
		672 BR R14	RETURN	MOS46720
		673 -----		MOS46730
		674 * TO CONVERT (R6) FROM BINARY TO UNARY PATTERN, IN R3		MOS46740
		675 *		MOS46750
858E	2431	676 UNARY LIS R3,1	INITIALIZE	MOS46760
85C0	C560 000F	677 UNARY1 CLAI R6,15	DONE ?	MOS46770
85C4	033E	678 BER R14	RETURN	MOS46780
85C6	0A33	679 AAR R3,R3	NO. SHIFT R3. (SLHLS R3,1)	****
85C8	2661	680 AIS R6,1	INCREMENT COUNTER	MOS46790
85CA	2205	681 BS UNARY1		MOS46800
		682 -----		***
		683 * RSHEX PRINTS CONTENTS OF R5 IN HEX		MOS46820
		684 * PRINTS UPTO 4 DIGITS (8 DIGITS, TABGT 32)		MOS46830
		685 *		MOS46840
				MOS46850
85CC	D000 9E50	686 RSHEX STM R0,RSAVE	STORE REGISTERS	MOS46860
85D0	0820	687 LDAR R2,R0	R2 = NO. OF DIGITS TO BE PRINTED	MOS46870
85D2	2721	688 SIS R2,1		MOS46880
85D4	4210 85F0	689 BM R5XB		MOS46890
85D8	9122	690 SLLS R2,2	R2 = 4(DIGITS-1)	MOS46900
85DA	0845	691 R5X LDAR R4,R5		MOS46910
85DC	CC42 0000	692 SRAL R4,0(R2)		MOS46920
85E0	C440 000F	693 NAI R4,15	R4 = HEX DIGIT	MOS46930
85E4	D344 8A34	694 LB R4,HEXTAB(R4)		MOS46940
85E8	41E0 86EC	695 R5XA BAL R15,OUTCHR		MOS46950
85EC	2724	696 SIS R2,4		MOS46960
85EE	221A	697 BNMS R5X	LOOP TILL ALL DIGITS	MOS46970
85F0	D1C0 9E50	698 R5XB LM R0,RSAVE	RESTORE REGISTERS	MOS46980
85F4	03CF	699 BR LINK	RETURN	MOS46990
		700 -----		***
		701 * TO CONVERT HEXADECIMAL DATA IN R1 TO ASCII CHAR & STORE @ 0(R2)		MOS47000
		702 *		MOS47010
				MOS47020

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85F6	D000 9E50	703	HEXASC	STM R0,RSAVE	STORE REGISTERS	MOS47030
85FA	0830	704		LDAR R3,R0	R3 = DIGITS	MOS47040
85FC	9132	705		SLLS R3,2		MOS47050
85FE	2734	706		SIS R3,4	R3 = 4(DIGITS)-4	MOS47060
8600	0841	707	HEXASC1	LDAR R4,R1	R4 = HEX DATA	MOS47070
8602	CC43 0000	708		SRAL R4,0(R3)		MOS47080
8606	C440 000F	709		NAI R4,15	R4 = HEX DIGIT TO BE CONVERTED	MOS47090
860A	D344 8A34	710		LB R4,HEXTAB(R4)		MOS47100
860E	D242 0000	711		STB R4,0(R2)	STORE ASCII CHAR	MOS47110
8612	2621	712		AIS R2,1		MOS47120
8614	2734	713		SIS R3,4		MOS47130
8616	221B	714		BNMS HEXASC1	LOOP TILL ALL DIGITS	MOS47140
8618	D100 9E50	715		LM R0,RSAVE	RESTORE REGISTERS	MOS47150
861C	030F	716		BR LINK	RETURN	MOS47160
717	*					MOS47170
718	*			* TO CONVERT BINARY DATA IN R1 INTO DECIMAL DIGITS		MOS47180
719	*			AND STORE THEM IN ASCII @ 0(R2)		MOS47190
720	*					MOS47200
861E	D000 9E50	721	DECASC	STM R0,RSAVE	COPY DIGIT COUNT	MOS47210
8622	0830	722		LDAR R3,R0	& ESTABLISH DECTAB INDEX.	MOS47220
8624	9131	723		SLLS R3,LADC		MOS47230
8626	2732	724		SIS R3,ADC		MOS47240
8628	2440	725	SDEC1	LIS R4,0	CLEAR MODULUS COUNTER	MOS47250
862A	4853 8A2A	726		LDA R5,DECTAB(R3)	LOAD LARGEST REQ. POWER OF 10.	MOS47260
862E	0515	727	SDEC2	CLAR R1,R5	EXCEEDS TEST VALUE ?	MOS47270
8630	2188	728		ELS SDEC3	BRANCH IF YES.	MOS47280
8632	0B15	729		SAR R1,R5	DECREMENT TEST VALUE	MOS47290
8634	2641	730		AIS R4,1	INCREMENT MODULUS COUNTER	MOS47300
8636	C540 000A	731		CLAI R4,10	VALID DECIMAL DIGIT ?	MOS47310
863A	2086	732		BLS SDEC2	BRANCH IF YES; ELSE	MOS47320
863C	274A	733		SIS R4,10	FORCE VALID DIGIT,	MOS47330
863E	2208	734		BS SDEC2	REPEAT DECREMENT.	MOS47340
8640	D344 8A34	735	SDEC3	LB R4,HEXTAB(R4)	CONVERT MODULUS COUNT TO ASCII	MOS47350
8644	D242 0000	736		STB R4,0(R2)	AND STORE AT DESTINATION MSB.	MOS47360
8648	2621	737		AIS R2,1	INCREMENT DESTINATION POINTER	MOS47370
864A	2732	738		SIS R3,ADC	DECREMENT DECTAB POINTER	MOS47380
864C	4310 8628	739		BNM SDEC1	FALL THROUGH ON DECTAB UNDERFLOW.	MOS47390
8650	D100 9E50	740		LM R0,RSAVE	RESTORE USER'S REGISTERS	MOS47400
8654	030F	741		BR LINK	RETURN.	MOS47410
742	*					MOS47420
743	*			* TO PRINT THE ASCII MESSAGE		MOS47430
744	*					MOS47440
8656	D000 9E50	745	PRINT	STM R0,RSAVE	STORE REGISTERS	MOS47450
865A	41F0 8858	746		BAL LINK,TSTDU		MOS47460
865E	2337	747		BZ P1		MOS47470
8660	4010 8A12	748		STH R1,WASDU	SET DU FLAGS	MOS47480
8664	4010 8A14	749		STH R1,WASDU1		MOS47490
8668	4300 86D4	750		B PRINT5	EXIT	MOS47500
866C	4820 8A12	751	P1	LH R2,WASDU		MOS47510
8670	4330 869E	752		BZ P3		MOS47520
8674	C810 0140	753		LDAI R1,X'140'	DELAY CONSTANT	MOS47530
8678	C800 1000	754	P4	LDAI R0,X'1000'		MOS47540
867C	27C1	755	P5	SIS R0,1		MOS47550

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867E	2031	756	BNZS	P5	MOS47560
8680	2711	757	SIS	R1,1	MOS47570
8682	2035	758	BNZS	P4	MOS47580
		759 *			LOOP TILL TIMEOUT (20 SEC FOR CRT WARM-UP)
8684	2440	760	LIS	R4,0	MOS47590
8686	4040 8A12	761	STH	R4,WASDU	MOS47600
868A	2541	762	LCS	R4,1	MOS47610
868C	4040 8A14	763	STH	R4,WASDU1	MOS47620
8690	2434	764	LIS	R3,4	MOS47630
8692	41F0 86EC	765 P2	BAL	LINK,OUTCHR	MOS47640
8696	2731	766	SIS	R3,1	MOS47650
8698	2023	767	BPS	P2	MOS47660
869A	4300 8A40	768	B	KEEP10	MOS47670
869E	4800 8ADE	769 P3	LH	RO,NOMSG+6	MOS47680
86A2	2335	770	BZS	PRINT2	MOS47690
86A4	4800 8AOC	771	LH	RO,ISITERR	MOS47700
86A8	4330 86D4	772	BZ	PRINT5	MOS47710
		773 *			NOT AN ERROR MSG. EXIT
86AC	D345 0000	774	PRINT2	LB R4,0(R5)	MOS47720
86B0	41F0 86EC	775	BAL	LINK,OUTCHR	MOS47730
86B4	274D	776	SIS	R4,13	MOS47740
86B6	2333	777	BZS	PRINT3	MOS47750
86B8	2651	778	AIS	R5,1	MOS47760
86BA	2207	779	BS	PRINT2	MOS47770
86BC	244A	780 PRINT3	LIS	R4,10	MOS47780
86BE	D310 800B	781	LB	R1,IOSAVE+1	MOS47790
86C2	2713	782	SIS	R1,3	MOS47800
86C4	2335	783	BZS	PRINT3A	MOS47810
86C6	41F0 86EC	784	BAL	LINK,OUTCHR	MOS47820
86CA	2541	785	LCS	R4,1	MOS47830
86CC	2302	786	BS	PRINT3B	MOS47840
86CE	2441	787	PRINT3A	LIS R4,1	MOS47850
86D0	41F0 86EC	788	PRINT3B	BAL LINK,OUTCHR	MOS47860
86D4	41F0 87D4	789	PRINT5	BAL LINK,TSTBRK	MOS47870
86D8	D100 9E50	790	LM	RO,RSAVE	MOS47880
86DC	03CF	791	BR	LINK	RESTORE REGISTERS
		792 *			RETURN
		793 *			----- SMALL SUPPORT ROUTINES
		794 *			
		795 *			TO OUTPUT CR,LF TO LIST DEVICE
		796 *			
86DE	D000 9E50	797	CRLF	STM RO,RSAVE	STORE REGISTERS
86E2	244D	798	LIS	R4,13	MOS47970
86E4	41F0 86EC	799	BAL	LINK,OUTCHR	MOS47980
86E8	4300 86BC	800	B	PRINT3	MOS47990
		801 *			LINE FEED, RESTORE, RETURN
		802 *			----- TO OUTPUT A CHARACTER TO THE LIST DEVICE
86EC	40F0 8A24	803	OUTCHR	STH R15,OUT,SAY	SAVE RETURN ADDRESS
86F0	D300 800B	804	LB	RO,IOSAVE+1	MOS48020
86F4	2704	805	SIS	RO,4	MOS48030
86F6	4230 8734	806	BNZ	OUTCHR2	MOS48040
86FA	4000 8A20	807	STH	RO,PAUSE	MOS48050
86FE	41F0 8858	808 OTC.O	BAL	LINK,TSTDU	MOS48060
					BRANCH IF NOT CAROUSEL
					ON LINE ?

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8702	4230 8770	809	BNZ	OUTO		MOS48090
8706	9D01	810	SSR	R0,R1	GET CAROUSEL STATUS	MOS48100
8708	2386	811	BNCS	OTC.1	BRANCH IF CHAR. IS TO BE READ	MOS48110
870A	4810 8A20	812	LH	R1,PAUSE	PAUSED NOW ?	MOS48120
870E	2038	813	BNZS	OTC.0	YES, LOOP	MOS48130
8710	4300 8734	814	B	OUTCHB2	NO, GO OUTPUT CHARACTER	MOS48140
8714	9EC1	815	OTC.1	RDR	GET CAROUSEL CHARACTER	MOS48150
8715	C410 007F	816	NAI	R1,X'7F'		MOS48160
871A	CB10 0012	817	SAI	R1,X'12'	DC2 ?	MOS48170
871E	2134	818	BNZS	OTC.3	NO, BRANCH	MOS48180
8720	4010 8A20	819	STH	R1,PAUSE	SET PAUSE FLAG	MOS48190
8724	23C8	820	BS	OUTCHR2	BRANCH	MOS48200
8726	2712	821	OTC.3	SIS	DC4 ?	MOS48210
8728	4230 86FE	822	BNZ	OTC.0	NO, GO WAIT FOR DC2	MOS48220
872C	40F0 8A20	823	STH	LINK,PAUSE	RESET PAUSE FLAG	MOS48230
8730	4300 86FE	824	B	OTC.0	GO WAIT FOR DC2	MOS48240
		825	*			MOS48250
8734	4010 8A20	826	OUTCHR2	STH	RESET FLAG	MOS48260
8738	41F0 8858	827	BAL	LINK,TSTDU	OFF-LINE ?	MOS48270
873C	4230 8770	828	BNZ	OUTO	BRANCH IF OFF-LINE	MOS48280
8740	4110 88B8	829	BAL	R1,SETUP	SET UP FOR OUTPUT	MOS48290
8744	9D01	830	OTC.4	SSR	WAIT FOR NOT BUSY	MOS48300
8746	4230 8770	831	BTG	3,OUTO	BRANCH IF OFF-LINE	MOS48310
874A	C510 000C	832	CLAI	R1,12	PASLA OFFLINE ?	MOS48320
874E	4330 8770	833	BE	OUTO	BRANCH: YES.	MOS48330
8752	C310 0008	834	TAI	R1,8	BUSY ?	MOS48340
8756	2039	835	BNZS	OTC.4	WAIT FOR NOT BUSY.	MOS48350
8758	9A04	836	WDR	R0,R4	OUTPUT DATA BYTE	MOS48360
875A	41F0 8858	837	OTC.5	BAL	DEVICE DU ?	MOS48370
875E	2139	838	BNZS	OUTO	YES, BRANCH	MOS48380
8760	D310 800B	839	LB	R1,IOSAVE+1		MOS48390
8764	0A11	840	AAR	R1,R1	(SLHLS R1,1)	****
8766	D301 8011	841	LB	R0,IO+1(R1)	GET CONSOLE WRITE ADDRESS	MOS48400
876A	9D01	842	SSR	R0,R1		MOS48410
876C	2089	843	BTBS	8,OTC.5		MOS48420
876E	2303	844	BS	OUT1	WAIT FOR NOT BUSY.	MOS48430
8770	4010 8A12	845	OUTO	STH	SET WASDU FLAG	MOS48440
8774	48F0 8A24	846	OUT1	LH		MOS48450
8778	030F	847	BR	LINK	RETURN AS SET UP ABOVE	MOS48460
		848	*			MOS48470
		849	*	TO GET A CHAR FROM KEYBOARD (IN REG R4)		MOS48480
		850	*			MOS48490
877A	4140 889C	851	GETCHR	BAL	PUT KB DEVICE IN READ MODE	MOS48500
877E	0890	852	LDAR	R9,R0	SAVE CONSOLE ADDRESS	MOS48510
8780	9D04	853	SSR	R0,R4		MOS48520
8782	2081	854	BTBS	8,1	IF BUSY, LOOP (POSSIBLE HANG) ***	MOS48530
8784	9B04	855	RDR	R0,R4	READ A CHARACTER IN R4	MOS48540
		856	*	TO ECHO RECEIVED CHARACTERS TO CONSOLE DEVICE IN FDX MODE		MOS48550
8786	D400 801A	857	ECHO	CLB	IS IT MICROBUS ?	MOS48560
878A	233B	858	BES	ECHO1	YES, BRANCH	MOS48570
878C	D390 89EC	859	LB	R9,CONRD		MOS48580
8790	C590 00A9	860	CLAI	R9,X'A9'	CAROUSEL ?	MOS48590
8794	2137	861	BNES	ECHRDN	YES, DO NOT ECHO	MOS48600
						MOS48610

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8796	D390 89EB	862	LB	R9,COMADR+1	MOS48620
879A	DD90 89E4	863	SS	R9,SINK	MOS48630
879E	2082	864	BTBS	8,2	MOS48640
87A0	9A94	865	ECHO1	WDR R9,R4	MOS48650
87A2	C440 007F	866	ECHRTN	NAI R4,X'7F'	MOS48660
87A6	03CF	867	BR	LINK	MOS48670
		868	*		MOS48680
		869	*	TO OUTPUT '?' TO CONSOLE	MOS48690
		870	*		MOS48700
87A8	41F0 86DE	871	QUESTN	BAL LINK,CRLF	MOS48710
87AC	40F0 8A0C	872	STH	LINK,ISITERR	MOS48720
87B0	C850 8A96	873	LDAI	R5,QMSG	MOS48730
87B4	41F0 8656	874	BAL	LINK,PRINT	MOS48740
87B8	2400	875	LIS	RO,0	MOS48750
87BA	4000 8A0C	876	STH	RO,ISITERR	MOS48760
87BE	4300 80CA	877	B	OPTIN1	MOS48770
		878	*		MOS48780
		879	*	IF BREAK KEY DEPRESSED, GO TO 'OPTIN' OR (BRKVECT); ELSE RETURN.	MOS48790
		880	*	BUT IF "BREAK" & CONTIN = 1, GO TO ABORT1.	MOS48800
		881	*		MOS48810
87C2	D000 9E70	882	TSTBRKX	STM RO,16*ADC+RSAVE	****
87C6	40F0 8A26	883	STH	LINK,BRK.SAV	****
87CA	C8F0 83A8	884	LDAI	LINK,TSTEND	****
87CE	40F0 8A0A	885	STH	LINK,BRKVECT	****
87D2	2305	886	BS	TSTBRK6	****
		887	*		MOS48860
		888	*		MOS48870
87D4	D000 9E70	889	TSTBRK	STM RO,16*ADC+RSAVE	MOS48880
87D8	40F0 8A26	890	STH	LINK,BRK.SAV	MOS48890
87DC	D300 89EA	891	TSTBRK6	LB RO,COMADR	MOS48900
87E0	9D01	892	SSR	RO,R1	MOS48910
87E2	4210 8848	893	BTC	1,TSTBRK3	MOS48920
87E6	C510 000C	894	CLAI	R1,X'0C'	MOS48930
87EA	4330 8848	895	BE	TSTBRK3	MOS48940
87EE	C310 0020	896	TAI	R1,X'20'	MOS48950
87F2	4330 8848	897	BZ	TSTBRK3	MOS48960
87F6	D320 8010	898	LB	R2,IO	MOS48970
87FA	C520 0005	899	CLAI	R2,5	MOS48980
87FE	2139	900	BWES	TSTBRK4	MOS48990
8800	9B02	901	TSTBRK5	RDR RO,R2	MOS49000
8802	9D01	902	SSR	RO,R1	MOS49010
8804	C310 0020	903	TAI	R1,X'20'	MOS49020
8808	4230 8800	904	BNZ	TSTBRK5	MOS49030
880C	4300 8834	905	B	TSTBRK2	MOS49040
8810	4820 89E6	906	TSTBRK4	LH R2,PASFLG	MOS49050
8814	233C	907	BZS	TSTBRK1	MOS49060
8816	C310 0008	908	TAI	R1,8	MOS49070
881A	4230 8848	909	BNZ	TSTBRK3	MOS49080
881E	9B02	910	RDR	RO,R2	MOS49090
8820	9D01	911	SSR	RO,R1	MOS49100
8822	2281	912	BFBS	8,1	MOS49110
8824	0822	913	LDAR	R2,R2	MOS49120
8826	4230 8848	914	BNZ	TSTBRK3	MOS49130
				ZERO CHARACTER ?	MOS49140
				BRANCH: JUST FRAMING ERROR	

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882A	2305	915	BS	TSTBRK2	MOS49150
882C	9E01	916	TSTBRK1	SSR R0,R1	MOS49160
882E	C310 0020	917	TAI	R1,X'20'	MOS49170
8832	2033	918	BNZS	TSTBRK1	MOS49180
8834	48F0 8AD2	919	TSTBRK2	LH LINK,CONTIN+6	*** MOS49190
8838	4230 8BF6	920	BNZ	OPTIN2	*** MOS49200
883C	48F0 8A0A	921	LH	R15,BRKVECT	MOS49210
8840	4330 8BF6	922	BZ	OPTIN2	MOS49220
8844	40F0 8A26	923	STH	R15,BRK.SAV	MOS49230
8848	2400	924	TSTBRK3	LIS R0,0	MOS49240
884A	40C0 8A0A	925	STH	R0,BRKVECT	MOS49250
884E	D1C0 9E70	926	LM	R0,16*ADC+RSAVE	MOS49260
8852	48F0 8A26	927	LH	LINK,BRK.SAV	MOS49270
8856	030F	928	BR	LINK	MOS49280
		929	*		MOS49290
		930	*	SEE IF CURRENT LIST DEVICE IS OFF-LINE (R1, CC NON-ZERO IF OFF)	MOS49300
		931	*		MOS49310
8858	2401	932	TSTDU	LIS R0,1	MOS49320
885A	4810 89E6	933		LH R1,PASFLG	MOS49330
885E	2333	934		BZS STSTDU0	MOS49340
8860	C8C0 00FC	935		LDAI R0,X'FC'	MOS49350
8864	D310 800B	936	STSTDU0	LB R1,IOSAVE+1	GET LIST DEVICE IDENTIFIER (R1) = 2,4,6,8,A... (SLHS R1,1)****
8868	0A11	937		AAR R1,R1	MOS49370
886A	D311 8010	938		LB R1,IO(R1)	MOS49380
886E	D210 89E4	939		STB R1,SINK	SAVE LIST DEVICE ADDRESS
8872	9D11	940		SSR R1,R1	MOS49390
8874	0410	941		NAR R1,RO	MOS49400
8876	C310 0001	942		TAI R1,1	MOS49410
887A	2135	943		BNZS STSTDU2	MOS49420
887C	C510 000C	944		CLAI R1,X'0C'	MOS49430
8880	2332	945		BES STSTDU2	MOS49440
8882	2511	946	STSTDU1	LCS R1,1	MOS49450
8884	D300 89E4	947	STSTDU2	LB R0,SINK	MOS49460
8888	C710 FFFF	948		XAI R1,-1	MOS49470
888C	030F	949		BR LINK	MOS49480
		950	*		MOS49490
		951	*	TO DIRECT INPUT AND OUTPUT TO CONSOLE DEVICE	MOS49500
		952	*		MOS49510
888E	D300 8010	953	SETKB	LB R0,IO	GET KEYBOARD DEVICE
8892	9410	954		EXBR R1,RO	MOS49530
8894	0610	955		OAR R1,RO	MOS49540
8896	4010 800A	956		STH R1,IOSAVE	MOS49550
889A	030F	957		BR LINK	MOS49560
		958	*		MOS49570
		959	*	TO PUT KEYBOARD DEVICE IN READ MODE	MOS49580
		960	*		MOS49590
889C	D300 89EA	961	KBREAD	LB R0,CONADR	MOS49600
88A0	DE00 89EC	962		OC R0,CONRD	MOS49610
88A4	DBC0 89E4	963		RD R0,SINK	MOS49620
88A8	4890 89E6	964		LH R9,PASFLG	MCS49630
88AC	4200 88AC	965		NOP *	MOS49640
88B0	2333	966	TTYGET	BZS KBXIT	MOS49650
88B2	DEC0 8A04	967		CC R0,CONRQ2S	MOS49660
					MOS49670

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88B6	0304	968	KBXIT	BR	R4	RETURN		MOS49680
		969	*				***	MOS49690
		970	* LIST DEVICE SET UP ROUTINE					MOS49700
		971	*					MOS49710
88B8	4010 8A28	972	SETUP	STH	R1,SET.RTN			MOS49720
88BC	D310 800B	973		LB	R1,IOSAVE+1	GET LIST DEVICE IDENTIFIER	****	MOS49730
88C0	0A11	974		AAR	R1,R1	HW INDEX (SLHS R1,1)		MOS49740
88C2	D3C1 8011	975		LB	R0,IO+1(R1)	GET LIST DEVICE ADDRESS		MOS49750
88C6	DEC1 89ED	976		OC	R0,CONWR(R1)			MOS49760
88CA	4810 8A28	977		LH	R1,SET.RTN			MOS49770
88CE	0301	978		BB	R1	RETURN	***	MOS49780
		979	*					MOS49790
		980	* LCW CCBE SET UP ROUTINE					MOS49800
		981	*					MOS49810
88D0	2410	982	LCORE	LIS	R1,0			MOS49820
88D2	2422	983		LIS	R2,2			MOS49830
88D4	C830 004E	984		LDAI	R3,X'4E'			MOS49840
88D8	24C0	985		LIS	R0,0			MOS49850
88DA	4840 0020	986		LH	R4,X'20'	SAVE CONSOLE STATUS		MOS49860
88DE	4001 0000	987	ZERO1	STH	R0,0(R1)			MOS49870
88E2	C110 88DE	988		BXLE	R1,ZERO1	ZERO CORE FROM 0 THRU X'4F'		MOS49880
88E6	4040 0020	989		STH	R4,X'20'	RESTORE CONSOLE STATUS		MOS49890
88EA	C830 8922	990		LDAI	R3,II			MOS49900
88EE	4030 0036	991		STH	R3,X'36'	ILL INST INT NEW PSW LOC		MOS49910
88F2	C840 895A	992		LDAI	R4,MM			MOS49920
88F6	4040 003E	993		STH	R4,X'3E'	M. M. INT NEW PSW LOC		MOS49930
88FA	C840 9E50	994		LDAI	R4,RSAVE			MOS49940
		995	*					MOS49950
		996	* SET UP LOW CORE FOR 16 BIT MACHINE					MOS49960
		997	*					MOS49970
88FE	4040 0022	998		STH	R4,X'22'	REG SAVE POINTER		MOS49980
8902	030F	999		BR	LINK	RETURN	***	MOS49990
		1000	*					MOS50000
		1001	* SPURIOUS INTERRUPT HANDLERS					MOS50010
		1002	*					MOS50020
		1003	*					MOS50030
		1004	*					MOS50040
8904	40E0 89E0	1005	COMM	STH	R14,OPSW			MOS50050
8908	40F0 89E2	1006		STH	R15,OLOC			MOS50060
890C	4800 8008	1007	COMM1	LH	R0,PSW2			MOS50070
8910	9520	1008		EPSR	R2,R0	NO INT. , REG SET 15		MOS50080
8912	41F0 8502	1009		BAL	LINK,ERR	PRINT "ERROR XXFN"		MOS50090
8916	40F0 8A0C	1010		STH	LINK,ISITEBR	FORCE PRINT		MOS50100
891A	41E0 855E	1011		BAL	RET,ERRPL1	PRINT "PSW PPPP LOC LLLL"		MOS50110
891E	4300 80CA	1012		B	OPTIN1	ENTER COMMAND MODE		MOS50120
		1013	*					MOS50130
		1014	* ILLEGAL INSTRUCTION INTERRUPT TRAP					MOS50140
		1015	*					MOS50150
8922	C820 895A	1016	II	LDAI	R2,MM	*	***	MOS50160
8926	4020 003E	1017		STH	R2,X'3E'	RESTORE ETPE MM POINTER	***	MOS50170
892A	C820 4632	1018		LDAI	R2,C'F2'			MOS50180
892E	4020 8A56	1019		STH	R2,ERRNO	SET ERROR NUMBER F2		MOS50190
8932	48E0 0030	1020		LH	R14,X'30'	OLD PSW		MOS50200

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8936	48E0 0032	1021	LH	R15,X'32'	OLD LOC	MOS50210
893A	4300 8904	1022	II32	B COMM	*	*** MOS50220
		1023	*			MOS50230
		1024	*	MACHINE MALFUNCTION INTERRUPT TRAP		MOS50240
		1025	*			MOS50250
		1026	MM0	EPSR R14,R14	CAPTURE MMINT PSW	*** MOS50260
		1027	LDAI	R2,MM	*	*** MOS50270
		1028	STH	R2,X'3E'	RESTORE ETPE MM POINTER	*** MOS50280
		1029	LDAR	R10,R14		MOS50290
		1030	NAI	R10,X'000F'	*	*** MOS50300
		1031	TAI	R10,6	CC = MEMORY ERROR ?	*** MOS50310
		1032	BZS	MM1	NO, BRANCH	*** MOS50320
		1033	BAL	LINK,PARERR	YES, PRINT ERROR (PARITY)	*** MOS50330
		1034	BS	MM1	*	*** MOS50340
		1035	*			*** MOS50350
		1036	MM	EPSR R10,R10	CAPTURE MMINT PSW	*** MOS50360
		1037	NAI	R10,X'000F'	*	*** MOS50370
		1038	MM1	LDAI R2,C'F3'		MOS50380
		1039	STH	R2,ERRNO	SET ERROR NUMBER F3	MOS50390
		1040	LH	R14,X'38'	OLD PSW (16 BIT PROCESSOR)	MOS50400
		1041	LH	R15,X'3A'	OLD LOC	MOS50410
		1042	MM32	NAI R14,X'FFF0'		MOS50420
		1043	OAR	R14,R10	R14 = COMPOSITE PSW	MOS50430
		1044	STH	R14,OPSW		MOS50440
		1045	STH	R15,CLOC		MOS50450
		1046	LDAI	R1,X'7FFF'		MOS50460
		1047	MM16	SIS R1,1	TIMEOUT	MOS50470
		1048	BPS	MM16		MOS50480
		1049	LDAI	R0,X'80F0'	R0 = X'80F0'	*** MOS50490
		1050	EPSR	R2,R0	HALT PROCESSOR	MOS50500
		1051	*			MOS50510
		1052	*	WHEN EXE/RUN IS DEPRESSED, ERROR MSG IS PRINTED.		MOS50520
		1053	*			MOS50530
		1054	MMC0M	LB R2,IO	GET CONSOLE DEVICE POINTER	MOS50540
		1055	SIS	R2,5	IS CONSOLE ON MICRO-IC BUS ?	MOS50550
		1056	BZS	MMC0MA	YES, BRANCH	MOS50560
		1057	LH	R2,PASFLG	IS CONSOLE ON PASLA ?	MOS50570
		1058	BZS	MMC0M1	NO, BRANCH	MOS50580
		1059	MMC0MA	LB R1,IO	YES, GET CONSOLE DEVICE IDENT	MOS50590
		1060	AAB	R1,R1	SET INDEX (SLHLS R1,1)	**** MOS50600
		1061	LB	R2,IO(R1)	GET CONSOLE DEVICE ADDRESS	MOS50610
		1062	OC	R2,CON2ND(R1)	ISSUE CONSOLE SPEED COMMAND	MOS50620
		1063	OC	R2,CONRD	ISSUE CONSOLEREAD COMMAND	MOS50630
		1064	RD	R2,SINK	DUMMY READ TO SET BUSY	MOS50640
		1065	*			MOS50650
		1066	MMC0M1	LB R1,IO+1	GET LIST DEVICE POINTER	MOS50660
		1067	SIS	R1,5	IS LIST DEVICE ON MICRO-IO BUS ?	MOS50670
		1068	BZS	MMC0M1A	YES, BRANCH	MOS50680
		1069	LH	R1,PASFLG2	IS LIST DEVICE ON PASLA ?	MOS50690
		1070	BZS	MMC0M2	NO, BRANCH	MOS50700
		1071	MMC0M1A	LB R1,IO+1	YES, GET LIST DEVICE POINTER	MOS50710
		1072	LB	R2,IO	GET CONSOLE POINTER	MOS50720
		1073	CLAR	R1,R2	CONSOLE = LIST DEVICE ?	MOS50730

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89C8	2338	1074	BES	MNCOM2	YES, BRANCH	MOS50740
89CA	0A11	1075	AAR	R1,R1	NO, SET INDEX (SLHLS R1,1) ****	MOS50750
89CC	D321 8011	1076	LB	R2,I0+1(R1)	GET LIST DEVICE ADDRESS	MOS50760
89D0	DE21 89F8	1077	OC	R2,LST2ND(R1)	ISSUE LIST SPEED COMMAND	MOS50770
89D4	DE21 89ED	1078	OC	R2,LSTWRT(R1)	ISSUE LIST WRITE COMMAND	MOS50780
		1079 *				MOS50790
89D8	4300 890C	1080	MNCOM2	B COMM1		MOS50800
		1081	*	*****		MOS50810
		1082	*	ETPE CONSTANTS & TABLES		MOS50820
		1083	*			MOS50830
89E0		1084		ALIGN 8		MOS50840
		1085	*			MOS50850
89E3	0000	1086	OPSW	DCX 0		MOS50860
89E2	0000	1087	OLOC	DCX 0		MOS50870
		1088	*			MOS50880
89E4	00	1089	SINK	DB 0	BIT BUCKET	MOS50890
89E5	00	1090		DB *		MOS50900
89E6	0000	1091	PASFLG	DCY 0	SET WHEN CONSOLE ON PASLA/PALM	MOS50910
89E8	0000	1092	PASFIG2	DCX 0	SET WHEN LIST DEVICE ON PASLA	MOS50920
		1093	*			MOS50930
		1094	*	ETPE IO COMMANDS		MOS50940
		1095	*			MOS50950
89EA	0000	1096	CONADR	DCX 0	CONSOLE DEVICE ADDRESS	MOS50960
89EC	0000	1097	COMBD	DCX 0	CONSOLE READ/WRITE COMMANDS	MOS50970
	0000 89ED	1098	CONWR	EQU CONRD+1		MOS50980
	0000 89ED	1099	LSTWRT	EQU CONWR	LIST DEVICE WRITE COMMAND	MOS50990
89EE	B1A3	1100	CRTRD	DCX B1A3	FOR CRT	MOS51000
89F0	A4D8	1101	CLIFRD	DCX A4D8	* CURRENT LOOP INTERFACE	MOS51010
89F2	0080	1102	LPWRT	DCX 0080	* LINE PRINTER	MOS51020
89F4	A1A3	1103	CARRD	DCX A1A3	* CAROUSEL 300	MOS51030
89F6	8202	1104	MREADC	DCX 8202	* MICROBUS	MOS51040
		1105	*			MOS51050
89F8	0000	1106	CON2ND	DCX 0	2ND COMMAND; ENABLE READ COMMAND	MOS51060
	0000 89F8	1107	LST2ND	EQU CON2ND	LIST DEVICE SPEED COMMAND	MOS51070
	0000 89F9	1108	COMEWRD	EQU CON2ND+1		MOS51080
89FA	F871	1109	CRT2ND	DCX F871	FOR CRT	MOS51090
89FC	0064	1110	CLIF2ND	DCX 0064	* CURRENT LOOP INTERFACE	MOS51100
89FE	0000	1111	DCX	0	* DUMMY HW FOR LP	MOS51110
8A00	F061	1112	CAR2ND	DCX F061	* CAROUSEL 300	MOS51120
8A02	0300	1113	DCX	0300	* DUMMY HW FOR MICROBUS	MOS51130
		1114	*			MOS51140
8A04	00	1115	CONRQ2S	DB 0	CONSOLE REQUEST TO SEND CMD	MOS51150
8A05	33	1116	CRTRQ2S	DB X"33"	FOR CRT	MOS51160
8A06	00	1117	DB	0	* DUMMY BYTE FOR CLI	MOS51170
8A07	00	1118	DB	0	* DUMMY BYTE FOR LP	MOS51180
8A08	23	1119	CARRQ2S	DB X"23"	* CAROUSEL 300	MOS51190
8A09	00	1120	DB	0	* DUMMY BYTE FOR MICROBUS	MOS51200
8A0A		1121	DB	*		MOS51210
		1122	*			MOS51220
8A0A	0000	1123	BRKVECT	DC Z(0)	BREAK KEY VECTOR	MOS51230
8A0C	0000	1124	ISITERR	DCX 0		MOS51240
8A0E	0000	1125	NOERR	DCX 0		MOS51250
8A10	0000	1126	SELTST	DCX 0	HIGHEST SELECTED TEST NUMBER	MOS51260

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8A12 0000	1127 WASDU	DCX	0	1 IF KEYBOARD DEVICE WAS OFF NON-ZERO IF TOTAL,TOTERR TO PRINT	MOS51270
8A14 0000	1128 WASDU1	DCX	0	NO. OF TIMES THE SELECTED TESTS RUN	MOS51280
8A16 0000	1129 TOTAL	DCX	0	TOTAL ERRORS DETECTED WHILE DU	MOS51290
8A18 0000	1130 TOTERR	DCX	0	CURRENT TEST NO. IN BINARY	MOS51300
8A1A 0000	1131 BTESTNO	DCX	0		MOS51310
8A1C 0000	1132 COUNT	DCX	0		MOS51320
8A1E 0000	1133 NEXTST	DCX	0	NEXT TEST NUMBER	MOS51330
8A20 0000	1134 PAUSE	DCX	0		MOS51340
	1135 *				***
8A22 0000	1136 COMRET	DCX	0		MOS51360
8A24 0000	1137 CUT.SAV	DCX	0		MOS51370
8A26 0000	1138 BRK.SAV	DCX	0		MOS51380
8A28 0000	1139 SET.RTN	DCX	0		MOS51390
	1140 *				MOS51400
8A2A 0001	1141 DECTAB	DC	1,10,100,1000,10000		MOS51410
8A2C 00CA					
8A2E 0064					
8A30 03E8					
8A32 2710					
8A34 3031 3233 3435 3637	1142 HEXTAB	DB	C'0123456789ABCDEF'		MOS51420
8A3C 3839 4142 4344 4546	1143	DB	*		MOS51430
	1145 *				
	1146 * ETPE MESSAGES				
	1147 *				
8A44 5445 5354 2020 2A2A	1148 TSTMSG	DC	C'TEST ***,X'0D00'		MOS51450
8A4C 0D00					MOS51460
0000 8A4A	1149 MTESTNO	EQU	TSTMSG+6		MOS51470
8A4E 45E2 524F 5220 2A2A	1150 ERMSG	DC	C'ERROR *****,X'0D00'		MOS51480
8A56 2A2A					MOS51490
8A58 0D00					MOS51500
0000 8A54	1151 ETESTNO	EQU	ERMSG+6	STORED BY ETPE	MOS51510
0000 8A56	1152 ERNO	EQU	ERMSG+8	STORE ERNO AS CHAR CONSTANT	MOS51520
8A5A 544F 5441 4C20 2020	1153 TOTMSG	DC	C'TOTAL TOTERR',X'0D00'		MOS51530
8A62 544F 5445 5252					
8A68 0D00					
8A6A 4E4F 2045 5252 4F52	1154 NOERMSG	DC	C'NO ERROR',X'0D00'		MOS51540
8A72 0D00					
8A74 5053 5720 2A2A 2A2A	1155 PSWMSG	DC	C'PSW **** LOC *****,X'0D00'		MOS51550
8A7C 2020 4C4F 4320 2A2A					
8A84 2A2A					
8A86 0D00					
0000 8A78	1156 ASCIPSW	EQU	PSWMSG+4		MOS51560
0000 8A7E	1157 LOCMRG	EQU	PSWMSG+10		MOS51570
0000 8A82	1158 ASCILOC	EQU	PSWMSG+14		MOS51580
8A88 454E 4420 4F46 2054	1159 EOTMSG	DC	C'END OF TEST',X'0D00'		MOS51590
8A90 4553 5420					
8A94 0D00					
8A96 3F0D	1160 QMSG	DC	X'3F0D'		MOS51600
8A98 2A0D	1161 AMSG	DC	X'2A0D'		MOS51610

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8A9A	FFFF	1162	BRKMSG	DC	X'FFFF',X'FFFF',C'BREAK TERMINATION',X'FFFF',X'ODOA'	MOS51620
8A9C	FFFF					
8A9E	4252 4541 4B20 5445					
8AA6	524D 494E 4154 494F					
8AAE	4E20					
8AB0	FFFF					
8AB2	ODOA					
		1164	*	*****	*****	MOS51640
		1165	*	OPTION/COMMAND TABLE		MOS51650
		1166	*			MOS51660
8AB4	0000 8AB4	1167	OPT	EQU *		MOS51670
8AC4	5445 5354 2020	1168	TEST	DC	C'TEST ',X'F800',X'0',X'0' *	MOS51680
8ABA	F800					
8ABC	0000					
8ABE	0000					
8AC0	4C4F 4F50 2020	1169	LOOP	DC	C'LOOP ',X'0',Z(LEVELIN),X'7FFF' *	MOS51690
8AC6	0000					
8AC8	82AE					
8ACA	7FFF					
8ACC	434F 4E54 494E	1170	CONTIN	DC	C'CONTIN',X'0',Z(LEVELIN),X'1' *	MOS51700
8AD2	0000					
8AD4	82AE					
8AD6	0001					
8AD8	4E4F 4D53 4720	1171	NOMSG	DC	C'NOMSG ',X'0',Z(LEVELIN),X'1' *	MOS51710
8ADE	0000					
8AE0	82AE					
8AE2	0001					
8AE4	5343 4F50 4520	1172	SCOPE	DC	C'SCOPE ',X'0',Z(LEVELIN),X'5' *	MOS51720
8AEA	0000					
8AEC	82AE					
8AEE	0005					
8AF0	4441 5441 2020	1173	DATA	DC	C'DATA ',X'FFFF',X'0',X'0' *	MOS51730
8AF6	FFFF					
8AF8	0000					
8AFA	0000					
8AFC	504F 554E 4420	1174	POUND	DC	C'POUND ',X'A',X'0',X'0' *	MOS51740
8B02	000A					
8B04	0000					
8B06	0000					
8B08	434F 4E20 2020	1175	CONSOLE	DC	C'CON ',X'0',Z(CON),X'0' *	**** MOS51750
8B0E	0000					
8B10	8B46					
8B12	0000					
	0000 8B14	1176	OPTEND2	EQU *		MOS51760
	0000 8B14	1177	OPTEND	EQU	OPTEND2	MOS51770
		1178	*			MOS51780
		1179	*	*****	*****	MOS51790
		1180	*			MOS51800
8B14	4C4F 4C49 4D20	1181	LOLIM	DC	C'LOLIM ',X'0',Z(LEVELIN),X'7FFC' *	0000 MOS51810
8B1A	0000					

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8B1C	82AE							
8B1E	7FFC							
8B20	4849 4C49 4D20	1182	HILIM	DC	C'HILIM ',X'7FFF',Z(LEVELIN),X'7FFF'* 7FFF			MOS51820
8B26	7FFF							
8B28	82AE							
8B2A	7FFF							
		1183	*		*****			MOS51830
		1184	*		*****			MOS51840
8B2C	4F50 5449 4F4E	1185	OPTION	DC	C'OPTION',X'0',X'0',X'0'			MOS51850
8B32	00C0							
8B34	00C0							
8B36	00C0							
8B38	5255 4E20 2020	1186	RUN	DC	C'RUN ',X'0',X'0',X'0'			MOS51860
8B3E	00C0							
8B40	0000							
8B42	0000							
8B44	FFFF	1187		DC	-1			MOS51870
		1188	*		*****			MOS51880
		1189	*		*****			MOS51890
8B46	8800	1190	CON	ECX	8800	RETURN TO CONSOLE (ILLEGAL)	****	MOS51900
8B48	43C0 80BE	1191		B	OPTIN	RETURN TO EXEC	****	MOS51910
		1192	*					MOS51920
		1193	*					MOS51930
		1194	*					MOS51940
8B4C	48E0 8ABA	1195	INIT	LH	R14,TEST+6			MOS51950
8B50	C6E0 8000	1196		OAI	R14,X'8000'	FORCE TEST 0		MOS51960
8B54	40E0 8ABA	1197		STH	R14,TEST+6			MOS51970
8B58	C3F0 0040	1198		TAI	R14,X'40'	IS TEST 9 SELECTED ?		MOS51980
8B5C	2335	1199		BZS	INIT6	NO, BRANCH		MOS51990
8B5E	C3E0 0020	1200		TAI	R14,X'20'	YES, IS TEST A SELECTED ?		MOS52000
8B62	4230 8BEO	1201		BNZ	ILTPRT	YES, BRANCH		MOS52010
		1202	*					MOS52020
8B66	08EF	1203	INIT6	LDAB	R14,LINK	SAVE RETURN ADDRESS		MOS52030
8B68	48F0 8B1A	1204		LH	LINK,LOLIM+6	GET LOLIM		MOS52040
8B6C	C5F0 7FFF	1205		CLAI	LINK,X'7FFF'	IS IT BELOW TEST PRGM ?		MOS52050
8B70	4380 8BE6	1206		BNL	HIOPRT	NO, BRANCH TO ERROR		MOS52060
8B74	45F0 8B26	1207		CLH	LINK,HILIM+6	IS LOLIM > HILIM ?		MOS52070
8B78	4380 8BE6	1208		BNL	HIOPRT	NO, BRANCH TO ERROR		MOS52080
8B7C	48F0 8B26	1209		LH	LINK,HILIM+6	GET HILIM		MOS52090
8B80	C5E0 8000	1210		CLAI	LINK,X'8000'	IS IT BELOW TEST PROGRAM ?		MOS52100
8B84	4380 8BE6	1211		BNL	HIOPRT	NO, BRANCH TO ERROR		MOS52110
8B88	2411	1212		LIS	R1,1			MOS52120
8B8A	DE10 800E	1213		OC	R1,NORM	PUT DISPLAY IN NORMAL MODE		MOS52130
8B8E	48C0 0020	1214		LH	R12,X'20'	SAVE CONSOLE STATUS		MOS52140
8B92	2531	1215		LCS	R3,1			MOS52150
8B94	41D0 8BB8	1216		BAL	R13,INIT1	TEST LOW MEMORY WITH -1		MOS52160
8B98	C830 AAAA	1217		LDAI	R3,X'AAAA'			MOS52170
8B9C	41D0 8BB8	1218		BAL	R13,INIT1	TEST LOW MEMORY WITH AAAA		MOS52180
8BA0	C830 5555	1219		LDAI	R3,X'5555'			MOS52190
8BA4	41D0 8BB8	1220		BAL	R13,INIT1	TEST LOW MEMORY WITH 5555		MOS52200
8BA8	2430	1221		LIS	R3,0			MOS52210
8BAA	41D0 8BB8	1222		BAL	R13,INIT1	TEST LOW MEMORY WITH 0		MOS52220
8BAE	41F0 88D0	1223		BAL	LINK,LCORE	RE-INITIALIZE LOW MEMORY		MOS52230

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8BB2 40C0 0020	1224	STH	R12,X'20'		MOS52240	
8BB6 03CE	1225	BR	R14	RESTORE CONSOLE STATUS RETURN TO INITRET (EXEC)	MOS52250	
	1226 *				MOS52260	
	1227 -----				MOS52270	
8B88 2460	1228	INIT1	LIS	R6,0	MOS52280	
8BBA 2472	1229		LIS	R7,2	MOS52290	
8BBC C880 003E	1230		LDAI	R8,X'3E'	MOS52300	
8BC0 4036 0000	1231	INIT2	STH	R3,0(R6)	MOS52310	
8BC4 C160 8BC0	1232		BXLE	R6,INIT2	MOS52320	
8BC8 2460	1233		LIS	R6,0	MOS52330	
8BCA 9426	1234	INIT3	EXBR	R2,R6	MOS52340	
8BCC 9812	1235		WHR	R1,R2	MOS52350	
8BCE 4846 0000	1236		LH	R4,0(R6)	MOS52360	
8BD2 0543	1237		CLAR	R4,R3	MOS52370	
8BD4 2333	1238		BES	INIT4	MOS52380	
8BD6 41F0 9BAE	1239		BAL	LINK,ERROR	MOS52390	
8BDA C160 8BCA	1240	INIT4	BXLE	R6,INIT3	MOS52400	
8BDE 03CD	1241		BR	R13	MOS52410	
	1242 -----				MOS52420	
	1243 *				MOS52430	
8BE0 C850 9CE2	1244	ILTSPRT	LDAI	R5,TSTREJ	PRINT: "ILLEGAL TEST SEQUENCE"	MOS52440
8BE4 23C3	1245		BS	HILOPRT1	BRANCH	MOS52450
	1246 *				MOS52460	
8BE6 C850 9CC8	1247	HILOPRT	LDAI	R5,HILOMSG	PRINT: "LOLIM > HILIM IS ILLEGAL"	MOS52470
	1248 *				MOS52480	
8BEA 4050 8AOC	1249	HILOPRT1	STH	R5,ISITERR	UNCONDITIONALLY PRINT:	MOS52490
8BEE 41F0 8656	1250		BAL	LINK,PRINT	ABORT TESTING SEQUENCE	MOS52500
8BF2 4300 80BE	1251		B	OPTIN		MOS52510
	1252 *				MOS52520	
	1253 * *****				MOS52530	
	1254 *				MOS52540	
8BF6 C850 8A9A	1255	OPTIN2	LDAI	R5,BRKMSG	PRINT: "BREAK TERMINATION" ****	MOS52550
8BFA 2208	1256		BS	HILOPRT1	BRANCH ****	MOS52560
	1257 *				MOS52570	
	1258 * *****				MOS52580	
8BFC 5331 3620 3139 2D32	1259	TITLE	DC	C'S16 19-221 MOS MEMORY TEST PART 2 '		MOS52590
8C04 3231 204D 4F53 204D						
8C0C 454D 4F52 5920 5445						
8C14 53E4 2050 4152 5420						
8C1C 3220						
8C1E 3036 2D32 3134 4630	1260		DC	C'06-214F02R00'	TEST PROGRAM NUMBER	MOS52600
8C26 3252 3030	1261		DC	X'0D0A'		MOS52610
8C2A 0D0A	1262 *					MOS52620
8C2C F800	1263	DEFTESTS	DCX	F800	DEFINES TESTS 0,1,2,3, & 4	MOS52630
	1264 *				AS THE DEFAULT TESTS	MOS52640
8C2E 000A	1265	MAXTST	DCX	A	DEFINES TESTS 0,1,2,3,4,5,6,7,8,9&A	MOS52650
	1266 *				AS LEGAL TEST NUMBERS.	MOS52660
	1268 *					MOS52680
	1269 * TESTS TABLE					MOS52690

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	1270 *				
8C30	1271	ALIGN 4			MOS52700
8C30 8C46	1272 TESTS	DC A(TEST0)	MEMORY SEARCH TEST		MOS52710
8C32 8C8A	1273	DC A(TEST1)	BIT SET-RESET TEST		MOS52720
8C34 8D1A	1274	DC A(TEST2)	MARCHING PATTERN TEST		MOS52730
8C36 8E34	1275	DC A(TEST3)	O & 1 WALK TEST		MOS52740
8C38 8EE6	1276	DC A(TEST4)	DOUBLE OPERATION COLUMN DISTURB TEST		MOS52750
8C3A 9072	1277	DC A(TEST5)	SHORT COUNT RELOCATABLE		MOS52760
	1278 *		HAMMER DISTURB TEST		MOS52770
8C3C 91F8	1279	DC A(TEST6)	DIAGONAL GALPAT TEST		MOS52780
8C3E 9380	1280	DC A(TEST7)	MEMORY HOLD TEST		MOS52790
8C40 94F2	1281	DC A(TEST8)	LONG COUNT RELOCATABLE		MOS52800
	1282 *		HAMMER DISTURB TEST		MOS52810
8C42 967A	1283	DC A(TEST9)	ECC DISTURB TEST		MOS52820
8C44 9912	1284	DC A(TESTA)	PARITY DISTURB TEST		MOS52830
	1285 * *****				MOS52840
	1286 * END	ETPE R03-05 (MODIFIED)		***	MOS52850
					MOS52860

TEST 0

1288 * TEST 0 MEMORY SEARCH TEST MOS52880
 1289 *
 1290 * PURPOSE: MOS52890
 1291 * THIS UTILITY ENABLES THE USER TO LIST EXISTANT, MOS52900
 1292 * RESPONSIVE LIMITS OF MEMORY. MOS52910
 1293 *
 1294 * ASSUMPTIONS: MOS52920
 1295 * MINIMUM MEMORY ALLOWABLE IS 64K BYTES. MOS52930
 1296 *
 1297 * DESIGN SPECIFICATIONS: MOS52940
 1298 * FORCE MEMORY LIMITS OF 0000-7FFF MOS52950
 1299 *
 1300 * OPTIONS: NONE MOS52960
 1301 *
 1302 * HOW TO RUN THE TEST: MOS52970
 1303 * ENTER "RUN" AND THE AVAILABLE MEMORY LOCATIONS WILL MOS52980
 1304 * BE PRINTED ON THE LIST DEVICE. MOS52990
 1305 *
 1306 * NOTE: MOS53000
 1307 * THIS TEST RESETS "LOLIM" AND "HILIM" TO CORRESPOND MOS53010
 1308 * TO THE BLOCK OF MEMORY PRINTED OUT. MOS53020
 MOS53030
 MOS53040
 MOS53050
 MOS53060
 MOS53070
 MOS53080

8C46 2460	1310 TEST0	LIS R6,0		MOS53100
8C48 4060 8B1A	1311 STH R6,LOLIM+6	STORE X'0' IN LOLIM		MOS53110
8C4C C880 7FFF	1312 LDAI R8,X'7FFF'			MOS53120
8C50 4080 8B26	1313 STH R8,HILIM+6	STORE X'7FFF' IN HILIM		MOS53130
8C54 24C4	1314 LIS R0,4			MOS53140
8C56 0816	1315 LDAB R1,R6			MOS53150
8C58 C820 9D6B	1316 LDAI R2,LOMSG+1			MOS53160
8C5C 41F0 85F6	1317 BAL LINK,HEXASC	PUT LOLIM IN MEMORY MESSAGE		MOS53170
8C60 0818	1318 LDAR R1,R8			MOS53180
8C62 C820 9D71	1319 LDAI R2,HIMSG+1			MOS53190
8C66 41F0 85F6	1320 BAL LINK,HEXASC	PUT HILIM IN MEMORY MESSAGE		MOS53200
8C6A C810 2030	1321 LDAI R1,C' 0'			MOS53210
8C6E D210 9D6A	1322 STB R1,LOMSG	PUT 0 IN FIRST MEMORY PRINTOUT		MOS53220
8C72 D210 9D70	1323 STB R1,HIMSG	PUT 0 IN SECOND MEMORY PRINTOUT		MOS53230
8C76 C850 9CB6	1324 LDAI R5,ASMEMMSG	LOAD MESSAGE ADDRESS		MOS53240
8C7A 41F0 8656	1325 BAL LINK,PRINT	PRINT MEMORY MESSAGE		MOS53250
8C7E C850 9D6A	1326 LDAI R5,LOMSG			MOS53260
8C82 41F0 8656	1327 BAL LINK,PRINT	PRINT LIMITS OF MEMORY UNDER TEST		MOS53270
8C86 43C0 83CE	1328 B KEEP7			MOS53280
	1329 * *****			MOS53290
	1330 * END TEST 0			MOS53300

TEST 1

1332 * TEST 1 BIT SET - RESET TEST MOS53320
 1333 *
 1334 * PURPOSE: MOS53330
 1335 * THIS TEST INSURES THAT ALL BITS IN THE AREA OF MEMORY MOS53340
 1336 * BEING TESTED CAN BE BOTH SET AND RESET. MOS53350
 1337 *
 1338 * ASSUMPTIONS: MOS53360
 1339 * MINIMUM 64KB MOS MEMORY MOS53370
 1340 *
 1341 * DESIGN SPECIFICATIONS: MOS53380
 1342 * 1. A WRITE AND THEN A READ IS EXECUTED TO ALL MEMORY MOS53390
 1343 * WITHIN THE "LOLIM" AND "HILIM" LIMITS. MOS53400
 1344 * 2. IF AN ERROR IS DETECTED, THE "SCOPE" OPTION MOS53410
 1345 * DICTATES HOW THE PROGRAM WILL REACT. MOS53420
 1346 *
 1347 * OPTIONS: MOS53430
 1348 * SCOPE - ERROR OPTION MODE MOS53440
 1349 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS53450
 1350 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS53460
 1351 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS53470
 1352 * 3 - PRINT ERROR DATA AND HALT MOS53480
 1353 * 4 - IGNORE ERROR MOS53490
 1354 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS53500
 1355 *
 1356 * HOW TO RUN THE TEST:
 1357 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE. MOS53510
 1358 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS53520
 MOS53530
 MOS53540
 MOS53550
 MOS53560
 MOS53570
 MOS53580

8C8A 4860 8B1A	1360 TEST1	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS53600
8C8E 4880 8B26	1361	LH R8,HILIM+6		MOS53610
8C92 2472	1362	LIS R7,2		MOS53620
8C94 2411	1363	LIS R1,1		MOS53630
8C96 2531	1364	LCS R3,1		MOS53640
	1365 *			MOS53650
8C98 C360 7FC0	1366 STORE11	TAI R6,X'7FC0'		MOS53660
8C9C 2133	1367	BNZS T1.1		MOS53670
8C9E C860 0040	1368	LDAI R6,X'40'	FORCE LOLIM	MOS53680
8CA2 4036 0000	1369 T1.1	STH R3,0(R6)	STORE BACKGROUND OF ALL 1'S	MOS53690
8CA6 C160 8CA2	1370	BXLE R6,T1.1		MOS53700
8CAA C840 3031	1371	LDAI R4,C'01'		MOS53710
8CAE 4040 8A56	1372	STH R4,ERRNO	ERRNO = C'01'	MOS53720
8CB2 4860 8B1A	1373	LH R6,LOLIM+6		MOS53730
	1374 *			MOS53740
8CB6 C360 7FC0	1375 READ11	TAI R6,X'7FC0'		MOS53750
8CBA 2133	1376	BNZS T1.11		MOS53760
8CBC C860 0040	1377	LDAI R6,X'40'	FORCE LOLIM	MOS53770
8CC0 41F0 87C2	1378 T1.11	BAL LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS53780
8CC4 4846 0000	1379	LH R4,0(R6)	LOAD DATA FROM LOC	MOS53790
8CC8 0543	1380	CLAR R4,R3	IS DATA AT LOC. OK ?	MOS53800
8CCA 2137	1381	BNES RTN11F	NO, BRANCH	MOS53810
8CCC C160 8CC0	1382 RTN11	BXLE R6,T1.11	CONTINUE UNTIL DONE	MOS53820

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TEST 1

8CD0	4860	8B1A	1383	LH	R6,LOLIM+6	MOS53830		
8CD4	2430		1384	LIS	R3,0	MOS53840		
8CD6	2304		1385	BS	STORE10	MOS53850		
			1386 *		BRANCH	MOS53860		
8CD8	41F0	9BAE	1387	RTN11F	BAL	LINK,ERROR	ERROR ROUTINE	MOS53870
8CDC	22C8		1388	BS	RTN11		RETURN	MOS53880
			1389 *					MOS53890
8CDE	C360	7FC0	1390	STORE10	TAI	R6,X'7FC0'		MOS53900
8CE2	2133		1391	BNZS	T1.2			MOS53910
8CE4	C860	0040	1392	LDAI	R6,X'40'		FORCE LOLIM	MOS53920
8CE8	4036	0000	1393	STH	R3,0(R6)		STORE BACKGROUND OF ALL 0'S	MOS53930
8CEC	C160	9CE8	1394	BXLE	R6,T1.2			MOS53940
8CF0	6110	8A56	1395	AHM	B1,ERRNO		ERRNO = C'02'	MOS53950
8CF4	4860	8B1A	1396	LH	R6,LOLIM+6			MOS53960
			1397 *					MOS53970
8CF8	C360	7FCG	1398	READ10	TAI	R6,X'7FC0'		MOS53980
8CFc	2133		1399	BNZS	T1.21			MOS53990
8CFE	C860	0040	1400	LDAI	R6,X'40'		FORCE LOLIM	MOS54000
8D02	41F0	87C2	1401	T1.21	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS54010
8D06	4846	0000	1402	LH	R4,(R6)		LOAD DATA FROM LOC	MOS54020
8D0A	2125		1403	BNZS	RTN10F		IF DATA NOT 0, BRANCH (DATA NG)	MOS54030
8DOC	C160	8D02	1404	RTN10	BXLE	R6,T1.21	CONTINUE UNTIL DONE	MOS54040
			1405 *					MOS54050
8D10	4300	83A8	1406	*	B	TSTEND	END OF TEST (RETURN TO EXEC)	MOS54060
			1407 *					MOS54070
8D14	41F0	9BAE	1408	RTN10F	BAL	LINK,ERROR	ERROR ROUTINE	MOS54080
8D18	2206		1409	BS	RTN10		RETURN	MOS54090
			1410 *					MOS54100
			1411 *	*****				MOS54110
			1412 *	END	TEST 1			MOS54120

TEST 2

1414 * TEST 2 MARCHING PATTERN TEST MOSS54140
 1415 * MOSS54150
 1416 * MOSS54160
 1417 * PURPOSE: MOSS54170
 1418 * THIS TEST CHECKS THAT THREE DIFFERENT BASE PATTERNS
 1419 * CAN BE WRITTEN, COMPLEMENTED, AND MARCHED THROUGH THE
 1420 * AVAILABLE MEMORY WITHOUT ERROR.
 1421 * ASSUMPTIONS: MOSS54180
 1422 * MINIMUM 64KB MOS MEMORY MOSS54190
 1423 * MOSS54200
 1424 * DESIGN SPECIFICATIONS: MOSS54210
 1425 * 1. (IN ASCENDING ORDER) WRITE AND READ THE BASE PATTERN.
 1426 * 2. (IN DESCENDING ORDER) WRITE AND READ THE
 1427 * COMPLEMENT PATTERN.
 1428 *
 1429 * OPTIONS: MOSS54230
 1430 * SCOPE - ERROR OPTION MODE MOSS54240
 1431 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOSS54250
 1432 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOSS54260
 1433 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOSS54270
 1434 * 3 - PRINT ERROR DATA AND HALT MOSS54280
 1435 * 4 - IGNORE ERROR MOSS54290
 1436 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOSS54300
 1437 *
 1438 * HOW TO RUN THE TEST:
 1439 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE. MOSS54310
 1440 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOSS54320
 MOSS54330
 MOSS54340
 MOSS54350
 MOSS54360
 MOSS54370
 MOSS54380
 MOSS54390
 MOSS54400

8D1A 2411	1442 TEST2	LIS R1,1	LOAD DISPLAY ADDRESS	MOSS54420
8D1C C840 893E	1443 LDAI R4,M40		SET NEW MM POINTER	MOSS54430
8D20 4040 003E	1444 STH R4,X'3E'			MOSS54440
8D24 24A0	1445 LIS R10,0			MOSS54450
8D26 25B1	1446 LCS R11,1			MOSS54460
8D28 24D0	1447 LIS R13,0	W/BACKGROUND = 0'S		MOSS54470
8D2A 41E0 8D58	1448 BAL R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)		MOSS54480
	1449 *	LCS R10,1		MOSS54490
8D2E 25A1	1450 LIS R11,0	W/BACKGROUND = F'S		MOSS54500
8D30 24B0	1451 BAL R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)		MOSS54510
8D32 41E0 8D58	1452 *	LCS R11,1		MOSS54520
	1453 *	BAL R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOSS54530
8D36 24D2	1454 LIS R13,2	W/BACKGROUND = A'S		MOSS54540
8D38 41E0 8D58	1455 BAL R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)		MOSS54550
	1456 *	LIS R10,0		MOSS54560
8D3C 24A0	1457 LCS R11,1	W/BACKGROUND = 5'S		MOSS54570
8D3E 25B1	1458 BAL R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)		MOSS54580
8D40 41E0 8D58	1459 *	LIS R10,0		MOSS54590
	1460 *	LCS R11,1		MOSS54600
8D44 C8D0 0100	1461 LDAI R13,X'100'	W/BACKGROUND =128-0'S,128-F'S,..		MOSS54610
8D48 41E0 8D58	1462 BAL R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)		MOSS54620
	1463 *	LCS R10,1		MOSS54630
8D4C 25A1	1464			MOSS54640

TEST 2

8D4E 24B0	1465	LIS	R11,0		MOS54650
8D50 41E0 8D58	1466	BAL	R14,CHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS54660
	1467 *				MOS54670
8D54 43C0 83A8	1468	B	TSTEND	END OF TEST (RETURN TO EXEC)	MOS54680
	1469 *				MOS54690
	1470 *****				MOS54700
	1471 *				MOS54710
8D58 4860 8B1A	1472	CHKLOC	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS54720
8D5C 4880 8B26	1473		LH 28,HILIM+6		MOS54730
8D60 2472	1474	LIS	R7,2		MOS54740
	1475 *				MOS54750
8D62 C360 7FC0	1476	CHKLOC1	TAI R6,X'7FC0'		MOS54760
8D66 2133	1477	BNZS	T2.1		MOS54770
8D68 C860 0040	1478	LDAI	R6,X'40'	FORCE LOLIM	MOS54780
8D6C 083A	1479	T2.1	LDAR R3,R10	STORE APPROPRIATE BACKGROUND PATTERN	MOS54790
8D6E C36D 0000	1480		TAI R6,0(R13)		MOS54800
8D72 2332	1481	BZS	CHKLOC2		MOS54810
8D74 083B	1482	LDAR	R3,R11		MOS54820
8D76 4036 0000	1483	CHKLOC2	STH R3,0(R6)	IN MEMORY	MOS54830
8D7A C160 8D6C	1484	CHKLOC25	BXLE R6,T2.1	FROM LOLIM TO HILIM	MOS54840
8D7E 4860 8B1A	1485		LH R6,LOLIM+6		MOS54850
	1486 *				MOS54860
8D82 C360 7FC0	1487	CHKLOC3	TAI R6,X'7FC0'		MOS54870
8D86 2133	1488	BNZS	T2.2		MOS54880
8D88 C860 0040	1489	LDAI	R6,X'40'		MOS54890
8D8C C840 3033	1490	T2.2	LDAI R4,C'03'		MOS54900
8D90 4040 8A56	1491		STH R4,ERRNO	ERRNO = C'03'	MOS54910
8D94 41F0 87C2	1492	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS54920
8D98 083A	1493	LDAR	R3,R10	GET APPROPRIATE BACKGRUND PATTERN	MOS54930
8D9A C36D 0000	1494		TAI R6,0(R13)		MOS54940
8D9E 2332	1495	BZS	CHKLOC4		MOS54950
8DA0 083B	1496	LDAR	R3,R11		MOS54960
8DA2 4846 0000	1497	CHKLOC4	LH R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS54970
8DA6 0543	1498	CLAR	R4,R3	EQUAL ?	MOS54980
8DA8 213E	1499	BNES	CHKLOC5F	NO, BRANCH	MOS54990
8DAA C730 FFFF	1500	CHKLOC5	XAI R3,-1	COMPLEMENT DATA PATTERN	MOS55000
8DAE 4036 0000	1501		STH R3,0(R6)	STORE C.D.P. AT LOC	MOS55010
8DB2 6110 8A56	1502	AHM	R1,ERRNO	ERRNO = C'04'	MOS55020
8DB6 4846 0000	1503		LH R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS55030
8DBA 0543	1504	CLAR	R4,R3	DATA = C.D.P. ?	MOS55040
8DBC 2137	1505	BNES	CHKLOC6F	NO, BRANCH	MOS55050
8DBE C160 8D8C	1506	CHKLOC6	BXLE R6,T2.2	CONTINUE UNTIL DONE(INCREMENTING)	MOS55060
8DC2 2307	1507		BS CHKLOC6A	BRANCH	MOS55070
	1508 *				MOS55080
8DC4 41F0 9BAE	1509	CHKLOC5F	BAL LINK,ERROR	ERROR ROUTINE	MOS55090
8DC8 220F	1510		BS CHKLOC5	RETURN	MOS55100
	1511 *				MOS55110
8DCA 41F0 9BAE	1512	CHKLOC6F	BAL LINK,ERROR	ERROR ROUTINE	MOS55120
8DCE 2208	1513		BS CHKLOC6		MOS55130
	1514 *				MOS55140
8DD0 4860 8B26	1515	CHKLOC6A	LH R6,HILIM+6		MOS55150
8DD4 C460 7FFE	1516		NAI R6,X'7FFE'		MOS55160
8DD8 4880 8B1A	1517		LH R8,LOLIM+6	ESTABLISH MEMORY LIMITS	MOS55170

TEST 2

8DDC	2572	1518	LCS	R7,2	MOS55180	
8DDE	C380 7FC0	1519	TAI	R8,X'7FC0'	MOS55190	
8DE2	2133	1520	BNZS	CHKLOC7	MOS55200	
8DE4	C880 0040	1521	LDAI	R8,X'40'	MOS55210	
		1522 *			MOS55220	
8DE8	063E	1523	CHKLOC7	LDAF R3,R11	MOS55230	
8DEA	C36D 0000	1524	TAI	R6,0(R13)	MOS55240	
8DEE	2332	1525	BZS	CHKLOC8	MOS55250	
8DF0	083A	1526	LDAR	R3,R10	MOS55260	
8DF2	C840 3035	1527	CHKLOC8	LDAI R4,C'05'	MOS55270	
8DF6	4040 8A56	1528	STH	R4,ERRNO	MOS55280	
8DFA	41F0 87C2	1529	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS55290
8DFE	C360 7FC0	1530	TAI	R6,X'7FC0'	MOS55300	
8E02	4330 8E22	1531	BZ	CHKLOC10	MOS55310	
8E06	4846 0000	1532	LH	R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS55320
8E0A	0543	1533	CLAR	R4,R3	DATA = C.D.P. ?	MOS55330
8E0C	213E	1534	BNES	CHKLOC9F	NO, BRANCH	MOS55340
8E0E	C730 FFFF	1535	CHKLOC9	XAI R3,-1	COMPLEMENT C.D.P. (O.D.P.)	MOS55350
8E12	4036 0000	1536	STH	R3,0(R6)	STORE PATTERN AT LOC	MOS55360
8E16	6110 8A56	1537	AHM	R1,ERRNO	ERRNO = C'06'	MOS55370
8E1A	4846 0000	1538	LH	R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS55380
8E1E	0543	1539	CLAR	R4,R3	DATA = O.D.P. ?	MOS55390
8E20	2137	1540	BNES	CHKLOC1F	NO, BRANCH	MOS55400
8E22	C060 8DE8	1541	CHKLOC10	BXH R6,CHKLOC7	CONTINUE UNTIL DONE(DECREMENTING)	MOS55410
		1542 *			MOS55420	
8E26	03CE	1543	BR	R14	RETURN	MOS55430
		1544 *			MOS55440	
8E28	41F0 9BAE	1545	CHKLOC9F	BAL LINK,ERROR	ERRCR ROUTINE	MOS55450
8E2C	220F	1546	BS	CHKLOC9	RETURN	MOS55460
		1547 *			MOS55470	
8E2E	41F0 9BAE	1548	CHKLOC1F	BAL LINK,ERROR	ERROR ROUTINE	MOS55480
8E32	2208	1549	BS	CHKLOC10	RETURN	MOS55490
		1550 *			MOS55500	
		1551 * *****			MOS55510	
		1552 * END TEST 2			MOS55520	

TEST 3

1554 * TEST 3 O & 1 WALK TEST MOS55540
 1555 * PURPOSE: MOS55550
 1556 * THIS TEST WALKS A 0 THROUGH A FIELD OF 1'S AND A 1 MOS55560
 1557 * THROUGH A FIELD OF 0'S. MOS55570
 1558 * ASSUMPTIONS: MOS55580
 1559 * MINIMUM 64KB MOS MEMORY MOS55590
 1560 * DESIGN SPECIFICATIONS: MOS55600
 1561 * 1. WITH A BACKGROUND OF ALL 1'S, A 0 IS WALKED THROUGH MOS55610
 1562 * EACH HALFWORD OF MEMORY. A READ AND COMPARE IS DONE MOS55620
 1563 * ON EACH LOCATION. MOS55630
 1564 * 2. WITH A BACKGROUND OF ALL 0'S, A 1 IS WALKED THROUGH MOS55640
 1565 * EACH HALFWORD OF MEMORY. A COMPARE IS DONE ON EACH MOS55650
 1566 * LOCATION. MOS55660
 1567 * OPTIONS: MOS55670
 1568 * SCOPE - ERROR OPTION MODE MOS55680
 1569 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS55690
 1570 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS55700
 1571 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS55710
 1572 * 3 - PRINT ERROR DATA AND HALT MOS55720
 1573 * 4 - IGNORE ERROR MOS55730
 1574 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS55740
 1575 * HOW TO RUN THE TEST: MOS55750
 1576 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE. MOS55760
 1577 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS55770
 1578 *
 1579 *
 1580 *
 1581 *
 1582 *

8E34	2411	1584	TEST3	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS55840
8E36	4860 8B1A	1585		LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS55850
8E3A	4880 8B26	1586		LH	R8,HILIM+6		MOS55860
8E3E	2472	1587		LIS	R7,2		MOS55870
8E40	C840 893E	1588		LDAI	R4,MMO		MOS55880
8E44	4040 003E	1589		STH	R4,X'3E'	SET NEW MM POINTER	MOS55890
8E48	2531	1590		LCS	R3,1		MOS55900
		1591 *					MOS55910
8E4A	C360 7FC0	1592	STORE31	TAI	R6,X'7FC0'		MOS55920
8E4E	2133	1593		BNZS	T3,1		MOS55930
8E50	C860 0040	1594		LDAI	R6,X'40'	FORCE LOLIM	MOS55940
8E54	4036 0000	1595	T3.1	STH	R3,0(R6)	STORE BACKGROUND OF ALL 1'S	MOS55950
8E58	C160 8E54	1596	T3S0	BXLE	R6,T3,1		MOS55960
8E5C	4860 8B1A	1597		LH	R6,LOLIM+6		MOS55970
8E60	C840 3037	1598		LDAI	R4,C'07'		MOS55980
8E64	4040 3A56	1599		STH	R4,ERRNO	ERRNO = C'07'	MOS55990
		1600 *					MOS56000
8E68	C360 7FC0	1601		TAI	R6,X'7FC0'		MOS56010
8E6C	2133	1602		BNZS	T3S1		MOS56020
8E6E	C860 0040	1603		LDAI	R6,X'40'		MOS56030
8E72	C8D0 0010	1604	T3S1	LDAI	R13,16		MOS56040

TEST 3

8E76	41F0 87C2	1605	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS56050
8E7A	C8C0 8000	1606	LDAI	R12,X'8000'	LOAD R12 (BIT 0 SET)	MOS56060
8E7E	2531	1607	T3S2	LCS R3,1	SET ALL BITS IN R3	MOS56070
8E80	073C	1608	XAR	R3,R12	RESET A BIT (0-15) IN R3	MOS56080
8E82	4036 0000	1609	STH	R3,0(36)	STORE DATA AT LOC	MOS56090
8E86	4846 0000	1610	LH	R4,0(36)	GET DATA FROM LOC	MOS56100
8E8A	0543	1611	CLAR	R4,R3	DATA EQUAL ?	MOS56110
8E8C	213A	1612	BNES	T3S3F	NO, BRANCH	MOS56120
8E8E	90C1	1613	SRHLS	R12,1	WALK 0 THRU HALFWORD OF 1'S	MOS56130
8E90	27D1	1614	SIS	R13,1	DONE W/THIS HALFWORD ?	MOS56140
8E92	203A	1615	BNZS	T3S2	NO, BRANCH UNTIL FINISHED	MOS56150
8E94	C160 8E72	1616	T3S3.4	BXLE R6,T3S1	CONTINUE UNTIL DONE(INCREMENTING)	MOS56160
8E98	4860 8B1A	1617	LH	R6,LOLIM+6		MOS56170
8E9C	2430	1618	LIS	R3,0		MOS56180
8E9E	23C4	1619	BS	STORE30	BRANCH	MOS56190
		1620	*			MOS56200
8EA0	41F0 9BAE	1621	T3S3F	BAL	LINK,ERROR	MOS56210
8EA4	22C9	1622	BS	T3S3	RETURN	MOS56220
		1623	*			MOS56230
8EA6	C360 7FC0	1624	STORE30	TAI	R6,X'7FC0'	MOS56240
8EAA	2133	1625	BNZS	T3.2		MOS56250
8EAC	C860 0040	1626	LDAI	R6,X'40'	FORCE LOLIM	MOS56260
8EB0	4036 0000	1627	T3.2	STH R3,0(R6)	STORE BACKGROUND OF ALL 0'S	MOS56270
8EB4	C160 8EB0	1628	T3S3.6	BXLE R6,T3.2		MOS56280
8EB8	4860 8B1A	1629	LH	R6,LOLIM+6		MOS56290
8EBC	6110 8A56	1630	AHM	R1,ERRNO	ERRNO = C'08'	MOS56300
		1631	*			MOS56310
8EC0	C360 7FC0	1632	T3S4	TAI	R6,X'7FC0'	MOS56320
8EC4	2133	1633	BNZS	T3.3		MOS56330
8EC6	C860 0040	1634	LDAI	R6,X'40'	FORCE LOLIM	MOS56340
8ECA	C8D0 0010	1635	T3.3	LDAI R13,16		MOS56350
8ECE	41F0 87C2	1636	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS56360
8ED2	C830 8000	1637	LDAI	R3,X'8000'	LOAD R3 (BIT 0 SET)	MOS56370
		1638	*			MOS56380
8ED6	4036 0000	1639	T3S5	STH R3,0(R6)	STORE DATA AT LOC	MOS56390
8EDA	4846 0000	1640	LH	R4,0(R6)	GET DATA FROM LOC	MOS56400
8EDE	0543	1641	CLAR	R4,R3	DATA EQUAL ?	MOS56410
8EE0	2138	1642	BNES	T3S6F	NO, BRANCH	MOS56420
8EE2	9031	1643	SRHLS	R3,1	WALK BIT THRU HALFWORD	MOS56430
8EE4	27D1	1644	SIS	R13,1	DONE W/THIS HALFWORD ?	MOS56440
8EE6	2038	1645	BNZS	T3S5	NO, BRANCH UNTIL FINISHED	MOS56450
8EE8	C160 8ECA	1646	T3S7	BXLE R6,T3.3	CONTINUE UNTIL DONE (INCREMENTING)	MOS56460
		1647	*			MOS56470
8EEC	43C0 83A9	1648	B	TSTEND	END OF TEST (RETURN TO EXEC)	MOS56480
		1649	*			MOS56490
8EF0	41F0 9BAE	1650	T3S6F	BAL	LINK,ERROR	MOS56500
8EF4	22C9	1651	BS	T3S6	RETURN	MOS56510
		1652	*	*****	*****	MOS56520
		1653	*	END TEST 3		MOS56530

TEST 4

1655 * TEST 4 DOUBLE OPERATION COLUMN DISTURB TEST MOS56550
 1656 * MOS56560
 1657 * MOS56570
 1658 * MOS56580
 1659 * MOS56590
 1660 * MOS56600
 1661 * MOS56610
 1662 * MOS56620
 1653 * MOS56630
 1664 * MOS56640
 1665 * 1. WITH 6 DIFFERENT BACKGROUND PATTERNS, A W-R-WC-
 1666 * RC-W-B-WC-RC SERIES IS EXECUTED AT EACH LOCATION. MOS56650
 1667 * 2. A COMPARE IS DONE UPON EACH READ OPERATION. MOS56660
 1668 * 3. A TEST (COMPARISON) OF THE REST OF MEMORY IS DONE MOS56670
 1669 * AFTER EACH SERIES OF OPERATIONS. MOS56680
 1670 * MOS56690
 1671 * MOS56700
 1672 * MOS56710
 1673 * MOS56720
 1674 * MOS56730
 1675 * MOS56740
 1676 * MOS56750
 1677 * MOS56760
 1678 * MOS56770
 1679 * MOS56780
 1680 * MOS56790
 1681 * MOS56800
 1682 * MOS56810
 HOW TO RUN THE TEST
 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE.
 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS56820

8EF6 2411	1684 TEST4	LIS R1,1	LOAD DISPLAY ADDRESS	MOS56840
8EF8 24A0	1685 LIS	R10,0		MOS56850
8EFA 25B1	1686 LCS	R11,1		MOS56860
8EFFC 24D0	1687 LIS	R13,0		MOS56870
8EFE 41E0 8F14	1688 BAL	R14,CHKCOL		MOS56880
	1589 *		W/BACKGROUND = 0'S	MOS56890
8F02 24D2	1690 LIS	R13,2	DO A DOUBLE OPERATION COLUMN	MOS56890
8F04 41E0 8F14	1691 BAL	R14,CHKCOL	DISTURB AND COMPLEMENT TEST	MOS56900
			W/BACKGROUND = 5'S	MOS56910
8F08 C8D0 0100	1693 LDAI	R13,X'100'	DO A DOUBLE OPERATION COLUMN	MOS56920
8FOC 41E0 8F14	1694 BAL	R14,CHKCOL	DISTURB AND COMPLEMENT TEST	MOS56930
	1695 *		W/BACKGROUND = 128-0'S, 128-F'S,...	MOS56940
8F10 4300 83A8	1696 B TSTEND		DO A DOUBLE OPERATION COLUMN	MOS56950
	1597 * *****		DISTURB AND COMPLEMENT TEST	MOS56960
			END OF TEST (RETURN TO EXEC)	MOS56970
8F14 4860 8B1A	1698 CHKCOL	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS56980
8F18 4880 8B26	1699 LH	R8,HILIM+6		MOS56990
8F1C 2472	1700 LIS	R7,2		MOS57000
8F1E C360 7FC0	1701 TAI	R6,X'7FC0'		MOS57010
8F22 2133	1702 BNZS	CHKCOL1		MOS57020
8F24 C860 0040	1703 LDAI	R6,X'40'	FORCE LOLIM	MOS57030
8F28 083A	1704 CHKC0L1	LDAR R3,R10	GET PROPER BACKGROUND PATTERN	MOS57040
8F2A C360 0000	1705 TAI	R6,0(R13)		MOS57050

TEST 4

8F2E	2332	1706	BZS	CHKCOL2	MOS57060
8F30	0838	1707	LDAR	R3,R11	MOS57070
8F32	4036 0000	1708	CHKCOL2	STH R3,0(R6)	MOS57080
8F36	C160 8528	1709	CHKCOL25	BXLE R6,CHKCOL1	MOS57090
8F3A	4860 831A	1710	LH R6,LOLIM+6	MOS57100	
8F3E	C360 7FC0	1711	TAI R6,X'7FC0'	MOS57110	
8F42	2133	1712	BNZS	CHKCOL3	MOS57120
8F44	C860 0040	1713	LDAI	R6,X'40'	MOS57130
		1714 *		FORCE LOLIM	MOS57140
8F48	C840 3033	1715	CHKCOL3	LDAI R4,C'03'	MOS57150
8F4C	4040 8A56	1716	STH	R4,ERRNO	MOS57160
8F50	41F0 87C2	1717	BAL	LINK,TSTBRKX	MOS57170
8F54	083A	1718	LDAR	R3,R10	MOS57180
8F56	C36D 0000	1719	TAI	R6,0(R13)	MOS57190
8F5A	2332	1720	BZS	CHKCOL4	MOS57200
8F5C	0838	1721	LDAR	R3,R11	MOS57210
8F5E	4846 0000	1722	CHKCOL4	LH R4,0(R6)	MOS57220
8F62	0543	1723	CLAR	R4,R3	MOS57230
8F64	4230 9042	1724	BNE	CHKCOL5F	MOS57240
8F68	C730 FFFF	1725	CHKCOL5	XAI R3,-1	MOS57250
8F6C	4036 0000	1726	STH	R3,0(R6)	MOS57260
8F70	6110 8A56	1727	AHM	R1,ERRNO	MOS57270
8F74	4846 0000	1728	LH	R4,0(R6)	MOS57280
8F78	0543	1729	CLAR	R4,R3	MOS57290
8F7A	4230 904A	1730	BNE	CHKCOL6F	MOS57300
8F7E	C730 FFFF	1731	CHKCOL6	XAI R3,-1	MOS57310
8F82	4036 0000	1732	STH	R3,0(R6)	MOS57320
8F86	C840 3039	1733	LDAI	R4,C'09'	MOS57330
8F8A	4040 8A56	1734	STH	R4,ERRNO	MOS57340
8F8E	4846 0000	1735	LH	R4,0(R6)	MOS57350
8F92	0543	1736	CLAR	R4,R3	MOS57360
8F94	4230 9052	1737	BNE	CHKCOL7F	MOS57370
8F98	C730 FFFF	1738	CHKCOL7	XAI R3,-1	MOS57380
8F9C	4036 0000	1739	STH	R3,0(R6)	MOS57390
8FA0	C840 3041	1740	LDAI	R4,C'0A'	MOS57400
8FA4	4040 8A56	1741	STH	R4,ERRNO	MOS57410
8FA8	4846 0000	1742	LH	R4,0(R6)	MOS57420
8FAC	0543	1743	CLAR	R4,R3	MOS57430
8FAE	4230 905A	1744	BNE	CHKCOL8F	MOS57440
8FB2	C160 8F48	1745	CHKCOL8	BXLE R6,CHKCOL3	MOS57450
8FB6	4860 8B26	1746	LH	R6,HILIM+6	MOS57460
8FBA	C460 FFFE	1747	NAI	R6,-2	MOS57470
8FBE	4880 8B1A	1748	LH	R8,LOLIM+6	MOS57480
8FC2	2572	1749	LCS	R7,2	MOS57490
8FC4	C380 7FC0	1750	TAI	R8,X'7FC0'	MOS57500
8FC8	2133	1751	BNZS	CHKCOL9	MOS57510
8FCA	C880 0040	1752	LDAI	R8,X'40'	MOS57520
		1753 *		FORCE LOLIM	MOS57530
8FCE	083B	1754	CHKCOL9	LDAR R3,R11	MOS57540
8FD0	C36D 0000	1755	TAI	R6,0(R13)	MOS57550
8FD4	2332	1756	BZS	CHKCOLA	MOS57560
8FD6	083A	1757	LDAR	R3,R10	MOS57570
8FD8	C840 3035	1758	CHKCOLA	LDAI R4,C'05'	MOS57580

STORE BACKGROUND PATTERN
TO ALL OF MEMORY UNDER TESTERRNO = C'03'
IF "BREAK" GO TO TSTEND ELSE RETURN
GET ORIGINAL DATA PATTERN (C.D.P.)GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT DATA PATTERN (C.D.P.)
STORE C.D.P. AT LOC
ERRNO = C'04'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT C.D.P. (O.D.P.)
STORE O.D.P. AT LOCERRNO = C'09'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT O.D.P.(C.D.P.)
STORE C.D.P. AT LOCERRNO = C'0A'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
CONTINUE UNTIL DONE(INCREMENTING
INITIALIZE MEMORY LIMITS
(HILIM MUST BE EVEN)

TEST 4

8FDC	4040 8A56	1759	STH	R4,ERRNO	ERRNO = C'05'	MOS57590	
8FE0	41E0 87C2	1760	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS57600	
8FE4	4846 0000	1761	LH	R4,0(R6)	GET DATA FROM LOC	MOS57610	
8FE8	0543	1762	CLAR	R4,R3	DATA EQUAL ?	MOS57620	
8FEA	4230 9062	1763	BNE	CHKCOLBF	NO, BRANCH	MOS57630	
8FEE	C730 FFFF	1764	CHKCOLB	XAI R3,-1	COMPLEMENT C.D.P.(O.D.P.)	MOS57640	
8FF2	4036 0000	1765	STH	R3,0(R6)	STORE O.D.P. AT LOC	MOS57650	
8FF6	6110 8A56	1766	AHM	R1,ERRNO	ERRNO = C'06'	MOS57660	
8FFA	4846 0000	1767	LH	R4,0(R6)	GET DATA FROM LOC	MOS57670	
8FFE	0543	1768	CLAR	R4,R3	DATA EQUAL ?	MOS57680	
9000	4230 906A	1769	BNE	CHKCOLCF	NO, BRANCH	MOS57690	
9004	C730 FFFF	1770	CHKCOLC	XAI R3,-1	COMPLEMENT O.D.P. (C.D.P.)	MOS57700	
9008	4036 0000	1771	STH	R3,0(R6)	STORE C.D.P. AT LOC	MOS57710	
900C	C840 3042	1772	LDAA	R4,C'0B'		MOS57720	
9010	4040 8A56	1773	STH	R4,ERRNO	ERRNO = C'0B'	MOS57730	
9014	4846 0000	1774	LH	R4,0(R6)	GET DATA FROM LOC	MOS57740	
9018	0543	1775	CLAR	R4,R3	DATA EQUAL ?	MOS57750	
901A	213E	1776	BNES	CHKCOLDF	NO, BRANCH	MOS57760	
901C	C730 FFFF	1777	CHKCOLD	XAI R3,-1	COMPLEMENT C.D.P.(O.D.P.)	MOS57770	
9020	4036 0000	1778	STH	R3,0(R6)	STORE O.D.P. AT LOC	MOS57780	
9024	6110 8A56	1779	AHM	R1,ERRNO	ERRNO = C'0C'	MOS57790	
9028	4846 0000	1780	LH	R4,0(R6)	GET DATA FROM LOC	MOS57800	
902C	0543	1781	CLAR	R4,R3	DATA EQUAL ?	MOS57810	
902E	2137	1782	BNES	CHKCOLEF	NO, BRANCH	MOS57820	
9030	C060 8FCE	1783	CHKCOLE	BXH R6,CHKCOL9	CONTINUE UNTIL DONE(DECREMENTING)	MOS57830	
9034	03CE	1784	BR	R14	RETURN	MOS57840	
9035	*	1785	-----				MOS57850
9036	41E0 9BAE	1786	CHKCOLDF	BAL	LINK,ERROR	MOS57860	
903A	220F	1787	BS	CHKCOLD	ERROR ROUTINE	MOS57870	
9038	*	1788	-----				MOS57880
903C	41E0 9BAE	1789	CHKCOLEF	BAL	LINK,ERROR	MOS57890	
9040	22C8	1790	BS	CHKCOLE	ERROR ROUTINE	MOS57900	
9041	*	1791	-----				MOS57910
9042	41E0 9BAE	1792	CHKCOL5F	BAL	LINK,ERROR	MOS57920	
9046	4300 8F68	1793	B	CHKCOL5	ERROR ROUTINE	MOS57930	
9048	*	1794	-----				MOS57940
904A	41E0 9BAE	1795	CHKCOL6F	BAL	LINK,ERROR	MOS57950	
904E	4300 8F7E	1796	B	CHKCOL6	ERROR ROUTINE	MOS57960	
904F	*	1797	-----				MOS57970
9052	41E0 9BAE	1798	CHKCOL7F	BAL	LINK,ERROR	MOS57980	
9056	4300 8F98	1799	B	CHKCOL7	ERROR ROUTINE	MOS57990	
9058	*	1800	-----				MOS58000
905A	41E0 9BAE	1801	CHKCOL8F	BAL	LINK,ERROR	MOS58010	
905E	4300 8FB2	1802	B	CHKCOL8	ERROR ROUTINE	MOS58020	
905F	*	1803	-----				MOS58030
9062	41E0 9BAE	1804	CHKCOLBF	BAL	LINK,ERROR	MOS58040	
9066	4300 8FEE	1805	B	CHKCOLB	ERROR ROUTINE	MOS58050	
9067	*	1806	-----				MOS58060
906A	41E0 9BAE	1807	CHKCOLCF	BAL	LINK,ERROR	MOS58070	
906E	4300 9004	1808	B	CHKCOLC	ERROR ROUTINE	MOS58080	
906F	*	1809	*****				MOS58090
9070	*	1810	END	TEST 4		MOS58100	

TEST 5

1812 * TEST 5 SHORT COUNT RELOCATABLE
 1813 * HAMMER DISTURB TEST
 1814 *
 1815 * PURPOSE:
 1816 * THIS TEST EXECUTES A SMALL, RELOCATABLE PROGRAM
 1817 * (16 HALFWORDS) THROUGHOUT MEMORY, LOOKING FOR "SOFT"
 1818 * FAILURES.
 1819 *
 1820 * ASSUMPTIONS:
 1821 * MINIMUM 64KB MOS MEMORY
 1822 *
 1823 * DESIGN SPECIFICATIONS:
 1824 * 1. THE TEST PROGRAM MUST USE 16 HALFWORDS HEAVILY,
 1825 * DUE TO THE INTERNAL CHIP ADDRESSING SCHEME.
 1826 * 2. THE TEST RUNS WITH A BACKGROUND PATTERN EQUAL TO
 1827 * THE CONTENTS OF "DATA".
 1828 * 3. THE TEST LOOPS 10 TIMES(INTERNAL TO THE MODULE).
 1829 * 4. THE ROUTINE (ROUTIN) IS EXECUTED 10 TIMES. THE ENTIRE
 1830 * ROUTINE IS THEN RELOCATED IN MEMORY AND EXECUTED 10
 1831 * TIMES. "ROUTIN" IS MOVED UP IN MEMORY UNTIL THE LAST
 1832 * TEST HALFWORD IS IN THE LAST MEMORY HALFWORD.
 1833 *
 1834 * OPTIONS:
 1835 * DATA - 16-BIT DATA PATTERN USED AS BACKGROUND
 1836 * POUND - NUMBER OF TIMES A'S & S'S ARE POUNDED IN MEMORY
 1837 * SCOPE - ERROR OPTION MODE
 1838 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST
 1839 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST
 1840 * 2 - PRINT ERROR DATA AND CONTINUE TEST
 1841 * 3 - PRINT ERROR DATA AND HALT
 1842 * 4 - IGNORE ERROR
 1843 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST
 1844 *
 1845 * HOW TO RUN THE TEST:
 1846 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE.
 1847 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE.

9072	4860 8B1A	1849	TEST5	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS58490
9076	4880 8B26	1850		LH	R8,HILIM+6		MOS58500
907A	0806	1851		LDAR	R0,R6	R0 = LOLIM	MOS58510
907C	0898	1852		LDAR	R9,R8	R9 = HILIM	MOS58520
907E	2572	1853		LIS	R7,2		MOS58530
9080	2411	1854		LIS	R1,1	LOAD DISPLAY ADDRESS	MOS58540
9082	C8A0 5555	1855		LDAI	R10,X'5555'		MOS58550
9086	C8B0 AAAA	1856		LDAI	R11,X'AAAA'		MOS58560
908A	C850 003E	1857		LDAI	R5,ENDMOV5-STLOOP+2	LOAD TEST ADDRESS DIFFERENCE	MOS58570
908E	2521	1858		LCS	R2,1		MOS58580
		1859 *					MOS58590
9090	C360 7FC0	1860		TAI	R6,X'7FC0'		MOS58600
9094	2133	1861		BNZS	T5S1		MOS58610
9096	C860 0040	1862		LDAI	R6,X'40'	FORCE LOLIM	MOS58620

TEST 5

909A	4026 0000	1863	T5S1	STH	R2,0(R6)	STORE BACKGROUND OF ALL 1'S	MOS58630
909E	C160 909A	1864	T5S1.5	BILE	R6,T5S1		MOS58640
90A2	4860 8B1A	1865		LH	R6,LOLIM+6		MOS58650
90A6	0B85	1866		SAR	R8,R5	ESTABLISH HIGH LIMIT	MOS58660
90A8	4210 9672	1867		BM	T8L0PRT	IF NEGATIVE, ERROR	MOS58670
90AC	C585 0046	1868		CLAI	R8,X'46'(R5)	MEMORY SPECIFIED LARGE ENOUGH ?	MOS58680
90B0	4280 9672	1869		BL	T8L0PRT	NO, ERROR	MOS58690
90B4	4080 9DC4	1870		STH	R8,VHILIM	SAVE TESTING HILIM VALUE	MOS58700
90B8	41E0 90E6	1871		BAL	R14,SFTSET	DO SHORT HAMMER DISTURB TEST	MOS58710
		1872	*				MOS58720
90BC	4860 8B1A	1873		LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS58730
90C0	0889	1874		LDAR	R8,R9	GET BG BXLE HILIM VALUE	MOS58740
90C2	2420	1875		LIS	R2,0		MOS58750
90C4	C360 7FC0	1876		TAI	R6,X'7FC0'		MOS58760
90C8	2133	1877		BNZS	T5S2		MOS58770
90CA	C860 0040	1878		LDAI	R6,X'40'	FORCE LOLIM	MOS58780
90CE	4026 0000	1879	T5S2	STH	R2,0(R6)	STORE BACKGROUND OF ALL 0'S	MOS58790
90D2	C160 90CE	1880	T5S2.5	BILE	R6,T5S2		MOS58800
90D6	4860 8B1A	1881		LH	R6,LOLIM+6		MOS58810
90DA	4880 9DC4	1882		LH	R8,VHILIM	RESTORE TESTING HILIM VALUE	MOS58820
90DE	41E0 90E6	1883		BAL	R14,SFTSET	DO SHORT HAMMER DISTURB TEST	MOS58830
		1884	*				MOS58840
90E2	4300 83A8	1885		B	TSTEND	END OF TEST (RETURN TO EXEC)	MOS58850
		1886	*				MOS58860
		1887	*			*****	MOS58870
		1888	*				MOS58880
90E6	C360 7FC0	1889	SFTSET	TAI	R6,X'7FC0'		MOS58890
90EA	2133	1890		BNZS	SFTSET1		MOS58900
90EC	C860 0040	1891		LDAI	R6,X'40'	FORCE LOLIM	MOS58910
		1892	*				MOS58920
90F0	48C0 8B02	1893	SFTSET1	LH	R12,POUND+6	LOAD EXECUTION COUNTER	MOS58930
90F4	41F0 87C2	1894		BAL	LINK,TSTBRKY	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS58940
90F8	D000 9DF0	1895		STM	R0,MOSSAVE+32	SAVE REGISTERS (0-F)	MOS58950
90FC	0816	1896		LDAR	R1,R6		MOS58960
90FE	D120 919C	1897		LM	R2,STLOOP	RELOCATE PROGRAM IN MEMORY	MOS58970
9102	D021 0002	1898		STM	R2,2(B1)		MOS58980
9106	D120 91B8	1899		LM	R2,STLOOP+28		MOS58990
910A	D021 001E	1900		STM	R2,30(B1)		MOS59000
910E	D1E0 91D4	1901		LM	R14,STLOOP+56		MOS59010
9112	D0E1 003A	1902		STM	R14,58(B1)		MOS59020
9116	2441	1903		LIS	R4,1		MOS59030
9118	9461	1904		EXBR	R6,R1		MOS59040
911A	9846	1905		WHR	R4,R6	DISPLAY ADDRESS UNDER TEST	MOS59050
911C	D100 9DF0	1906		LM	R0,MOSSAVE+32	RESTORE REGISTERS (0-F)	MOS59060
9120	4060 9DC2	1907		STH	R6,VLOLIM	SAVE LOCATION UNDER TEST	MOS59070
9124	41D6 0002	1908		BAL	R13,2(R6)	BRANCH TO "STLOOP"	MOS59080
		1909	*				MOS59090
		1910	*			TEST BACKGROUND PATTERN	MOS59100
		1911	*				MOS59110
9128	D000 9DF0	1912	BGTST	STM	R0,MOSSAVE+32		MOS59120
912C	C840 3045	1913		LDAI	R4,C'OE'		MOS59130
9130	4040 8A56	1914		STH	R4,ERRNO	ERRNO = C'OE'	MOS59140
9134	0832	1915		LDAR	R3,R2	LOAD BACKGROUND PATTERN	MOS59150

TEST 5

9136	0886	1916	LDAR	R8,R6	MOS59160
9138	08C6	1917	LDAR	R12,R6	MOS59170
913A	0B85	1918	SAR	R8,R5	MOS59180
913C	08E0	1919	LDAR	R6,R0	MOS59190
913E	05E8	1920	CLAR	R6,R8	MOS59200
9140	4380 9162	1921	BNL	BGTST3	MOS59210
9144	C360 7FC0	1922	TAI	R6,X'7FC0'	MOS59220
9148	2133	1923	BNZS	BGTST1	MOS59230
914A	C860 0040	1924	LDAI	R6,X'40'	MOS59240
914E	4846 0000	1925	BGTST1	LH R4,0(R6)	MOS59250
9152	0543	1926	CLAR	R4,R3	MOS59260
9154	2134	1927	BNES	BGTST2.5	MOS59270
9156	C160 914E	1928	BXLE	R6,BGTST1	MOS59280
915A	2304	1929	BS	BGTST3	MOS59290
		1930	*		MOS59300
915C	41E0 9BAE	1931	BGTST2.5	BAL LINK,ERROR	MOS59310
9160	2205	1932	BS	BGTST2	MOS59320
		1933	*		MOS59330
9162	08EC	1934	BGTST3	LDAR R6,R12	MOS59340
9164	0A65	1935	AAR	R6,R5	MOS59350
9166	26E2	1936	AIS	R6,2	MOS59360
9168	0889	1937	LDAR	R8,R9	MOS59370
916A	05E8	1938	CLAR	R6,R9	MOS59380
916C	4380 918E	1939	BNL	BGTST6	MOS59390
9170	C360 7FC0	1940	TAI	R6,X'7FC0'	MOS59400
9174	2133	1941	BNZS	BGTST4	MOS59410
9176	C860 0040	1942	LDAI	R6,X'40'	MOS59420
917A	4846 0000	1943	BGTST4	LH R4,0(R6)	MOS59430
917E	0543	1944	CLAR	R4,R3	MOS59440
9180	2134	1945	BNES	BGTST5.5	MOS59450
9182	C160 917A	1946	BXLE	R6,BGTST4	MOS59460
9186	2304	1947	BS	BGTST6	MOS59470
		1948	*		MOS59480
9188	41E0 9BAE	1949	BGTST5.5	BAL LINK,ERROR	MOS59490
918C	2205	1950	BS	BGTST5	MOS59500
		1951	*		MOS59510
918E	D100 9DF0	1952	BGTST6	LM R0,MCSSAVE+32	MOS59520
9192	4026 0000	1953	STH	R2,0(R6)	MOS59530
9196	C160 90F0	1954	BGTST7	BXLE R6,SFTSET1	MOS59540
919A	03CE	1955	BR	R14	MOS59550
		1956	*		MOS59560
		1957	*	*****	MOS59570
		1958	*	(R6)	MOS59580
919C	40A6 0000	1959	STOCP	STH R10,0(R6)	MOS59590
91A0	45A6 0000	1960	CLH	R10,0(R6)	MOS59600
91A4	4230 91D8	1961	BNE	FITERE1	MOS59610
91A8	40E6 0000	1962	LOPRTN1	STH R11,0(R6)	MOS59620
91AC	45B6 0000	1963	CLH	R11,0(R6)	MOS59630
91B0	4230 91DC	1964	BNE	FITTER2	MOS59640
91B4	0A65	1965	LOPRTN2	AAR R6,R5	MOS59650
91B6	40A6 0000	1966	STH	R10,0(R6)	MOS59660
91B8	45A6 0000	1967	CLH	R10,0(R6)	MOS59670
91B8	4230 91D8	1968	BNE	FITTER1	MOS59680

TEST 5

91C2	40E6 0000	1969	LOPRTN3	STH	R11,0(R6)	YES, STORE SECOND DATA PATTERN	MOS59690
91C6	45B6 0000	1970		CLH	R11,0(R6)	DATA EQUAL ?	MOS59700
91CA	4230 91DC	1971		BNE	FITERR2	NO, BRANCH TO ERROR	MOS59710
91CE	0B65	1972		SAR	R6,R5	REVERT TO FIRST LOCATION	MOS59720
91D0	27C1	1973	LOPRTN4	SIS	R12,1	DECREMENT POUND COUNTER	MOS59730
91D2	4236 0002	1974		BNZ	2(R6)	BRANCH IF NOT DONE	MOS59740
91D6	03CD	1975	LOPRTN5	BR	R13	RETURN	MOS59750
	0000 91D8	1976	ENDMCV5	EQJ	*	(R6)+62	MOS59760
		1977	*				MOS59770
		1978	*			*****	MOS59780
		1979	*				MOS59790
91D8	083A	1980	FITERR1	LDAR	R3,R10	LOAD EXPECTED DATA	MOS59800
91DA	23C2	1981		BS	FITERR3		MOS59810
		1982	*				MOS59820
91DC	083B	1983	FITERR2	LDAR	R3,R11	LOAD EXPECTED DATA	MOS59830
		1984	*				MOS59840
91DE	C840 3044	1985	FITERR3	LDAI	R4,C'0D'		MOS59850
91E2	4040 8A56	1986		STH	R4,ERRNC	SET ERRNO = C'0D'	MOS59860
91E6	4846 0000	1987		LH	R4,0(R6)		MOS59870
91EA	41F0 9BAE	1988		BAL	LINK,ERROR	PRINT ERROR TTOO	MOS59880
91EE	4560 9DC2	1989		CLH	R6,VLOLIM	IS LOC UNDER TEST TRUE ?	MOS59890
91F2	033D	1990		BER	R13	YES, RETURN	MOS59900
91F4	0B65	1991		SAR	R6,R5	NO, CORRECT THE LOC	MOS59910
91F6	030D	1992		BR	R13	RETURN	MOS59920
		1993	*				MOS59930
		1994	*			*****	MOS59940
		1995	*	END	TEST 5		MOS59950

TEST 6

1997 * TEST 6 DIAGONAL GALPAT TEST
1998 *
1999 * PURPOSE:
2000 * THE TEST RUNS A GALLOPING PATTERN ON ALL DIAGONALS OF
2001 * EACH 16K RAM AND CHECKS THAT NO BACKGROUND LOCATIONS
2002 * HAVE CHANGED DURING THE DIAGONAL TEST.
2003 *
2004 * ASSUMPTIONS:
2005 * MINIMUM 64KB MOS MEMORY
2006 *
2007 * DESIGN SPECIFICATIONS:
2008 * 1. THE TEST IS EXECUTED FOR EACH OF THE SIX BACKGROUND
2009 * PATTERNS.
2010 * 2. AN ALTERNATE R-W-R-W-B-W-R-W-R(ETC) IS DONE TO A TEST
2011 * CELL AND FOLLOWING CELLS ON THE DIAGONAL SUCESSIVELY.
2012 * 3. THE TEST CELL IS MOVED ONE CELL UP THE DIAGONAL AND
2013 * THE PROCEDURE IS REPEATED.
2014 * 4. AFTER THE DIAGONAL IS COMPLETED, THE BACKGROUND
2015 * PATTERN IN THE REST OF EACH 16K CHIP AS TESTED.
2016 * 5. THE DIAGONAL IS THEN MOVED AND 2-4 ABOVE ARE REPEATED
2017 * UNTIL ALL DIAGONALS HAVE BEEN TRAVERSED.
2018 *
2019 * OPTIONS:
2020 * SCOPE - ERROR OPTION MODE
2021 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST
2022 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST
2023 * 2 - PRINT ERROR DATA AND CONTINUE TEST
2024 * 3 - PRINT ERROR DATA AND HALT
2025 * 4 - IGNORE ERROR
2026 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST
2027 *
2028 * HOW TO RUN THE TEST:
2029 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE.
2030 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE.

91F8	2410	2032	TEST6	LIS	R1,0	MOS60320
91FA	4010 9DC2	2033		STH	R1,VLOLIM	FORCE VLOLIM = 0
91FE	2404	2034		LIS	R0,4	MOS60340
9200	C820 9D6A	2035		LDAI	R2,LOMSG	MOS60350
9204	41F0 85F6	2036		BAL	LINK,HEXASC	MOS60360
9208	C810 7FFF	2037		LDAI	R1,X'7FFF'	MOS60370
920C	4010 9DC4	2038		STH	R1,VHILIM	FORCE VHILIM = 0
9210	C820 9D70	2039		LDAI	R2,HIMSG	MOS60390
9214	41F0 85F6	2040		BAL	LINK,HEXASC	MOS60400
9218	C850 9D50	2041		LDAI	R5,T6MSG	MOS60410
921C	41F0 8656	2042		BAL	LINK,PRINT	PRINT LIMITS UNDER DIAG. GALPAT TEST
9220	C850 9D6A	2043		LDAI	R5,LOMSG	MOS60430
9224	41F0 8656	2044		BAL	LINK,PRINT	MOS60440
9228	2411	2045		LIS	R1,1	MOS60450
922A	C820 0102	2046		LDAI	R2,X'102'	LOAD CELL INCREMENT VALUE
922E	C890 00FE	2047		LDAI	R9,X'FE'	LOAD TOP OF COLUMN MASK VALUE

TEST 6

9232	C8C0 7FFF	2048	LDAI	R12,X'7FFE'	LOAD CHIP LIMIT MASK	MOS60480	
9236	24A0	2049	LIS	R10,0		MOS60490	
9238	25E1	2050	ICS	R11,1		MOS60500	
923A	24D0	2051	LIS	R13,0	W/BACKGROUND = 0'S	MOS60510	
923C	41E0 926A	2052	BAL	R14,TEST6ALL	DO DIAGONAL GALPAT TEST	MOS60520	
		2053 *				MOS60530	
9240	25A1	2054	LCS	R10,1		MOS60540	
9242	24B0	2055	LIS	R11,0	W/BACKGROUND = F'S	MOS60550	
9244	41E0 926A	2056	BAL	R14,TEST6ALL	DO DIAGONAL GALPAT TEST	MOS60560	
		2057 *				MOS60570	
9248	24D2	2058	LIS	R13,2	W/BACKGROUND = A'S/CHIP	MOS60580	
924A	41E0 926A	2059	BAL	R14,TEST6ALL	DO DIAGONAL GALPAT TEST	MOS60590	
		2060 *				MOS60600	
924E	24A0	2061	LIS	R10,0		MOS60610	
9250	25E1	2062	LCS	R11,1	W/BACKGROUND = 5'S/CHIP	MOS60620	
9252	41E0 926A	2063	BAL	R14,TEST6ALL	DO DIAGONAL GALPAT TEST	MOS60630	
		2064 *				MOS60640	
9256	C8D0 0100	2065	LDAI	R13,X'100'	W/BACKGROUND = 128-0'S, 128-F'S,..	MOS60650	
925A	41E0 926A	2066	BAL	R14,TEST6ALL	DO DIAGONAL GALPAT TEST	MOS60660	
		2067 *				MOS60670	
925E	25A1	2068	LCS	R10,1		MOS60680	
9260	24B0	2069	LIS	R11,0	W/BACKGROUND = 128-F'S, 128-0'S,..	MOS60690	
9262	41E0 926A	2070	BAL	R14,TEST6ALL	DO DIAGONAL GALPAT TEST	MOS60700	
		2071 *				MOS60710	
9266	4300 83A8	2072	B	TSTEND	END OF TEST (RETURN TO EXEC)	MOS60720	
		2073 *				MOS60730	
		2074 *	*****	*****	*****	MOS60740	
		2075 *				MOS60750	
926A	4860 9DC2	2076	TEST6ALL	IH	R6,VLOLIM	LOAD AVAILABLE MEMORY LIMITS	MOS60760
926E	4880 9DC4	2077		IH	R8,VHILIM		MOS60770
9272	2472	2078		LIS	R7,2		MOS60780
		2079 *					MOS60790
9274	C3E0 7FC0	2080	TAI	R6,X'7FC0'			MOS60800
9278	2133	2081	BNZS	T6S1			MOS60810
927A	C860 0040	2082	LDAI	R6,X'40'	FORCE LOLIM		MOS60820
927E	083A	2083	T6S1	LDAR	R3,R10	GET APPROPRIATE BACKGROUND PATTERN	MOS60830
9280	C36D 0000	2084		TAI	R6,0(R13)		MOS60840
9284	2332	2085		BZS	T6S2		MOS60850
9286	083B	2086		LDAR	R3,R11		MOS60860
9288	4036 0000	2087	T6S2	STH	R3,0(R6)	STORE BACKGROUND PATTERN	MOS60870
928C	C160 927E	2088	T6S2.5	BXLE	R6,T6S1	TO ALL AVAILABLE MEMORY	MOS60880
		2089 *					MOS60890
9290	2400	2090	T6S3	LIS	R0,0	R0 = X0	MOS60900
9292	0880	2091	T6S4	LDAR	R8,R0	R8 = TEST CELL	MOS60910
9294	0870	2092	T6S5	LDAR	R7,R0	R7 = RUNNING CELL	MOS60920
9296	C380 7FC0	2093	T6S6	TAI	R8,X'7FC0'	TEST CELL < X'40' ?	MOS60930
929A	4330 9310	2094		BZ	INCRTC2	YES, BRANCH	MOS60940
929E	C370 7FC0	2095		TAI	R7,X'7FC0'	RUNNING CELL < X'40' ?	MOS60950
92A2	4330 92F0	2096		BZ	INCRRC	YES, BRANCH	MOS60960
92A6	0578	2097		CLAR	R7,R8	RUNNING CELL = TEST CALL ?	MOS60970
92A8	4330 92F0	2098		BE	INCRRC	YES, INCREMENT THE RUNNING CELL	MOS60980
92AC	0868	2099		LDAR	R6,R8	R6 = TEST CELL	MOS60990
92AE	083B	2100		LDAR	R3,R11	LOAD COMPLEMENT DATA PATTERN(C.D.P.)	MOS61000

TEST 6

92B0	C36D 0000	2101	TAI	R6,0(R13)	MOS61010
92B4	2332	2102	BZS	T6\$7	MOS61020
92B6	083A	2103	LDAR	R3,R10	MOS61030
92B8	4036 0000	2104	T6\$7	STH R3,0(R6)	MOS61040
92BC	C840 3130	2105	LDAI	R4,C'10'	MOS61050
92C0	4040 8A56	2106	STH	R4,ERRNO	MOS61060
92C4	4846 0000	2107	LH	R4,0(R6)	MOS61070
92C8	0543	2108	CLAR	R4,R3	MOS61080
92CA	4230 9370	2109	BNE	T6\$ER10	MOS61090
92CE	4036 0000	2110	T6\$8	STH R3,0(R6)	MOS61100
92D2	0867	2111	LDAR	R6,R7	MOS61110
92D4	6110 8A56	2112	AH	R1,ERRNO	MOS61120
92D8	083A	2113	LDAR	R3,R10	MOS61130
92DA	C36D 0000	2114	TAI	R6,0(R13)	MOS61140
92DE	2332	2115	BZS	T6\$9	MOS61150
92E0	083B	2116	LDAR	R3,R11	MOS61160
92E2	4846 0000	2117	T6\$9	LH R4,0(R6)	MOS61170
92E6	0543	2118	CLAR	R4,R3	MOS61180
92E8	4230 9378	2119	BNE	T6\$ER11	MOS61190
92EC	4036 0000	2120	T6\$10	STH R3,0(R6)	MOS61200
		2121	*		MOS61210
92F0	0867	2122	INCRRC	LDAR R6,R7	MOS61220
92F2	0469	2123	NAR	R6,R9	MOS61230
92F4	0569	2124	CLAR	R6,R9	MOS61240
92F6	2335	2125	BES	INCRTC	MOS61250
92F8	0A72	2126	AAR	R7,R2	MOS61260
92FA	047C	2127	NAR	R7,R12	MOS61270
92FC	43C0 9296	2128	B	T6\$6	MOS61280
		2129	*		MOS61290
9300	0868	2130	INCRTC	LDAR R6,R8	MOS61300
9302	083A	2131	LDAR	R3,R10	MOS61310
9304	C36D 0000	2132	TAI	R6,0(R13)	MOS61320
9308	2332	2133	BZS	INCRTC1	MOS61330
930A	083B	2134	LDAR	R3,R11	MOS61340
930C	4036 0000	2135	INCRTC1	STH R3,0(R6)	MOS61350
9310	0868	2136	INCRTC2	LDAR R6,R8	MOS61360
9312	0469	2137	NAR	R6,R9	MOS61370
9314	0569	2138	CLAR	R6,R9	MOS61380
9316	2335	2139	BES	INCRX0	MOS61390
9318	0A82	2140	AAR	R8,R2	MOS61400
931A	048C	2141	NAR	R8,R12	MOS61410
931C	4300 9294	2142	B	T6\$5	MOS61420
		2143	*		MOS61430
9320	41F0 87C2	2144	INCRX0	BAL LINK,TSTBRKX	MOS61440
		2145	*		MOS61450
9324	D000 9DF0	2146	CKBG60	STM R0,MOS\$SAVE+32	MOS61460
9328	C860 0040	2147	LDAI	R6,X'40'	MOS61470
932C	C880 7FFE	2148	LDAI	R8,X'7FFE'	MOS61480
9330	2472	2149	LIS	R7,2	MOS61490
9332	C840 3045	2150	LDAI	R4,C'0E'	MOS61500
9336	4040 8A56	2151	STH	R4,ERRNO	MOS61510
		2152	*	ERRNO = C'0E'	MOS61520
933A	083A	2153	CKBG61	LDAR R3,R10	MOS61530

TEST 6

933C C36D 0000	2154	TAI	R6,0(R13)	MOS61540
9340 2322	2155	BZS	CKBG62	MOS61550
9342 083B	2156	LDAR	R3,R11	MOS61560
9344 4846 0000	2157	CKBG62	LH R4,0(R6)	MOS61570
9348 0543	2158	CLAR	R4,R3	MOS61580
934A 2134	2159	BNES	CKBG64	MOS61590
934C C160 933A	2160	CKBG63	BYLE R6,CKBG61	MOS61600
9350 23C4	2161	BS	CKBG65	MOS61610
	2162 *			MOS61620
9352 41F0 9BAE	2163	CKBG64	BAL LINK,ERROR	MOS61630
9356 22C5	2164	BS	CKBG63	MOS61640
	2165 *			MOS61650
9358 D1C0 9DF0	2166	CKBG65	LM R0,MOSSAVE+32	MOS61660
935C CAC0 0100	2167	AAI	R0,X'100'	MOS61670
9360 9480	2168	EXBR	R8,R0	MOS61680
9362 2471	2169	LIS	R7,1	MOS61690
9364 9878	2170	WHR	R7,R8	MOS61700
9366 C5C0 8000	2171	CLAI	R0,X'8000'	MOS61710
936A 4280 9292	2172	BL	T6S4	MOS61720
936E 030E	2173	BR	314	MOS61730
	2174 *			MOS61740
9370 41F0 9BAE	2175	T6ER10	BAL LINK,ERROR	MOS61750
9374 4300 92CE	2176	B	T6S8	MOS61760
	2177 *			MOS61770
9378 41F0 9BAE	2178	T6ER11	BAL LINK,ERROR	MOS61780
937C 4300 92EC	2179	B	T6S10	MOS61790
	2180 *			MOS61800
	2181 * *****			MOS61810
	2182 * END TEST 6			MOS61820

TEST 7

2184 * TEST 7 MEMORY HOLD TEST MOS61840
 2185 * MOS61850
 2186 * MOS61860
 2187 * PURPOSE MOS61870
 2188 * THIS TEST CHECKS THE ABILITY OF THE MOS MEMORY REFRESH
 CIRCUIT TO OPERATE IN THE EVENT OF A POWER FAILURE. MOS61880
 2189 * MOS61890
 2190 * ASSUMPTIONS: MOS61900
 2191 * MINIMUM 64KB MOS MEMORY & BATTERY BACK-UP POWER SUPPLY. MOS61910
 2192 * MOS61920
 2193 * DESIGN SPECIFICATIONS: MOS61930
 2194 * 1. A BACKGROUND PATTERN IS WRITTEN TO ALL MEMORY. MOS61940
 2195 * 2. POWER IS REMOVED FOR 30 SECONDS(MINIMUM). MOS61950
 2196 * 3. UPON RESTART, THE PROGRAM READS MEMORY 8 TIMES MOS61960
 2197 * CHECKING FOR ERRORS. MOS61970
 2198 * MOS61980
 2199 * OPTIONS MOS61990
 2200 * SCOPE - ERROR OPTION MODE MOS62000
 2201 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS62010
 2202 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS62020
 2203 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS62030
 2204 * 3 - PRINT ERROR DATA AND HALT MOS62040
 2205 * 4 - IGNORE ERROR MOS62050
 2206 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS62060
 2207 * MOS62070
 2208 * HOW TO RUN THE TEST: MOS62080
 2209 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE. MOS62090
 2210 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS62100

9380	4860 8B1A	2212	TEST7	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS62120
9384	4880 8B25	2213		LH	R8,HILIM+6		MOS62130
9388	2788	2214		SIS	R8,8		MOS62140
938A	2478	2215		LIS	R7,8		MOS62150
938C	2411	2216		LIS	R1,1	LOAD DISPLAY ADDRESS	MOS62160
938E	24A0	2217		LIS	R10,0	LOAD 4 DATA PATTERNS	MOS62170
9390	25B1	2218		LCS	R11,1		MOS62180
9392	C8C0 AAAA	2219		LDAI	R12,X'AAAA'		MOS62190
9396	C8D0 5555	2220		LDAI	R13,X'5555'		MOS62200
939A	C360 7FC0	2221		TAI	R6,X'7FC0'		MOS62210
939E	2133	2222		BNZS	T7S1		MOS62220
93A0	C860 0040	2223		LDAI	R6,X'40'	FORCE LOLIM	MOS62230
93A4	40A6 0000	2224	T7S1	STH	R10,0(R6)		MOS62240
93A8	40B6 0002	2225		STH	R11,2(R6)		MOS62250
93AC	40C6 0004	2226		STH	R12,4(R6)		MOS62260
93B0	40D6 0006	2227		STH	R13,6(R6)	STORE DATA PATTERNS	MOS62270
93B4	C160 93A4	2228	T7S1.5	BXLE	R6,T7S1	FROM LOLIM TO HILIM	MOS62280
93B8	C850 9402	2229		LDAI	R5,T7MM1		MOS62290
93BC	4050 003E	2230		STH	R5,X'3E'	SET VECTOR FOR MM ON POWER DOWN	MOS62300
93C0	C850 9E30	2231		LDAI	R5,MMSAVE		MOS62310
93C4	4050 0022	2232		STH	R5,X'22'	SET T7 MM POINTER	MOS62320
93C8	9555	2233		EPSR	R5,R5		MOS62330
93CA	C450 FFF0	2234		NAI	R5,X'FFF0'	MASK OFF CC TO ZERO	MOS62340

TEST 7

93CE	4050 003C	2235	STH	R5,X'3C'		MOS62350
93D2	C850 9D78	2236	T7OUTMSG	LDAI R5,T7MSG	UNCONDITIONALLY PRINT:	MOS62360
93D6	4050 8A0C	2237	STH	R5,ISITERR	"POWER DOWN PROC. FOR 30 SECONDS"	MOS62370
93DA	41E0 8656	2238	BAL	LINK,PRINT		MOS62380
93DE	2450	2239	LIS	R5,0		MOS62390
93E0	4050 8A0C	2240	STH	R5,ISITERR		MOS62400
93E4	25E1	2241	LCS	R14,1	ESTABLISH WAIT COUNTERS	MOS62410
93E6	C820 0080	2242	T7S2	LDAI R2,128		MOS62420
		2243	*			MOS62430
93EA	2721	2244	T7S3	SIS R2,1		MOS62440
93EC	2031	2245	BNZS	T7S3	WAIT 256* SF INSTRUCTION TIMES	MOS62450
93EE	C8FC 94EA	2246	LDAI	LINK,T7END		MOS62460
93F2	4CFC 8A0A	2247	STH	LINK,BRKVECT	SET BREAK VECTOR	MOS62470
93F6	41E0 87D4	2248	BAL	LINK,TSTBRK	IF "BREAK" GO TO T7END ELSE RETURN	MOS62480
93FA	27E1	2249	SIS	R14,1		MOS62490
93FC	203F	2250	BNZS	T7S2	WAIT 30 SECONDS FOR MM	MOS62500
93FE	43C0 93D2	2251	B	T7OUTMSG	ON POWER DOWN	MOS62510
		2252	*			MOS62520
		2253	*	*****	*****	MOS62530
		2254	*			MOS62540
9402	C8E0 9418	2255	T7MM1	LDAI R14,T7MM2	SET VECTOR FOR MM	MOS62550
9406	40E0 003E	2256	STH	R14,X'3E'	ON POWER UP	MOS62560
940A	95EE	2257	EPSR	R14,R14		MOS62570
940C	C6E0 8000	2258	OAI	R14,X'8000'	FORCE BUSY BIT SET	MOS62580
9410	C4E0 FFF0	2259	NAI	R14,X'FFF0'	MASK OFF CC TO ZERO	MOS62590
9414	954E	2260	EPSR	R4,R14	WAIT FOR SECOND MM (PSW = X'80F0')	MOS62600
9416	22CA	2261	BS	T7MM1	BRANCH ON RUN W/O SECOND MM	MOS62610
		2262	*			MOS62620
		2263	*	*****	*****	MOS62630
		2264	*			MOS62640
9418	D3E0 8010	2265	T7MM2	LB R14,IO	GET CONSOLE POINTER	MOS62650
941C	27E5	2266	SIS	R14,5	IS CONSOLE ON PASLA ?	MOS62660
941E	2334	2267	BZS	T7MM2A	YES, BRANCH	MOS62670
9420	48E0 89E6	2268	LH	R14,PASFLG	IS CONSOLE ON PASLA ?	MOS62680
9424	233C	2269	BZS	T7MM3	NO, BRANCH	MOS62690
9426	D3E0 8010	2270	T7MM2A	LB R14,IO	GET CONSOLE POINTER	MOS62700
942A	0AEE	2271	AAR	R14,R14	SET INDEX	MOS62710
942C	D34E 8010	2272	LB	R4,IO(R14)	GET CONSOLE ADDRESS	MOS62720
9430	DE4E 89F8	2273	OC	R4,CON2ND(R14)	ISSUE CONSOLE SPEED COMMAND	MOS62730
9434	DE40 89EC	2274	OC	R4,CONRD	ISSUE CONSOLE READ COMMAND	MOS62740
9438	DB40 89E4	2275	RD	R4,SINK	DUMMY READ TO SET BUSY	MOS62750
		2276	*			MOS62760
943C	D3E0 8011	2277	T7MM3	LB R14,IO+1	GET LIST DEVICE POINTER	MOS62770
9440	27F5	2278	SIS	R14,5	IS LIDT DEVICE ON MICRO-IO BUS ?	MOS62780
9442	2334	2279	BZS	T7MM3A	YES, BRANCH	MOS62790
9444	48E0 89E8	2280	LH	R14,PASFLG2	IS LIST DEV ON PASLA ?	MOS62800
9448	233D	2281	BZS	T7MMCOM	NO, BRANCH	MOS62810
944A	D3E0 8011	2282	T7MM3A	LB R14,IO+1	GET LIST POINTER	MOS62820
944E	D340 8010	2283	LB	R4,IO	GET CONSOLE POINTER	MOS62830
9452	05E4	2284	CLAR	R14,R4	CONSOLE = LIST POINTER ?	MOS62840
9454	2337	2285	BES	T7MMCOM	YES, BRANCH	MOS62850
9456	D34E 8011	2286	LB	R4,IO+1(R14)	GET LIST DEV ADDRESS	MOS62860
945A	DE4E 89F8	2287	OC	R4,LST2ND(R14)	ISSUE LIST SPEED COMMAND	MOS62870

TEST 7

	945E	DE4E 89ED	2288	OC	R4,LSTWRT(R14)	ISSUE LIST WRITE COMMAND	MOS62880
			2289 *				MOS62890
9462	48E0 8008		2290 T7MMCOM	IH	R14,PSW2		MOS62900
9466	950E		2291	EPSR	R0,R14	PSW = X'30F0'	MOS62910
9468	C840 893E		2292	LDAI	R4,MMO		MOS62920
946C	4040 003E		2293	STH	R4,X'3E'	SET NEW MM POINTER	MOS62930
9470	C840 9E50		2294	LDAI	R4,RSAVE		MOS62940
9474	4040 0022		2295	STH	R4,X'22'	RESET ETPE MM POINTER	MOS62950
9478	24E8		2296	LIS	R14,8	LOAD MEMORY CHECK COUNTER	MOS62960
947A	C840 3230		2297	LDAI	R4,C'20'		MOS62970
947E	4040 8A56		2298	STH	R4,ERRNO	ERRNO = C'20'	MOS62980
9482	2472		2299	LIS	R7,2		MOS62990
			2300 *				MOS63000
9484	4860 BB1A		2301 T7S4	IH	R6,LOLIM+6		MOS63010
9488	6110 8A56		2302	A5M	R1,ERRNO	INCREMENT ERRNO (21-28)	MOS63020
948C	C360 7FC0		2303	TAI	R6,X'7FC0'		MOS63030
9490	2133		2304	BNZS	T7S5		MOS63040
9492	C860 0040		2305	LDAI	R6,X'40'	FORCE LOLIM	MOS63050
			2306 *				MOS63060
9496	083A		2307 T7S5	LDAR	R3,R10	GET FIRST DATA PATTERN	MOS63070
9498	4846 0000		2308	LH	R4,0(R6)	LOAD DATA FROM LOC	MOS63080
949C	0543		2309	CLAR	R4,R3	DATA EQUAL ?	MOS63090
949E	2333		2310	BES	T7S6	YES, BRANCH	MOS63100
94A0	41E0 9BAE		2311	BAL	LINK,ERROR	NO, ERROR	MOS63110
94A4	083B		2312 T7S6	LDAR	R3,R11	GET SECOND DATA PATTERN	MOS63120
94A6	2662		2313	AIS	R6,2	INCREMENT LOC COUNTER	MOS63130
94A8	4846 0000		2314	LH	R4,0(R6)	LOAD DATA FROM LOC	MOS63140
94AC	0543		2315	CLAR	R4,R3	DATA EQUAL ?	MOS63150
94AE	2333		2316	BES	T7S7	YES, BRANCH	MOS63160
94B0	41E0 9BAE		2317	BAL	LINK,ERROR	NO, ERROR	MOS63170
94B4	083C		2318 T7S7	LDAR	R3,R12	GET THIRD DATA PATTERN	MOS63180
94B6	2662		2319	AIS	R6,2	INCREMENT LOC COUNTER	MOS63190
94B8	4846 0000		2320	LH	R4,0(R6)	LOAD DATA FROM LOC	MOS63200
94BC	0543		2321	CLAR	R4,R3	DATA EQUAL ?	MOS63210
94BE	2333		2322	BES	T7S8	YES, BRANCH	MOS63220
94C0	41E0 9BAE		2323	BAL	LINK,ERROR	NO, ERROR	MOS63230
94C4	083D		2324 T7S8	LDAR	R3,R13	GET FOURTH DATA PATTERN	MOS63240
94C6	2662		2325	AIS	R6,2	INCREMENT LOC COUNTER	MOS63250
94C8	4846 0000		2326	LH	R4,0(R6)	LOAD DATA FROM LOC	MOS63260
94CC	0543		2327	CLAR	R4,R3	DATA EQUAL ?	MOS63270
94CE	2333		2328	BES	T7S9	YES, BRANCH	MOS63280
94D0	41E0 9BAE		2329	BAL	LINK,ERROR	NO, ERROR	MOS63290
94D4	C160 9496		2330 T7S9	BXLE	R6,T7S5	CHECK LOLIM TO HILIM	MOS63300
94D8	C8F0 94EA		2331	LDAI	LINK,T7END		MOS63310
94DC	40F0 8A0A		2332	STH	LINK,BRKVECT		MOS63320
94E0	41F0 87D4		2333	BAL	LINK,TSTBRK	IF "BREAK" GO TO T7END ELSE RETURN	MOS63330
94E4	27E1		2334	SIS	R14,1	CHECKED MEMORY 8 TIMES ?	MOS63340
94E6	4230 9484		2335	BNZ	T7S4	NO, REPEAT	MOS63350
94EA	41E0 88D0		2336 T7END	BAL	LINK,LCORE	RESET LOW CORE	MOS63360
94EE	4300 83A8		2337	B	TSTEND	YES, END OF TEST(RETURN TO EXEC)	MOS63370
			2338 *				MOS63380
			2339 *				MOS63390
			2340 *	END	TEST 7		MOS63400

TEST 8

2342 * TEST 8 (OPTIONAL TEST) LONG COUNT RELOCATABLE
 2343 * HAMMER DISTURB TEST MOS63420
 2344 * MOS63430
 2345 * PURPOSE: MOS63440
 2346 * THE TEST EXERCISES THE MOS MEMORY IN AN ENVIRONMENT MOS63450
 2347 * SIMILAR TO THAT OF AN OPERATING SYSTEM. MOS63460
 2348 * MOS63470
 2349 * ASSUMPTIONS: MOS63480
 2350 * MINIMUM 64KB MOS MEMORY MOS63490
 2351 * MCS63500
 2352 * DESIGN SPECIFICATIONS: MCS63510
 2353 * THIS IS AN "OVERNIGHT" (VERY LONG) TEST DESIGNED TO MOS63520
 2354 * POINT OUT POSSIBLE "SOFT" FAILURE LOCATIONS IN MOS MOS63530
 2355 * MEMORY. (SIMILAR TO TEST 5) MCS63540
 2356 * MCS63550
 2357 * OPTIONS: MOS63560
 2358 * DATA - 16-BIT BACKGROUND DATA PATTERN MOS63570
 2359 * SCOPE - ERROR OPTION MODE MOS63580
 2360 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS63590
 2361 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS63600
 2362 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS63610
 2363 * 3 - PRINT ERROR DATA AND HALT MOS63620
 2364 * 4 - IGNORE ERROR MOS63630
 2365 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS63640
 2366 * MOS63650
 2367 * HOW TO RUN THE TEST:
 2368 * 1. ENTER "SCOPE" & "DATA" OPTIONS VIA CONSOLE DEVICE.
 2369 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS63660
 MOS63670
 MOS63680
 MOS63690

94F2 4860 3B1A	2371 TEST8	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS63710
94F6 4880 8326	2372	LH R8,HILIM+6		MOS63720
94FA 08A6	2373	LDAR R10,R6	R10 = LOLIM	MOS63730
94FC 08B8	2374	LDAR R11,R8	R11 = HILIM	MOS63740
94FE 0878	2375	LDAR R7,R8		MOS63750
9500 0876	2376	SAR R7,R6		MOS63760
9502 C570 009C	2377	CLAI R7,ENDMOV8-MOVPRG+6	IS HILIM - LOLIM LARGE ENOUGH ?	MOS63770
9506 4280 9672	2378	BL T8L0PRT	IF NOT, BRANCH AND PRINT ERROR	MOS63780
950A 2411	2379	LIS R1,1	LOAD DISPLAY ADDRESS	MOS63790
950C 4850 8AF6	2380	LH R5,DATA+6	LOAD BACKGROUND DATA PATTERN	MOS63800
9510 2472	2381	LIS R7,2		MOS63810
9512 C820 0098	2382	LDAI R2,ENDMOV8-MOVPRG+2		MOS63820
9516 C360 7FC0	2383	TAI R6,X'7FC0'		MOS63830
951A 2133	2384	BNZS T8SW		MOS63840
951C C860 0040	2385	LDAI R6,X'40'		MOS63850
9520 4056 0000	2386 T8SW	STH R5,0(R6)	STORE BACKGROUND DATA PATTERN	MOS63860
9524 C160 9520	2387 T8SW1	BXLE R6,T8SW	FROM LCLIM TO HILIM	MCS63870
9528 4860 8B1A	2388	LH R6,LOLIM+6		MOS63880
952C C360 7FC0	2389 T8SW2	TAI R6,X'7FC0'		MOS63890
9530 2133	2390	BNZS T8SW3		MOS63900
9532 C860 0040	2391	LDAI R6,X'40'	FORCE LOLIM	MOS63910
	2392 *			MOS63920

TEST 8

9536	D000 9DF0	2393	T8SW3	STM	R0,MOSSAVE+32	SAVE REGISTERS (0-F)	MOS63930
953A	0816	2394		LDAR	R1,R6		MOS63940
953C	D120 95DC	2395		LM	R2,MOVPRG	MOVE SUB INTO TEST AREA	MOS63950
9540	D021 0032	2396		STM	R2,2(R1)		MOS63960
9544	D120 95F8	2397		LM	R2,MOVPRG+28		MOS63970
9548	D021 001E	2398		STM	R2,30(R1)		MOS63980
954C	D120 9614	2399		LM	R2,MOVPRG+56		MOS63990
9550	D021 003A	2400		STM	R2,58(R1)		MOS64000
9554	D120 9630	2401		LM	R2,MOVPRG+84		MOS64010
9558	D021 0056	2402		STM	R2,86(R1)		MOS64020
955C	D120 964C	2403		LM	R2,MOVPRG+112		MOS64030
9560	D021 0072	2404		STM	R2,114(R1)		MOS64040
9564	D1B0 9668	2405		LM	B11,MOVPRG+140		MOS64050
9568	D0B1 008E	2406		STM	R11,142(R1)		MOS64060
956C	D100 9DF0	2407		LM	R0,MOSSAVE+32	RESTORE REGISTERS	MOS64070
9570	C840 893E	2408		LDAI	R4,M0		MOS64080
9574	4040 003E	2409		STM	R4,X'3E'	SET NEW MM POINTER	MOS64090
9578	0B82	2410		SAR	R8,R2		MOS64100
		2411 *					MOS64110
957A	41F0 87C2	2412	T8SX	BAL	LINK,TSTBRKX	IF "BREAK" GO TO "OPTIN" ELSE RETURN	MOS64120
957E	C840 3044	2413		LDAI	R4,C'0D'		MOS64130
9582	4040 8A56	2414		STM	R4,ERRNO	ERRNO = C'0D'	MOS64140
9586	41E6 0002	2415		BAL	R14,2(R6)	BRANCH TO "MOVPRG"	MOS64150
		2416 *					MOS64160
958A	D0C0 9DF0	2417		STM	R0,MOSSAVE+32	SAVE REGISTERS (0-F)	MOS64170
958E	0816	2418		LDAR	R1,R6		MOS64180
9590	D1B1 008C	2419		LM	R11,140(R1)	RELOCATE SUB IN MEMORY (+2)	MOS64190
9594	D0B1 008E	2420		STM	R11,142(R1)		MOS64200
9598	D121 0070	2421		LM	R2,112(R1)		MOS64210
959C	D021 0072	2422		STM	R2,114(R1)		MOS64220
95A0	D121 0054	2423		LM	R2,84(R1)		MOS64230
95A4	D021 0056	2424		STM	R2,86(R1)		MOS64240
95A8	D121 0038	2425		LM	R2,56(R1)		MOS64250
95AC	D021 003A	2426		STM	R2,58(R1)		MOS64260
95B0	D121 001C	2427		LM	R2,28(R1)		MOS64270
95B4	D021 001E	2428		STM	R2,30(R1)		MOS64280
95B8	D121 0000	2429		LM	R2,0(R1)		MOS64290
95BC	D021 0002	2430		STM	R2,2(R1)		MOS64300
95C0	9461	2431		EXBR	R6,R1		MOS64310
95C2	2441	2432		LIS	R4,1		MOS64320
95C4	9846	2433		WHR	R4,R6	DISPLAY ADDRESS UNDER TEST	MOS64330
95C6	D100 9DF0	2434		LM	R0,MOSSAVE+32	RESTORE REGISTERS (0-F)	MOS64340
		2435 *					MOS64350
95CA	4056 FFFE	2436		STM	R5,-2(R6)	RESTORE BACKGROUND AT OLD TEST LOC	MOS64360
95CE	08EB	2437		LDAR	R8,R11		MOS64370
95D0	CB82	2438		SAR	R8,R2		MOS64380
95D2	0568	2439		CLAR	R6,R8	DONE ?	MOS64390
95D4	4280 957A	2440		BL	T8SX	NO, BRANCH (CONTINUE)	MOS64400
95D8	4300 83A8	2441		B	TSTEND	YES, END OF TEST (RETURN TO EXEC)	MOS64410
		2442 *					MOS64420
		2443 *					MOS64430
		2444 *	(R6)	LIS	R3,0		MOS64440
		2445 MOVPRG				INITIALIZE DATA PATTERN	MOS64450

TEST 8

95DE	9E14	2446	SSB	R1,R4	EXERCISE BIT NO.3 IN INSTR. STREAM	MOS64460
		2447 *				MOS64470
95E0	4036 0000	2448	MOVPRG1	STH R3,0(R6)	STORE PATRN AT LOW TEST LOC	MOS64480
95E4	4846 0000	2449	LH	R4,0(R6)	LOAD FROM LOW LOC	MOS64490
95E8	0543	2450	CLAR	R4,R3	EQUAL ?	MOS64500
95EA	2134	2451	BNES	MOVPRG2F	NO, BRANCH	MOS64510
95EC	2731	2452	MOVPRG2	SIS R3,1	YES, DECREMENT DATA PATTERN	MCS64520
95EE	2037	2453	BNZS	MOVPRG1	REPEAT TILL DONE	MOS64530
95F0	23C4	2454	BS	MOVPRG22	BRANCH	MOS64540
		2455 *				MOS64550
95F2	41F0 9BAE	2456	MOVPRG2F	BAL	LINK, ERROR	MCS64560
95F5	2205	2457		ES	MOVPRG2	MOS64570
		2458 *				MOS64580
95F8	0842	2459	MOVPRG22	LDAR R4,R11		MOS64590
95FA	0846	2460	SAR	R4,R6		MOS64600
95FC	0542	2461	CLAR	R4,R2	IS TEST AREA LARGE ENOUGH ?	MOS64610
95FE	218F	2462	BLS	MOVPRG28	NO, BRANCH	MOS64620
9600	0A62	2463	AAR	R6,R2	YES, INCREMENT TEST CELL	MOS64630
9602	4036 0000	2464	MOVPRG15	STH R3,0(R6)	STORE PATRN AT HIGH TEST LOC	MOS64640
9606	4846 0000	2465	LH	R4,0(R6)	LOAD FROM HIGH LOC	MOS64650
960A	0543	2466	CLAR	R4,R3	EQUAL ?	MOS64660
960C	2135	2467	BNES	MOVPRG9F	NO, BRANCH	MOS64670
960E	2731	2468	MOVPRG25	SIS R3,1	YES, DECREMENT DATA PATTERN	MOS64680
9610	2037	2469	BNZS	MOVPRG15	REPEAT TILL DONE	MOS64690
9612	0B62	2470	SAR	R6,R2	DECREMENT TEST CELL	MOS64700
9614	2304	2471	BS	MOVPRG28	BRANCH	MOS64710
		2472 *				MOS64720
9616	41F0 9BAE	2473	MOVPRG9F	BAL	LINK, ERROR	MOS64730
961A	2206	2474		BS	MOVPRG25	MOS64740
		2475 *				MOS64750
961C	0886	2476	MOVPRG28	LDAR R8,R6		MOS64760
961E	08C6	2477	LDAR	R12,R6	SAVE TEST LOCATION COUNTER	MOS64770
9620	0835	2478	LDAR	R3,R5	GET BACKGROUND DATA PATTERN	MOS64780
9622	C840 3045	2479	LDAI	R4,C'OE'		MCS64790
9626	4040 8A56	2480	STH	R4,ERRNO	ERRNO = C'OE'	MOS64800
962A	086A	2481	LDAR	R6,R10		MOS64810
962C	C360 7FC0	2482	TAI	R6,X'7FC0'	IS LOC < X'40' ?	MOS64820
9630	2133	2483	BNZS	MOVPRG29	NO, BRANCH	MOS64830
9632	C860 0040	2484	LDAI	R6,X'40'	YES, FORCE LOC TO X'40'	MOS64840
9636	0568	2485	MOVPRG29	CLAR R6,R8	IS LOW BACKGROUND AREA PRESENT ?	MOS64850
9638	238C	2486	BNLS	MOVPRG5	NO, BRANCH	MOS64860
963A	4846 0000	2487	MOVPRG3	LH R4,0(R6)		MOS64870
963E	0543	2488	CLAR	R4,R3	IS LOW BACKGROUND PATTERN OK ?	MOS64880
9640	2135	2489	BNES	MOVPRG4F	NO, BRANCH	MOS64890
9642	2662	2490	MOVPRG4	AIS R6,2	INCREMENT LOW LOCATION COUNTER	MOS64900
9644	0568	2491	CLAR	R6,R8	FINISHED LOW BACKGROUND TESTING ?	MOS64910
9646	2086	2492	BLS	MOVPRG3		MOS64920
9648	23C4	2493	BS	MOVPRG5	BRANCH	MCS64930
		2494 *				MOS64940
964A	41F0 9BAE	2495	MOVPRG4F	BAL	LINK, ERROR	MOS64950
964E	2206	2496		BS	MOVPRG4	MOS64960
		2497 *				MOS64970
9650	0868	2498	MOVPRG5	LDAR R6,R8	RESTORE LOC COUNTER	MOS64980

TEST 8

9652	0A62	2499	AHR	R6,R2	MOS64990
9654	2662	2500	AIS	R6,2	MOS65000
9656	056E	2501	MOVPRG6	CLAR R6,R11	MOS65010
9658	238A	2502	BNLS	MOVPRG8	MOS65020
965A	4846 0000	2503	LH	R4,0(R6)	MOS65030
965E	0543	2504	CLAR	R4,23	MOS65040
9660	2133	2505	BNES	MOVPRG7F	MOS65050
9662	2662	2506	MOVPRG7	AIS R6,2	MOS65060
9664	22C7	2507	BS	MOVPRG6	MOS65070
		2508	*		MOS65080
9666	41F0 9BAE	2509	MOVPRG7F	BAL LINK,ERROR	MOS65090
966A	22C4	2510	BS	MOVPRG7	MOS65100
		2511	*		MOS65110
966C	C86C 0002	2512	MOVPRG8	LDAI R6,2(R12)	MOS65120
9670	03CE	2513	BR	R14	MOS65130
	0000 9672	2514	ENDMOV8	EQU *	MOS65140
		2515	*		MOS65150
		2516	*	*****	MOS65160
		2517	*		MOS65170
9572	C850 9D9E	2518	T8LOPRT	LDAI R5,T8LOMSG	MOS65180
9676	43C0 3BEA	2519	B	HILOPRT1	MOS65190
		2520	*		MOS65200
		2521	*	*****	MOS65210
		2522	*	END TEST 8	MOS65220

TEST 9

ECC DISTURB TEST

2524 * TEST 9-1 MARCHING PATTERN TEST MOS65240
 2525 * MOS65250
 2526 * PURPOSE: MOS65260
 2527 * THIS TEST CHECKS THAT THREE DIFFERENT BASE PATTERNS MOS65270
 2528 * CAN BE WRITTEN, COMPLEMENTED, AND MARCHED THROUGH THE MOS65280
 2529 * AVAILABLE MEMORY WITHOUT ERROR. MOS65290
 2530 * MOS65300
 2531 * ASSUMPTIONS: MOS65310
 2532 * MINIMUM 64KB MOS MEMORY MOS65320
 2533 * MOS65330
 2534 * DESIGN SPECIFICATIONS: MOS65340
 2535 * 1. (IN ASCENDING ORDER) WRITE AND READ THE BASE PATTERN. MOS65350
 2536 * 2. (IN DESCENDING ORDER) WRITE AND READ THE MOS65360
 2537 * COMPLEMENT PATTERN. MOS65370
 2538 * MOS65380
 2539 * OPTIONS: MOS65390
 2540 * SCOPE - ERROR OPTION MODE MOS65400
 2541 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS65410
 2542 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS65420
 2543 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS65430
 2544 * 3 - PRINT ERROR DATA AND HALT MOS65440
 2545 * 4 - IGNORE ERROR MOS65450
 2546 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS65460
 2547 * MOS65470
 2548 * HOW TO RUN THE TEST: MOS65480
 2549 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE. MOS65490
 2550 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS65500

967A	2411	2552	TEST9	LIS R1,1	LOAD DISPLAY ADDRESS	MOS65520
967C	C840 893E	2553		LDAI R4,MM0		MOS65530
9680	4C40 003E	2554		STH R4,X'3E'	SET NEW MM POINTER	MOS65540
9684	24A0	2555		LIS R10,0		MOS65550
9686	C850 8001	2556		LDAI R11,X'8001'		MOS65560
968A	24E0	2557		LIS R13,0	W/BACKGROUND = 0'S	MOS65570
968C	41E0 96C0	2558		BAL R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS65580
		2559 *				MOS65590
9690	C8A0 8001	2560		LDAI R10,X'8001'		MOS65600
9694	24E0	2561		LIS R11,0	W/BACKGROUND = F'S	MOS65610
9696	41E0 96C0	2562		BAL R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS65620
		2563 *				MOS65630
969A	24E2	2564		LIS R13,2	W/BACKGROUND = A'S	MOS65640
969C	41E0 96C0	2565		BAL R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS65650
		2566 *				MOS65660
96A0	24A0	2567		LIS R10,0		MOS65670
96A2	C8E0 8001	2568		LDAI R11,X'8001'	W/BACKGROUND = S'S	MOS65680
96A6	41E0 96C0	2569		BAL R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS65690
		2570 *				MOS65700
96AA	C8D0 0100	2571		LDAI R13,X'100'	W/BACKGROUND = 128-0'S,128-F'S...	MOS65710
96AE	41E0 96C0	2572		BAL R14,KHKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS65720
		2573 *				MOS65730
96B2	C8A0 8001	2574		LDAI R10,X'8001'		MOS65740

TEST 9 ECC DISTURB TEST

96B6	24E0	2575	LIS	R11,0		
96B8	41E0 96C0	2576	BAL	R14,KHKLOC	W/BACKGROUND =128-F'S,128-0'S, ETC DO A SINGLE DISTURB TEST (MIN-MAX)	MOS65750 MOS65760 MOS65770
96BC	4300 9794	2577 *			END TEST GOTO NEXT HALF OF TEST	MOS65780 MOS65790 MOS65800 MOS65810
		2578	B	TEST98		
		2579 *				
		2580 *			*****	
		2581 *				
96C0	4860 BB1A	2582	KHKLOC	LH R6,LCLIM+6	INITIALIZE MEMORY LIMITS	MOS65820
96C4	4880 BB26	2583		LH R8,HILIM+6		MOS65830
96C8	2472	2584	LIS	R7,2		MOS65840
96CA	C360 7FC0	2585	TAI	R6,X'7FC0'		MOS65850
96CE	2133	2586	BNZS	KHKLOC1		MOS65860
96D0	C860 0040	2587	LDAI	R6,X'40'	FORCE LOLIM	MOS65870 MOS65880
96D4	083A	2588 *				
96D6	C360 0000	2589	KHKLOC1	LDAR R3,R10	STORE APPROPRIATE BACKGROUND PATTERN	MOS65890
96DA	2332	2590		TAI R6,0(R13)		MOS65900
96DC	0838	2591	BZS	KHKLOC2		MOS65910
96DE	4036 0000	2592	LDAR	R3,R11		MOS65920
96E2	C160 96D4	2593	KHKLOC2	STH R3,0(36)	IN MEMORY	MOS65930
96E6	4860 BB1A	2594	KHKLOC25	BXLE R6,KHKLOC1	FROM LOLIM TO HILIM	MOS65940
96EA	C360 7FC0	2595		LH R6,LCLIM+5		MOS65950
96EE	2133	2596	TAI	R6,X'7FC0'		MOS65960
96F0	C860 0040	2597	BNZS	KHKLOC3		MOS65970
		2598	LDAI	R6,X'40'	FORCE LOLIM	MOS65980
		2599 *				MOS65990
96F4	C840 3033	2600	KHKLOC3	LDAI R4,C'03'		MOS66000
96F8	4040 8A56	2601	STH	R4,ERRNO	ERRNO = C'03'	MOS66010
96FC	41E0 87C2	2602	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS66020
9700	083A	2603	LDAR	R3,R10	GET APPROPRIATE BACKGROUND PATTERN	MOS66030
9702	C360 0000	2604	TAI	R6,0(R13)		MOS66040
9706	2332	2605	BZS	KHKLOC4		MOS66050
9708	083B	2606	LDAR	R3,R11		MOS66060
970A	4846 0000	2607	KHKLOC4	LH R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS66070
970E	0543	2608	CLAR	R4,R3	EQUAL ?	MOS66080
9710	213E	2609	BNES	KHKLOC5F	NO, BRANCH	MOS66090
9712	C730 8001	2610	KHKLOC5	XAI R3,X'8001'	COMPLEMENT DATA PATTERN	MOS66100
9716	4036 0000	2611	STH	R3,0(R6)	STORE C.D.P. AT LOC	MOS66110
971A	6110 8A56	2612	AH	R1,ERRNO	ERRNO = C'04'	MOS66120
971E	4846 0000	2613	LH	R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS66130
9722	0543	2614	CLAR	R4,R3	DATA = C.D.P. ?	MOS66140
9724	2137	2615	BNES	KHKLOC6F	NO, BRANCH	MOS66150
9726	C160 96F4	2616	KHKLOC6	BXLE R6,KHKLOC3	CONTINUE UNTIL DONE(INCREMENTING)	MOS66160
972A	23C7	2617	BS	KHKLOC6A	BRANCH	MOS66170
		2618 *				MOS66180
972C	41E0 93AE	2619	KHKLOC5F	BAL LINK,ERROR	ERROR ROUTINE	MOS66190
9730	220F	2620		BS KHKLOC5	RETURN	MOS66200
		2621 *				MOS66210
9732	41E0 93AE	2622	KHKLOC6F	BAL LINK,ERROR	ERROR ROUTINE	MOS66220
9736	22C8	2623		BS KHKLOC6		MOS66230
		2624 *				MOS66240
9738	4860 BB26	2625	KHKLOC6A	LH R6,HILIM+6		MOS66250
973C	C460 7FFE	2626	NAI	R6,X'7FFE'		MOS66260
9740	4880 BB1A	2627	LH	R8,LOLIM+6	ESTABLISH MEMORY LIMITS	MOS66270

TEST 9

ECC DISTURB TEST

9744	2572	2628	LCS	R7,2	MOS66280	
9746	C380 7FC0	2629	TAI	R8,X'7FC0'	MOS66290	
974A	2133	2630	BNS	KHKLOC7	MOS66300	
974C	C880 0040	2631	LDAI	R8,X'40'	MOS66310	
		2632 *		FORCE LOLIM	MOS66320	
9750	083B	2633	KHKLOC7	LDAR R3,R11	GET C.D.P. FOR LOC UNDER TEST	MOS66330
9752	C36D 0000	2634	TAI	R6,0(R13)		MOS66340
9756	2332	2635	BZS	KHKLOC8		MOS66350
9758	083A	2636	LDAR	R3,R10		MOS66360
975A	C840 3035	2637	KHKLOC8	LDAI R4,C'05'		MOS66370
975E	4040 8A56	2638	STH	R4,ERRNO	ERRNC = C'05'	MOS66380
9762	41F0 37C2	2639	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS66390
9766	4946 0000	2640	LH	R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS66400
976A	0543	2641	CLAR	R4,R3	DATA = C.D.P. ?	MOS66410
976C	213E	2642	BNES	KHKLOC9F	NO, BRANCH	MOS66420
976E	C730 8001	2643	XAI	R3,X'8001'	COMPLEMENT C.D.P. (O.D.P.)	MOS66430
9772	4036 0000	2644	STH	R3,0(R6)	STORE PATTERN AT LOC	MOS66440
9776	6110 8A56	2645	AHM	R1,ERRNO	ERRNO = C'06'	MOS66450
977A	4846 0000	2646	LH	R4,0(R6)	GET DATA FROM LOC UNDER TEST	MOS66460
977E	0543	2647	CLAR	R4,R3	DATA = O.D.P. ?	MOS66470
9780	2137	2648	BNES	KHKLOC1F	NO, BRANCH	MOS66480
9782	0060 9750	2649	KHKLOC10	BXH R6,KHKLOC7	CONTINUE UNTIL DONE(DECREMENTING)	MOS66490
		2650 *				MOS66500
9786	030E	2651	BR	R14	RETURN	MOS66510
		2652 *				MOS66520
9788	41F0 9BAE	2653	KHKLOC9F	BAL LINK,ERROR	ERROR ROUTINE	MOS66530
978C	22CF	2654	BS	KHKLOC9	RETURN	MOS66540
		2655 *				MOS66550
978E	41F0 9BAZ	2656	KHKLOC1F	BAL LINK,ERROR	ERROR ROUTINE	MOS66560
9792	22CB	2657	BS	KHKLOC10	RETURN	MOS66570
		2658 *				MOS66580
		2659 *				MOS66590
		2660 *	END	TEST 9-1		MOS66600

TEST 9

ECC DISTURB TEST

2652 * TEST 9-2 DOUBLE OPERATION COLUMN DISTURB TEST MOS66620
 2663 * MOS66630
 2664 * MOS66640
 2665 * PURPOSE: THIS TEST CHECKS THAT A DOUBLE OPERATION ON AN ADJACENT MOS66650
 2655 * COLUMN DOES NOT DISTURB THE TEST COLUMN. MOS66660
 2667 * MOS66670
 2668 * ASSUMPTIONS: MOS66680
 2669 * MINIMUM 64 KB MOS MEMORY MOS66690
 2670 * MOS66700
 2671 * DESIGN SPECIFICATIONS: MOS66710
 2672 * 1. WITH 6 DIFFERENT BACKGROUND PATTERNS, A W-R-WC- MOS66720
 2673 * RC-W-R-WC-RC SERIES IS EXECUTED AT EACH LOCATION. MOS66730
 2674 * 2. A COMPARE IS DONE UPON EACH READ OPERATION. MOS66740
 2675 * 3. A TEST (COMPARISON) OF THE REST OF MEMORY IS DONE MOS66750
 2676 * AFTER EACH SERIES OF OPERATIONS. MOS66760
 2677 * MOS66770
 2678 * OPTIONS: MOS66780
 2679 * SCOPE - ERROR OPTION MODE MOS66790
 2680 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS66800
 2681 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MCS66810
 2682 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS66820
 2683 * 3 - PRINT ERROR DATA AND HALT MOS66830
 2684 * 4 - IGNORE ERROR MOS66840
 2685 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS66850
 2686 * MOS66860
 2687 * HOW TO RUN THE TEST MOS66870
 2688 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE. MOS66880
 2689 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE. MOS66890

9794	2411	2691	TEST9B	LIS	R1,1	LOAD DISPLAY ADDRESS	MOS66910
9796	24A0	2692		LIS	R10,0		MOS66920
9798	C8E0 8001	2693		LDAI	R11,X'8001'		MOS66930
979C	24D0	2694		LIS	R13,0		MOS66940
979E	41E0 97B4	2695		BAL	R14,KHKCOL	W/BACKGROUND = 0'S	MOS66950
		2696 *				DO A DOUBLE OPERATION COLUMN DISTURB AND COMPLEMENT TEST	MOS66960
97A2	24D2	2697		LIS	R13,2	W/BACKGROUND = 5'S	MOS66970
97A4	41E0 97B4	2698		BAL	R14,KHKCOL	DO A DOUBLE OPERATION COLUMN DISTURB AND COMPLEMENT TEST	MOS66980
97A8	C8E0 0100	2700		LDAI	R13,X'100'	W/BACKGROUND = 128-0'S, 128-F'S,...	MOS67000
97AC	41E0 97B4	2701		BAL	R14,KHKCOL	DO A DOUBLE OPERATION COLUMN DISTURB AND COMPLEMENT TEST	MOS67010
97B0	43C0 83A8	2702 *				END OF TEST (RETURN TO EXEC)	MOS67020
		2703		B	TSTEND		MOS67030
		2704 *				*****	MOS67040
97B4	48E0 8B1A	2705	KHKCOL	LH	R6,LOLIM+6	INITIALIZE MEMORY LIMITS	MOS67050
97B8	4880 8B26	2706		LH	R8,HILIM+6		MOS67060
97BC	2472	2707		LIS	R7,2		MOS67070
97BE	C3E0 7FC0	2708		TAI	R6,X'7FC0'		MOS67080
97C2	2133	2709		BNZS	KHKCOL1		MOS67090
97C4	C8E0 0040	2710		LDAI	R6,X'40'	FORCE LOLIM	MOS67100
97C8	083A	2711	KHKCOL1	LDAR	R3,R10	GET PROPER BACKGROUND PATTERN	MOS67110
97CA	C3E0 0000	2712		TAI	R6,0(R13)		MOS67120

TEST 9

ECC DISTURB TEST

97CE 2332	2713	BZS	KHKCOL2	MOS67130
97D0 083B	2714	LDAR	R3,R11	MOS67140
97D2 4036 0000	2715	KHKCOL2	STH R3,0(R6)	MOS67150
97D6 C160 97C8	2716	KHKCOL25	BXLE R6,KHKCOL1	MOS67160
97DA 4860 BB1A	2717	LH	R6,LOLIM+6	MOS67170
97DE C360 7FC0	2718	TAI	R6,X'7FC0'	MOS67180
97E2 2133	2719	BNZS	KHKCOL3	MOS67190
97E4 C860 0040	2720	LDAI	R6,X'40'	MOS67200
	2721 *			MOS67210
97E8 C840 3033	2722	KHKCOL3	LDAI R4,C'03'	MOS67220
97EC 4040 8A56	2723	STH	R4,ERRNO	MOS67230
97F0 41F0 87C2	2724	BAL	LINK,TSTBRKX	MOS67240
97F4 083A	2725	LDAR	R3,R10	MOS67250
97F6 C36D 0000	2726	TAI	R6,0(R13)	MOS67260
97FA 2332	2727	BZS	KHKCOL4	MOS67270
97FC 083B	2728	LDAR	R3,R11	MOS67280
97FE 4846 0000	2729	KHKCOL4	LH R4,0(R6)	MOS67290
9802 0543	2730	CLAR	R4,R3	MOS67300
9804 4230 98E2	2731	BNE	KHKCOL5F	MOS67310
9808 C730 8001	2732	KHKCOL5	XAI R3,X'8001'	MOS67320
980C 4036 0000	2733	STH	R3,0(R6)	MOS67330
9810 6110 8A56	2734	AHM	R1,ERRNO	MOS67340
9814 4846 0000	2735	LH	R4,0(R6)	MOS67350
9818 0543	2736	CLAR	R4,R3	MOS67360
981A 4230 98EA	2737	BNE	KHKCOL6F	MOS67370
981E C730 8001	2738	KHKCOL6	XAI R3,X'8001'	MOS67380
9822 4036 0000	2739	STH	R3,0(R6)	MOS67390
9826 C840 3039	2740	LDAI	R4,C'09'	MOS67400
982A 4040 8A56	2741	STH	R4,ERRNO	MOS67410
982E 4846 0000	2742	LH	R4,0(R6)	MOS67420
9832 0543	2743	CLAR	R4,R3	MOS67430
9834 4230 98F2	2744	BNE	KHKCOL7F	MOS67440
9838 C730 8001	2745	KHKCOL7	XAI R3,X'8001'	MOS67450
983C 4036 0000	2746	STH	R3,0(R6)	MOS67460
9840 C840 3041	2747	LDAI	R4,C'0A'	MOS67470
9844 4040 8A56	2748	STH	R4,ERRNO	MOS67480
9848 4846 0000	2749	LH	R4,0(R6)	MOS67490
984C 0543	2750	CLAR	R4,R3	MOS67500
984E 4230 98FA	2751	BNE	KHKCOL8F	MOS67510
9852 C160 97E8	2752	KHKCOL8	BXLE R6,KHKCOL3	MOS67520
9856 4860 BB25	2753	LH	R6,HILIM+6	MOS67530
985A C460 7FFE	2754	NAI	R6,X'7FFE'	MOS67540
985E 4880 BB1A	2755	LH	R8,LOLIM+6	MOS67550
9862 2572	2756	LCS	R7,2	MOS67560
9864 C380 7FC0	2757	TAI	R8,X'7FC0'	MOS67570
9868 2133	2758	BNZS	KHKCOL9	MOS67580
986A C880 0040	2759	LDAI	R8,X'40'	MOS67590
	2760 *			MOS67600
986E 083B	2761	KHKCOL9	LDAR R3,R11	MOS67610
9870 C36D 0000	2762	TAI	R6,0(R13)	MOS67620
9874 2332	2763	BZS	KHKCOLA	MOS67630
9876 083A	2764	LDAR	R3,R10	MOS67640
9878 C840 3035	2765	KHKCOLA	LDAI R4,C'05'	MOS67650

STORE BACKGROUND PATTERN
TO ALL OF MEMORY UNDER TEST

FORCE LOLIM

ERRNO = C'03'
IF "BREAK" GO TO TSTEND ELSE RETURN
GET ORIGINAL DATA PATTERN (O.D.P.)

GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT DATA PATTERN (C.D.P.)
STORE C.D.P. AT LOC

ERRNO = C'04'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT C.D.P. (O.D.P.)
STORE O.D.P. AT LOC

ERRNO = C'09'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT O.D.P.(C.D.P.)
STORE C.D.P. AT LOC

CONTINUE UNTIL DONE(INCREMENTING
INITIALIZE MEMORY LIMITS
(HILIM MUST BE EVEN)

TEST 9

ECC DISTURB TEST

987C	4040	8A56	2766	STH	R4,ERRNO	ERRNO = C'05'	MOS67560
9880	41F0	87C2	2767	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS67670
9884	4846	0000	2768	LH	R4,0(R6)	GET DATA FROM LOC	MOS67680
9888	0543		2769	CLAR	R4,R3	DATA EQUAL ?	MOS67690
988A	4230	9902	2770	BNE	KHKCOLBF	NO, BRANCH	MOS67700
988E	C730	8001	2771	KHKCOLB	XAI R3,X'8001'	COMPLEMENT C.D.P.(O.D.P.)	MOS67710
9892	4036	0000	2772	STH	R3,0(R6)	STORE O.D.P. AT LOC	MOS67720
9896	6110	8A56	2773	AHM	R1,ERRNO	ERRNO = C'06'	MOS67730
989A	4846	0000	2774	LH	R4,0(R6)	GET DATA FROM LOC	MOS67740
989E	0543		2775	CLAR	R4,R3	DATA EQUAL ?	MOS67750
98A0	4230	990A	2776	BVE	KHKCOLCF	NO, BRANCH	MOS67760
98A4	C730	8001	2777	KHKCOLC	XAI R3,X'8001'	COMPLEMENT O.D.P. (C.D.P.)	MOS67770
98A8	4036	0000	2778	STH	R3,0(R6)	STORE C.D.P. AT LOC	MOS67780
98AC	C840	3042	2779	LDAI	R4,C'0B'		MOS67790
98B0	4040	8A56	2780	STH	R4,ERRNO	ERRNO = C'0B'	MOS67800
98B4	4846	0000	2781	LH	R4,0(R6)	GET DATA FROM LOC	MOS67810
98B8	0543		2782	CLAR	R4,R3	DATA EQUAL ?	MOS67820
98BA	213E		2783	BNES	KHKCOLDF	NO, BRANCH	MOS67830
98BC	C730	8001	2784	KHKCOLD	XAI R3,X'8001'	COMPLEMENT C.D.P.(O.D.P.)	MOS67840
98C0	4036	0000	2785	STH	R3,0(R6)	STORE O.D.P. AT LOC	MOS67850
98C4	6110	8A56	2786	AHM	R1,ERRNO	ERRNO = C'0C'	MOS67860
98C8	4846	0000	2787	LH	R4,0(R6)	GET DATA FROM LOC	MOS67870
98CC	0543		2788	CLAR	R4,R3	DATA EQUAL ?	MOS67880
98CE	2137		2789	BNES	KHKCOLEF	NO, BRANCH	MOS67890
98D0	C060	986E	2790	KHKCOLE	BXH R6,KHKCOL9	CONTINUE UNTIL DONE(DECREMENTING)	MOS67900
98D4	030E		2791	BR	R14	RETURN	MOS67910
			2792	*			MOS67920
98D6	41F0	9BAE	2793	KHKCOLDF	BAL	LINK,ERROR	MOS67930
98DA	220F		2794	BS	KHKCOLD	ERROR ROUTINE	MOS67940
			2795	*		RETURN	MOS67950
98DC	41F0	9BAE	2796	KHKCOLEF	BAL	LINK,ERROR	MOS67960
98E0	2208		2797	BS	KHKCOLE	ERROR ROUTINE	MOS67970
			2798	*		RETURN	MOS67980
98E2	41F0	9BAE	2799	KHKCOLSF	BAL	LINK,ERROR	MOS67990
98E6	4300	9808	2800	B	KHKCOL5	ERROR ROUTINE	MOS68000
			2801	*		RETURN	MOS68010
98EA	41F0	9BAE	2802	KHKCOL6F	BAL	LINK,ERROR	MOS68020
98EE	4300	981E	2803	B	KHKCOL6	ERROR ROUTINE	MOS68030
			2804	*		RETURN	MOS68040
98F2	41F0	9BAE	2805	KHKCOL7F	BAL	LINK,ERROR	MOS68050
98F6	4300	9838	2806	B	KHKCOL7	ERROR ROUTINE	MOS68060
			2807	*		RETURN	MOS68070
98FA	41F0	9BAE	2808	KHKCOL8F	BAL	LINK,ERROR	MOS68080
98FE	4300	9852	2809	B	KHKCOL8	ERROR ROUTINE	MOS68090
			2810	*		RETURN	MOS68100
9902	41F0	9BAE	2811	KHKCOL8F	BAL	LINK,ERROR	MOS68110
9906	4300	989E	2812	B	KHKCOLB	ERROR ROUTINE	MOS68120
			2813	*		RETURN	MOS68130
990A	41F0	9BAE	2814	KHKCOLCF	BAL	LINK,ERROR	MOS68140
990E	4300	98A4	2815	B	KHKCOLC	ERROR ROUTINE	MOS68150
			2816	*		*****	MOS68160
			2817	*	END	TEST 9-2	MOS68170

TEST A

PARITY DISTURB TEST

2819	*	TEST A-1	MARCHING PATTERN TEST	MOS68190
2820	*			MOS68200
2821	*	PURPOSE:		MOS68210
2822	*	THIS TEST CHECKS THAT THREE DIFFERENT BASE PATTERNS		MOS68220
2823	*	CAN BE WRITTEN, COMPLEMENTED, AND MARCHED THROUGH THE		MOS68230
2824	*	AVAILABLE MEMORY WITHOUT ERROR.		MOS68240
2825	*			MOS68250
2826	*	ASSUMPTIONS:		MOS68260
2827	*	MINIMUM 64KB MOS MEMORY		MOS68270
2828	*			MOS68280
2829	*	DESIGN SPECIFICATIONS:		MOS68290
2830	*	1. (IN ASCENDING ORDER) WRITE AND READ THE BASE PATTERN.		MOS68300
2831	*	2. (IN DESCENDING ORDER) WRITE AND READ THE		MOS68310
2832	*	COMPLEMENT PATTERN.		MOS68320
2833	*			MOS68330
2834	*	OPTIONS:		MOS68340
2835	*	SCOPE - ERROR OPTION MODE		MOS68350
2836	*	0 - PRINT ERROR DATA AND SKIP TO NEXT TEST		MOS68360
2837	*	1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST		MOS68370
2838	*	2 - PRINT ERROR DATA AND CONTINUE TEST		MOS68380
2839	*	3 - PRINT ERROR DATA AND HALT		MOS68390
2840	*	4 - IGNORE ERROR		MOS68400
2841	*	5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST		MOS68410
2842	*			MOS68420
2843	*	HOW TO RUN THE TEST:		MOS68430
2844	*	1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE.		MOS68440
2845	*	2. ENTER "RUN" AND THE TEST WILL EXECUTE.		MOS68450

9912	2411	2847	TESTA	LIS R1,1	LOAD DISPLAY ADDRESS	MOS68470
9914	C840 893E	2848		LDAI R4,MM0		MOS6848C
9918	4040 003E	2849		STH R4,X'3E'	SET NEW MM POINTER	MOS68490
991C	24A0	2850		LIS R10,0		MOS68500
991E	24E1	2851		LIS R11,1		MOS68510
9920	24D0	2852		LIS R13,0	W/BACKGROUND = 0'S	MOS68520
9922	41E0 9950	2853		BAL R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS68530
		2854	*			MOS68540
9926	24A1	2855		LIS R10,1		MOS68550
9928	24E0	2856		LIS R11,0	W/BACKGROUND = F'S	MOS68560
992A	41E0 9950	2857		BAL R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS68570
		2858	*			MOS68580
992E	24D2	2859		LIS R13,2	W/BACKGROUND = A'S	MOS68590
9930	41E0 9950	2860		BAL R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS68600
		2861	*			MOS68610
9934	24A0	2862		LIS R10,0		MOS68620
9936	24B1	2863		LIS R11,1	W/BACKGROUND = 5'S	MOS68630
9938	41E0 9950	2864		BAL R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS68640
		2865	*			MOS68650
993C	C8D0 0100	2866		LDAI R13,X'100'	W/BACKGROUND =128-0'S,128-F'S,..	MOS68660
9940	41E0 9950	2867		BAL R14,CLKLOC	DO A SINGLE DISTURB TEST (MIN-MAX)	MOS68670
		2868	*			MOS68680
9944	24A1	2869		LIS R10,1		MOS68690

TEST A

PARITY DISTURB TEST

9946	2420	2870	LIS	R11,0			MOS68700
9948	41E0 9950	2971	BAL	R14,CLKLOC	W/BACKGROUND =128-F'S,128-0'S, ETC DO A SINGLE DISTURB TEST (MIN-MAX)		MOS68710
		2872 *					MOS68720
994C	4300 9A24	2873	B	TESTAB	END OF TEST (GOTO NEXT TEST SECTION)		MOS68730
		2874 *					MOS68740
		2875 *			*****		MOS68750
		2876 *					MOS68760
9950	48F0 8B1A	2877	CLKLCC	LH R6,LOLIM+6	INITIALIZE MEMORY LIMITS		MOS68770
9954	48E0 8E26	2878		LH R8,HILIM+6			MOS68780
9958	2472	2879	LIS	R7,2			MOS68790
995A	C360 7FC0	2880	TAI	R6,X'7FC0'			MOS68800
995E	2133	2881	BNZS	CLKLOC1			MOS68810
9960	C860 0040	2882	LDAI	R6,X'40'	FORCE LOLIM		MOS68820
		2883 *					MOS68830
9964	083A	2884	CLKLOC1	LDAR R3,R10	STORE APPROPRIATE BACKGROUND PATTERN		MOS68840
9966	C36D 0000	2885		TAI R6,0(R13)			MOS68850
996A	2332	2886	BZS	CLKLOC2			MOS68860
996C	083B	2887	LDAR	R3,R11			MOS68870
996E	4036 0000	2888	CLKLCC2	STH R3,0(R6)	IN MEMORY		MOS68880
9972	C160 9964	2889	CLKLCC25	BXLE R6,CLKLOC1	FROM LOLIM TO HILIM		MOS68890
9976	48E0 8B1A	2890		LH R6,LOLIM+6			MOS68900
997A	C360 7FC0	2891	TAI	R6,X'7FC0'			MOS68910
997E	2133	2892	BNZS	CLKLOC3			MOS68920
9980	C860 0040	2893	LDAI	R6,X'40'	FORCE LOLIM		MOS68930
		2894 *					MOS68940
9984	C840 3033	2895	CLKLOC3	LDAI R4,C'03'			MOS68950
9988	4040 8A56	2896		STH R4,ERRNO	ERRNO = C'03'		MOS68960
998C	41F0 87C2	2897	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN		MOS68970
9990	083A	2898	LDAR	R3,R10	GET APPROPRIATE BACKGRUND PATTERN		MOS68980
9992	C36D 0000	2899		TAI R6,0(R13)			MOS68990
9996	2332	2900	BZS	CLKLOC4			MOS69000
9998	083B	2901	LDAR	R3,R11			MOS69010
999A	4846 0000	2902	CLKLOC4	LH R4,0(R6)	GET DATA FROM LOC UNDER TEST		MOS69020
999E	0543	2903	CLAR	R4,R3	EQUAL ?		MOS69030
99A0	213E	2904	BNES	CLKLOC5F	NO, BRANCH		MOS69040
99A2	C730 0001	2905	CLKLCC5	XAI R3,1	COMPLEMENT DATA PATTERN		MOS69050
99A5	4036 0000	2906		STH R3,0(R6)	STORE C.D.P. AT LOC		MOS69060
99AA	6110 8A56	2907	AHM	R1,ERRNO	ERRNO = C'04'		MOS69070
99AE	4846 0000	2908		LH R4,0(R6)	GET DATA FROM LOC UNDER TEST		MOS69080
99B2	0543	2909	CLAR	R4,R3	DATA = C.D.P. ?		MOS69090
99B4	2137	2910	BNES	CLKLOC6F	NO, BRANCH		MOS69100
99B6	C160 9984	2911	CLKLOC6	BXLE R6,CLKLOC3	CONTINUE UNTIL DONE(INCREMENTING)		MOS69110
99BA	23C7	2912	BS	CLKLOC6A	BRANCH		MOS69120
		2913 *					MOS69130
99BC	41F0 9BAE	2914	CLKLOC5F	BAL LINK,ERROR	ERROR ROUTINE		MOS69140
99C0	22CF	2915		BS CLKLOC5	RETURN		MOS69150
		2916 *					MOS69160
99C2	41F0 9BAE	2917	CLKLOC6F	BAL LINK,ERROR	ERROR ROUTINE		MOS69170
99C6	22C8	2918		BS CLKLOC6			MOS69180
		2919 *					MOS69190
99C8	48E0 8E26	2920	CLKLOC6A	LH R6,HILIM+6			MOS69200
99CC	C460 7FFE	2921		NAI R6,X'7FFE'			MOS69210
99D0	4880 8B1A	2922	LH	R8,LOLIM+6	ESTABLISH MEMORY LIMITS		MOS69220

TEST A

PARITY DISTURB TEST

99D4	2572	2923	LCS	R7,2	MOS69230
99D6	C380 7FC0	2924	TAI	R8,X'7FC0'	MOS69240
99DA	2133	2925	BZS	CLKLOC7	MOS69250
99DC	C880 0040	2926	LDAI	R8,X'40'	MOS69260
		2927 *		FORCE LOLIM	MOS69270
99E0	083B	2928	CLKLOC7	LDAI R3,R11	MOS69280
99E2	C36D 0000	2929	IAI	R6,0(R13)	MOS69290
99E6	2332	2930	BZS	CLKLOC8	MOS69300
99E8	033A	2931	LDAI	R3,R10	MOS69310
99EA	C340 3035	2932	CLKLOC6	LDAI R4,C'05'	MOS69320
99EE	4040 8A56	2933	STH	R4,ERRNO	MOS69330
99F2	41F0 87C2	2934	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN
99F6	4946 0000	2935	LH	R4,0(R6)	GET DATA FROM LOC UNDER TEST
99FA	0543	2936	CLAR	R4,R3	DATA = C.D.P. ?
99FC	213E	2937	BNES	CLKLOC9F	NO, BRANCH
99FE	C730 0001	2938	CLKLOC9	XAI R3,1	COMPLEMENT C.D.P. (O.D.P.)
9A02	4036 0000	2939	STH	R3,0(R6)	STORE PATTERN AT LOC
9A06	6110 8A56	2940	AHM	R1,ERRNO	ERREMO = C'05'
9A0A	4846 0000	2941	LH	R4,0(R6)	GET DATA FROM LOC UNDER TEST
9A0E	0543	2942	CLAR	R4,R3	DATA = O.D.P. ?
9A10	2137	2943	BNES	CLKLOC1F	NO, BRANCH
9A12	C060 99E0	2944	CLKLOC10	BXH R6,CLKLOC7	CONTINUE UNTIL DONE(DECREMENTING)
		2945 *			
9A16	03CE	2946	BB	R14	RETURN
		2947 *			
9A18	41F0 9BAE	2948	CLKLOC9F	BAL LINK,ERROR	ERROR ROUTINE
9A1C	220F	2949	BS	CLKLOC9	RETURN
		2950 *			
9A1E	41F0 9BAE	2951	CLKLOC1F	BAL LINK,ERROR	ERROR ROUTINE
9A22	22C9	2952	BS	CLKLOC10	RETURN
		2953 *			
		2954 *			*****
		2955 *	END	TEST A-1	MOS69550

TEST A

PARITY DISTURB TEST

2957 * TEST A-2 DOUBLE OPERATION COLUMN DISTURB TEST MOS69570
 2958 *
 2959 * PURPOSE:
 2960 * THIS TEST CHECKS THAT A DOUBLE OPERATION ON AN ADJACENT
 2961 * COLUMN DOES NOT DISTURB THE TEST COLUMN.
 2962 *
 2963 * ASSUMPTIONS:
 2964 * MINIMUM 64 KB MOS MEMORY
 2965 *
 2966 * DESIGN SPECIFICATIONS:
 2967 * 1. WITH 6 DIFFERENT BACKGROUND PATTERNS, A W-R-WC-
 2968 * RC-W-R-WC-RC SERIES IS EXECUTED AT EACH LOCATION.
 2969 * 2. A COMPARE IS DONE UPON EACH READ OPERATION.
 2970 * 3. A TEST (COMPARISON) OF THE REST OF MEMORY IS DONE
 2971 * AFTER EACH SERIES OF OPERATIONS.
 2972 *
 2973 * OPTIONS:
 2974 * SCOPE - ERROR OPTION MODE
 2975 * 0 - PRINT ERROR DATA AND SKIP TO NEXT TEST MOS69750
 2976 * 1 - PRINT BAD CHIP NUMBER(S) AND SKIP TO NEXT TEST MOS69760
 2977 * 2 - PRINT ERROR DATA AND CONTINUE TEST MOS69770
 2978 * 3 - PRINT ERROR DATA AND HALT MOS69780
 2979 * 4 - IGNORE ERROR MOS69790
 2980 * 5 - PRINT BAD CHIP NUMBER(S) AND CONTINUE TEST MOS69800
 2981 *
 2982 * HOW TO RUN THE TEST
 2983 * 1. ENTER THE "SCOPE" OPTION VIA THE CONSOLE DEVICE.
 2984 * 2. ENTER "RUN" AND THE TEST WILL EXECUTE.
 MOS69810
 MOS69820
 MOS69830
 MOS69840

9A24 2411	2986	TESTAB	IIS	R1,1	LOAD DISPLAY ADDRESS	MOS69860
9A25 24A0	2987		IIS	R10,0		MOS69870
9A28 24E1	2988		LIS	R11,1		MOS69880
9A2A 24D0	2989		LIS	R13,0		MOS69890
9A2C 41E0 9A42	2990		BAL	R14,CLKCOL	W/BACKGROUND = 0'S DO A DOUBLE OPERATION COLUMN DISTURB AND COMPLEMENT TEST	MOS69900 MOS69910
9A30 24D2	2991	*				
9A32 41E0 9A42	2992		LIS	R13,2	W/BACKGROUND = 5'S DO A DOUBLE OPERATION COLUMN	MOS69920 MOS69930
9A36 C810 0100	2993		BAL	R14,CLKCOL	DISTURB AND COMPLEMENT TEST	MOS69940
9A3A 41E0 9A42	2994	*			W/BACKGROUND = 128-0'S, 128-F'S, ... DO A DOUBLE OPERATION COLUMN	MOS69950 MOS69960
9A3E 43C0 83A8	2995		LDAI	R13,X'100'	DISTURB AND COMPLEMENT TEST	MOS69970
	2996		BAL	R14,CLKCOL	END OF TEST (RETURN TO EXEC)	MOS69980
	2997	*			*****	MOS69990
	2998		B	TSTEND	INITIALIZE MEMORY LIMITS	MOS70000
	2999	*	*****	*****	*****	MOS70010
9A42 4860 BB1A	3000	CLKCOL	LH	R6,LOLIM+6		MOS70020
9A46 4880 BB26	3001		LH	R8,HILIM+6		MOS70030
9A4A 2472	3002		LIS	R7,2		MOS70040
9A4C C360 7FC0	3003		TAI	R6,X'7FC0'		MOS70050
9A50 2133	3004		BNZS	CLKCOL1		MOS70060
9A52 C860 0040	3005		LDAI	R6,X'40'	FORCE LOLIM GET PROPER BACKGROUND PATTERN	MOS70070
9A56 083A	3006	CLKCCL1	LDAR	R3,R10		
9A58 C36D 0000	3007		TAI	R6,0(R13)		

TEST A

PARITY DISTURB TEST

9A5C	2332	3008	BZS	CLKCOL2	MOS70080
9A5E	083B	3009	LDAR	R3,R11	MOS70090
9A60	4036 0000	3010	CLKCOL2	STH R3,0(R6)	MOS70100
9A64	C160 9A56	3011	CLKCOL25	BXLE R6,CLKCOL1	MOS70110
9A68	486C 8B1A	3012	LH	R6,LOLIM+6	MCS70120
9A6C	C360 7FC0	3013	TAI	R6,X'7FC0'	MOS70130
9A70	2133	3014	BNZS	CLKCOL3	MOS70140
9A72	C860 0040	3015	LDAI	R6,X'40'	MOS70150
		3016 *		FORCE LOLIM	MOS70160
9A76	C840 3033	3017	CLKCOL3	LDAI R4,C'03'	MCS70170
9A7A	4040 8A56	3018	STH	R4,ERRNO	MOS70180
9A7E	41F0 87C2	3019	BAL	LINK,TSTBRKX	MOS70190
9A82	083A	3020	LDAR	R3,R10	MOS70200
9A84	C36D 0000	3021	TAI	R6,0(R13)	MOS70210
9A88	2332	3022	BZS	CLKCOL4	MOS70220
9A8A	083B	3023	LDAR	R3,R11	MOS70230
9A8C	4846 0000	3024	CLKCOL4	LH R4,0(R6)	MOS70240
9A90	0543	3025	CLAP	R4,R3	MOS70250
9A92	4230 9B70	3026	BNE	CLKCOL5F	MOS70260
9A96	C730 0001	3027	CLKCOL5	XAI R3,1	MOS70270
9A9A	4C36 0000	3028	STH	R3,0(R6)	MOS70280
9A9E	6110 8A55	3029	AHM	R1,ERRNO	MOS70290
9AA2	4846 0000	3030	LH	R4,0(R6)	MOS70300
9AA6	0543	3031	CLAR	R4,R3	MOS70310
9AA8	4230 9B78	3032	BNE	CLKCOL6F	MOS70320
9AAC	C730 0001	3033	CLKCCL6	XAI R3,1	MOS70330
9AB0	4036 0000	3034	STH	R3,0(R6)	MOS70340
9AB4	C64C 3039	3035	LDAI	R4,C'09'	MOS70350
9AB8	4040 8A56	3036	STH	R4,EPRNO	MCS70360
9ABC	4846 0000	3037	LH	R4,0(R6)	MOS70370
9AC0	0543	3038	CLAR	R4,R3	MOS70380
9AC2	4230 9B80	3039	BNE	CLKCOL7F	MOS70390
9AC6	C730 0001	3040	CLKCCL7	XAI R3,1	MOS70400
9ACA	4036 0000	3041	STH	R3,0(R6)	MOS70410
9ACE	C840 3041	3042	LDAI	R4,C'0A'	MOS70420
9AD2	4040 8A56	3043	STH	R4,ERRNO	MCS70430
9AD6	4846 0000	3044	LH	R4,0(R6)	MOS70440
9ADA	0543	3045	CLAR	R4,R3	MOS70450
9ADC	4230 9B88	3046	BNE	CLKCOL8F	MOS70460
9AE0	C160 9A76	3047	CLKCOL8	BXLE R6,CLKCOL3	MOS70470
9AE4	4860 8B26	3048	LH	R6,HILIM+6	MOS70480
9AE8	C460 FFFE	3049	NAI	R6,-2	MOS70490
9AEC	4880 8B1A	3050	LH	R8,LCLIM+6	MOS70500
9AF0	2572	3051	LCS	R7,2	MOS70510
9AF2	C380 7FC0	3052	TAI	R8,X'7FC0'	MOS70520
9AF6	2133	3053	BNZS	CLKCOL9	MOS70530
9AF8	C880 0040	3054	LDAI	R8,X'40'	MOS70540
		3055 *		FORCE LOLIM	MOS70550
9AFC	083B	3056	CLKCOL9	LDAR R3,R11	MOS70560
9AFE	C36D 0000	3057	TAI	R6,0(R13)	MOS70570
9B02	2332	3058	BZS	CLKCOLA	MOS70580
9B04	083A	3059	LDAR	R3,R10	MOS70590
9B06	C840 3035	3060	CLKCOLA	LDAI R4,C'05'	MOS70600

STORE BACKGROUND PATTERN
TO ALL OF MEMORY UNDER TEST

ERRNO = C'03'
IF "BREAK" GO TO TSTEND ELSE RETURN
GET ORIGINAL DATA PATTERN (O.D.P.)

GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT DATA PATTERN (C.D.P.)
STORE C.D.P. AT LOC

ERRNO = C'04'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT C.D.P. (O.D.P.)
STORE O.D.P. AT LOC

ERRNO = C'09'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
COMPLEMENT O.D.P.(C.D.P.)
STORE C.D.P. AT LOC

ERRNO = C'0A'
GET DATA FROM LOC
DATA EQUAL ?
NO, BRANCH
CONTINUE UNTIL DONE(INCREMENTING
INITIALIZE MEMORY LIMITS
(HILIM MUST BE EVEN)

GET COMPLEMENT DATA PATTERN(C.D.P.)

TEST A

PARITY DISTURB TEST

980A	4040	8A56	3061	STH	R4,ERRNO	ERRNO = C'05'	MOS70610	
980E	41F0	87C2	3062	BAL	LINK,TSTBRKX	IF "BREAK" GO TO TSTEND ELSE RETURN	MOS70620	
9812	4846	0000	3063	LH	R4,0(R6)	GET DATA FROM LOC	MOS70630	
9816	0543		3064	CLAR	R4,R3	DATA EQUAL ?	MOS70640	
9818	4230	9390	3065	BNE	CLKCOLBF	NO, BRANCH	MOS70650	
981C	C730	0001	3066	CLKCOLB	XAI	COMPLEMENT C.D.P.(O.D.P.)	MOS70660	
9820	4036	0000	3067	STH	R3,0(R6)	STORE C.D.P. AT LOC	MOS70670	
9824	6110	8A56	3068	AHM	R1,ERRNO	ERRNO = C'06'	MOS70680	
9828	4346	0000	3069	LH	R4,0(R6)	GET DATA FROM LOC	MOS70690	
982C	0543		3070	CLAR	R4,R3	DATA EQUAL ?	MOS70700	
982E	4230	9298	3071	BNE	CLKCOLCF	NO, BRANCH	MOS70710	
9832	C730	0001	3072	CLKCOLC	XAI	COMPLEMENT O.D.P. (C.D.P.)	MOS70720	
9836	4036	0000	3073	STH	R3,0(R6)	STORE C.D.P. AT LOC	MOS70730	
983A	C840	3042	3074	LDAI	R4,C'0B'	ERRNO = C'0B'	MOS70740	
983E	4040	8A56	3075	STH	R4,ERRNO	GET DATA FROM LOC	MOS70750	
9842	4846	0000	3076	LH	R4,0(R6)	DATA EQUAL ?	MOS70760	
9846	0543		3077	CLAR	R4,R3	NO, BRANCH	MOS70770	
9848	213E		3078	BNES	CLKCOLDF	COMPLEMENT C.D.P.(O.D.P.)	MOS70780	
984A	C730	0001	3079	CLKCOLD	XAI	STORE C.D.P. AT LOC	MOS70790	
984E	4036	0000	3080	STH	R3,0(R6)	ERRNO = C'0C'	MOS70800	
9852	6110	8A56	3081	AHM	R1,ERRNO	GET DATA FROM LOC	MOS70810	
9856	4846	0000	3082	LH	R4,0(R6)	DATA EQUAL ?	MOS70820	
985A	0543		3083	CLAF	R4,R3	NO, BRANCH	MOS70830	
985C	2137		3084	BNES	CLKCOLEF	CONTINUE UNTIL DONE(DECREMENTING)	MOS70840	
985E	C060	9AFC	3085	CLKCOLE	BXH	RETURN	MOS70850	
9862	03CE		3086	BR	R14		MOS70860	
			3087	*	-----		MOS70870	
9864	41F0	9BAE	3088	CLKCCLDF	BAL	LINK,ERROR	ERROR ROUTINE	MOS70880
9868	220F		3089	BS	CLKCOLD	RETURN	MOS70890	
			3090	*	-----		MOS70900	
986A	41F0	9BAE	3091	CLKCCLEF	BAL	LINK,ERROR	ERROR ROUTINE	MOS70910
986E	2208		3092	BS	CLKCOLE	RETURN	MOS70920	
			3093	*	-----		MOS70930	
9870	41F0	9BAE	3094	CLKCOL5F	BAL	LINK,ERROR	ERROR ROUTINE	MOS70940
9874	4300	9A96	3095	B	CLKCOL5	RETURN	MOS70950	
			3096	*	-----		MOS70960	
9878	41F0	9BAE	3097	CLKCOL6F	BAL	LINK,ERROR	ERROR ROUTINE	MOS70970
987C	4300	9AAC	3098	B	CLKCOL6	RETURN	MOS70980	
			3099	*	-----		MOS70990	
9880	41F0	9BAE	3100	CLKCOL7F	BAL	LINK,ERROR	ERROR ROUTINE	MOS71000
9884	4300	9AC6	3101	B	CLKCOL7	RETURN	MOS71010	
			3102	*	-----		MOS71020	
9888	41F0	9BAE	3103	CLKCOL8F	BAL	LINK,ERROR	ERROR ROUTINE	MOS71030
988C	4300	9AE0	3104	B	CLKCOL8	RETURN	MOS71040	
			3105	*	-----		MOS71050	
9890	41F0	9BAE	3106	CLKCOLBF	BAL	LINK,ERROR	ERROR ROUTINE	MOS71060
9894	4300	9B1C	3107	B	CLKCOLB	RETURN	MOS71070	
			3108	*	-----		MOS71080	
9898	41F0	9BAE	3109	CLKCOLCF	BAL	LINK,ERROR	ERROR ROUTINE	MOS71090
989C	4300	9B32	3110	B	CLKCOLC	RETURN	MOS71100	
			3111	*	*****	*****	MOS71110	
			3112	*	END	TEST A-2	MOS71120	

COMMON ERROR ROUTINE

9BA0 D000 9DD0	3114 PARERR	STM R0,MOSSAVE	SAVE CALLING REGISTERS	MOS71140
9BA4 C8F0 3132	3115 LDAI R15,C'12'		SET ERRNO = C'12'	MOS71150
9BA8 40F0 8A56	3116 STH R15,ERRNO		BRANCH	MOS71160
9BAC 2308	3117 BS ERROP3			MOS71170
	3118 *			MOS71180
	3119 * COMMON ERROR ROUTINE		CALL: BAL LINK,ERROR	MOS71190
	3120 *			MOS71200
	3121 * R6= LOCATION OF ERROR	R3= DATA EXPECTED R4= DATA READ		MOS71210
	3122 *			MOS71220
9BAE D000 9DD0	3123 ERPCR	STM R0,MOSSAVE	SAVE CALLING REGISTERS	MOS71230
9BB2 95EE	3124 EPSR	R14,R14	GET CONCURRENT PSW	MOS71240
9BB4 C4EC FFF0	3125 NAI R14,X'FFFF'		MASK OFF ALL BUT CC	MOS71250
9BB8 C6E0 0004	3126 CAI R14,4		ADD MEMORY MALFUNCTION CC	MOS71260
	3127 *			MOS71270
9BBC 41F0 8502	3128 ERROR3	BAL LINK,ERR	PRINT THE ERROR NUMBER	MOS71280
9BC0 25F1	3129 LCS	LINK,1		MOS71290
9BC2 40F0 8A0E	3130 STH	LINK,NOERR	SET ERROR FLAG FOR EXEC.	MOS71300
9BC6 48F0 8AEA	3131 LH	LINK,SCOPE+6		MOS71310
9BCA 27F1	3132 SIS	LINK,1	IS SCOPE = 1 ?	MOS71320
9BCC 4330 9C5A	3133 BZ	PARTNO	YES, PRINT PART NUMBER.	MOS71330
9BD0 27F3	3134 SIS	LINK,3	IS SCOPE = 4 ?	MOS71340
9BD2 4330 9C46	3135 BZ	ERORTN2	YES, RETURN	MOS71350
9BD6 27F1	3136 SIS	LINK,1	IS SCOPE = 5 ?	MOS71360
9BD8 4330 9C5A	3137 BZ	PARTNO	YES, PRINT PART NO. & CONTINUE	MOS71370
9BDC 24C4	3138 ERROR1	LIS R0,4		MOS71380
9BDE 0816	3139 LDAR	R1,36		MOS71390
9BE0 C820 9D1F	3140 LDAI	R2,ADRMSG+1		MOS71400
9BE4 41F0 85F6	3141 BAL	LINK,HEXASC	STORE LOCATION UNDER TEST	MOS71410
9BE8 0813	3142 LDAR	R1,R3		MOS71420
9BEA C820 9D2E	3143 LDAI	R2,DTAEXP		MOS71430
9BEE 41F0 85F6	3144 BAL	LINK,HEXASC	STORE DATA EXPECTED	MOS71440
9BF2 0814	3145 LDAR	R1,R4		MOS71450
9BF4 C820 9D3E	3146 LDAI	R2,DTARED		MOS71460
9BF8 41F0 85F6	3147 BAL	LINK,HEXASC	STORE DATA READ	MOS71470
9BFC 081E	3148 LDAR	R1,R14		MOS71480
9BFE C820 9D4A	3149 LDAI	R2,DTAPSW		MOS71490
9C02 41F0 85F6	3150 BAL	LINK,HEXASC	STORE CONCURRENT PSW	MOS71500
9C06 24C1	3151 LIS	R0,1		MOS71510
9C08 9014	3152 SRHLS	R1,4		MOS71520
9C0A C410 0007	3153 NAI	R1,7		MOS71530
9C0E C820 9D1E	3154 LDAI	R2,ADRMSG		MOS71540
9C12 41F0 85F6	3155 BAL	LINK,HEXASC		MOS71550
9C16 9456	3156 EXBR	R5,R6		MOS71560
9C18 98C5	3157 WHR	R0,R5	DISPLAY ERROR LOCATION	MOS71570
9C1A C850 9D1A	3158 ERROR2	LDAI R5,ERRORMSG		MOS71580
9C1E 4050 8A0C	3159 STH	R5,ISITERR	SET ISITERR	MOS71590
9C22 41F0 8656	3160 BAL	LINK,PRINT	PRINT THE ERROR DATA	MOS71600
9C26 2450	3161 LIS	R5,0		MOS71610
9C28 4050 8A0C	3162 STH	R5,ISITERR	RESET ISITERR	MOS71620
	3163 *			MOS71630
9C2C 48F0 8AEA	3164 ERORTN	LH LINK,SCOPE+6		MOS71640
9C30 4330 83A8	3165 BZ	TSTEND		MOS71650
9C34 27F1	3166 SIS	LINK,1	IF SCOPE = 0 OR SCOPE = 1,	MOS71660

COMMON ERROR ROUTINE

9C36 4330 83A8	3167	BZ	TSTEND	GO TO NEXT TEST	MOS71670
9C3A 27F2	3168	SIS	LINK,2	IS SCOPE = 3 ?	MOS71680
9C3C 4330 842A	3169	BZ	ABORT1	YES, ABORT TESTING SEQUENCE	MOS71690
9C40 D100 9DD0	3170	ERORTN1	LH RO,MOSSAVE	NO, RESTORE CALLING REGISTERS AND	MOS71700
9C44 030F	3171	BR	LINK	RETURN	MOS71710
	3172 *				MOS71720
9C46 48F0 8A18	3173	ERORTN2	LH LINK,TOTERR	IF SCOPF = 4	MOS71730
9C4A 26F1	3174	AIS	LINK,1	INDEX THE ERROR COUNTER	MOS71740
9C4C 40F0 8A18	3175	STH	LINK,TOTERR		MOS71750
9C50 C5F0 7FFF	3176	CLAI	LINK,X'7FFF'	TOTERR = MAXIMUM ?	MOS71760
9C54 203A	3177	BNES	ERORTN1	NO, RETURN	MOS71770
9C56 43C0 8494	3178	B	HALT9	YES, WAIT FOR PRINTOUT	MOS71780

9C5A C850 2041	3180	PARTING	LDAI R5,C' A'	LOAD AND	MOS71800
9C5E D250 9D14	3181		STB R5,CHIPNO	STORE DRIVE & CHIP ROW NUMBER	MOS71810
9C62 C850 2030	3182		LDAI R5,C' 0'		MOS71820
9C66 D250 9D15	3183		STB R5,CHIPNO+1		MOS71830
9C6A 0734	3184		XAR R3,R4	DETERMINE BIT(S) THAT FAILED	MOS71840
9C6C 2410	3185		LIS R1,0	INITIALIZE CHIP NUMBER	MOS71850
9C6E C530 FFFF	3186		CLAI R3,-1	DID ALL BITS FAIL ?	MOS71860
9C72 2137	3187		BNES C03	NO, BRANCH	MOS71870
9C74 C840 4646	3188		LDAI R4,C'FF'		MOS71880
9C78 4040 9D16	3189		STH R4,CHIPNO+2	YES, STORE 8KB ROW IDENTIFIER	MOS71890
9C7C 2430	3190		LIS R3,0		MOS71900
9C7E 23CC	3191		BS C05	CONTINUE	MOS71910
9C80 0A33	3192	C03	AAR R3,R3	DECIPHER FAILING BIT NUMBER(S)	MOS71920
	3193 *			(00-09,10-16) (SLHLS B3,1) ****	MOS71930
9C82 2185	3194		BCS C04		MOS71940
9C84 2611	3195		AIS R1,1		MOS71950
9C86 C510 0010	3196		CLAI R1,16	CHIP NUMBER = 16 ?	MOS71960
9C8A 2085	3197		BLS C03	NO, BRANCH	MOS71970
9C8C 2402	3198	C04	LIS R0,2		MOS71980
9C8E C820 9D15	3199		LDAI R2,CHIPNO+2	CONVERT TO DECIMAL AND	MOS71990
9C92 41F0 861E	3200		BAL LINK,DECASC	STORE IN ERROR MESSAGE	MOS72000
9C96 C850 9CFA	3201	C05	LDAI R5,CHIPMSG		MOS72010
9C9A 4050 8A0C	3202		STH R5,ISITERR	SET ISITERR	MOS72020
9C9E 41F0 8656	3203		BAL LINK,PRINT	PRINT SUSPECTED CHIP NUMBER	MOS72030
9CA2 2450	3204		LIS R5,0		MOS72040
9CA4 4050 8A0C	3205		STH R5,ISITERR	RESET ISITERR	MOS72050
9CA8 0833	3206		LDAR R3,R3	HAVE ALL SUSPECT CHIPS BEEN PRINTED?	MOS72060
9CAA 4230 9C80	3207		BNZ C03	NO, BRANCH	MOS72070
9CAE D100 9DD0	3208		LH RO,MOSSAVE	YES, RESTORE REGISTERS AND	MOS72080
9CB2 43C0 9BDC	3209		B ERROR1	GO PRINT ERROR DATA	MOS72090
	3210 *				MOS72100
	3211 * *****				MOS72110
	3212 * END COMMON ERROR ROUTINE				MOS72120

CHKSUM FILE

		3214 *				
		3215 *	TEST MESSAGES			MOS72140
		3216 *				MOS72150
9CB6	4153 5349 474E 4544	3217 ASMEMMSG DC	C'ASSIGNED MEMORY ',X'0DOA'			MOS72160
9CBE	204D 454D 4F52 5920					MOS72170
9CC6	0DCA					
9CC8	4C4F 4C49 4D20 3E20	3218 HIL0MSG DC	C'LOLIM > HILIM IS ILLEGAL',X'0DOA'			MCS72180
9CDC	4849 4C49 4D20 4953					
9CD8	2049 4C4C 4547 414C					
9CE0	0DCA					
9CE2	494C 4C45 4741 4C20	3219 TSTPBJ DC	C'ILLEGAL TEST SEQUENCE ',X'0DOA'			MCS72190
9CEA	5445 5354 2053 4551					
9CF2	5545 4E43 4520					
9CF8	0DCA					
9CFA	5355 5350 4543 5445	3220 CHIPMSG DC	C'SUSPECTED BAD CHIP NUMBER '			MOS72200
9D02	4420 4241 4420 4348					
9D0A	4950 204E 554D 4245					
9D12	5220					
9D14	4130 2A2A	3221 CHIPNO DC	C'A0**',X'0DOA'			MOS72210
9D18	0DCA					
9D1A	4C4F 4320	3222 ERRORMSG DC	C'LOC '			MOS72220
		3223 *				MOS72230
9D1E	2A2A 2A2A 2A20 2044	3224 ADRMSG DC	C***** DATA EXP '			MOS72240
9D26	4154 4120 4558 5020					
9D2E	2A2A 2A2A 2020 4441	3225 DTAEXP DC	C***** DATA READ '			MOS72250
9D36	5441 2052 4541 4420					
9D3E	2A2A 2A2A 2020 5053	3226 DTARED DC	C***** PSW = '			MOS72260
9D46	5720 3E20					
9D4A	2A2A 2A2A	3227 DTAPSW DC	C*****',X'0DOA'			MOS72270
9D4E	0DCA					
9D50	4D45 4D4F 5259 2055	3228 T6MSG DC	C'MEMORY UNDER GALPAT TEST',X'0DOA'			MOS72280
9D58	4E44 4552 2047 414C					
9D60	5041 5420 5445 5354					
9D68	0DCA					
9D6A	3030 3030 302D 3037	3229 LOMSG DC	C'00000-07FFF ',X'0DOA'			MOS72290
9D72	4646 4620					
9D76	0DCA					
	0000 9D70	3230 HIMSG EQU	LOMSG+6			MOS72300
		3231 *				MOS72310
9D78	504F 5745 5220 444F	3232 T7MSG DC	C'POWER DOWN PROCESSOR FOR 30 SECONDS ',X'0DOA'			MOS72320
9D80	574E 2050 524F 4345					
9D88	5353 4F52 2046 4F52					
9D90	2033 3020 5345 434F					
9D98	4E44 5320					
9D9C	0DOA					
9D9E	4849 4C49 4D20 2D20	3233 T8LCMSG DC	C'HILIM - LOLIM IS < REQUIRED ',X'0DOA'			MOS72330
9DA6	4C4F 4C49 4D20 4953					
9DAE	203C 2052 4551 5549					
9DB6	5245 4420					
9DBA	0DCA					
		3234 * *****				MOS72340
		3235 * END TEST MESSAGE FILE				MOS72350
	0000 9DBB	3236 LN2B EQU	**-1			MOS72360

CHKSUM FILE

	3238	*		MOS72380
	3239	*	TEST PROGRAM STORAGE AREA	MOS72390
	3240	*		MOS72400
	3241	*	*****	MOS72410
	3242	*		MOS72420
9DBC	3243	CPTBUF	DS 6	OPTION INPUT BUFFER
9DC2	3244	VLOLIM	DS 2	VIRTUAL LOW LIMIT
9DC4	3245	VLHILIM	DS 2	VIRTUAL HIGH LIMIT
	3246	*		MOS72460
	3247	*	*****	MOS72470
	3248	*		MOS72480
9DC8	3249		ALIGN 8	MOS72490
	3250	*		MOS72500
9DC8	3251	PSWSAVE	DS 8	PPF REGISTER SAVE AREA
9DD0	3252	MOSSAVE	DS 64	S16MMT REGISTER SAVE AREA
9E10	3253	ERRSAVE	DS 32	REG STORAGE FOR ERROR ROUTINES
9E30	3254	MMSAVE	DS 32	T7 MM REGISTER SAVE AREA
9E50	3255	RSAVE	DS 160	REGISTER SAVE AREA
9EFO	3256		DB *	MOS72560
	3257	*	*****	MOS72570
	3258	*	END TEST PROGRAM 06-214F02R00 PART 2 SECTION 2	*** MOS72580

CHKSUM/M17 PUNCHER

9EF0	2400		3260	SCHKSUM	LIS	R0,0	PUNCH M17 TAPE WITH CHECKSUM	MOS72600
9EF2	9510		3261		EPSR	R1,R0	SELECT REG. SET 0 & CLEAR PSW	MOS72610
			3262	*				MOS72620
9EF4	C810 8000		3263		LDAI	R1,ORIGIN1	LOAD START ADDRESS	MOS72630
9EF8	2421		3264		LIS	R2,1	LOAD INCREMENT VALUE	MOS72640
9EFA	C830 9DBB		3265		LDAI	R3,LNZB	LOAD FINAL ADDRESS	MOS72650
9EFE	2440		3266		LIS	R4,0	INITIALIZE CHKSUM BYTE	MOS72660
			3267	*				MOS72670
9F00	D351 0000		3268	SGEN	LB	R5,0(R1)		MOS72680
9F04	0745		3269		XAR	R4,R5	CALCULATE CHKSUM BYTE	MOS72690
9F06	C110 9F00		3270		BXLE	R1,SGEN		MOS72700
9F0A	D240 0099		3271		STB	R4,NN+3	CHECKSUM BYTE TO BOOT LOADER	MOS72710
			3272	*				MOS72720
9F0E	C810 0080		3273	STAPE	LDAI	R1,X'0080'		MOS72730
9F12	9E21		3274		OCR	R2,R1	DISPLAY IN NORMAL MODE	MOS72740
9F14	9444		3275		EXBR	R4,R4		MOS72750
9F16	9824		3276		WHR	R2,R4	DISPLAY CHKSUM BYTE (TO D1)	MOS72760
9F18	9411		3277		EXBR	R1,R1		MOS72770
9F1A	95C1		3278		EPSR	R0,R1	HALT PROCESSOR	MOS72780
			3279	*				MOS72790
			3280	-----				MOS72800
			3281	*				MOS72810
9F1C	D360 007A		3282	SPUNCH	LB	R6,X'7A'	GET BOUTDV (PUNCH) ADDRESS.	MOS72820
9F20	DE60 007B		3283		OC	R6,X'7B'	START TAPE PUNCH	MOS72830
9F24	9D60		3284		SSR	R6,R0		MOS72840
9F26	2081		3285		BTBS	8,1		MOS72850
9F28	41F0 9F6A		3286		BAL	R15,STAPL	PUNCH LEADER	MOS72860
9F2C	9411		3287		EXBR	R1,R1	(R1) = X'0080'	MOS72870
9F2E	C830 00CF		3288		LDAI	R3,X'CF'		MOS72880
			3289	*				MOS72890
9F32	DA61 0000		3290	SPNCH1	WD	R6,0(R1)	PUNCH BOOT LOADER	MOS72900
9F36	9C60		3291		SSR	R6,R0		MOS72910
9F38	2081		3292		BTBS	8,1		MOS72920
9F3A	C110 9F32		3293		BXLE	R1,SPNCH1		MOS72930
9F3E	41F0 9F70		3294		BAL	R15,STAPL1	PUNCH ONE-FOLD GAP.	MOS72940
			3295	*				MOS72950
9F42	D340 0099		3296		LB	R4,NN+3	GET CHECKSUM BYTE	MOS72960
9F46	C810 8000		3297		LDAI	R1,ORIGIN1	(NORMALLY X'A00')	MOS72970
9F4A	C830 9DBB		3298		LDAI	R3,LNZB		MOS72980
			3299	*				MOS72990
9F4E	D351 0000		3300	SPNCH2	LB	R5,0(R1)	PUNCH PROGRAM	MOS73000
9F52	0745		3301		XAR	R4,R5		MOS73010
9F54	9A65		3302		WDR	R6,R5		MOS73020
9F56	9401		3303		EXBR	R0,R1		MOS73030
9F58	9820		3304		WHR	R2,R0	DATA ADDRESS TO DISPLAY.	MOS73040
9F5A	9D60		3305		SSR	R6,R0		MOS73050
9F5C	2081		3306		BTBS	8,1		MOS73060
9F5E	C110 9F4E		3307		BXLE	R1,SPNCH2		MOS73070
9F62	41F0 9F6A		3308		BAL	R15,STAPL	PUNCH TRAILER.	MOS73080
9F66	4300 9F0E		3309	B	STAPE		DISPLAY CHECKSUM, HALT PROCESSOR.	MOS73090

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3311 * SCHKSUM/M17 PUNCHER (CONTINUED)

3312 *				MOS73110
3313 *				MOS73120
9F6A C800 0100	3314 STAPL	LDAI	R0,256	MOS73130
9F6E 2303	3315	BS	STAPLP	MOS73140
	3316 *			MOS73150
9F70 C800 0080	3317 STAPL1	LDAI	R0,128	MOS73160
	3318 *			MOS73170
9F74 2701	3319 STAPLP	SIS	R0,1	MOS73180
9F76 032F	3320	BNPR	R15	MOS73190
9F78 2430	3321	LIS	R3,0	MOS73200
9F7A 9A63	3322	WDR	R6,R3	MOS73210
9F7C 9D68	3323	SSR	R6,R8	MOS73220
9F7E 2081	3324	BTBS	8,1	MOS73230
9F80 2206	3325	BS	STAPLP	MOS73240
	3326 *			MOS73250
9F82	3327 *			MOS73260
	3328 END			MOS73270
				MOS73280

ASSEMBLED BY CAL 03-066R05-01 (32-BIT)

START OPTIONS: T=16,CROSS,ERLST,

NO CAL ERRORS

NO CAL WARNINGS

2 PASSES

\$CHKSUM	0000 9EF0	3260*				
\$DEC1	0000 8628	725*	739			
\$DEC2	0000 862E	727*	732	734		
\$DEC3	0000 8640	728	735*			
\$GEN	0000 9F00	3268*	3270			
\$PNCH 1	0000 9F32	3290*	3293			
\$PNCH 2	0000 9F4E	3300*	3307			
\$PUNCH	0000 9F1C	3282*				
\$TAPE	0000 9F0E	3273*	3309			
\$TAPL	0000 9F6A	3286	3308	3314*		
\$TAPL1	0000 9F70	3294	3317*			
\$TAPLP	0000 9F74	3315	3319*	3325		
\$STDUO	0000 8864	934	936*			
\$STDU1	0000 8882	946*				
\$STDU2	0000 8884	943	945	947*		
ABORT	0000 83E8	501*				
ABORT 1	0000 842A	520*	3169			
ABORT 2	0000 8468	543*				
ABORT 3	0000 8432	513	523*			
ABSTOP	0000 9F82					
ADC	0000 0002	724	738	882	889	926
ADRMMSG	0000 9D1E	3140	3154	3224*		
AMSG	0000 8A98	216	1161*			
ASCILOC	0000 8A82	643	1158*			
ASCIPSW	0000 8A78	640	1156*			
ASHEMMMSG	0000 9CB6	1324	3217*			
BGTST	0000 9128	1912*				
BGTST 1	0000 914E	1923	1925*	1928		
BGTST 2	0000 9156	1928*	1932			
BGTST 2.5	0000 915C	1927	1931*			
BGTST 3	0000 9162	1921	1929	1934*		
BGTST 4	0000 917A	1941	1943*	1946		
BGTST 5	0000 9182	1946*	1950			
BGTST 5.5	0000 9188	1945	1949*			
BGTST 6	0000 918E	1939	1947	1952*		
BGTST 7	0000 9196	1954*				
BOOT	0000 0088	91	94*			
BRK.SAV	0000 8A26	883	890	923	927	1138*
BRKMSG	0000 8A9A	1162*	1255			
BRKVECT	0000 8A0A	885	921	925	1123*	2247
BTESTNO	0000 8A1A	442	455	472	495	551
C300ADR	0000 8018	141*				
CAR2ND	0000 8A00	1112*				
CARRD	0000 89F4	1103*				
CARRQ2S	0000 8A08	1119*				
CHIPMSG	0000 9CFA	3201	3220*			
CHIPNO	0000 9D14	3181	3183	3189	3199	3221*

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CHKCOL	0000 8F14	1688	1691	1694	1698*
CHKCOL1	0000 8F28	1702	1704*	1709	
CHKCOL2	0000 8F32	1706	1708*		
CHKCOL25	0000 8F36	1709*			
CHKCOL3	0000 8F48	1712	1715*	1745	
CHKCOL4	0000 8F5E	1720	1722*		
CHKCOL5	0000 8F68	1725*	1793		
CHKCOL5F	0000 9042	1724	1792*		
CHKCOL6	0000 8F7E	1731*	1796		
CHKCOL16F	0000 904A	1730	1795*		
CHKCOL7	0000 8F98	1738*	1793		
CHKCOL7F	0000 9052	1737	1798*		
CHKCOL8	0000 8FB2	1745*	1802		
CHKCOL8F	0000 905A	1744	1801*		
CHKCOL9	0000 8FCE	1751	1754*	1783	
CHKCOLA	0000 8FD8	1756	1758*		
CHKCOLB	0000 8FEE	1764*	1805		
CHKCOLBF	0000 9062	1763	1804*		
CHKCOLC	0000 9004	1770*	1808		
CHKCOLCF	0000 906A	1769	1807*		
CHKCOLD	0000 901C	1777*	1787		
CHKCOLDF	0000 9036	1776	1786*		
CHKCOLE	0000 9030	1783*	1790		
CHKCOLEF	0000 903C	1782	1789*		
CHKLOC	0000 8D58	1448	1452	1455	1459
CHKLOC1	0000 8E62	1476*			1462
CHKLOC10	0000 8E22	1531	1541*	1549	
CHKLOC1F	0000 8E2E	1540	1548*		
CHKLOC2	0000 8E76	1481	1483*		
CHKLOC25	0000 8D7A	1484*			
CHKLOC3	0000 8D82	1487*			
CHKLOC4	0000 8DA2	1495	1497*		
CHKLOC5	0000 8DAA	1500*	1510		
CHKLOC5F	0000 8DC4	1499	1509*		
CHKLOC6	0000 8DBE	1506*	1513		
CHKLOC6A	0000 8DD0	1507	1515*		
CHKLOC6F	0000 8DCA	1505	1512*		
CHKLOC7	0000 8DE8	1520	1523*	1541	
CHKLOC8	0000 8DF2	1525	1527*		
CHKLOC9	0000 8E0E	1535*	1546		
CHKLOC9F	0000 8E28	1534	1545*		
CKBG60	0000 9324	2146*			
CKBG61	0000 933A	2153*	2160		
CKBG62	0000 9344	2155	2157*		
CKBG63	0000 934C	2160*	2164		
CKBG64	0000 9352	2159	2163*		
CKBG65	0000 9358	2161	2166*		
CLIF2ND	0000 89FC	1110*			
CLIFADR	0000 8914	139*			
CLIFRD	0000 89F0	1101*			
CLKCOL	0000 9A42	2990	2993	2996	3000*
CLKCOL1	0000 9A56	3004	3006*	3011	
CLKCOL2	0000 9A60	3008	3010*		
CLKCOL25	0000 9A64	3011*			
CLKCOL3	0000 9A76	3014	3017*	3047	

CLKCOL4	0000 9A8C	3022	3024*
CLKCOL5	0000 9A96	3027*	3095
CLKCOL5F	0000 9B70	3026	3094*
CLKCOL6	0000 9AAC	3033*	3098
CLKCOL6F	0000 9B78	3032	3097*
CLKCOL7	0000 9AC6	3040*	3101
CLKCOL7F	0000 9B80	3039	3100*
CLKCOL8	0000 9AE0	3047*	3104
CLKCOL8F	0000 9B88	3046	3103*
CLKCOL9	0000 9AFC	3053	3056* 3085
CLKCOLA	0000 9B06	3058	3060*
CLKCOLB	0000 9B1C	3066*	3107
CLKCOLBF	0000 9B90	3065	3106*
CLKCOLC	0000 9B32	3072*	3110
CLKCOLCF	0000 9B98	3071	3109*
CLKCOLD	0000 9B4A	3079*	3089
CLKCOLDF	0000 9B64	3078	3088*
CLKCOLE	0000 9B5E	3085*	3092
CLKCOLEF	0000 9B6A	3084	3091*
CLKLOC	0000 9950	2853	2857 2860 2864 2867 2871 2877*
CLKLOC1	0000 9964	2881	2884* 2889
CLKLOC10	0000 9A12	2944*	2952
CLKLOC1F	0000 9A1E	2943	2951*
CLKLOC2	0000 996E	2886	2888*
CLKLOC25	0000 9972	2889*	
CLKLOC3	0000 9984	2892	2895* 2911
CLKLOC4	0000 999A	2900	2902*
CLKLOC5	0000 99A2	2905*	2915
CLKLOC5F	0000 99BC	2904	2914*
CLKLOC6	0000 99B6	2911*	2918
CLKLOC6A	0000 99C8	2912	2920*
CLKLOC6F	0000 99C2	2910	2917*
CLKLOC7	0000 99E0	2925	2928* 2944
CLKLOC8	0000 99EA	2930	2932*
CLKLOC9	0000 99FE	2938*	2949
CLKLOC9F	0000 9A18	2937	2948*
C03	0000 9C80	3187	3192* 3197 3207
C04	0000 9C8C	3194	3198*
C05	0000 9C96	3191	3201*
COMM	0000 8904	1005*	1022
COMM1	0000 890C	1007*	1080
COMRET	0000 8A22	610	617 1136*
CON	0000 8B46	1175	1190*
CON2ND	0000 89F8	177	186 187 1062 1106* 1107 1108 2273
CONADR	0000 89EA	183	862 891 961 1096*
CONENRD	0000 89F9	1108*	
CONRD	0000 89EC	184	185 197 859 962 1063 1097* 1098 2274
CONRQ2S	0000 8A04	171	189 190 967 1115*
CONSOLE	0000 8B08	1175*	
CONTIN	0000 8ACC	512	919 1170*
CONWRT	0000 89ED	976	1098* 1099
COUNT	0000 8A1C	469	484 486 1132*
CRLF	0000 86DE	204	212 287 329 355 408 425 565 797* 871
CRT2ND	0000 89FA	1109*	
CRTRD	0000 89EE	1100*	

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		2907	2940	2986	3029	3068	3081	3139	3142	3145	3148	3152	3153	3185
		3195	3196	3261	3263	3268	3270	3273	3274	3277	3277	3278	3287	3287
		3290	3293	3297	3300	3303	3307							
R10	0000 000A	65*	1029	1030	1031	1036	1036	1037	1043	1445	1450	1457	1464	1479
		1493	1526	1585	1704	1718	1757	1855	1959	1960	1966	1967	1980	2049
		2054	2061	2068	2083	2103	2113	2131	2153	2217	2224	2307	2373	2481
		2555	2560	2567	2574	2589	2603	2636	2692	2711	2725	2764	2850	2855
R11	0000 000B	2852	2869	2884	2898	2931	2987	3006	3020	3059				
		67*	1446	1451	1458	1465	1482	1496	1523	1686	1707	1721	1754	1856
		1962	1963	1969	1970	1983	2050	2055	2062	2069	2086	2100	2116	2134
		2156	2213	2225	2312	2374	2405	2406	2419	2420	2437	2459	2501	2556
		2561	2563	2575	2592	2606	2633	2693	2714	2728	2761	2851	2856	2863
R12	0000 000C	2870	2887	2901	2928	2988	3009	3023	3055					
		68*	220	238	247	258	368	371	382	399	418	658	1214	1224
		1606	1608	1613	1893	1917	1934	1973	2048	2127	2141	2219	2226	2318
		2477	2512											
R13	0000 000D	69*	1216	1218	1220	1222	1241	1447	1454	1461	1480	1494	1524	1604
		1614	1635	1644	1587	1690	1693	1705	1719	1755	1908	1975	1990	1992
		2051	2058	2065	2084	2101	2114	2132	2154	2220	2227	2324	2557	2564
		2571	2590	2604	2634	2694	2697	2700	2712	2726	2762	2852	2859	2866
R14	0000 000E	2885	2899	2929	2989	2992	2995	3007	3021	3057				
		70*	276	286	322	369	372	374	397	400	669	672	678	1005
		1020	1026	1026	1029	1040	1042	1043	1044	1195	1196	1197	1198	1200
		1203	1225	1448	1452	1455	1459	1462	1466	1543	1688	1691	1694	1784
		1871	1883	1901	1902	1955	2052	2056	2059	2063	2066	2070	2173	2241
		2249	2255	2256	2257	2257	2258	2259	2260	2265	2266	2268	2270	2271
		2271	2272	2273	2277	2278	2280	2282	2284	2286	2287	2288	2290	2291
		2296	2334	2415	2513	2558	2562	2565	2569	2572	2576	2651	2695	2698
		2701	2791	2853	2857	2860	2864	2867	2871	2946	2990	2993	2996	3086
		3124	3124	3125	3126	3148								
R15	0000 000F	72*	198	206	227	374	383	409	410	411	529	530	652	653
		654	656	660	661	695	803	921	923	1006	1021	1041	1045	3115
R2	0000 0002	3116	3286	3294	3308	3320								
		58*	90	110	116	154	156	161	166	168	170	171	175	175
		176	177	184	185	186	187	195	195	196	213	214	282	283
		288	289	291	292	298	301	301	323	331	333	335	340	357
		358	447	450	453	455	456	457	458	460	462	463	472	473
		474	557	599	603	604	610	615	616	617	618	640	643	687
		688	690	692	696	711	712	736	737	751	898	899	901	906
		910	913	913	983	1008	1016	1017	1018	1019	1027	1028	1038	1039
		1050	1054	1055	1057	1061	1062	1063	1064	1072	1073	1076	1077	1078
		1234	1235	1316	1319	1858	1863	1875	1879	1897	1898	1899	1900	1915
		1953	2035	2039	2046	2126	2140	2242	2244	2382	2395	2396	2397	2398
		2399	2400	2401	2402	2403	2404	2410	2421	2422	2423	2424	2425	2426
		2427	2428	2429	2430	2438	2461	2463	2470	2499	3140	3143	3146	3149
R3	0000 0003	3154	3199	3264	3274	3276	3304							
		59*	95	96	97	162	163	166	182	183	192	192	196	197
		198	255	259	263	265	285	298	323	332	336	401	572	575
		676	679	679	704	705	706	708	713	722	723	724	726	738
		764	766	984	990	991	1215	1217	1219	1221	1231	1237	1364	1369
		1380	1384	1393	1479	1482	1483	1493	1496	1498	1500	1501	1504	1523
		1526	1533	1535	1536	1539	1590	1595	1607	1608	1609	1611	1618	1627
		1637	1639	1641	1643	1704	1707	1708	1718	1721	1723	1725	1726	1729
		1731	1732	1736	1738	1739	1743	1754	1757	1762	1764	1765	1768	1770
		1771	1775	1777	1778	1781	1915	1926	1944	1980	1983	2083	2086	2087

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		2100	2103	2104	2108	2110	2113	2116	2118	2120	2131	2134	2135	2153
		2156	2158	2307	2309	2312	2315	2318	2321	2324	2327	2445	2448	2450
		2452	2464	2466	2468	2478	2488	2504	2589	2592	2593	2603	2606	2608
		2610	2611	2614	2633	2636	2641	2643	2644	2647	2711	2714	2715	2725
		2728	2730	2732	2733	2736	2738	2739	2743	2745	2746	2750	2761	2764
		2769	2771	2772	2775	2777	2778	2782	2784	2785	2788	2884	2887	2888
		2898	2901	2903	2905	2906	2909	2928	2931	2936	2938	2939	2942	3006
		3009	3010	3020	3023	3025	3027	3028	3031	3033	3034	3038	3040	3041
		3045	3056	3059	3064	3066	3067	3070	3072	3073	3077	3079	3080	3083
		3142	3184	3186	3190	3192	3192	3206	3206	3265	3288	3298	3321	3322
R4	0000 0004	60*	99	100	101	103	111	113	189	190	191	193	193	216
		218	228	230	231	233	235	242	244	248	274	279	289	294
		299	300	303	306	311	313	314	314	316	317	318	319	333
		338	351	353	367	370	388	402	573	654	662	664	668	670
		691	692	693	694	694	707	708	709	710	710	711	725	730
		731	733	735	735	736	760	761	762	763	774	776	780	785
		787	798	836	851	853	855	865	866	968	986	989	992	993
		994	998	1236	1237	1371	1372	1379	1380	1402	1443	1444	1490	1491
		1497	1498	1503	1504	1527	1528	1532	1533	1538	1539	1588	1589	1598
		1599	1610	1611	1640	1641	1715	1716	1722	1723	1728	1729	1733	1734
		1735	1736	1740	1741	1742	1743	1758	1759	1761	1762	1767	1768	1772
		1773	1774	1775	1780	1781	1903	1905	1913	1914	1925	1926	1943	1944
		1985	1986	1987	2105	2106	2107	2108	2117	2118	2150	2151	2157	2158
		2260	2272	2273	2274	2275	2283	2284	2286	2287	2288	2292	2293	2294
		2295	2297	2298	2308	2309	2314	2315	2320	2321	2326	2327	2408	2409
		2413	2414	2432	2433	2446	2449	2450	2459	2460	2461	2465	2466	2479
		2480	2487	2488	2503	2504	2553	2554	2600	2601	2607	2608	2613	2614
		2637	2638	2640	2641	2646	2647	2722	2723	2729	2730	2735	2736	2740
		2741	2742	2743	2747	2748	2749	2750	2765	2766	2768	2769	2774	2775
		2779	2780	2781	2782	2787	2788	2848	2849	2895	2896	2902	2903	2908
		2909	2932	2933	2935	2936	2941	2942	3017	3018	3024	3025	3030	3031
		3035	3036	3037	3038	3042	3043	3044	3045	3060	3061	3063	3064	3069
		3070	3074	3075	3076	3077	3082	3083	3145	3184	3188	3189	3266	3269
		3271	3275	3275	3276	3296	3301							
R5	0000 0005	61*	101	103	104	104	106	107	108	111	113	119	205	257
		259	296	297	309	309	321	321	324	340	394	398	465	493
		526	527	566	567	570	578	631	645	691	726	727	729	774
		778	873	1244	1247	1249	1255	1324	1326	1857	1866	1868	1918	1935
		1965	1972	1991	2041	2043	2229	2230	2231	2232	2233	2233	2234	2235
		2236	2237	2239	2240	2380	2386	2436	2478	2518	3156	3157	3158	3159
		3161	3162	3180	3181	3182	3183	3201	3202	3204	3205	3268	3269	3300
		3301	3302											
R5HEX	0000 85CC	342	571	579	686*									
R5X	0000 85DA	691*	697											
R5XA	0000 85E8	695*												
R5XB	0000 85F0	689	698*											
R6	0000 0006	62*	98	108	115	171	172	173	173	256	257	264	277	281
		330	346	347	349	376	381	398	651	659	660	666	677	680
		1228	1231	1232	1233	1234	1236	1240	1310	1311	1315	1360	1366	1368
		1369	1370	1373	1375	1377	1379	1382	1383	1390	1392	1393	1394	1396
		1398	1400	1402	1404	1472	1476	1478	1480	1483	1484	1485	1487	1489
		1494	1497	1501	1503	1506	1515	1516	1524	1530	1532	1536	1538	1541
		1585	1592	1594	1595	1596	1597	1601	1603	1609	1610	1616	1617	1624
		1626	1627	1628	1629	1632	1634	1639	1640	1646	1698	1701	1703	1705
		1708	1709	1710	1711	1713	1719	1722	1726	1728	1732	1735	1739	1742

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SINK	0000 89E4	863	939	947	963	1064	1089*	2275
ST	0000 8022	154*						
START	0000 8032	154	160*					
START2	0000 801E	123	153*					
STLOOP	0000 919C	1857	1897	1899	1901	1959*		
STORE10	0000 8CDE	1385	1390*					
STORE11	0000 8C98	1366*						
STORE30	0000 8FA6	1619	1624*					
STORE31	0000 8E4A	1592*						
T1.1	0000 8CA2	1367	1369*	1370				
T1.11	0000 8CC0	1376	1378*	1382				
T1.2	0000 8CE8	1391	1393*	1394				
T1.21	0000 8D02	1399	1401*	1404				
T2.1	0000 8D6C	1477	1479*	1484				
T2.2	0000 8D8C	1488	1490*	1506				
T3.1	0000 8E54	1593	1595*	1596				
T3.2	0000 8EB0	1625	1627*	1628				
T3.3	0000 8ECA	1633	1635*	1646				
T3S0	0000 8E58	1596*						
T3S1	0000 8E72	1602	1604*	1616				
T3S2	0000 8E7E	1607*	1615					
T3S3	0000 8E8E	1613*	1622					
T3S3.4	0000 8E94	1616*						
T3S3.6	0000 8EB4	1628*						
T3S3F	0000 8EA0	1612	1621*					
T3S4	0000 8EC0	1632*						
T3S5	0000 8ED6	1639*	1645					
T3S6	0000 8EE2	1643*	1651					
T3S6F	0000 8EF0	1642	1650*					
T3S7	0000 8EE8	1646*						
T5S1	0000 909A	1861	1863*	1864				
T5S1.5	0000 909E	1864*						
T5S2	0000 90CE	1877	1879*	1880				
T5S2.5	0000 90D2	1880*						
T6ER10	0000 9370	2109	2175*					
T6ER11	0000 9378	2119	2178*					
T6MSG	0000 9D50	2041	3228*					
T6S1	0000 927E	2081	2083*	2088				
T6S10	0000 92EC	2120*	2179					
T6S2	0000 9288	2085	2087*					
T6S2.5	0000 928C	2088*						
T6S3	0000 9290	2090*						
T6S4	0000 9292	2091*	2172					
T6S5	0000 9294	2092*	2142					
T6S6	0000 9296	2093*	2128					
T6S7	0000 92B8	2102	2104*					
T6S8	0000 92CE	2110*	2176					
T6S9	0000 92E2	2115	2117*					
T7END	0000 94E1	2246	2331	2336*				
T7MM1	0000 9402	2229	2255*	2261				
T7MM2	0000 9418	2255	2265*					
T7MM2A	0000 9426	2267	2270*					
T7MM3	0000 943C	2269	2277*					
T7MM3A	0000 944A	2279	2282*					
T7MMCCM	0000 9462	2281	2285	2290*				

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